

Enclosure 1

**General Atomics-Electronic Systems Inc. Report
25402-011-V1A-HARA-00266-001 General Atomics HARA,**

"RM-1000 EMC Test Report, TVA (Non-Prop)"

dated November 11, 1999

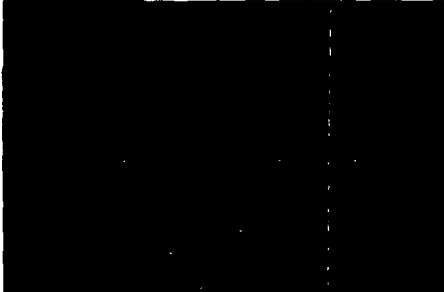
Non-Proprietary

REVISIONS

REV	DESCRIPTION	DATE	APPROVED
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25402-011-V1A-HARA-00266-001
 General Atomics HARA
 RM-1000 EMC Test Report, TVA (Non-Prop)

DOCUMENT
 CLASSIFICATION
 CHANGE



BECHTEL POWER CORPORATION		Job Number: 25402									
SUPPLIER DOCUMENT REVIEW STATUS											
STATUS CODE:											
1	<input type="checkbox"/>	Work may proceed.	3 <input type="checkbox"/> Rejected. Revise and resubmit.								
1C	<input type="checkbox"/>	Work may proceed. Editorial comments need only be incorporated if revised for other purposes.	4 <input checked="" type="checkbox"/> Review not required. Work may proceed.								
2	<input type="checkbox"/>	Revise and resubmit. Work may proceed subject to incorporation of changes indicated.	PO 77469-77448								
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	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	N/A	
Status By:	Joe Temples <i>Joe Temples</i>						DATE	11/23/99			

SHEET	29	30	31	32	33	34	35	36	37	38	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54	55	56	
REV																													
SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	
REV																													



DRAWN	J. MEISNER	DATE	11-11-99				
CHECKED				RM-1000 EMC TEST REPORT, TVA			
ENGR	<i>John Meisner</i>	DATE	11-11-99				
ENGR REV	<i>W. Wong</i>	DATE	11-11-99				
PROJ MGR	<i>W. Newman</i>	DATE	11-11-99	SIZE	FSCM NO.	DRAWING NO.	REV
MFG ENGR				A	58307	04038800	—
QUAL MGR	<i>C.M. Miller</i>	DATE	11-11-99	RELEASE	<i>apennoni 11/11/99</i>		SHEET
ENGR MGR				DRAWING LEVEL	2		1 OF 218

DWG NO. 04038800

RM-1000 EMC TESTING

1. Introduction

This report describes the Electromagnetic Compatibility (EMC) testing specified by Sorrento Electronics (SE) for the RM-1000 radiation monitoring equipment supplied to Tennessee Valley Authority (TVA). Testing reported here was conducted at TÜV Product Services in San Diego, and included requirements for RM-1000 monitor systems of several SE projects. Two series of tests reported here are applicable to the TVA project to replace SE's original supply of analog RP ratemeters with RM-1000 modules.

The first test series was completed from November 4 through November 12, 1997, performed by TÜV's EMC Engineer, [REDACTED]. The second test series took place from November 24 and 25, 1998, performed by TÜV's EMC Engineer, Dave Marshall. Walter Wong, of Sorrento Electronics, was the project engineer for both test series to verify the operational status of the Equipment Under Test (EUT) and maintain the engineering log during testing.

The first test series was the initial effort for the RM-1000 EMC evaluation and was applicable to a process monitor channel, with an RM-1000 and a scintillator detector. The second test series was the primary RM-1000 system test in accordance with the SE EMC Test Plan approved by TVA. This second test included low- and high-range area monitor channels and auxiliary equipment for output devices.

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2. Purpose of EMC Tests

The purpose of the electromagnetic compatibility (EMC) tests was to measure levels of conducted and radiated interference emitted from the EUT and to determine its immunity to external electromagnetic signals and fields. The test results were compared with the specified limits, which were designed to accommodate sets of EMC requirements of several projects. The focus of this report is for compatibility to the specific TVA contract requirements.

The first test series was intended to reveal any unacceptable susceptibility and/or emissions in the RM-1000/detector electronics only. Therefore, this test did not require an entire RM-1000 system. Because the tested RD-33 detector included a preamplifier common to all applicable process detectors, the testing was primarily intended to verify adequate EMC compliance of this component. The RM-1000 detector processing electronics are identical for all process monitors. Once the detector performance was successfully verified in the first test, the second series of area monitor testing is then adequate to prove compliance for the scintillation, process channel as well. Therefore, the second series of testing, with both [REDACTED] [REDACTED], verified EMC compliance of all process and area monitors.

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The remainder of this report will address the second series of testing only. Appendix A includes the TÜV Test Report for the first series of testing.

4. Reference Documents

TVA Standards:

SS E18.14.01 Standard Specification, Electromagnetic Interference (EMI) Testing Requirements for Electronic Devices, Revision 3

IEC Standards:

IEC 1000-4-2 (1995) Electrostatic Discharge
IEC 1000-4-3 (1995) Radiated RF Fields [ENV50140 1993]
IEC 1000-4-4 (1995) Electrical Fast Transmits/Burst
IEC 1000-4-5 (1995) Surge Transients
IEC 1000-4-6 (1996) Conducted RF Disturbance [ENV50141 1993]
IEC 1000-4-11 (1994) Voltage Dips, Interruptions and Variations

EPRI Standards:

EPRI TR-102323 Final Report, Sept. 1994, Guidelines for Electromagnetic Interference Testing in Power Plants

EN Standards:

EN 55011, Class A (1991) Conducted and Radiated Emissions
[EN 50081-2 1995]

MIL Standards:

MIL-STD-461D (1993)
CS-101 Conducted Susceptibility, Power Leads
CE-102 Conducted Emissions, Power Leads

Test Reports (Appendixes to this report):

TÜV Report No. S7439-03 (13Nov1997) RM-1000 Radiation Monitor, Single Channel
TÜV Report No. S8569-02 (11Dec1998) RM-1000 Radiation Monitor, Two Channel

SE Documents:

04509000, Rev A System Installation Configuration, RFI/EMI Test, RM-1000
04509005, Rev A Test Procedure, RM-1000 EMC Emission and Susceptibility
ECO-17656 Engineering Change Order, RM-1000 Product Improvement For EMC

6. Test Configuration

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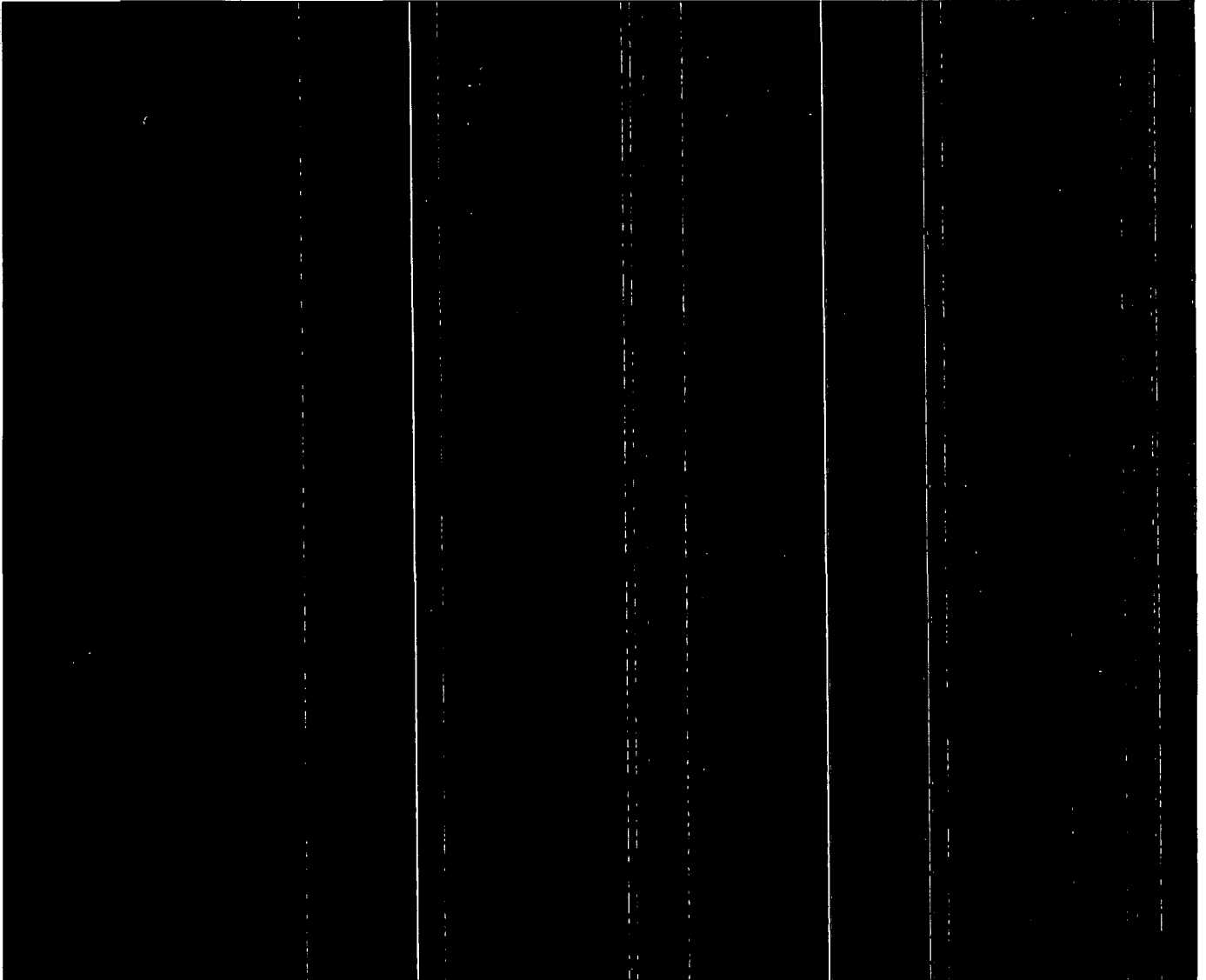


Figure 1. RM-1000 EMC Test Configuration

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The following table provides a description for each EUT input/output (I/O) cable designation.

<u>I/O Cable Designation</u>	<u>I/O Cable Description</u>
[REDACTED]	

All EUT I/O cables were tested for noise susceptibility [REDACTED]. These cables were run [REDACTED].

7. Monitoring of EUT

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A [REDACTED] the operation of the EUT during immunity tests. [REDACTED] the RM-1000 analog outputs and trips.

8. Operational Mode

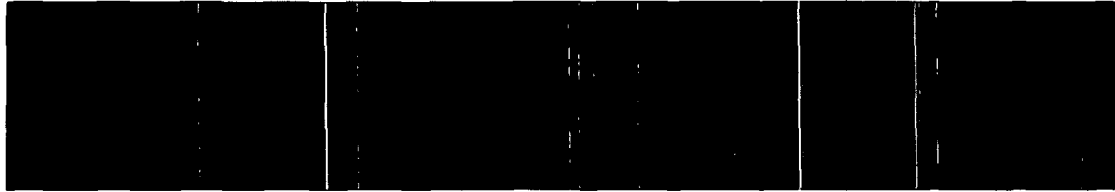
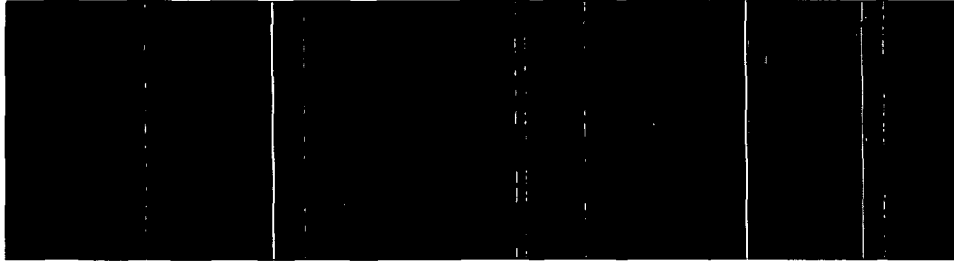
Pre-test and post-test verification of the monitor system was performed to ensure proper operation and to establish baseline data.


The monitor equipment was placed in its normal operational condition prior to EMC testing.

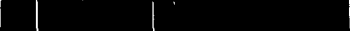
9. System Modifications

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1. Following the tests, the RM-1000 design was modified to provide enhanced EMC performance as follows



2. SE Drawing, 04509000 shows the final test configuration including the location of  to pass specific immunity and emissions testing.

3. After testing, the external RM-1000 24V-power supply 



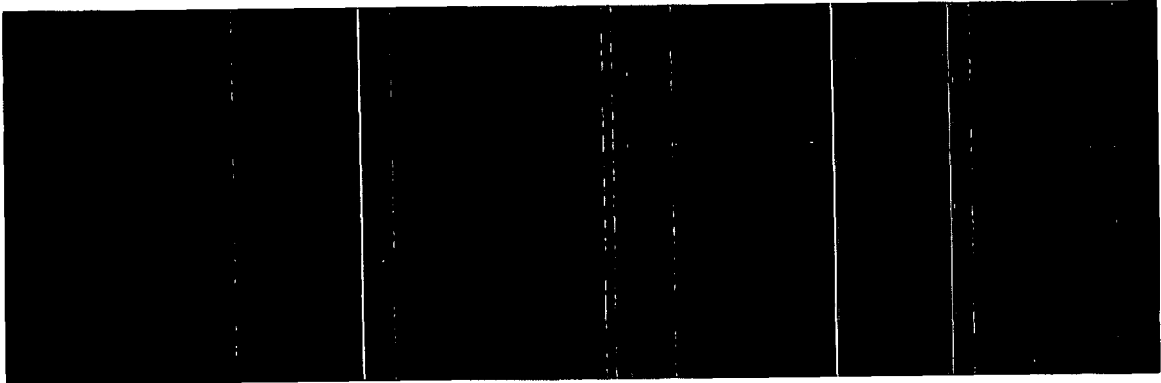
10. Emission Criteria

The acceptance criteria for the EUT was to demonstrate compliance with the applicable conducted and radiated RF emission limits specified in Table 1.

11. Immunity Criteria

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1. Equipment shall not malfunction and shall not have undesired response, degraded performance or permanent damage when subjected to the immunity tests. A malfunction shall be determined to be a loss of safety function, which is the ability to detect an increase in radiation levels, and an undesired response is a false indication of excessive radiation levels.
2. There shall be no High [REDACTED], Alert Alarms ([REDACTED]) or Failure Alarm generated when the system is subjected to the immunity test transients. Additionally, these alarms shall be maintained during immunity testing when they existed prior to the test.
3. There shall be no variation in the Activity Level (cpm or Amps), as determined from the analog output signals, [REDACTED] when the system is subjected to the immunity tests. Based on the baseline data collected (see section 12), the following tabulated pass/fail criteria were applied to the [REDACTED] readings obtained during immunity testing.

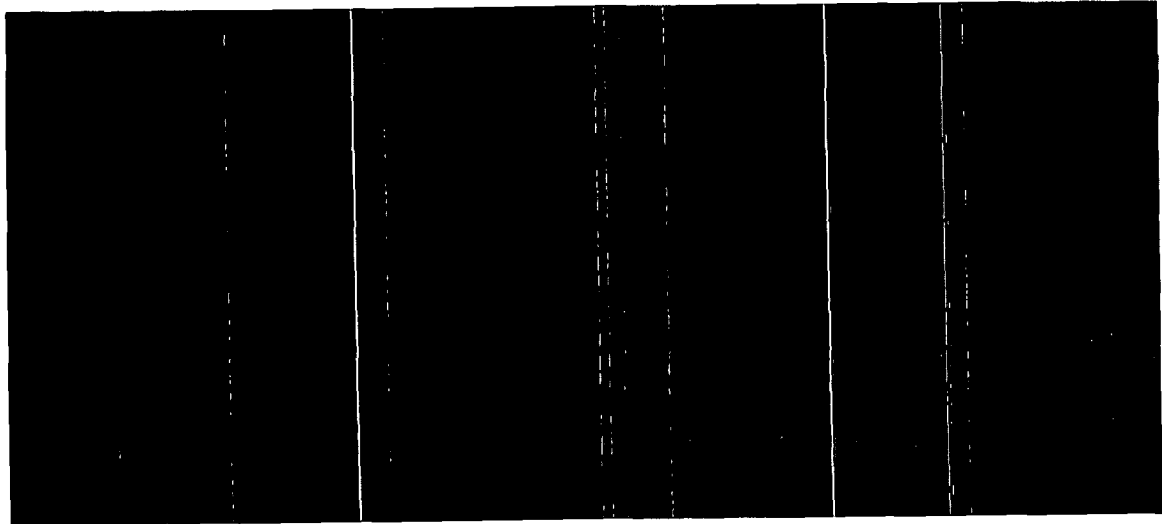


4. Failure of fuses or surge limiting protective devices during the surge immunity test will not be deemed a failure of the EUT.
5. At the conclusion of all testing, the EUT must successfully pass a complete functional test.

12. Test Summary

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1. Tables 2 and 3 provide the test result summaries for the Scintillation detector and [REDACTED] channels.
2. Appendix A provides the TÜV EMC Test Report for the Single Channel [REDACTED] Detector) monitor. Appendix B provides the TÜV EMC Test Report for the Dual Channel Monitor Assembly [REDACTED]
3. Radiated Emission (EN 55011, Class A) Testing:



4. Conducted Emissions (MIL-STD-461D, CE-102) Tests:

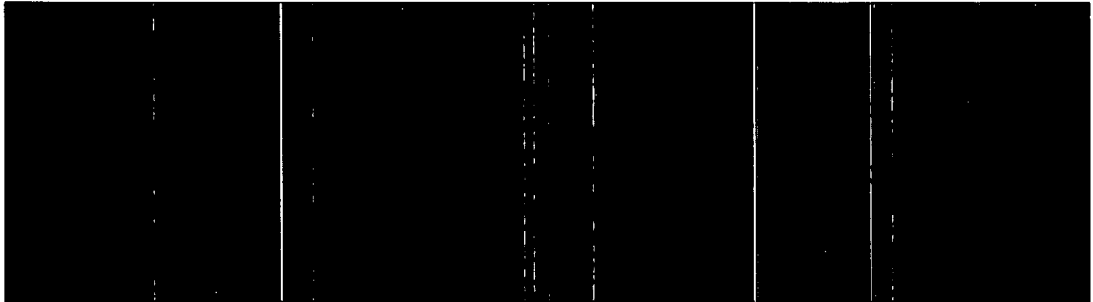


¹ this cable is inside the RM-1000 modules.

5. Immunity Testing (General):

Baseline data was collected prior to EMC testing. The results are as follows:

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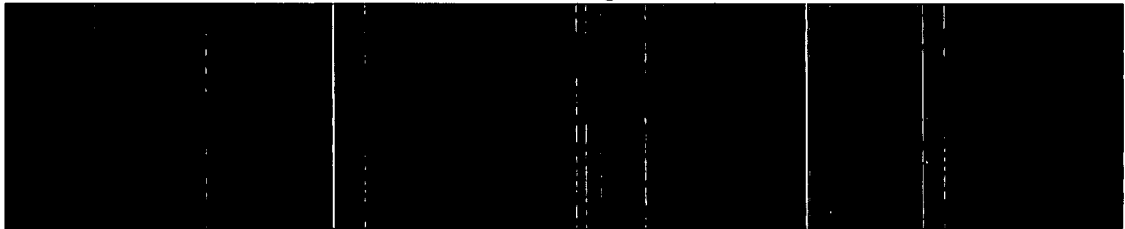
Immunity test pass/fail criteria were applied to these nominal values.

Immunity transients were NOT injected onto the [redacted] cable for the [redacted] module. This module is not part of the EUT.

The [redacted] module was visually monitored during all tests except the Radiated Field Immunity test (IEC 1000-4-3) to verify that the circuitry driving these signals were not upset. Local Indicator meter and alarm trips followed the EUT operation.

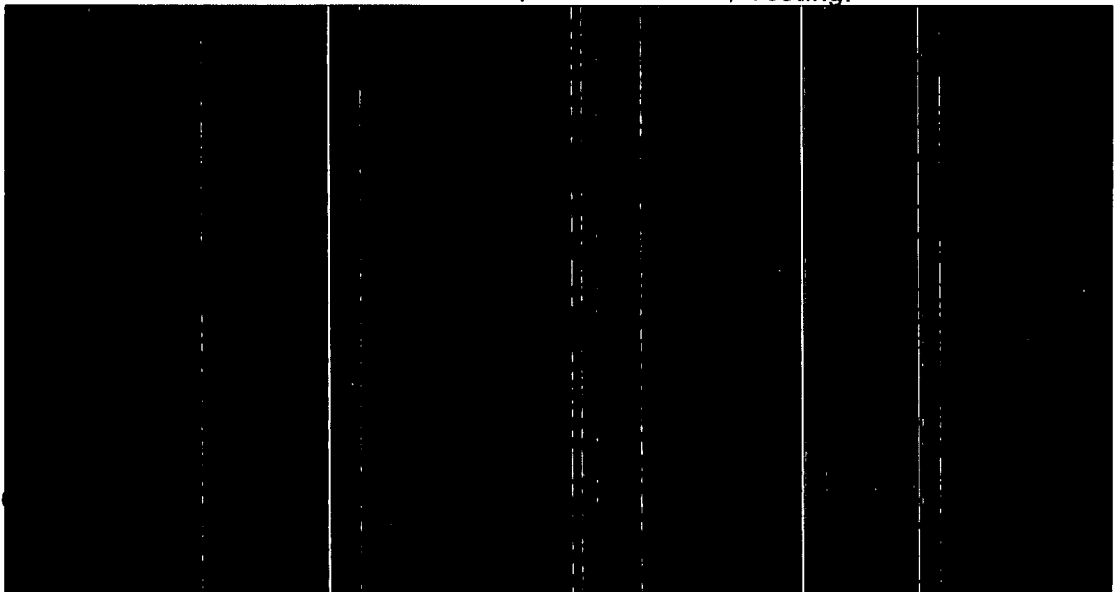
6. Radiated Field Immunity (IEC 1000-4-3) Testing:

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7. HF (High Frequency) Conducted Immunity (IEC 1000-4-6) Testing:

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8. LF (Low Frequency) Conducted Immunity (MIL-STD-461D, CS-101) Testing:

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These tests did not require additional mitigation measures for any cables to pass at [REDACTED]. In fact, the test was passed at [REDACTED] also.

9. Electrical Fast Transient (EFT) Immunity (IEC 1000-4-4) Testing:

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AC Cables: [REDACTED]

I/O Cables: [REDACTED]

[REDACTED]

10. Electrostatic Discharge Immunity (IEC 1000-4-2) Testing:

[REDACTED]

11. Surge Immunity (IEC 1000-4-5) Testing:

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[REDACTED]

12. Voltage Dips, Interruptions and Variations Immunity (IEC 1000-4-11) Testing:

[REDACTED]

13. Conclusion

The RM-1000 monitor system successfully passed all of EMC immunity testing and emission requirements after the modifications cited in Section 8 were implemented.

Table 1 EMC TEST PLAN FOR TVA RM-1000s

TEST TYPE	TEST STANDARD	FREQUENCY RANGE	TEST LEVEL/LIMIT	ANTENNA DISTANCE	ANTENNA TYPE
HF Radiated RF Susceptibility	IEC 1000-4-3 (IEC 801-3)	27 MHz to 80 MHz 80 MHz to 1000 MHz	10 V/meter	3 meters	Biconical Log-periodic
LF Conducted RF Susceptibility	MIL-STD-461D, CS-101	30 Hz to 150 kHz	6.3 V RMS	Not Applicable	Not Applicable
HF Conducted RF Susceptibility	IEC 1000-4-6 (IEC 801-6)	150 kHz to 400 MHz	10 V (emf)	Not Applicable	Not Applicable
Surge Susceptibility	IEC 1000-4-5 (IEC 801-5)	NA	+ 3 kV (open circuit voltage)	Not Applicable	Not Applicable
EFT Susceptibility	IEC 1000-4-4 (IEC 801-4)	NA	Power leads: + 4 kV Data/control leads: + 2 kV	Not Applicable	Not Applicable
Electrostatic Discharge Susceptibility	IEC 1000-4-2 (IEC 801-2)	NA	Contact discharge: + 4 kV Air discharge: + 8 kV	Not Applicable	Not Applicable
Radiated RF Emissions	CENELEC EN 55011, Group 1, Class A	30 MHz to 230 MHz 230 MHz to 1 GHz	30 dB μ V/meter 37 dB μ V/meter	30 meter 30 meter	Biconical Log-periodic
Conducted RF Emissions	MIL-STD-461D, CE-102	10 kHz to 500 kHz 500 kHz to 400 MHz	100 dB μ V 66 dB μ V	Not Applicable	Not Applicable

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Table 2 EMC TEST RESULTS FOR RM-1000 SYSTEMS (SCINTILLATION DETECTOR)

TEST PARAMETER	STANDARD	FREQUENCY RANGE	TEST LEVEL/LIMIT	ANTENNA DISTANCE	ANTENNA TYPE	TEST RESULTS
HF Radiated RF Susceptibility	IEC 1000-4-3	80 MHz to 1000 MHz	10 V/meter	3 meters	Biconical Log-periodic	
LF Conducted RF Susceptibility	MIL-STD-461D CS-101	30 Hz to 150 kHz	6.3 V RMS	NA	NA	
HF Conducted RF Susceptibility	IEC 1000-4-6	150 kHz to 80 MHz	10 V (emf)	NA	NA	
Surge Susceptibility	IEC 1000-4-5	NA	+ 3 kV (open circuit voltage)	NA	NA	
EFT Susceptibility	IEC 1000-4-4	NA	Power leads: + 4 kV Data/control leads: + 2 kV	NA	NA	
Electrostatic Discharge Susceptibility	IEC 1000-4-2	NA	Contact discharge: + 4 kV Air discharge: + 8 kV	NA	NA	
Radiated RF Emissions	CENELEC EN 55011, Group 1, Class A	30 MHz to 230 MHz 230 MHz to 1 GHz	30 dB μ V/meter 37 dB μ V/meter	30 meter 30 meter	Biconical Log-periodic	
Conducted RF Emissions	MIL-STD-461D CE-102	10 kHz to 500 kHz 500 kHz to 400 MHz (1)	100 dB μ V 66 dB μ V	NA	NA	

Notes:

- 1) Ac line impedance stabilization network is only calibrated out to 100 MHz.

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Table 3 EMC TEST RESULTS FOR RM-1000 SYSTEMS (ION CHAMBER & GMT DETECTORS)

TEST PARAMETER	STANDARD	FREQUENCY RANGE	TEST LEVEL/LIMIT	ANTENNA DISTANCE	ANTENNA TYPE	TEST RESULTS
HF Radiated RF Susceptibility	IEC 1000-4-3	80 MHz to 1000 MHz	10 V/meter	3 meters	Biconical Log-periodic	
LF Conducted RF Susceptibility	MIL-STD-461D CS-101	30 Hz to 150 kHz	6.3 V RMS	NA	NA	
HF Conducted RF Susceptibility	IEC 1000-4-6	150 kHz to 80 MHz	10 V (emf)	NA	NA	
Surge Susceptibility	IEC 1000-4-5	NA	± 3 kV (open circuit voltage)	NA	NA	
EFT Susceptibility	IEC 1000-4-4	NA	Power leads: ± 4 kV Data/control leads: ± 2 kV	NA	NA	
Electrostatic Discharge Susceptibility	IEC 1000-4-2	NA	Contact discharge: ± 4 kV Air discharge: ± 8 kV	NA	NA	
Radiated RF Emissions	CENELEC EN 55011, Group 1, Class A	30 MHz to 230 MHz 230 MHz to 1 GHz	30 dB μ V/meter 37 dB μ V/meter	30 meter 30 meter	Biconical Log-periodic	
Conducted RF Emissions	MIL-STD-461D CE-102	10 kHz to 500 kHz 500 kHz to 400 MHz (1)	100 dB μ V 66 dB μ V	NA	NA	

Notes:

1) Ac line impedance stabilization network is only calibrated out to 100 MHz.

APPENDIX A

TÜV Test Report

S7439-03

13Nov1997

**RM-1000 Radiation Monitor
Single Channel**



Report No. S7439-03

EMC - TEST REPORT

SORRENTO ELECTRONICS TEST STANDARDS*

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Test Report File No. : **S7439-03** Date of Issue: 13 November 1997

Model / Serial No. : **RM-1000 / [REDACTED]**

Product Type : **Radiation Monitor, Single Channel**

Applicant : **SORRENTO ELECTRONICS**

Manufacturer : **SORRENTO ELECTRONICS**

License holder : **SORRENTO ELECTRONICS**

Address : **10240 Flanders Court**
: **San Diego, CA 92121**

Test Result : **[REDACTED]**

Test Project Number
References : **S101743901-03**

Total pages - Test Report : 18

(*) All tests performed per Sorrento Electronics' Test Standards (see Appendix E.)

(**) See General Remarks for modification(s) to EUT and explanation.

TÜV Product Service, Inc. is a subcontractor to TÜV Product Service, GmbH according to the principles outlined in ISO/IEC Guide 25 and EN 45001.

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RF Radiated Emissions (30 MHz - 1 GHz - EN 55011)	
RF Conducted Emissions (150 kHz - 30 MHz - EN 55011)	
RF Conducted Emissions (MIL-STD-461D, CE102, 10 kHz - 100 MHz)	
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Technical Documentation

Test Data Sheets and Test Setup Drawing(s)	<u>TD1</u>
--------------------------------------------	------------

Appendices

Appendix A	<u>A1</u>
Test Setups (Photographs)	
Appendix B	<u>B1</u>
Product Information Form(s)	
Appendix C	<u>C1</u>
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Testing Facility Approval Certificates: VCCI (3), NVLAP, EN 45001	
Appendix E	<u>E1</u>
Supplemental Information	



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IMMUNITY TEST REGULATIONS :

The immunity tests were performed according to the following regulations :

-
- DIN VDE 0843 Part 2 / 9.1987
 - DIN VDE 0843 Part 3 / 2.1988
 - DIN VDE 0843 Part 4 / 4.1987
 - DIN VDE 0847 Part 2 / 9.1987 E
 - DIN VDE 0847 Part 4 / 1.1987 E
 - DIN VDE 0750 Part 1-3 / 3.1992 E
 - DIN VDE 0872 Part 20 / 8.1989

-
- EN 50082-1 / 1992
 - EN 50082-2 / 1995
 - EN 55104 / 1995
 - EN 60601-1-2 / 1993

-
- IEC 1000-4-2 / 1995*
 - IEC 1000-4-3 / 1995*
 - IEC 1000-4-4 / 1995*
 - IEC 1000-4-5 / 1995*
 - IEC 1000-4-6 / 1995*
 - IEC 1000-4-8 / 1993
 - IEC 1000-4-11 / 1994

- MIL-STD-461D (CS101)*
- MIL-STD-461D (CE102)*

- ENV 50140 / 1993
- ENV 50141 / 1993
- ENV 50204

- EN 55011 / 1991*

- Group 1
- Class A

- Group 2
- Class B

- CISPR 11 (1990)*

- Group 1
- Class A

- Group 2
- Class B

(*) All tests performed per Sorrento Electronics' Test Standards (see Appendix E).



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Environmental Conditions In The Laboratory:

	<u>Actual</u>
Temperature:	: 22-24 °C
Relative Humidity:	: 43-46 %
Atmospheric Pressure:	: 996-100.8 kPa

Power Supply Utilized:

Power supply system : 

Symbol Definitions:

- - Applicable
- - Not Applicable



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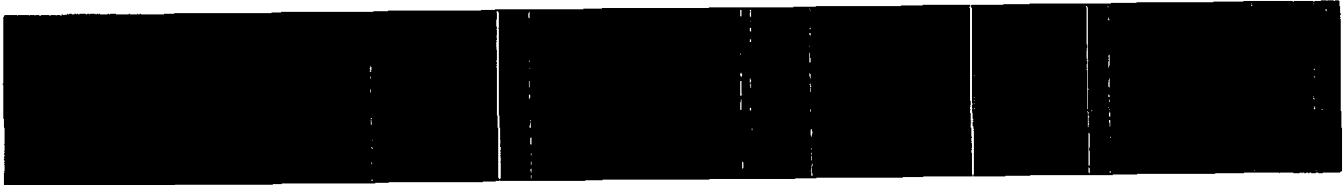
Immunity Test Conditions: ELECTROSTATIC DISCHARGE (ESD)

The immunity against *ELECTROSTATIC DISCHARGE (ESD)* events was performed in the following location at the San Diego Testing Facility :

- Test not applicable

- TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- SR-1, Shielded Room, 12' x 24' x 10', Metal, Compact Anechoic Chamber

Test Equipment Used :



Test Specification:

Discharge Voltage (Air):

Discharge Voltage (Contact):

Discharge Impedance:

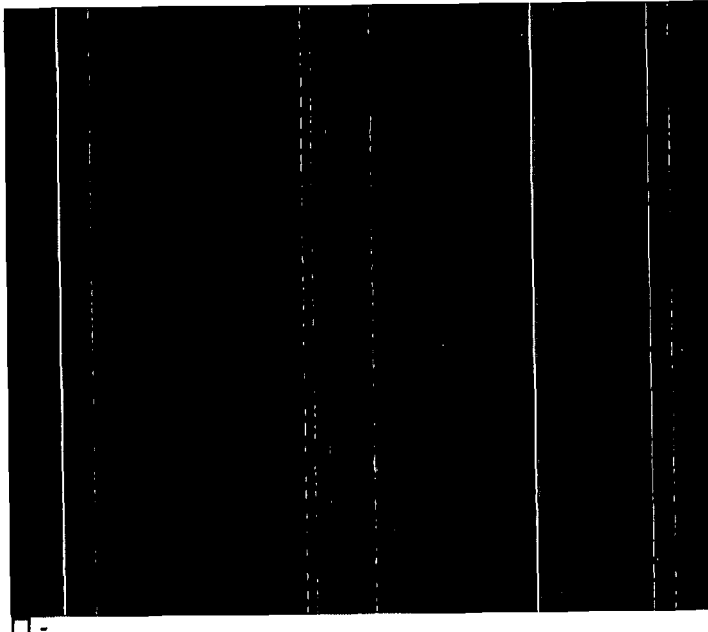
Discharge Repetition Rate:

Number of Discharges:

Kind of Discharges:

Polarity:

Location of Discharge:





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Immunity Test Conditions: ELECTROSTATIC DISCHARGE (ESD), continued

Result :

[Redacted]

Remarks:

[Redacted]



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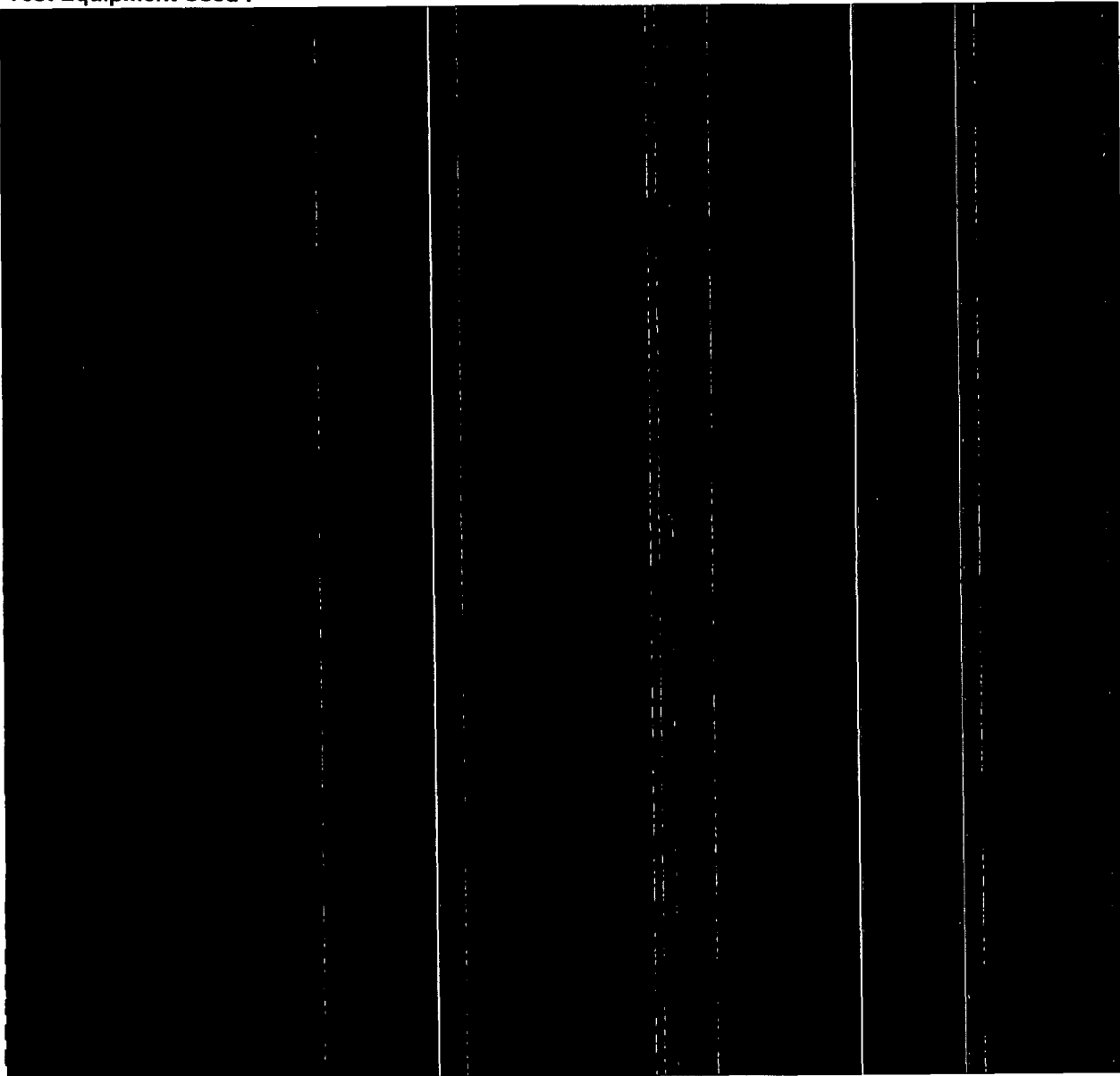
Immunity Test Conditions: RADIATED ELECTROMAGNETIC FIELDS

The immunity against *RADIATED ELECTROMAGNETIC FIELDS* exposure was performed in the following location at the San Diego Testing Facility:

- Test not applicable

- - SR-1, Shielded Room, 12' x 24' x 10', Metal, Compact Anechoic Chamber
- - SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber

Test Equipment Used :



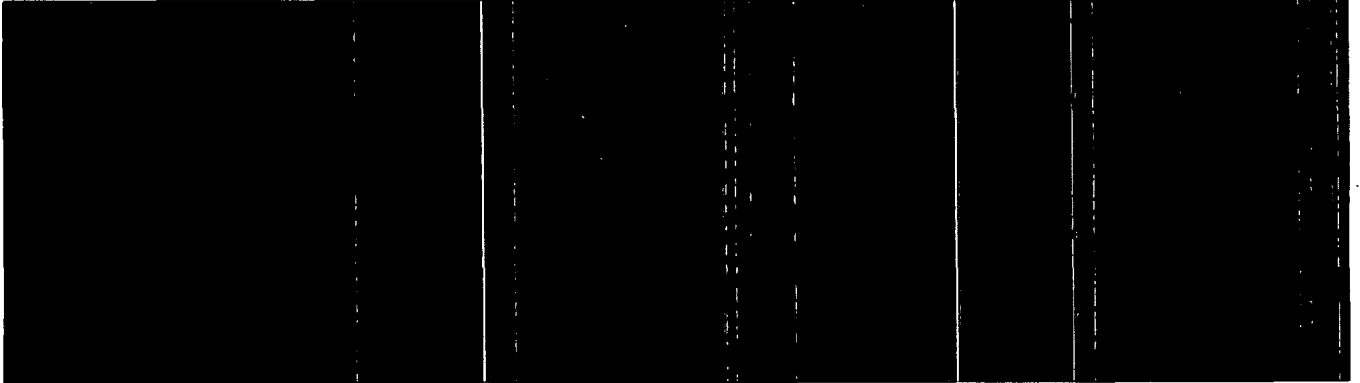


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Immunity Test Conditions: RADIATED ELECTROMAGNETIC FIELDS, continued

Test Equipment Used (continued):



Test Specification:

Frequency Range:

Field Strength:

Distance Antenna - EUT:

Modulation:

Step:

Polarization of Antenna:

Test Specification:

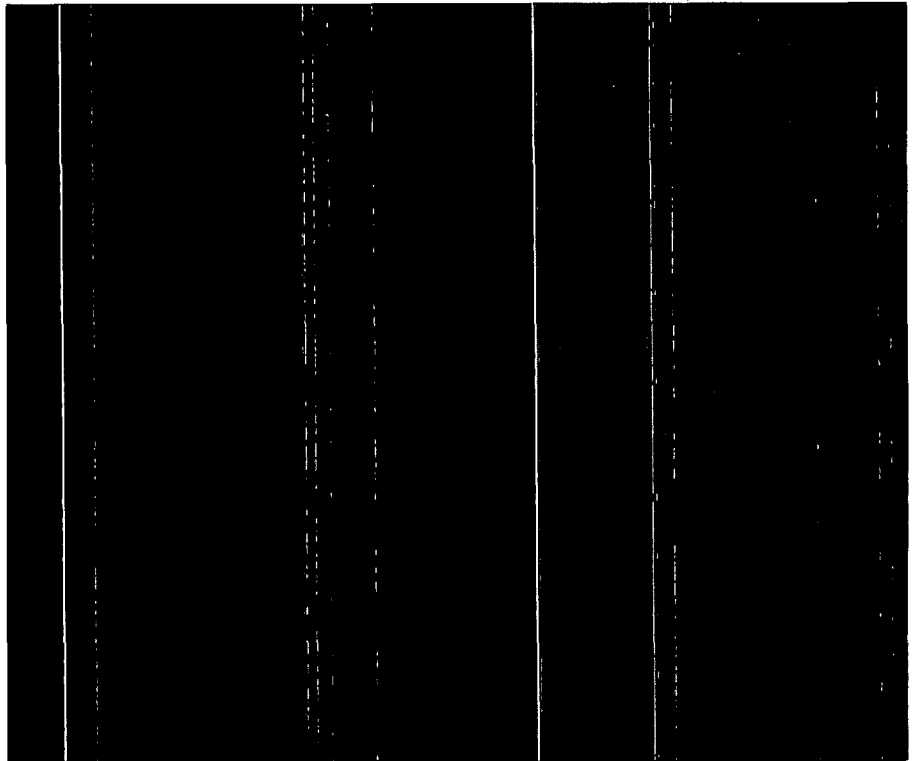
Frequency Range:

Field Strength:

Distance Antenna - EUT:

Modulation:

Polarization of Antenna:



Result :



Remarks:





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Immunity Test Conditions: FAST TRANSIENTS (BURST)

The immunity against *FAST TRANSIENTS (BURST)* events was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :



Test Specification:

Pulse Amplitude - AC Power Port:

Pulse Amplitude - DC Power Port:

Pulse Amplitude - Signal/Data
Non control Port:

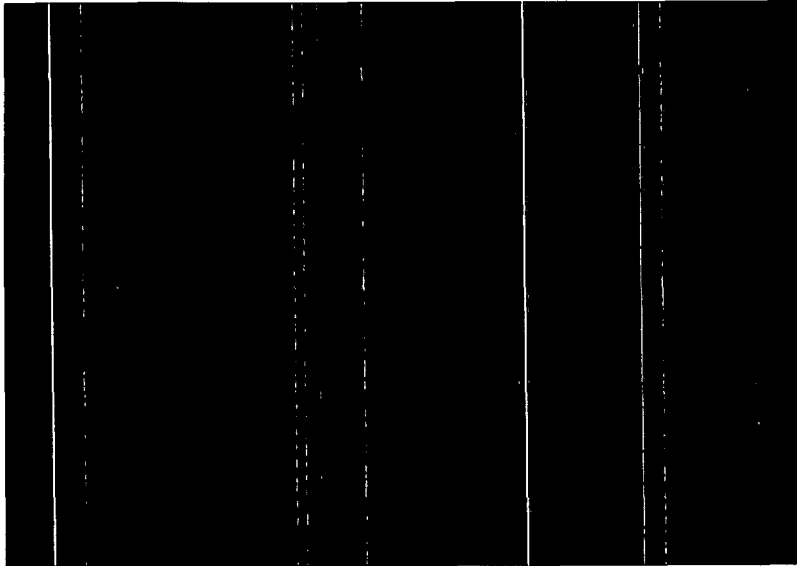
Pulse Amplitude - Process:
Measurement & Control Port

Burst Frequency:

Time of Coupling:

Coupling Method:

Polarity:





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**BUSINESS
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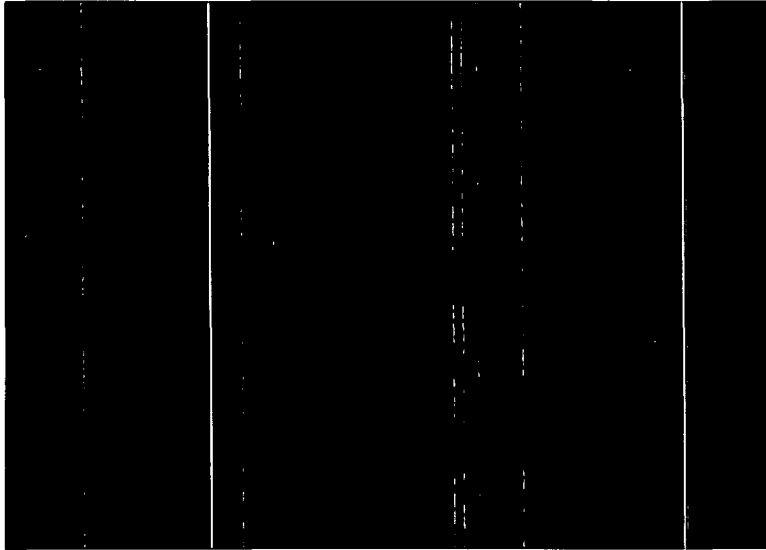
Immunity Test Conditions: FAST TRANSIENTS (BURST), continued

Location of Coupling:

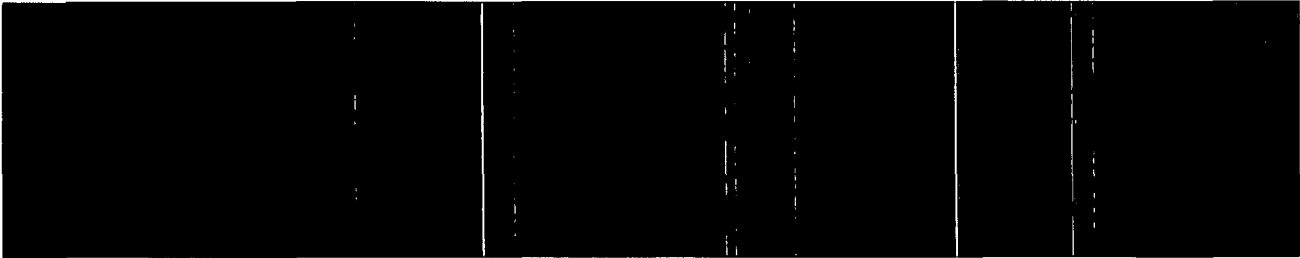
name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



Result :





Report No. S7439-03

**BUSINESS
SENSITIVE**

Immunity Test Conditions: SURGE TRANSIENTS

The immunity against *SURGE TRANSIENTS* events was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- - TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- - TR-2, Non-Shielded Room, 10' x 19' x 9'
- - TR-3, Non-Shielded Room, 10' x 19' x 9'
- - TR-4, Non-Shielded Room, 10' x 19' x 9'
- - SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber

Test Equipment Used :



Test Specification:

Pulse Amplitude - AC Power Port:
(Common Mode)

Source Impedance:
(Common Mode)

Pulse Amplitude - AC Power Port:
(Differential Mode)

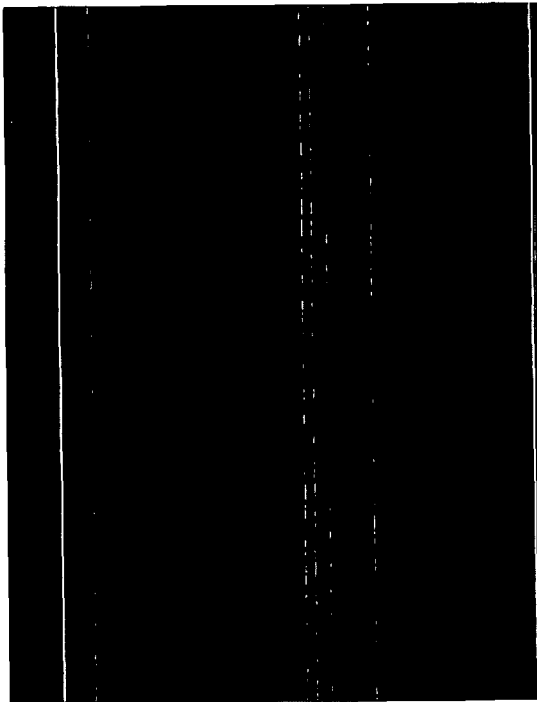
Source Impedance:
(Differential Mode)

Pulse Amplitude - DC Power Port:

Pulse Amplitude - Signal/Data
Non control Port:

Pulse Amplitude - Process:
Measurement & Control Port

Source Impedance:





Report No. S7439-03

BUSINESS SENSITIVE

Immunity Test Conditions: SURGE TRANSIENTS, continued

Test Specification (continued):

Number of Surges:

Angle:

Repetition Rate:

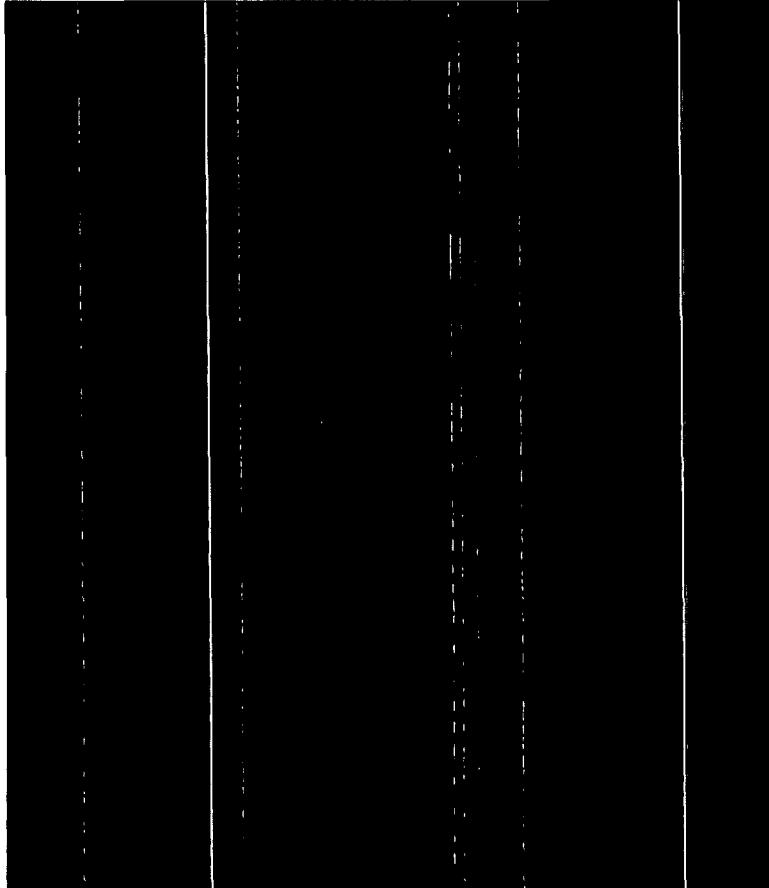
Polarity:

Location of Coupling:

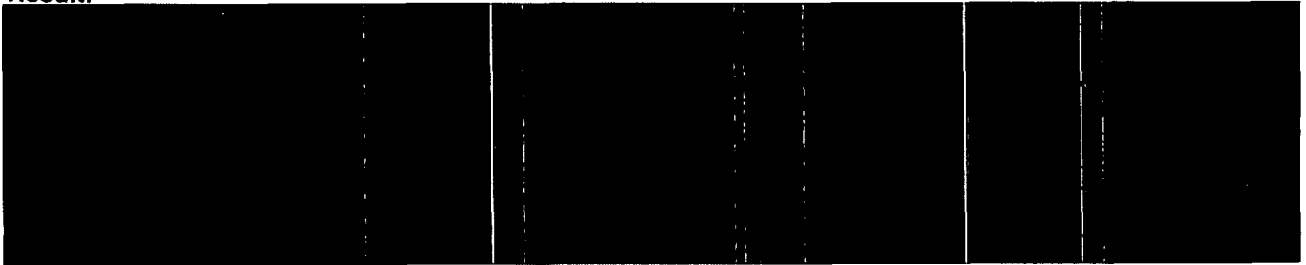
name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



Result:





Report No. S7439-03

BUSINESS
SENSITIVE

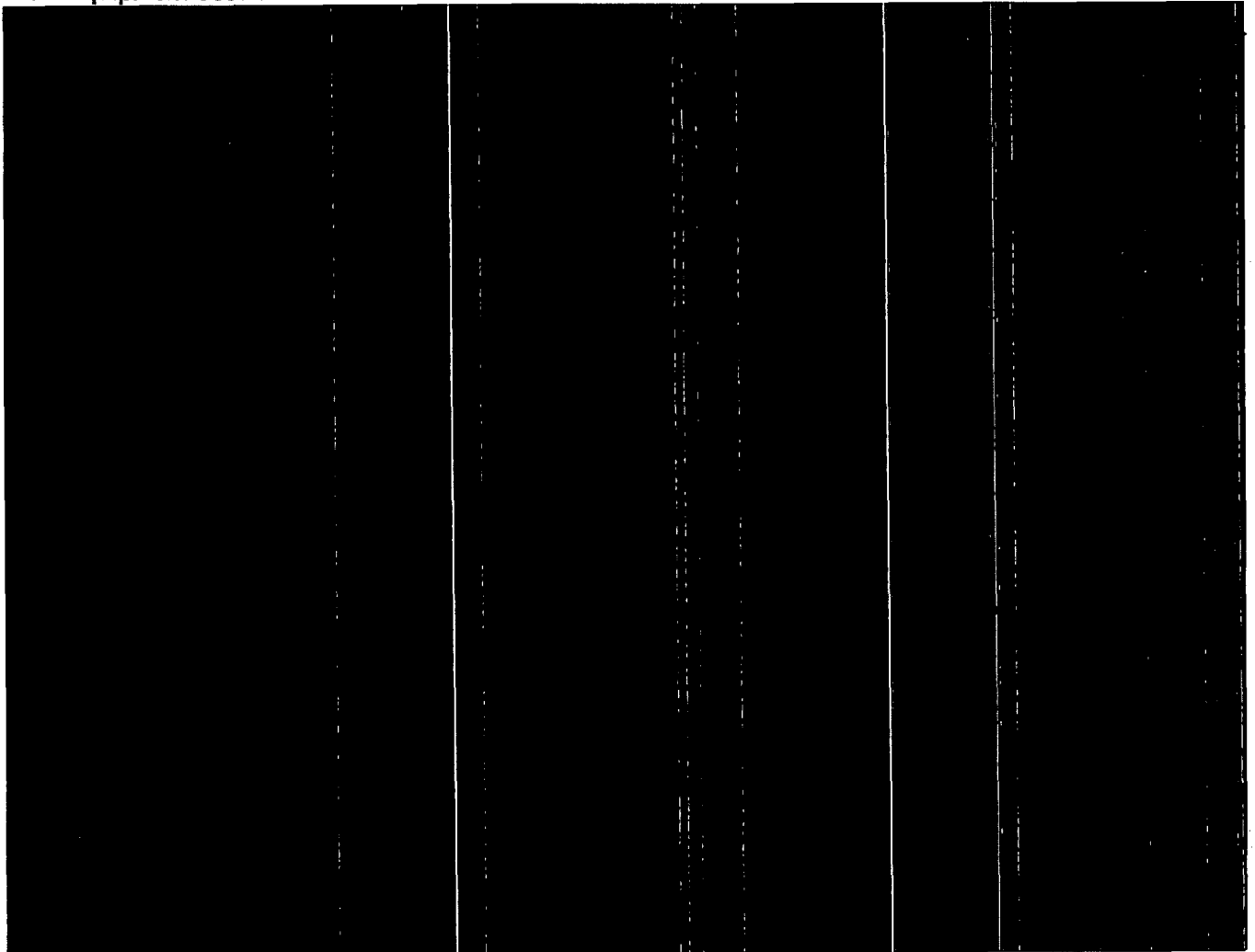
Immunity Test Conditions: CONDUCTED DISTURBANCE

The immunity against *CONDUCTED DISTURBANCE* events, induced by radio frequency fields above 9 kHz, was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :





Report No. S7439-03

**BUSINESS
SENSITIVE**

Immunity Test Conditions: CONDUCTED DISTURBANCE (continued):

Test Equipment Used (continued):



Test Specification:

Frequency Range:

Voltage Level (EMF):

Modulation:

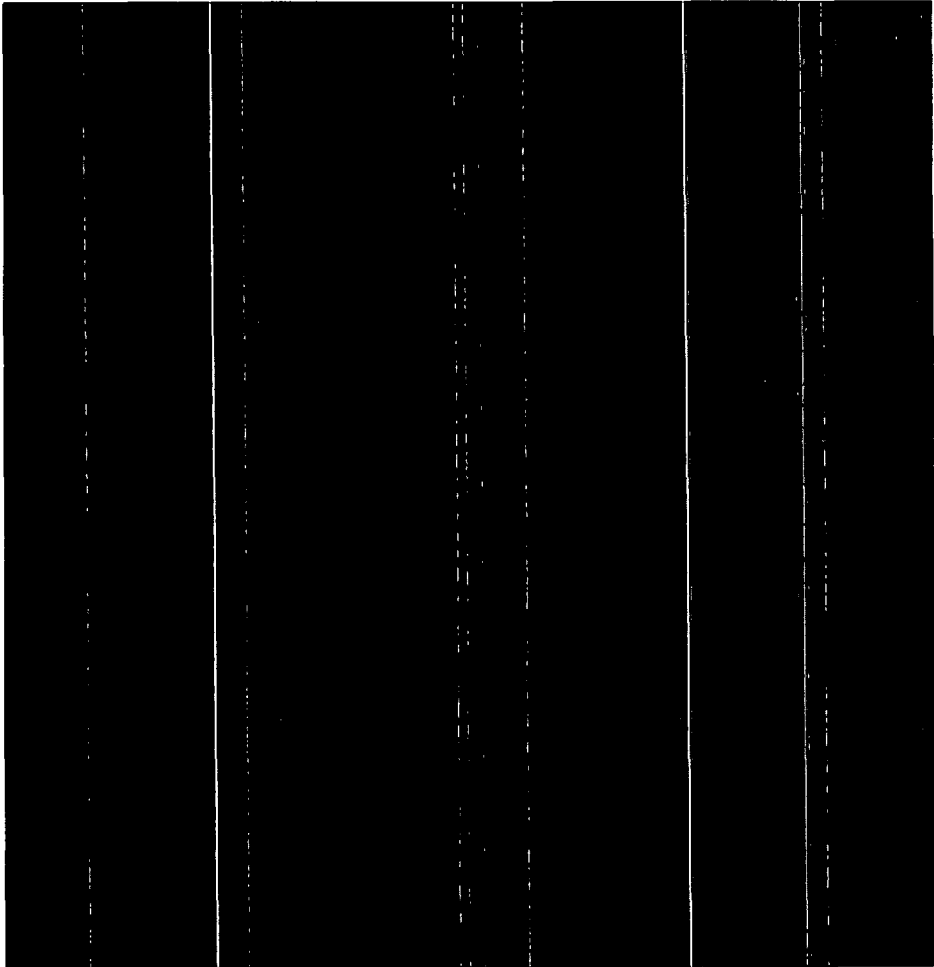
Step:

Location of Coupling:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



Result :



Remarks:





Report No. S7439-03

BUSINESS
SENSITIVE

Emissions Test Conditions: RADIATED EMISSIONS (Electric Field) EN 55011, Group 1, Class A

The *RADIATED EMISSIONS (ELECTRIC FIELD)* measurements, in the frequency range of 30 MHz-1000 MHz, were tested in a horizontal and vertical polarization at the following test location :

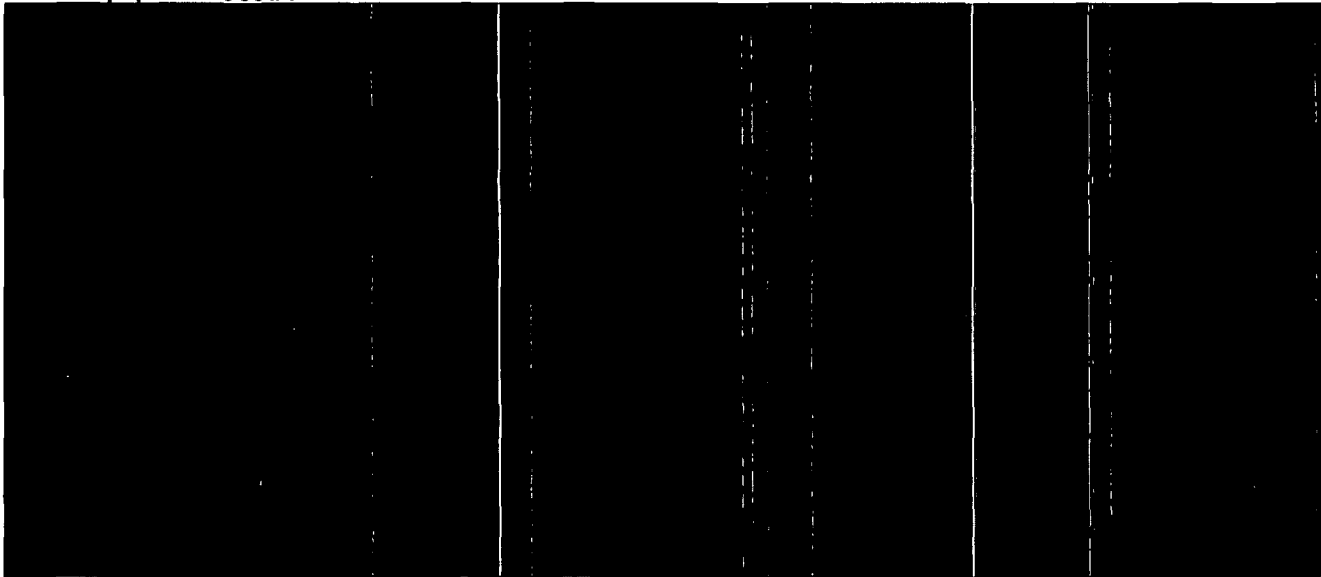
- Test not applicable

- Roof (Small Open Area Test Site)
- Canyon #1 (10- and 30-Meter Open Area Test Site), Carroll Canyon, San Diego
- Canyon #2 (3- and 10-Meter Open Area Test Site), Carroll Canyon, San Diego

Testing was performed at a test distance of :



Test Equipment Used :



Result :



Remarks:





Report No. S7439-03

**BUSINESS
SENSITIVE**

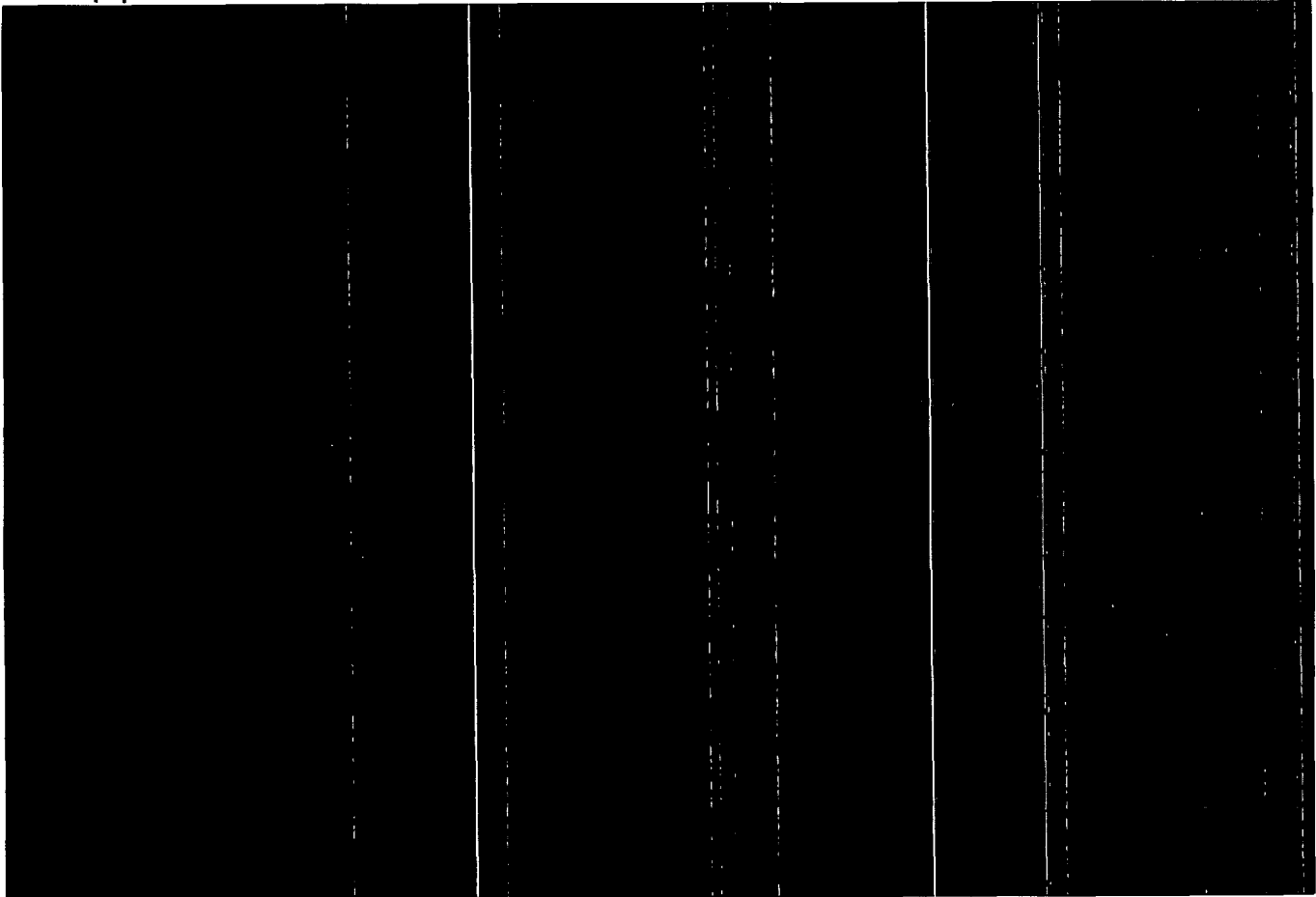
Emissions Test Conditions: CONDUCTED EMISSIONS (Interference Voltage) EN 55011, Group 1, Class A

The CONDUCTED EMISSIONS (INTERFERENCE VOLTAGE) measurements were performed at the following test location:

- Test not applicable

- SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :



Result : [Redacted]

Remarks: [Redacted]



Report No. S7439-03

**BUSINESS
SENSITIVE**

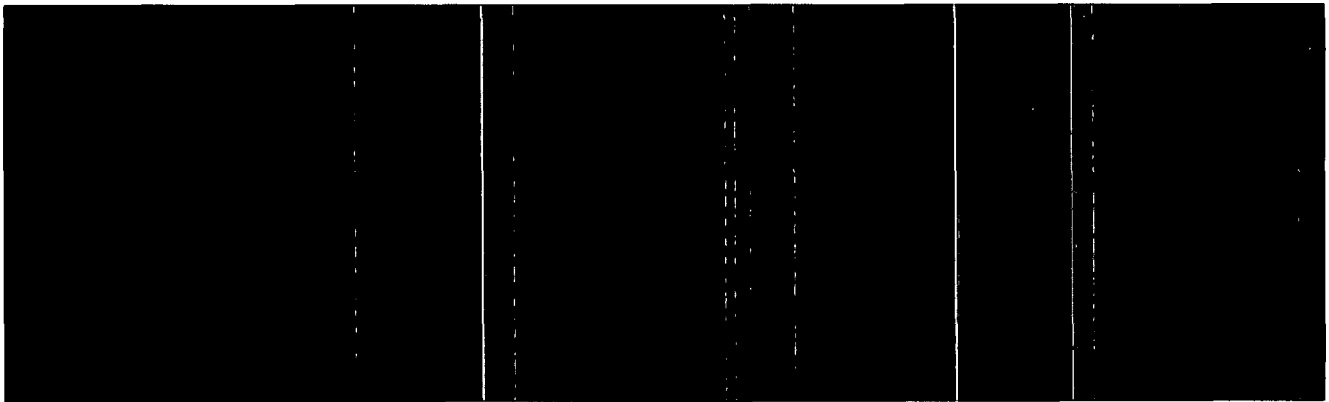
Test Conditions: CE102 - Conducted Emissions, Power Lines, 0.01 - 100 MHz

The *Conducted Emissions, Power Lines* test was performed in the following location at the San Diego Testing Facility :

- Test not applicable

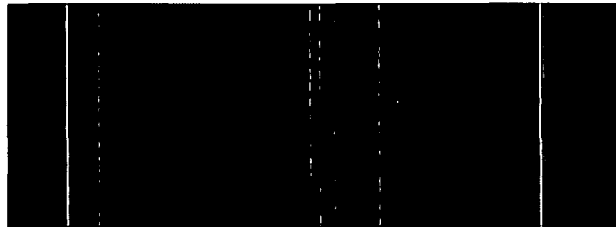
- TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber

Test Equipment Used :



Test Specification:

Frequency:



Band:

LISN:

Result :



Remarks:





Report No. S7439-03

**BUSINESS
SENSITIVE**

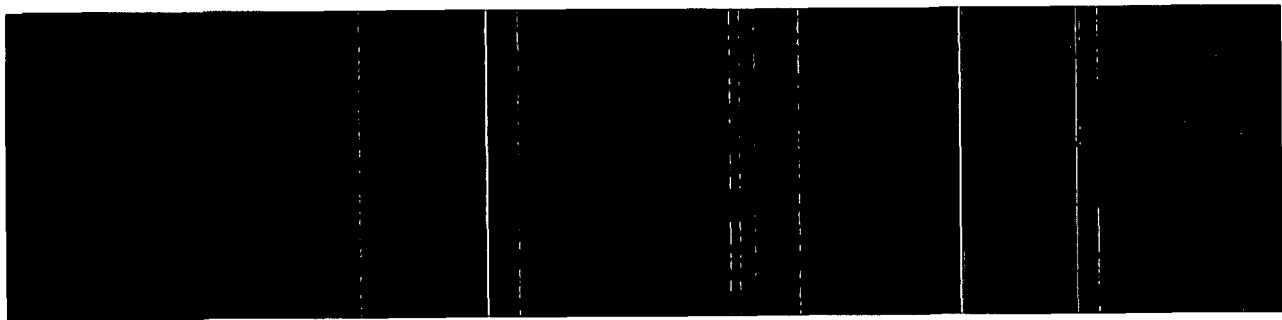
Immunity Test Conditions: CONDUCTED SUSCEPTIBILITY, Power Leads, 30 Hz - 150 kHz (CS101)

The *CONDUCTED SUSCEPTIBILITY* test was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- TR-1, Shielded Room, 16.5' x 10' x 7.5', Copper Screen Chamber
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber

Test Equipment Used :

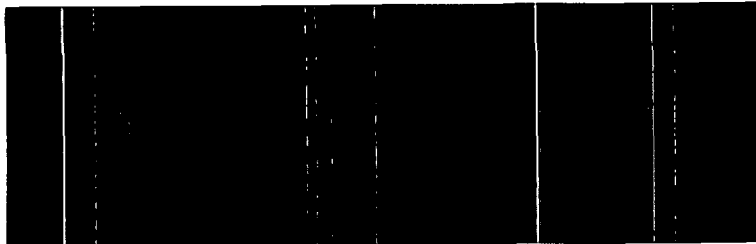


Test Specification:
Frequency Range:

Vrms:

Injected Voltage Vrms:

Injection Location:



Result :



Remarks:





Report No. S7439-03

Equipment Under Test (EUT) Test Operation Mode - Immunity Tests :

The equipment under test was operated under the following conditions during immunity testing :

- Standby
- Test Program (H - Pattern)
- Test Program (Color Bar)
- Test Program (Customer Specified)
- Practice Operation
- Normal Operating Mode
- _____

Configuration of the equipment under test:

- See Constructional Data Form in Appendix B - Page B2
- See Product Information Form(s) in Appendix B - Page B2

The following peripheral devices and interface cables were connected during the testing:

- | | |
|-----------------------------------------------------|-----------------|
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - unshielded power cable | |
| <input type="checkbox"/> - unshielded cables | |
| <input type="checkbox"/> - shielded cables | MPS. No.: _____ |
| <input type="checkbox"/> - customer specific cables | |
| <input type="checkbox"/> - _____ | |
| <input type="checkbox"/> - _____ | |



Report No. S7439-03

**BUSINESS
 SENSITIVE**

GENERAL REMARKS:

(*) All tests performed per Sorrento Electronics' Test Standards (see Appendix E).

SUMMARY:

Test	Result
Electrostatics Discharge (EN 61000-4-2)	
Radiated Electromagnetic Fields (EN 61000-4-3)	
Fast Transients (Burst) (EN 61000-4-4)	
Surge Transients (EN 61000-4-5)	
Conducted Disturbance (EN 61000-4-6)	
RF Radiated Emissions (EN 55011)	
RF Conducted Emissions (EN 55011)	
RF Conducted Emissions (CE102)	
RF Conducted Susceptibility (CS101)	

All tests according to the regulations cited on page 3 were

- Performed*

- Not Performed

The Equipment Under Test



Statement of Measurement Uncertainty

The data and results referenced in this document are true and accurate. There may be some degree or level of measurement uncertainty. As EN 45001 does not allow recommendations to be included in the test report, the reader is encouraged to request a copy of the TÜV policy concerning pass or fail judgment with respect to possible measurement uncertainties.

Equipment Received Date: 04 November 1997

Testing Start Date: 04 November 1997

Testing End Date: 12 November 1997

- TÜV PRODUCT SERVICE, INC. -

Responsible Engineer:



(EMC Test Engineer)

Responsible Engineer:



(Senior EMC Engineer)



Report No. S7439-03

Technical Documentation

Test Data Sheets
and
Test Setup Drawing(s)

Page TD1 of TD39

Rev.No 1.0



Report No. S7439-03

BUSINESS SENSITIVE

ESD IMMUNITY (Test Point Map)

Test Report #: S7439 Test Area: TR 2
Test Method: EN61000-4-2 Date: 5 Nov 97



EUT Model #: RM-1000 EUT POWER: [X] 230 Vac/50 Hz [] 120 Vac/60 Hz [] Other:

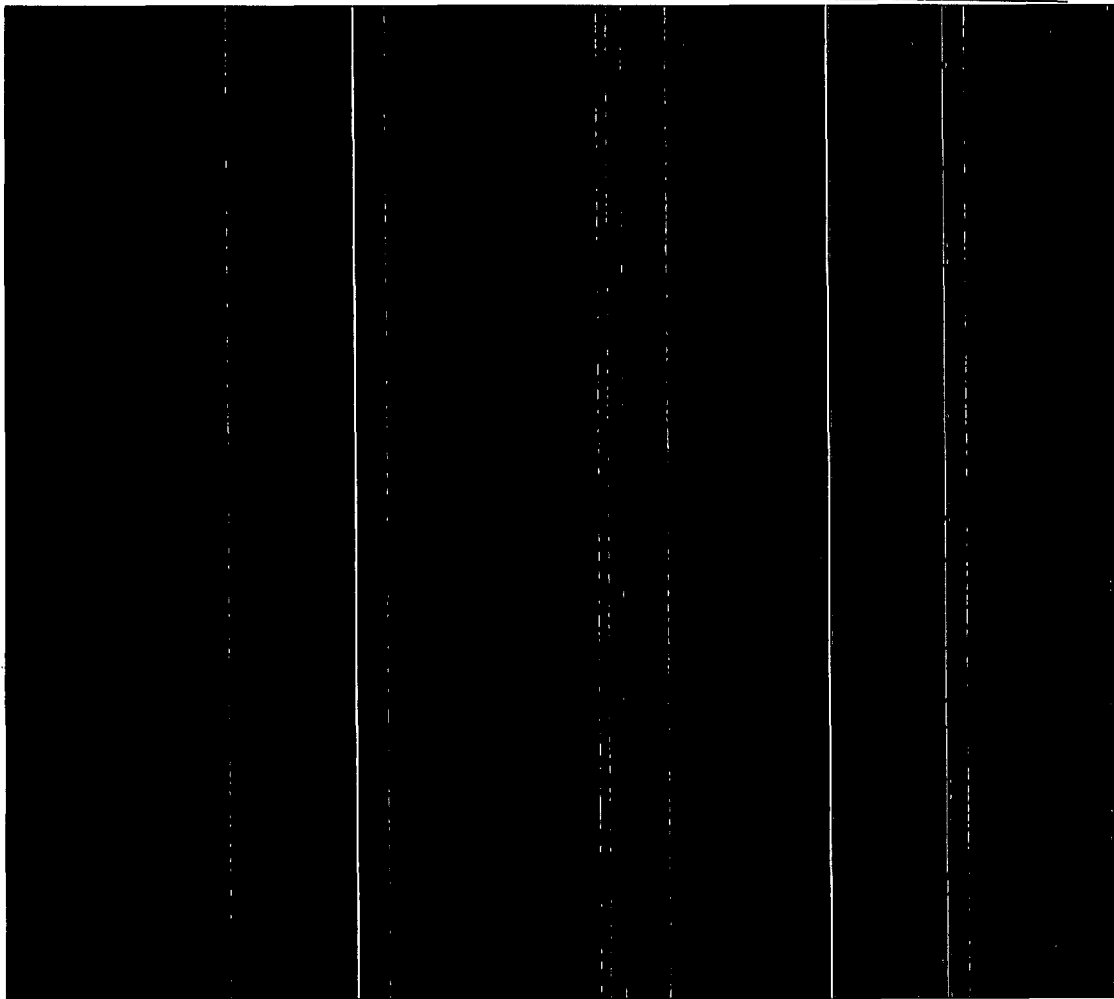
Temperature: 23 °C

EUT Description: RADIATION MONITOR

Air Pressure: 100.5 kPa

NOTES:

Relative Humidity: 44 %



Tested By: [Redacted] Print Signature [Redacted]
Reviewed by: [Redacted] Print Signature [Redacted]



Report No. S7439-03

BUSINESS SENSITIVE

ESD IMMUNITY

Test Report #: S7439
Test Method: EN 61000-4-2

Test Area: TR2
Date: 5 Nov 97/12 Nov 97



EUT Model #: RM-1000

EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other:

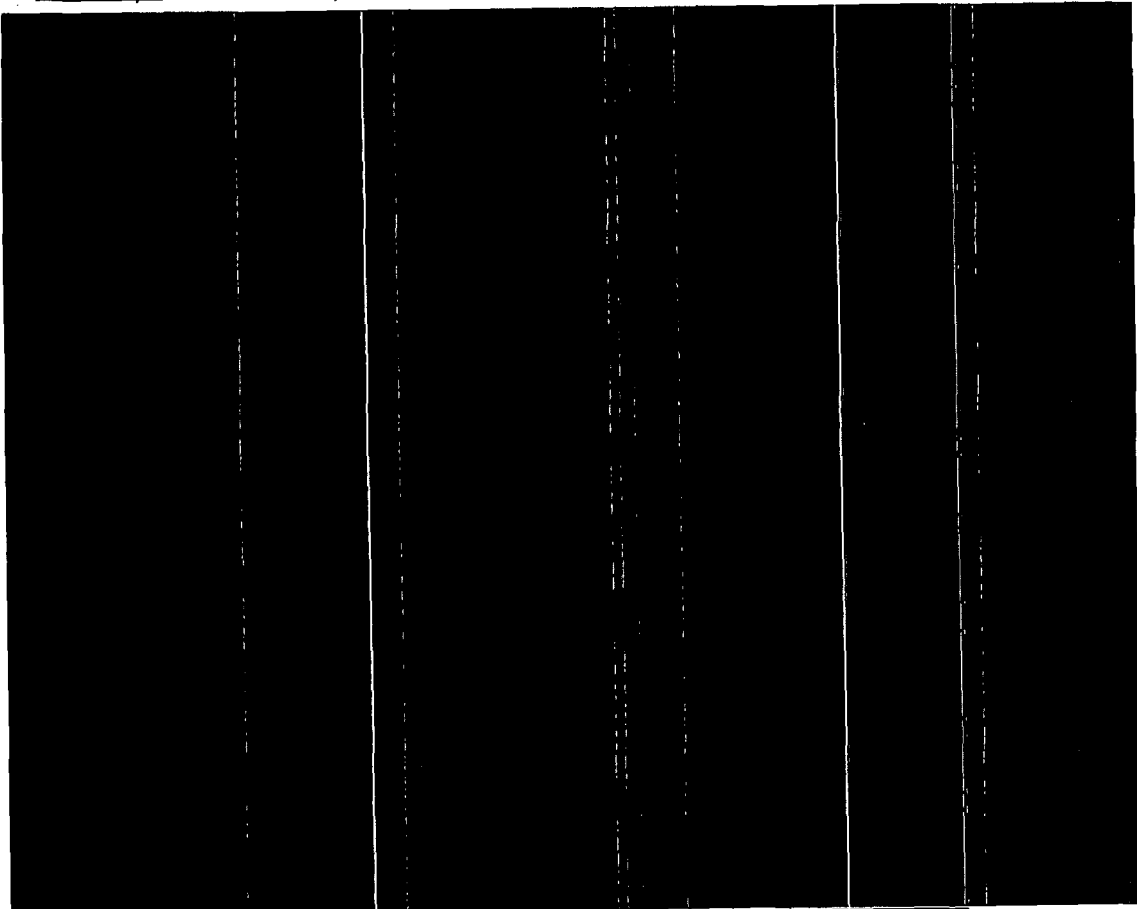
Temperature: 23 °C

EUT Description: RADIATION MONITOR SIN ART 013

Air Pressure: 1005 kPa

NOTES: [REDACTED]

Relative Humidity: 44 %



Tested by: [REDACTED]

Reviewed: [REDACTED]

Printed

Signature

(*) Indirect (**) Direct

ESDC.DOC Rev 05.97



Report No. S7439-03

BUSINESS SENSITIVE

ESD IMMUNITY

Test Report #: 57439 Test Area: TR2
Test Method: EN 61000-4-2 Date: 12 NOV 97



EUT Model #: RM-1000
EUT Description: Radiation Monitor Single Channel
EUT Power: 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____

Temperature: 24 °C
Air Pressure: 996 kPa
Relative Humidity: 43 %

NOTES: [Redacted]

[Large redacted area]

Tested by: [Redacted] _____
Reviewed by: [Redacted] _____
Printed Signature

(*) Indirect (**) Direct

ESDC.DOC Rev 05.97

BUSINESS SENSITIVE

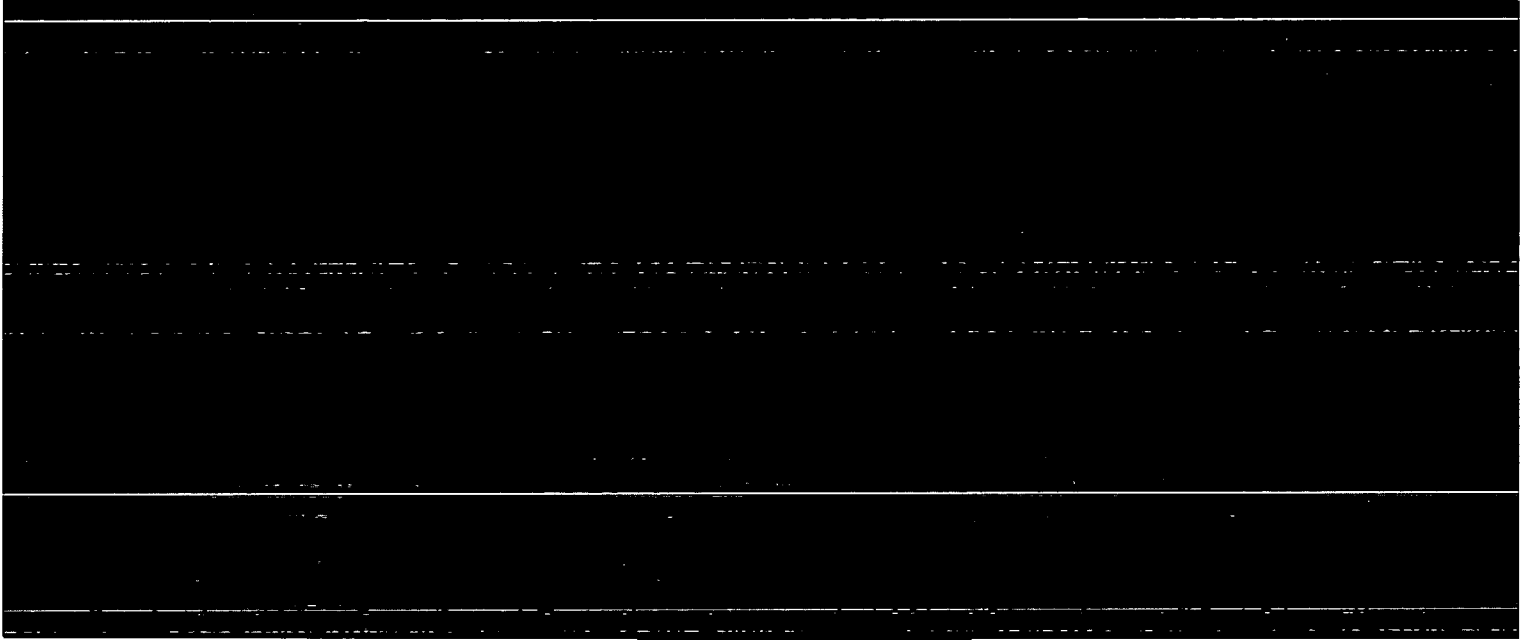
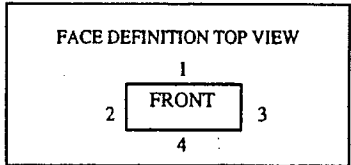


RADIATED IMMUNITY

Test Report #: 57439 Test Area: S/R 1
 Test Method: _____ Date: 4 Nov 97
 Test Method: IEC 1000-4-3 EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____

Temperature: 23 °C
 Air Pressure: 100.7 kPa
 Relative Humidity: 58 %

EUT Model #: RM-1000
 EUT Description: Radiation Monitor, Single Channel
 NOTES: _____



Tested by: _____
 Reviewed by: _____
 Printed _____ Signature _____

RADIMU.DOC Rev 05.97



PRODUCT SERVICE



Report No. S7439-03

BUSINESS SENSITIVE

EFT/BURST IMMUNITY

Test Report #: S7439 Test Area: SR4
Test Method: IEC 1000-4-4 Date: 6 Nov 97/12 Nov 97



EUT Model #: RM-1000 EUT POWER: [X] 230 Vac/50 Hz [] 120 Vac/60 Hz [] Other:
EUT Description: Radiation Monitor, Side Channel Temperature: 22 °C
Air Pressure: 100.6 kPa
Relative Humidity: 46 %

NOTES:



Tested By: [Redacted]
Reviewed by: [Redacted]
Printed / Signature

EFT.DOC Rev 03.97



Report No. S7439-03

BUSINESS SENSITIVE

SURGE IMMUNITY

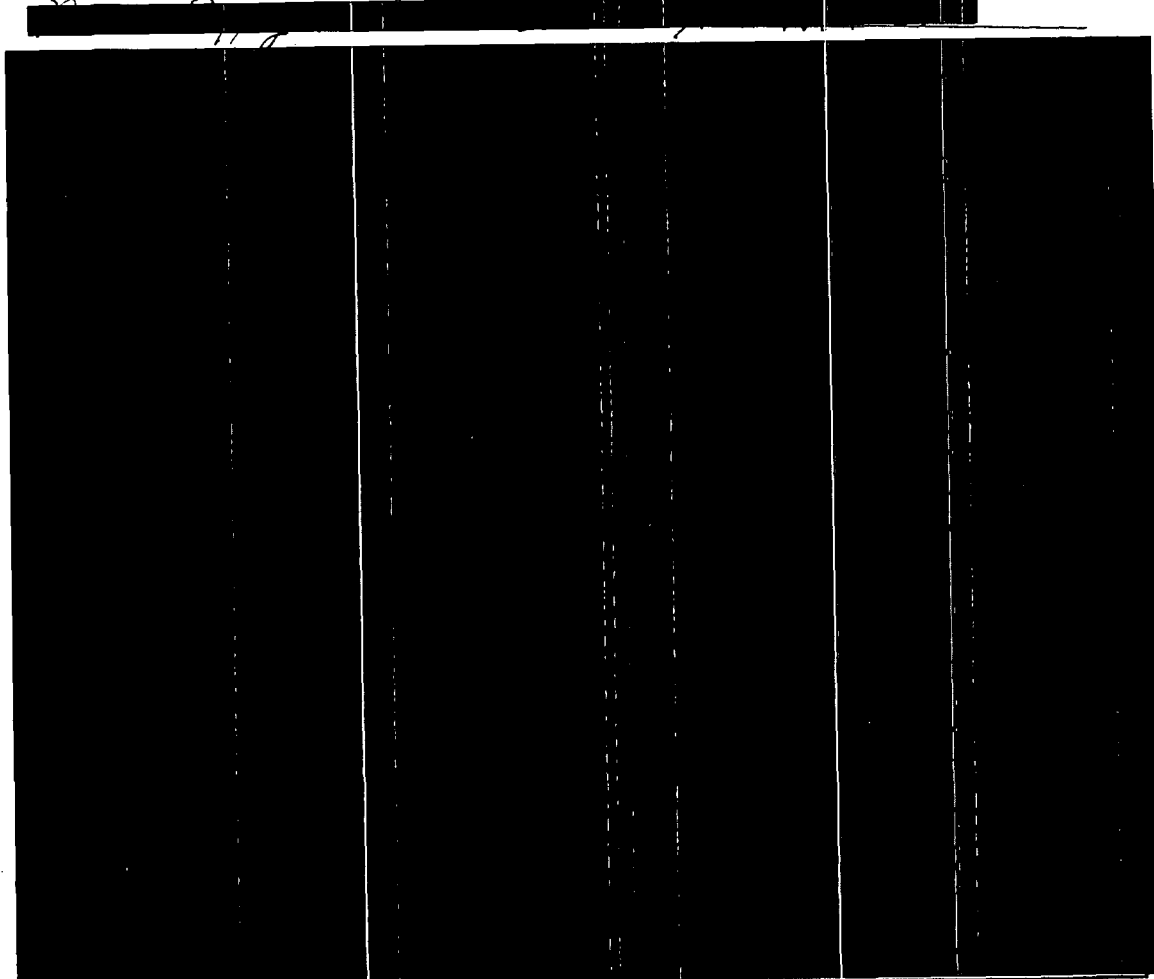
Test Report #: S7439 Test Area: TR-3
Test Method: IEC 1000-4-5 Date: 6 Nov 97
EUT Model #: RM-1000 EUT POWER: 230 Vac/50 Hz



Temperature: 23 °C
Air Pressure: 100.4 kPa
Relative Humidity: 45 %

EUT Description: RADIATION MONITOR, Single Channel

NOTES:



Tested By: [Redacted]
Reviewed by: [Redacted] Printed Signature [Redacted]



Report No. S7439-03

BUSINESS SENSITIVE

SURGE IMMUNITY

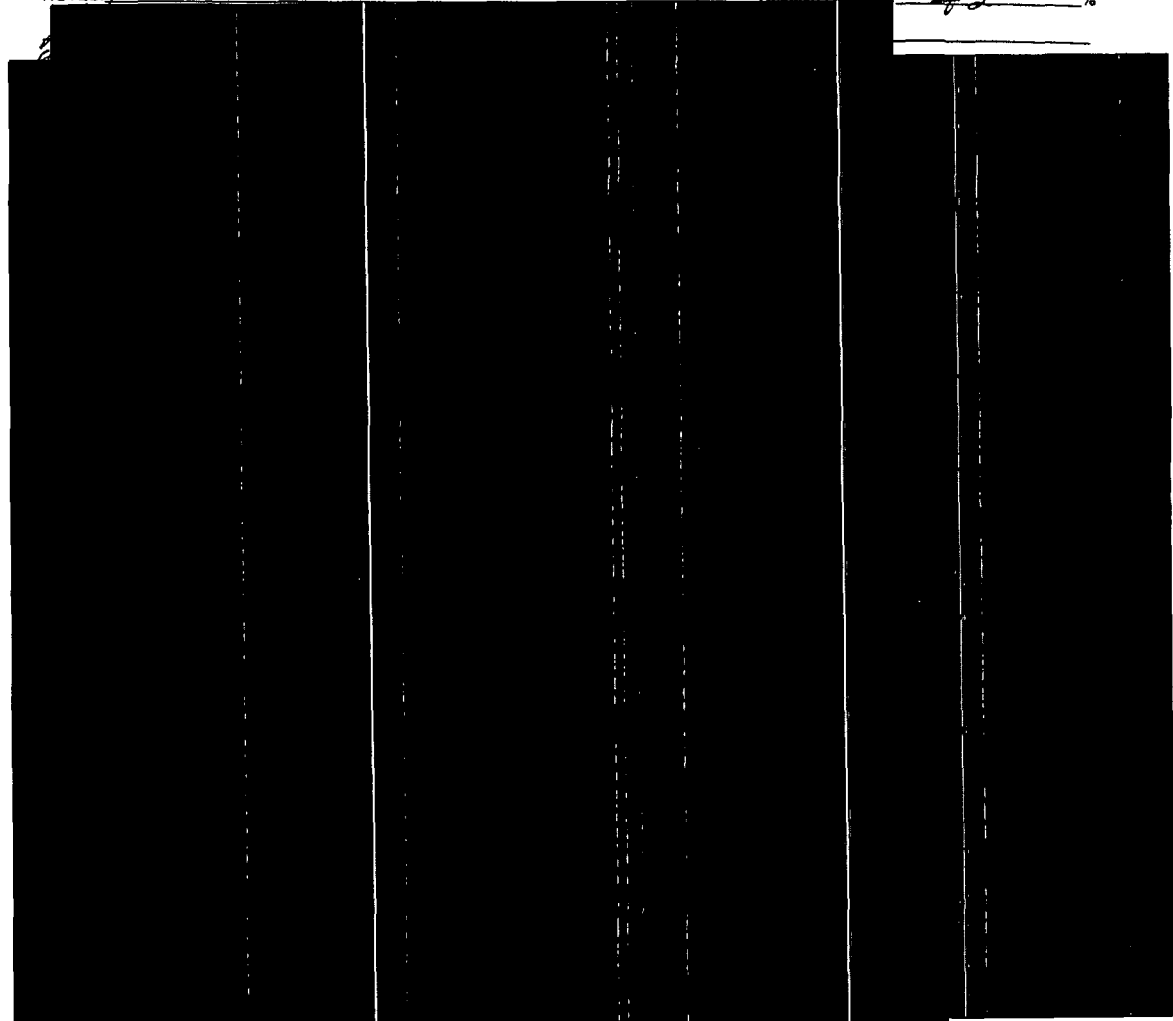
Test Report #: S7439 Test Area: YR-1
Test Method: _____ Date: 12 Nov 97

Test Method: IEC 1000-4-5
EUT Model #: RM-1000 EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____

EUT Description: Radiation Monitor, Single Channel

Temperature: 23 °C
Air Pressure: 996 kPa
Relative Humidity: 43 %

NOTES: _____



Tested By: _____

Reviewed by: _____

Printed

Signature

SURG.DOC Rev 03.97

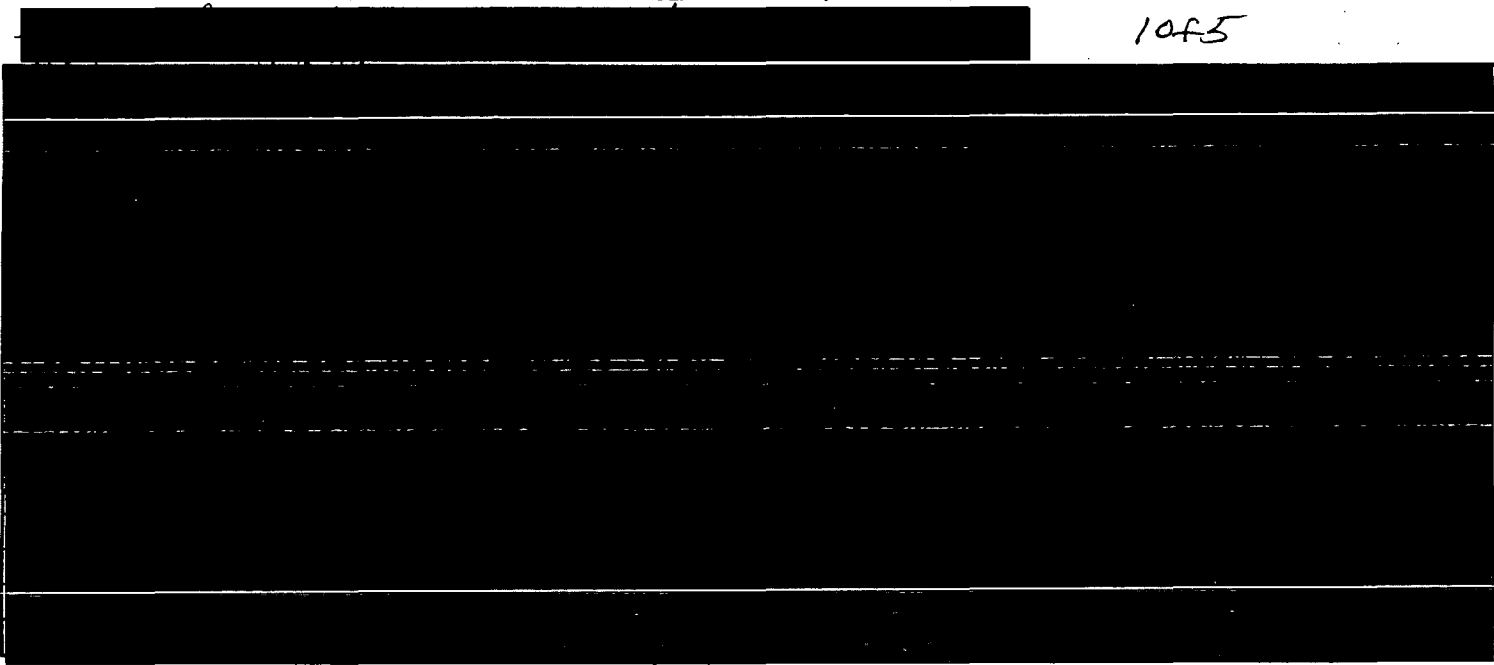
BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: S7439 Test Area: 8/R3
 Test Method: _____ Date: 7 Nov 97
 EUT Model #: RM-1000 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____ Temperature: 23 °C
 EUT Description: Radiation Monitor, Single Channel Air Pressure: 100.8 kPa
 NOTES: _____ Relative Humidity: 45 %

1045



Tested By: _____
 Reviewed: _____
 Printed Signature

COND.DOC Rev 03.97

BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: S7439 Test Area: S/R3

Test Method: _____ Date: 7 Nov 97

IEC 1000-4-6 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz

EUT Model #: RM-1000 Other: _____

Temperature: 23 °C

EUT Description: Radiation Monitor, Single Channel

Air Pressure: 100.8 kPa

NOTES: _____

Relative Humidity: 45 %

[REDACTED TEST RESULTS]

2045

Tested By: [REDACTED]

Reviewed by: [REDACTED] Printed Signature

COND.DOC Rev 03.97



BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: S 7439 Test Area: S/R 3

Test Method: _____ Date: 7 Nov 97

IEC 1000-4-6 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz

EUT Model #: RM-1000 Other: _____

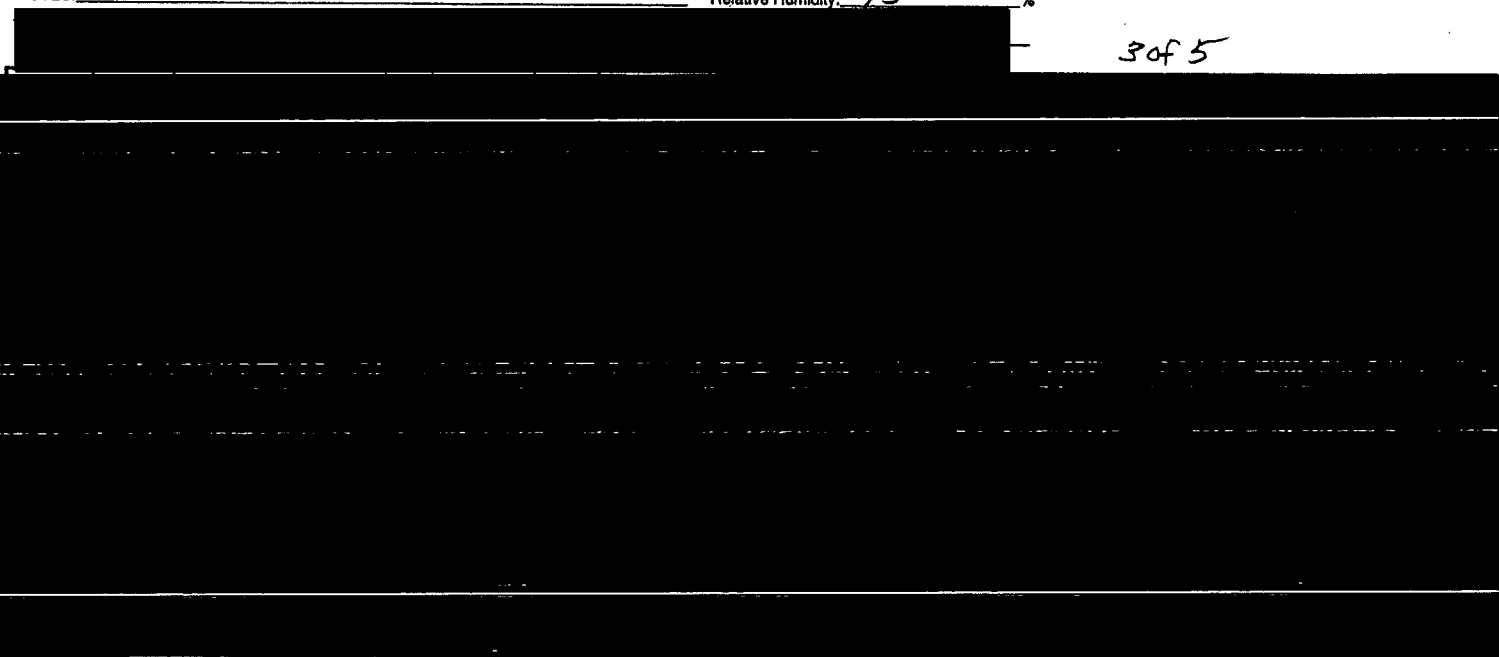
EUT Description: Radiation Monitor, Single Channel

Temperature: 23 °C

Air Pressure: 100.2 kPa

Relative Humidity: 45 %

NOTES: _____



3 of 5

Tested By: _____

Reviewed by: _____
Printed Signature

COND.DOC Rev 03.97



BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: S7439 Test Area: S/R 3

Test Method: _____ Date: 7 Nov 97

IEC 1000-4-6 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz

EUT Model #: RM-1000 Other: _____

Temperature: 23 °C

EUT Description: Radiation Monitor, Single Channel

Air Pressure: 100.6 kPa

NOTES: _____

Relative Humidity: 44 %

[Redacted]

4 of 5

[Large Redacted Area]

Tested By: [Redacted]

Reviewed by: [Redacted]

Printed

Signature

COND.DOC Rev 03.97

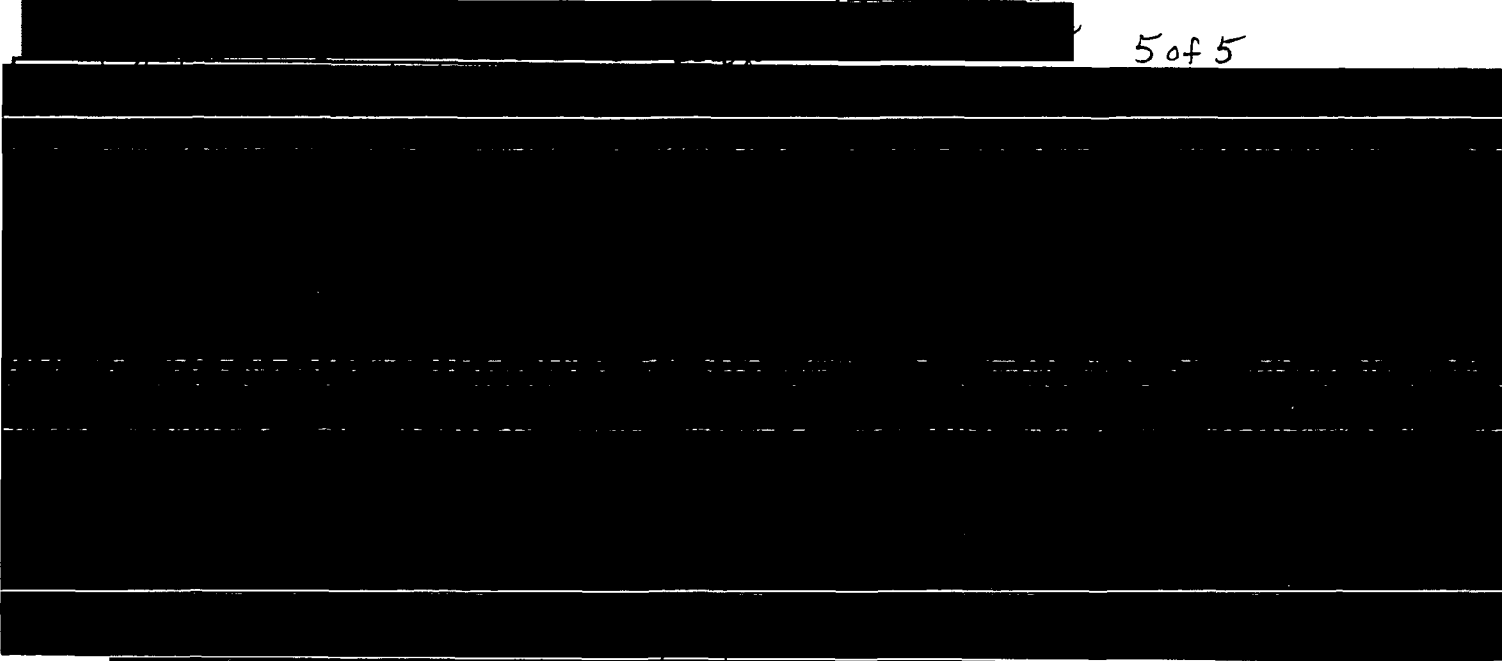


BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: 27439 Test Area: S/P 3
 Test Method: _____ Date: 7 Nov 97
IEC 1000-4-6 EUT POWER:
 EUT Model #: RM-1000 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____ Temperature: 23 °C
 EUT Description: Radiation Monitor, Single Channel Air Pressure: 100.6 kPa
 NOTES: _____ Relative Humidity: 44 %



5 of 5

Tested By: _____
 Printed Signature
 Reviewed by: _____
 Printed Signature

COND.DOC Rev 03.97



PRODUCT SERVICE

Report No. S7439-03

BUSINESS
SENSITIVE

REPORT NO. S7439
COMPANY: Sorrento Electronics Inc.
EUT: RM-1000 Radiation Monitor
EUT MODE: Normal

SPEC: EN 55011-A



25402-011-V1A-HARA-00266-001
General Atomics HARA
RM-1000 EMC Test Report, TYA (Non-Prop)



PRODUCT SERVICE



Report No. S7439-03

**BUSINESS
SENSITIVE**

REPORT No: S7439

SPEC: EN 55011-A

CUSTOMER: Sorrento Electronics Inc.

TEST DIST: [REDACTED]

E U T: RM-1000 Radiation Monitor

TEST SITE: 1

EUT MODE: Normal

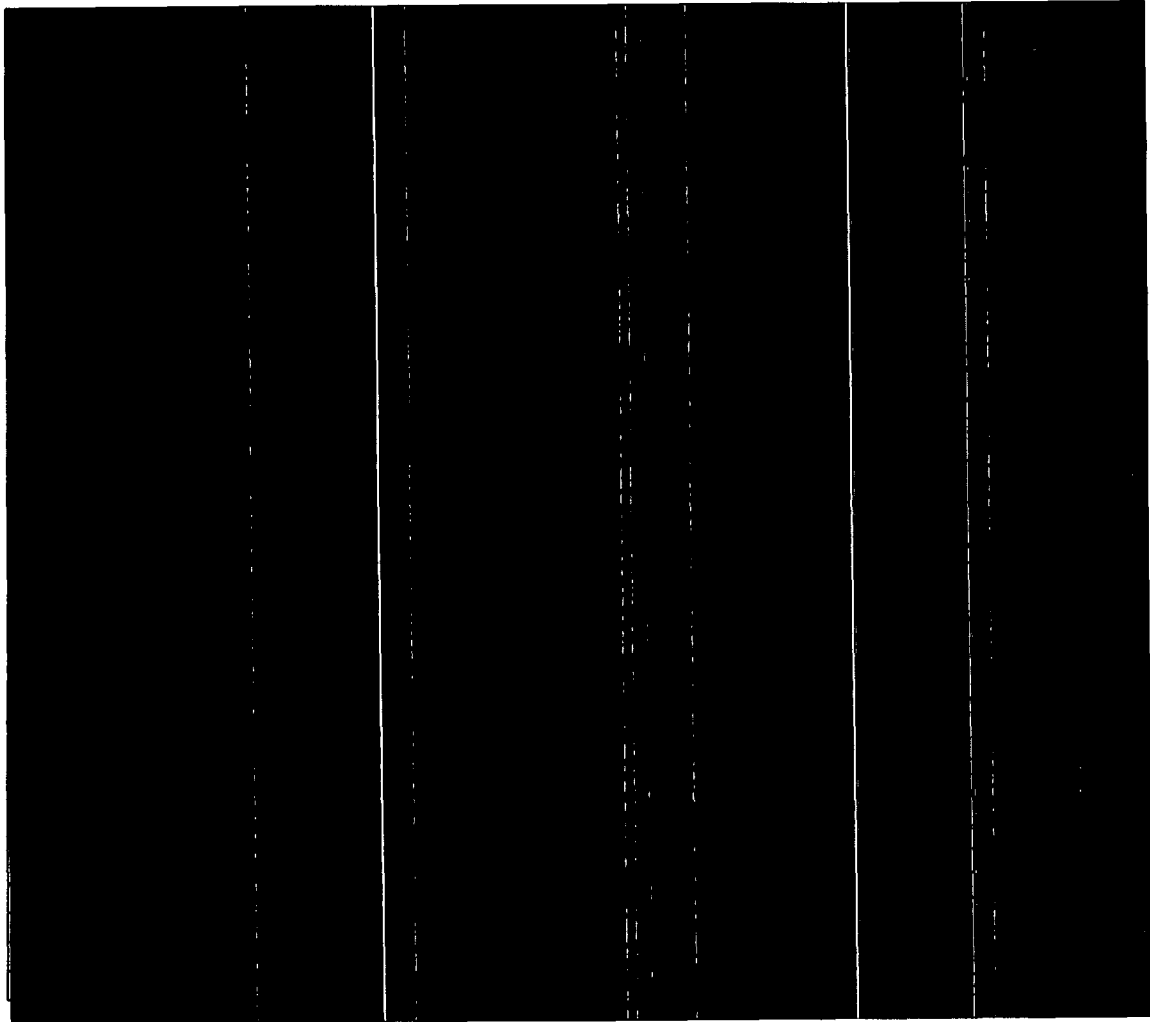
BICONICAL: 451

DATE: 5-Nov-97 TESTED BY: [REDACTED]

LOG PERIODIC: 242

NOTES: [REDACTED]

RCVR: 427

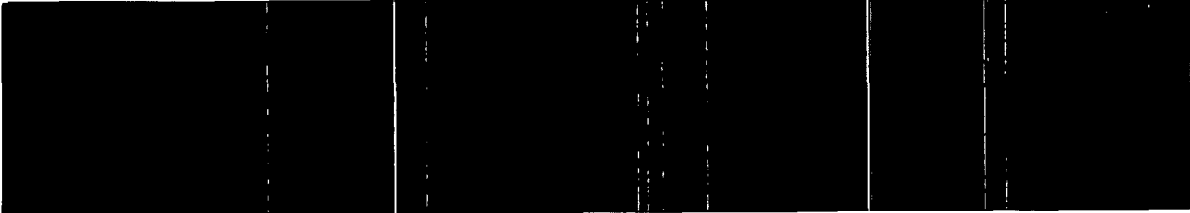




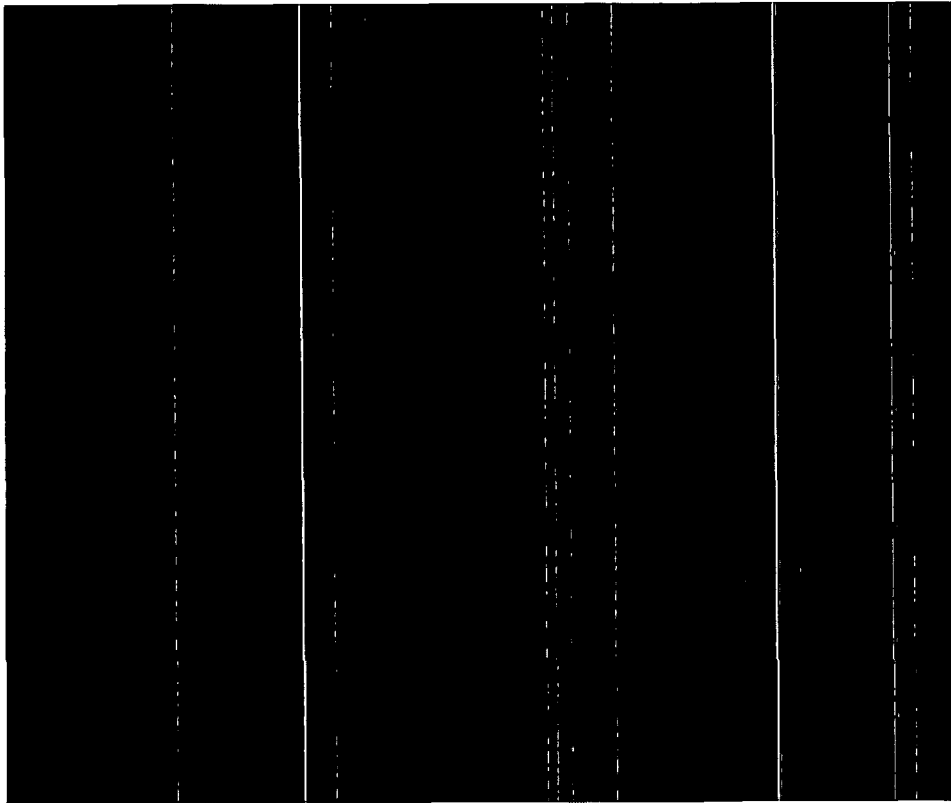
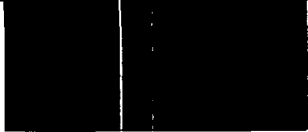
Report No. S7439-03

BUSINESS
SENSITIVE

TUV Product Service
POWERLINE CONDUCTED RFI
EUT: RM-1000 Radiation Monitor
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [Redacted]
Test Spec: EN 55011 Class A Group 1
Comment: [Redacted]
Date: 05. Nov 97 09:04



Final Measurement:



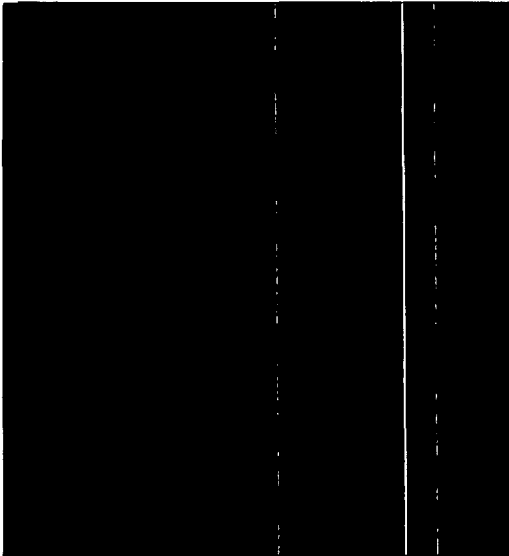


Report No. S7439-03

BUSINESS
SENSITIVE

TUV Product Service
POWERLINE CONDUCTED RFI
EUT: RM-1000 Radiation Monitor
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A Group 1
Comment: [REDACTED]
Date: 05. Nov 97 09:04

Final Measurement Results:





Report No. S7439-03

**BUSINESS
SENSITIVE**

TUV Product Service
POWERLINE CONDUCTED RFI
EUT: RM-1000 Radiation Monitor
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A Group 1
Comment: [REDACTED]
Date: 05. Nov 97 08:52



Final Measurement: [REDACTED]



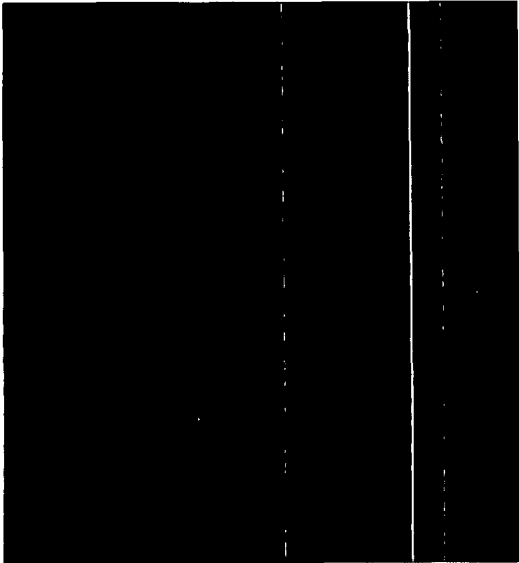


Report No. S7439-03

BUSINESS
SENSITIVE

TUV Product Service
POWERLINE CONDUCTED RFI
EUT: RM-1000 Radiation Monitor
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A Group 1
Comment: [REDACTED]
Date: 05. Nov 97 08:52

Final Measurement Results:





Report No. S7439-03

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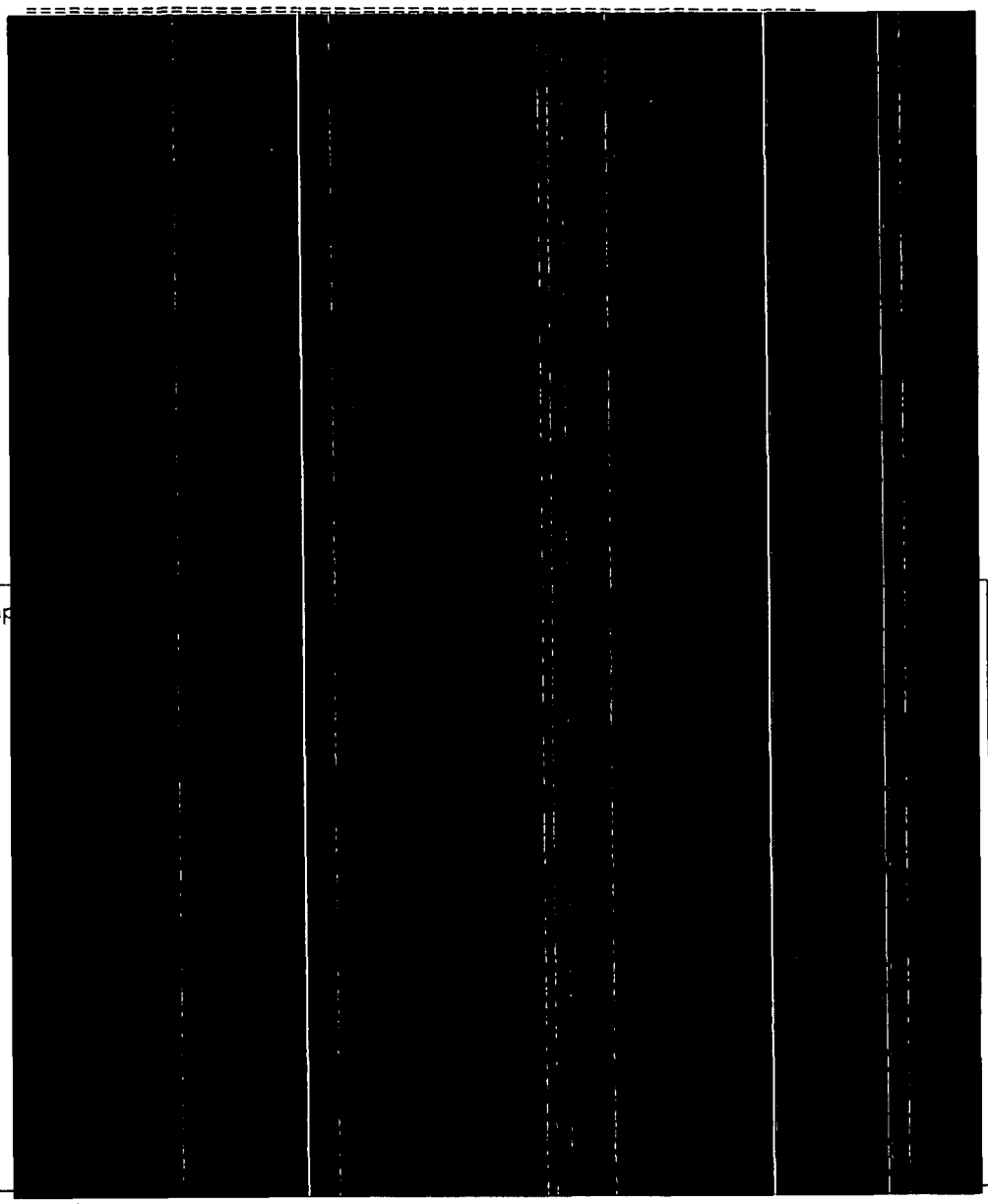


Report No. S7439-03

BUSINESS
SENSITIVE

=====
TUV Product Service . 12 Nov 1997 08:53:52
=====

4. MIL-STD 461D CE102/LISN
4.3 MIL-STD 461D CE102/lisn



hp



Report No. S7439-03

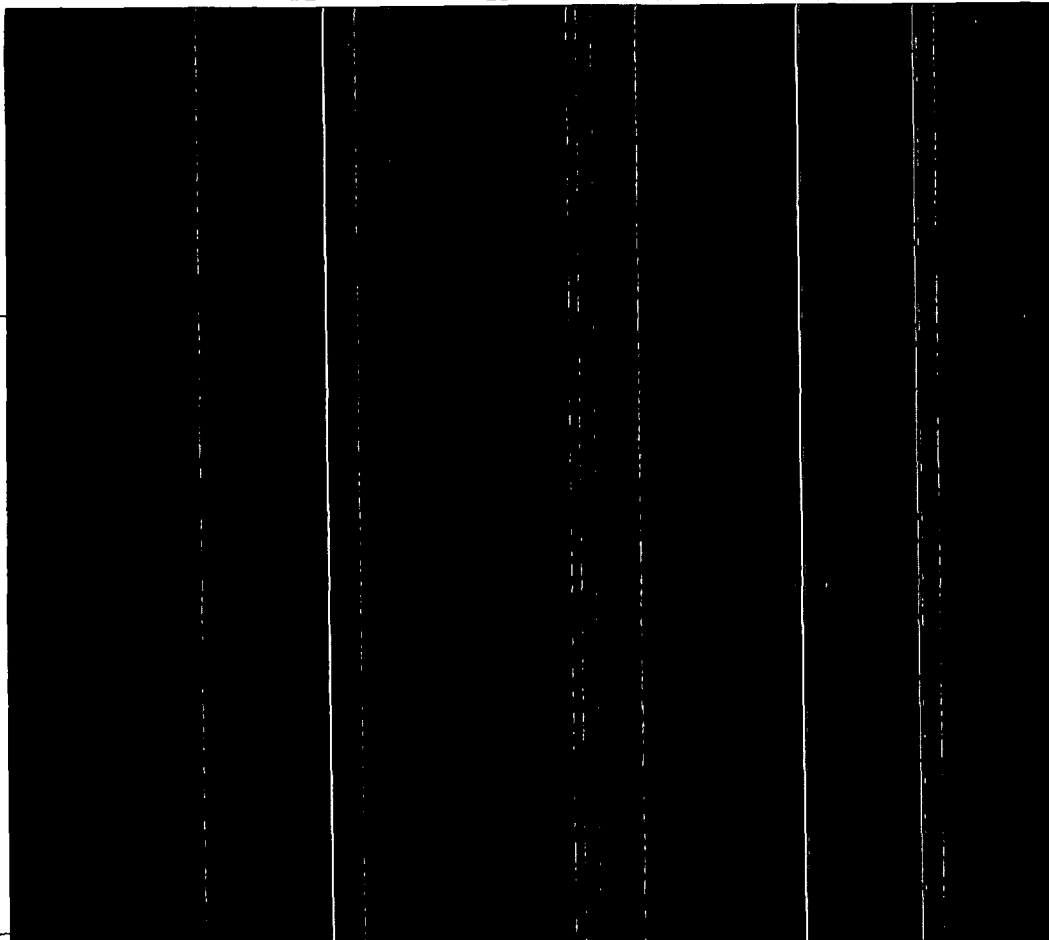
BUSINESS
SENSITIVE

=====

TUV Product Service

12 Nov 1997 14:14:26

=====





Report No. S7439-03

BUSINESS SENSITIVE

=====

TUV Product Service

12 Nov 1997 14:31:40

=====



Report No. S7439-03



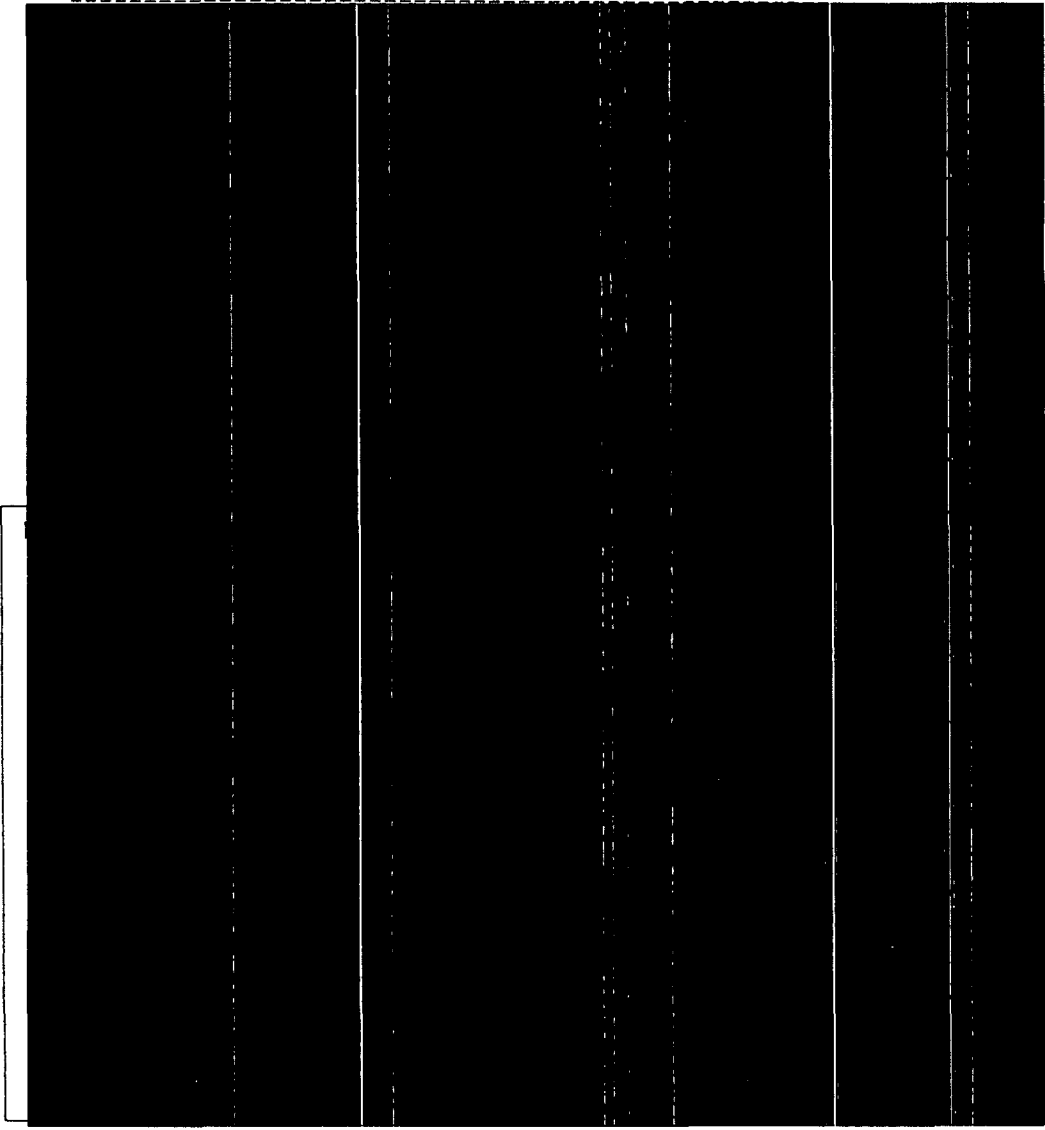
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Report No. S7439-03

BUSINESS
SENSITIVE

=====
TUV Product Service 12 Nov 1997 09:38:34
=====
4. MIL-STD 461D CE102/LISN
4.3 MIL-STD 461D CE102/lisn
=====





Report No. S7439-03

BUSINESS SENSITIVE

MIL-STD-461D

CS101 Conducted Susceptibility, 120 Hz - 50 kHz



Client: SORRENTO

Test Report #: S7439

Test Area: 9/R3

Date: 11 Nov 1997

EUT Model #: RM-1000

EUT Power: 120 Vac/400

28 Vdc

Other: _____

EUT Description: Radiation Monitor, Single Channel



NOTES:

1. [Redacted]
2. [Redacted]

Tested by: [Redacted]

Reviewed by: [Redacted]

Printed

Signature

CS01.DOC Rev 11.97



Report No. S7439-03

BUSINESS SENSITIVE

MIL-STD-461D

CS101 Conducted Susceptibility, 120 Hz - 50 kHz



Client: SORRENTO

Test Report #: 52439

Test Area: SRS

Date: 11 Nov 1997

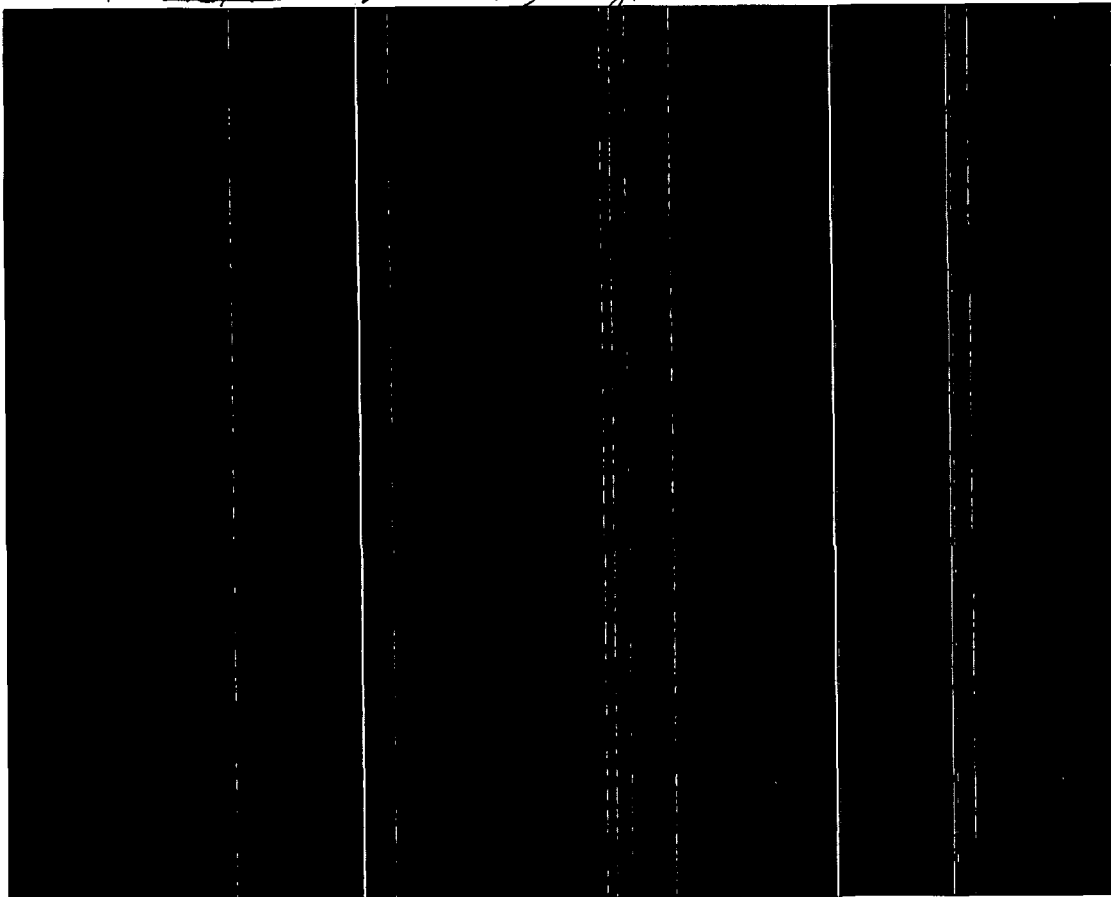
EUT Model #: RM-1000

EUT Power: 120 Vac/400

28 Vdc

Other: _____

EUT Description: Radiation Monitor, Single Channel



NOTES:

1. [Redacted]
2. [Redacted]

Tested by: [Redacted]

Reviewed by: [Redacted]

Printed

Signature

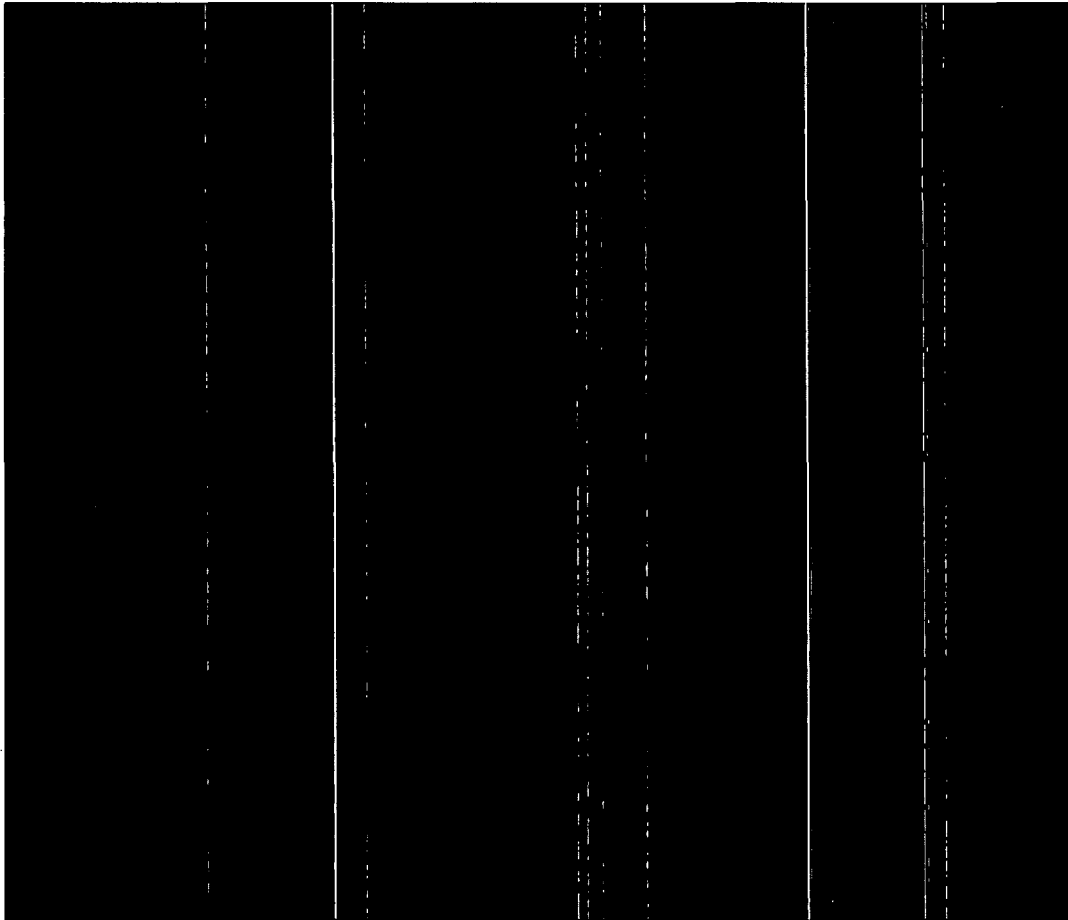
CS01.DOC Rev 11.97



Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration Reference for ESD, Tabletop Unit

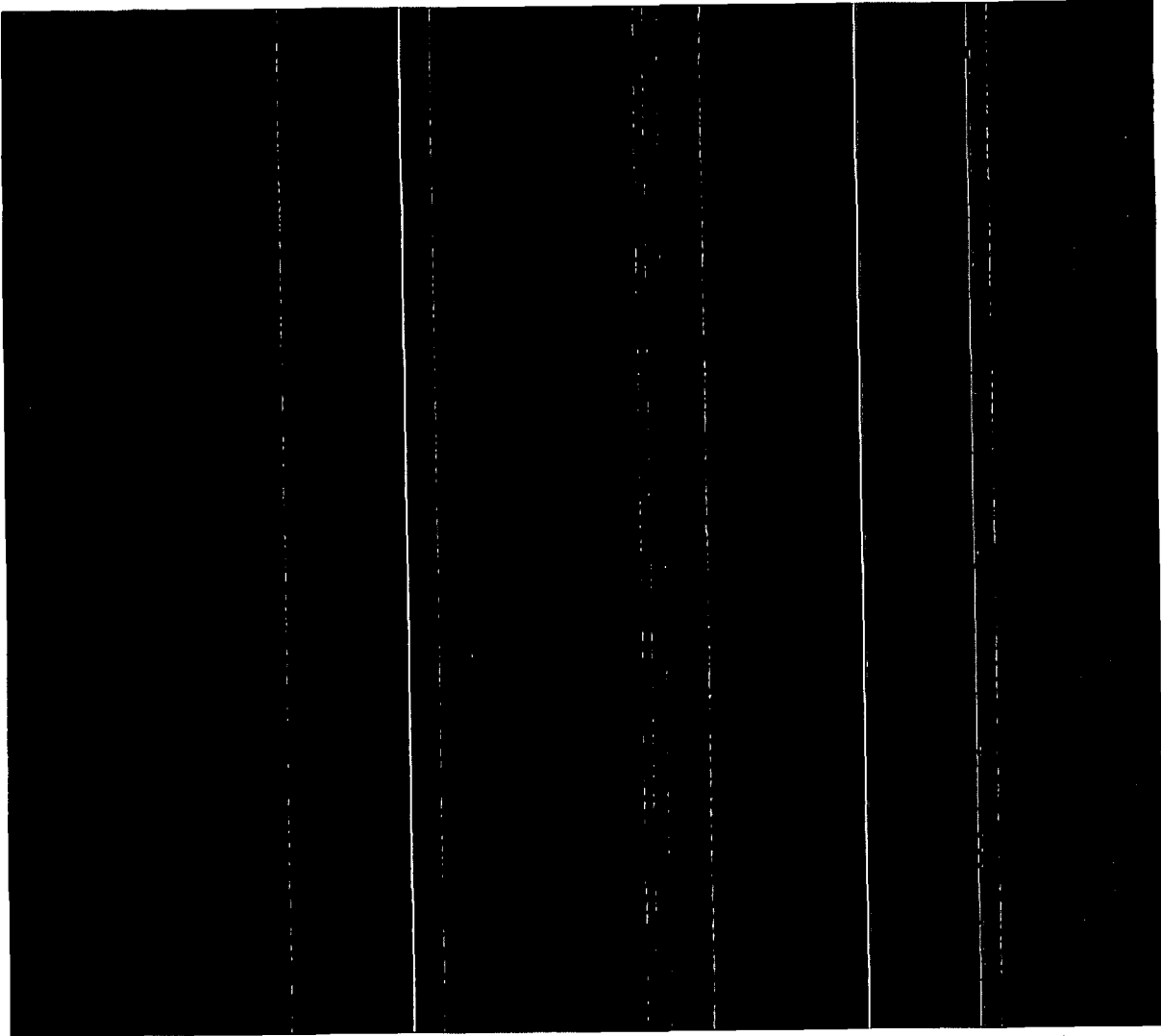




Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration for Radiated E-Fields Immunity

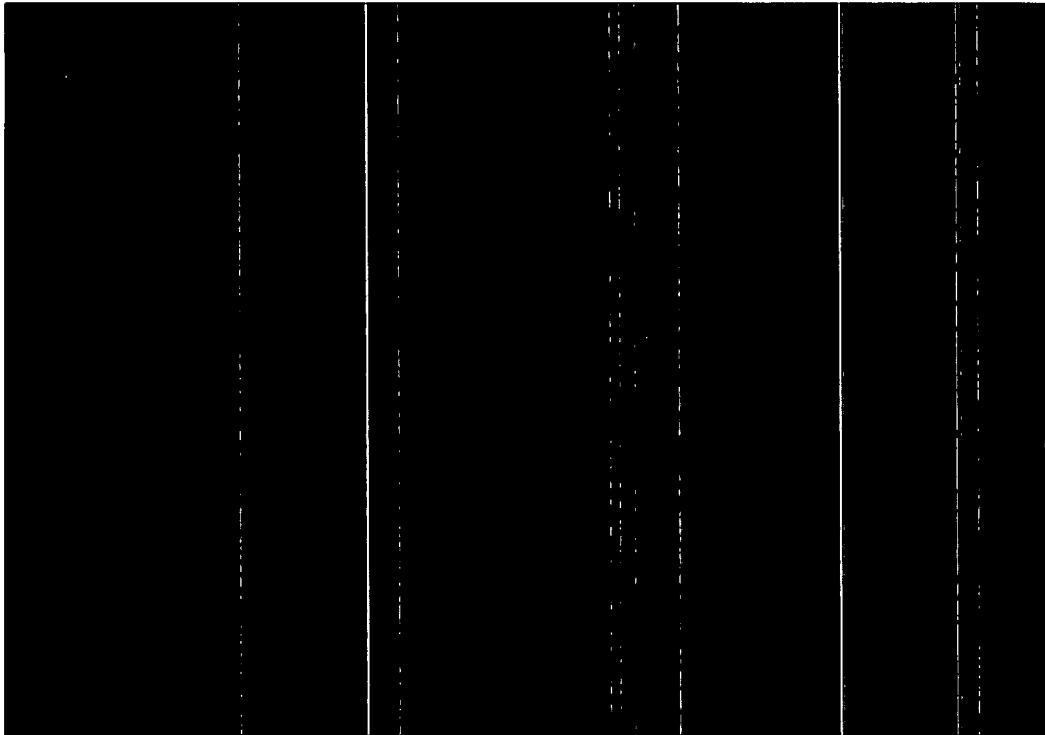




Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration for Electrical Fast Transient/Burst Immunity

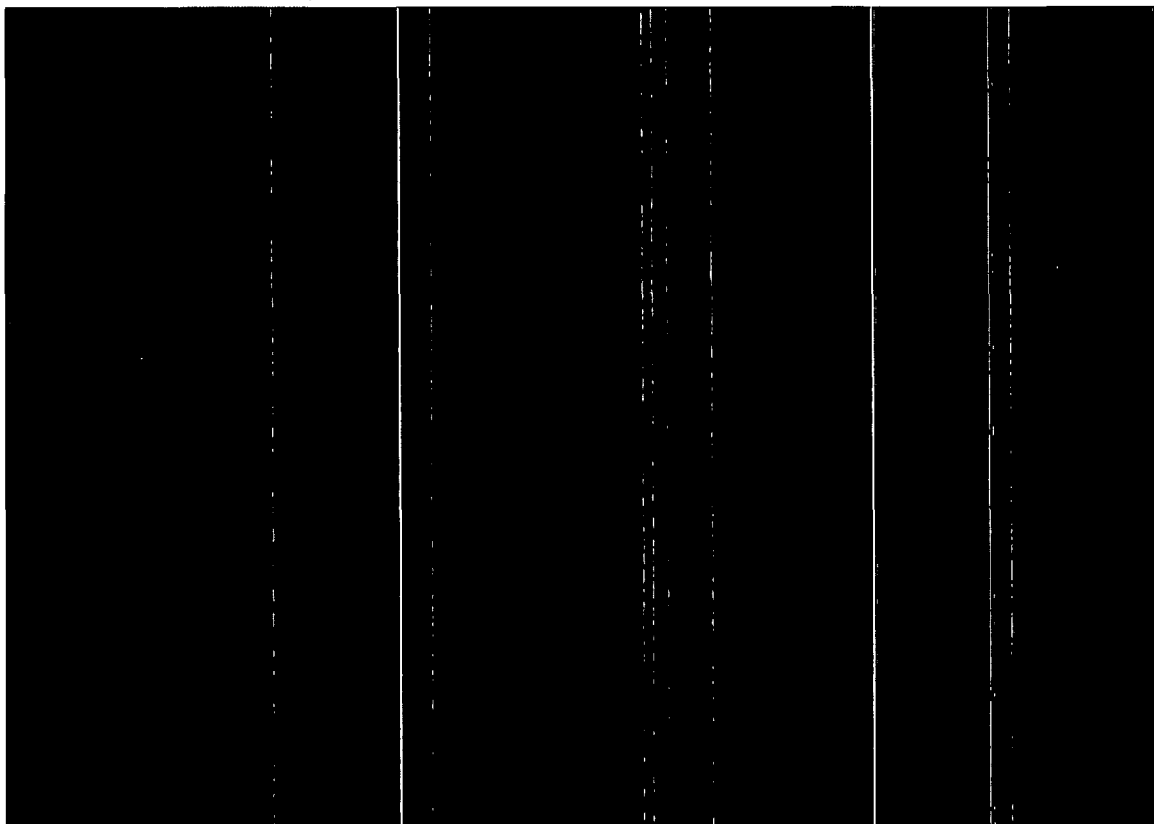




Report No. S7439-03

BUSINESS
SENSITIVE

Test Equipment Connections for Electrical Fast Transient/Burst Injection - Power Leads

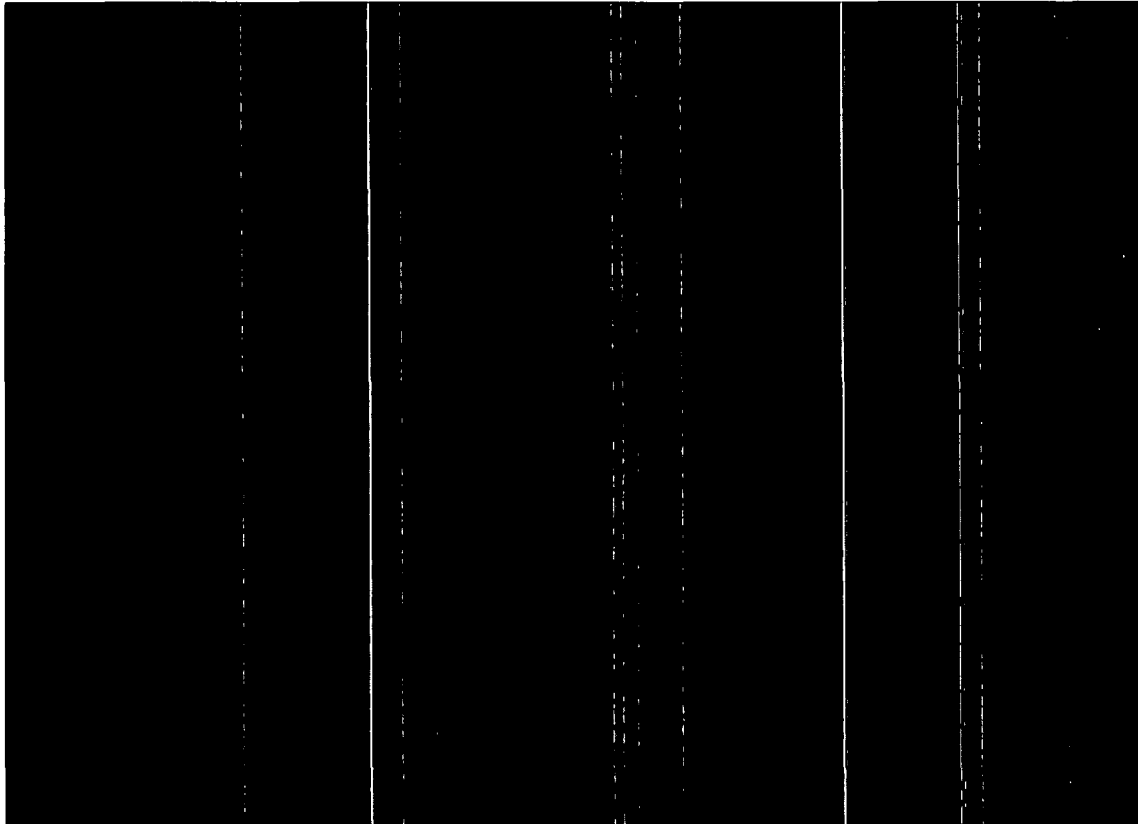




Report No. S7439-03

**BUSINESS
SENSITIVE**

Test Equipment Connections for Electrical Fast Transient/Burst Injection - Cables





Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration for Surge Immunity



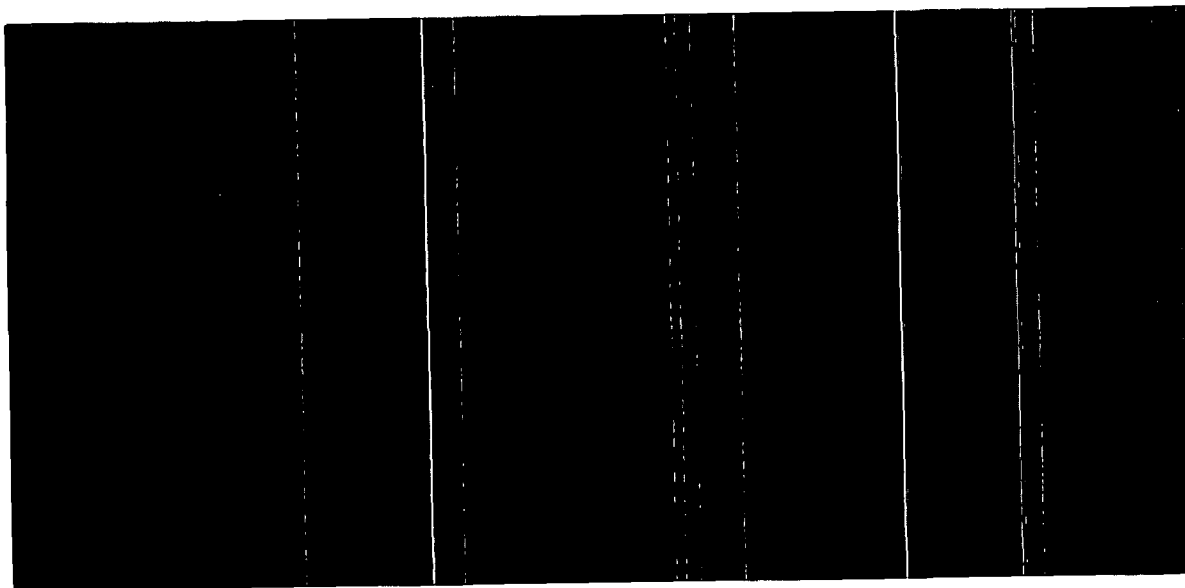


PRODUCT SERVICE

Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration for Immunity to Conducted Disturbances

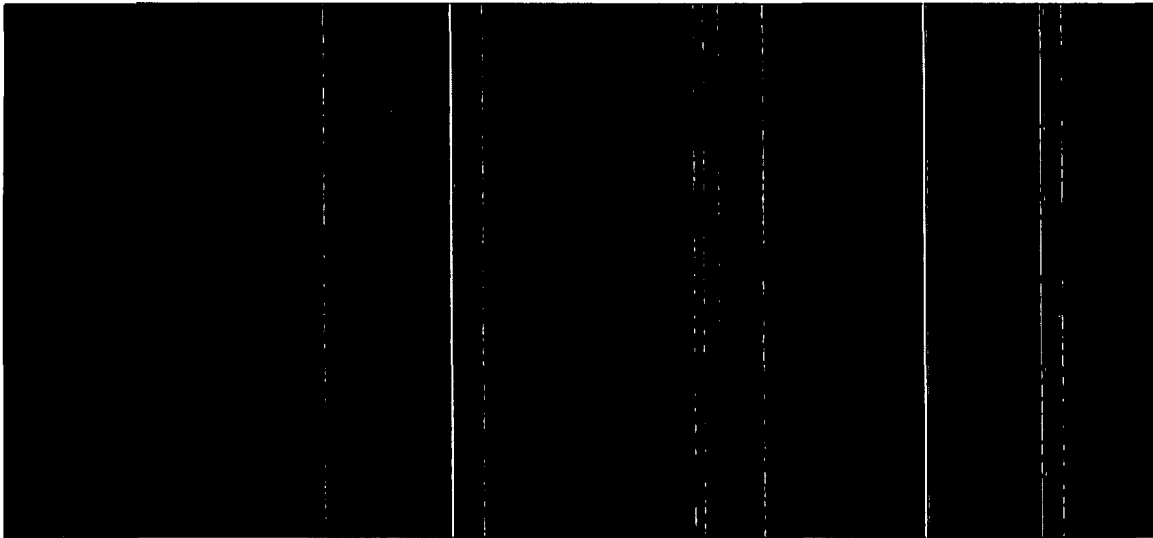




Report No. S7439-03

BUSINESS
SENSITIVE

Test Configuration for Immunity to Conducted Disturbances

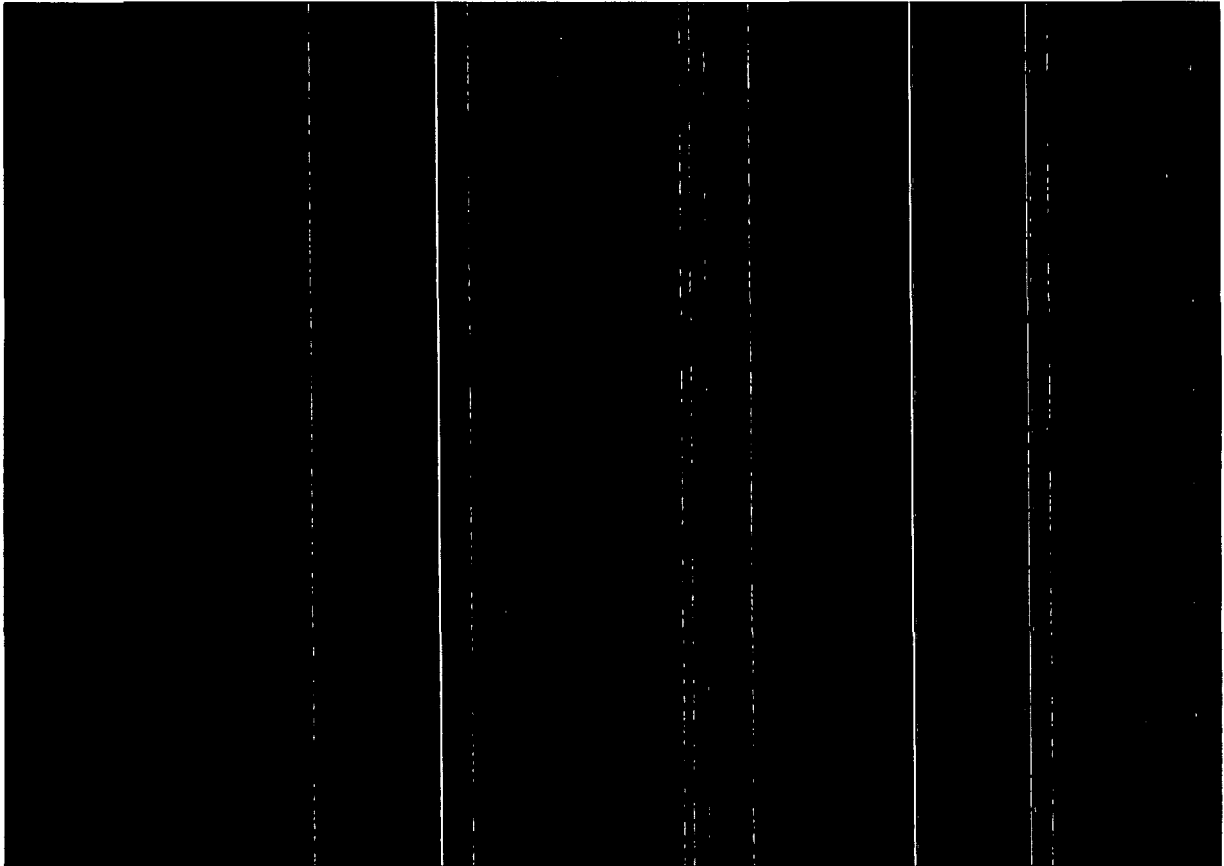




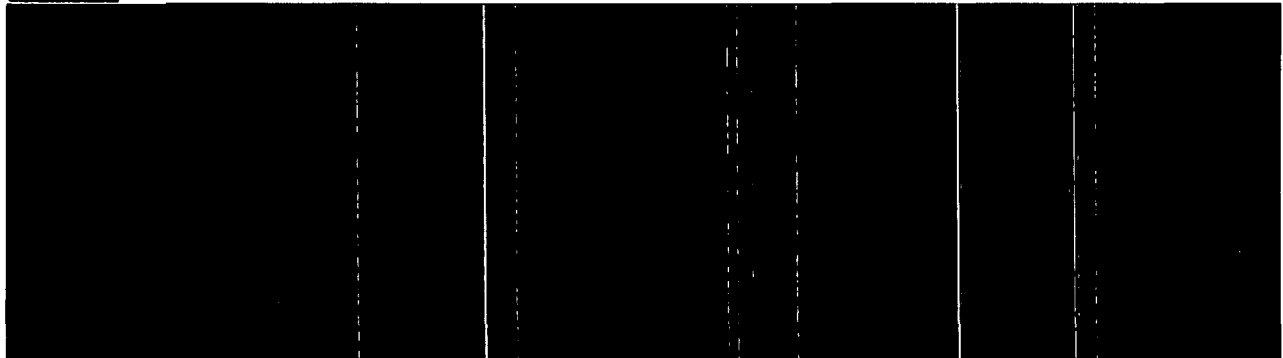
Report No. S7439-03

**BUSINESS
SENSITIVE**

Radiated Emission Test Setup, 30 to 1,000 MHz



LEGEND:

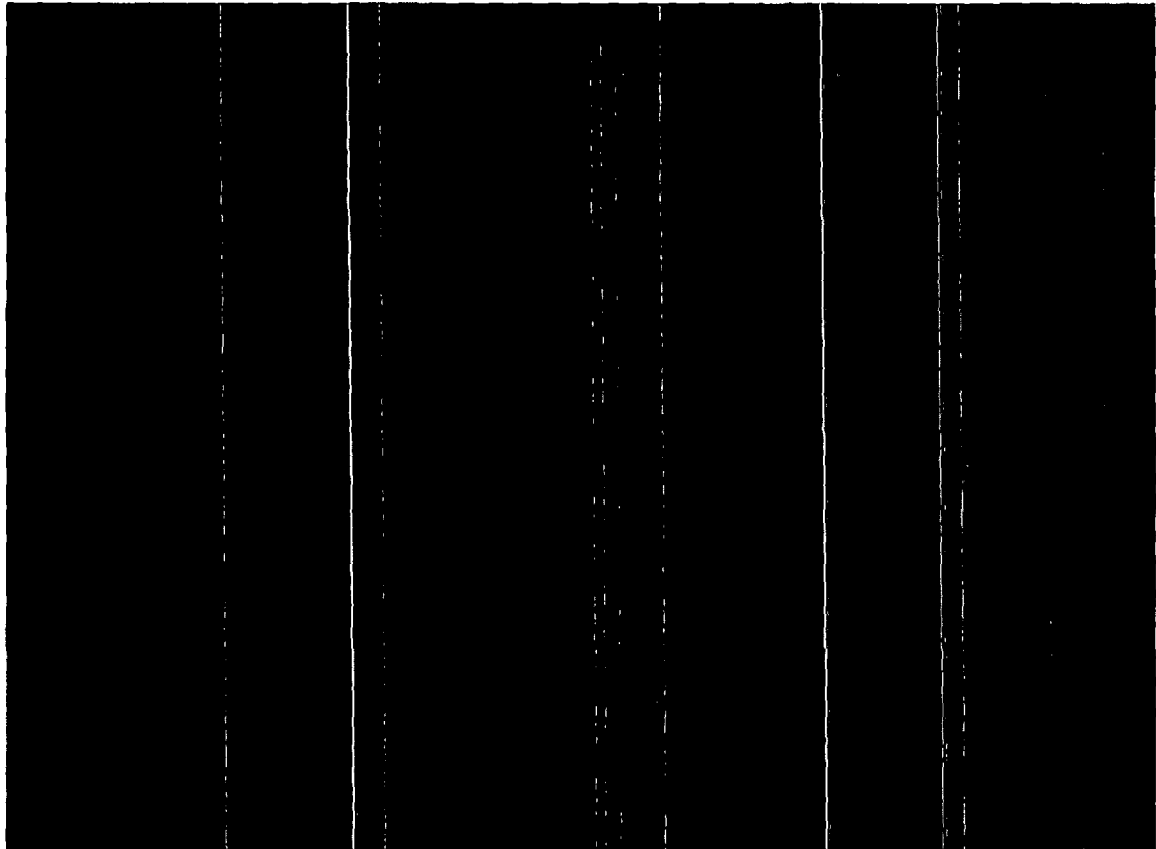




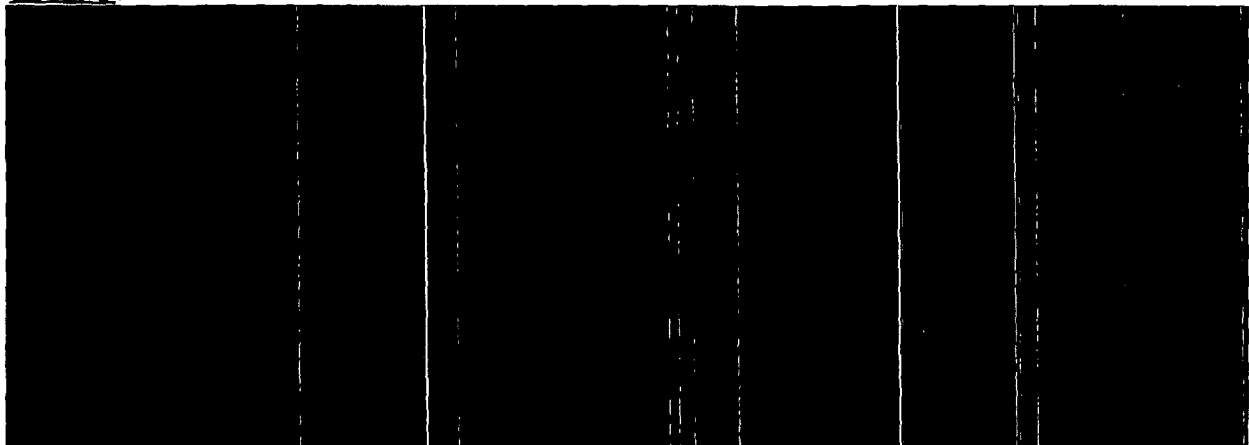
Report No. S7439-03

**BUSINESS
SENSITIVE**

Conducted Emission Test Setup, 0.15 TO 30 MHz



LEGEND:





Report No. S7439-03

BUSINESS
SENSITIVE



CE102 TEST SETUP

Report No. S7439-03



Appendix A

Photographs



Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Electrostatic Discharge (ESD)
IEC 1000-4-2/EN 61000-4-2

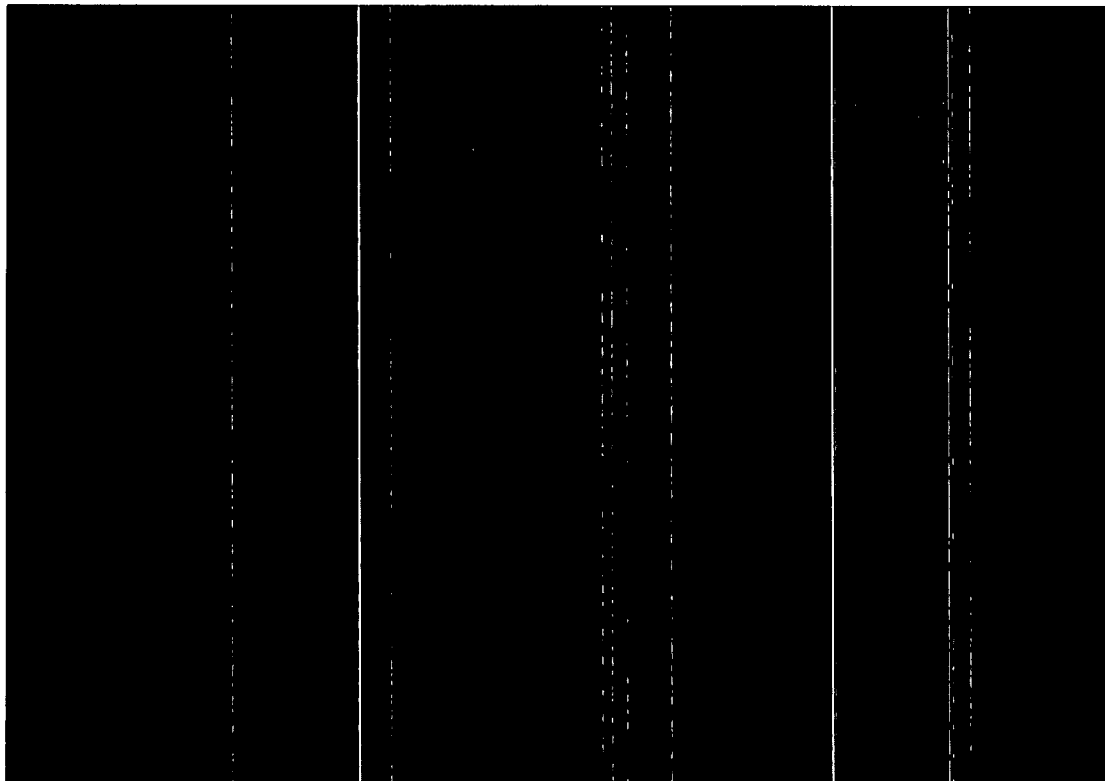




Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Electrostatic Discharge (ESD)
IEC 1000-4-2/EN 61000-4-2

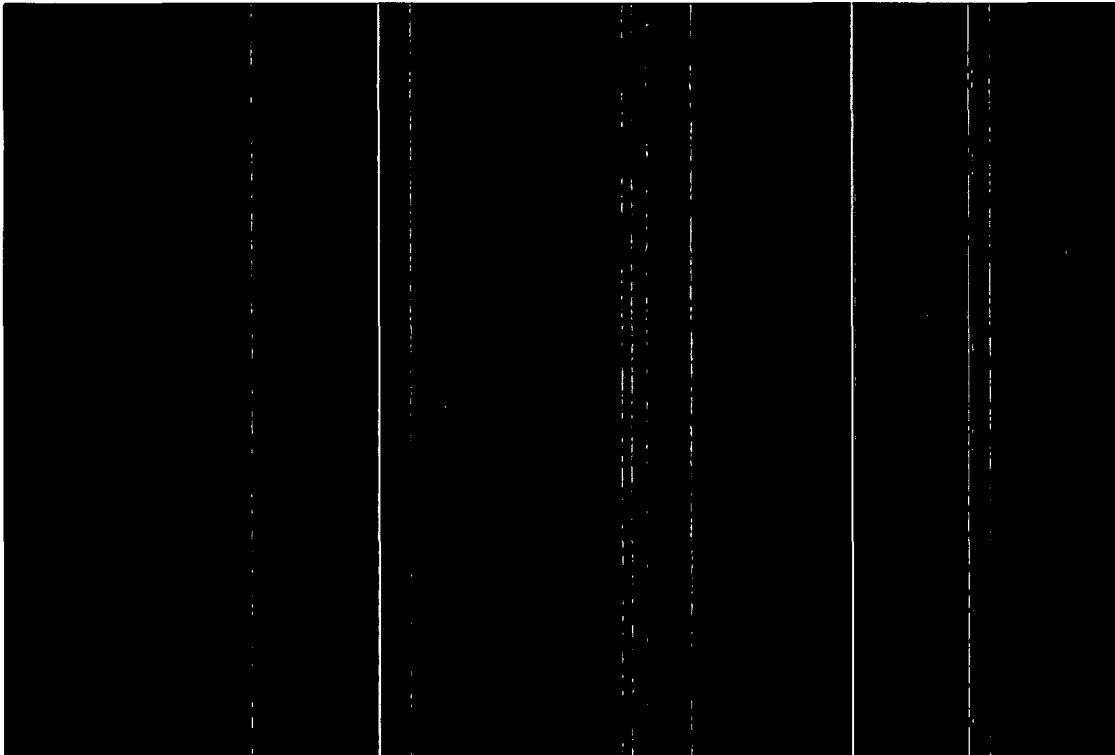




Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Radiated Electromagnetic Field
IEC 1000-4-3/ENV 50140



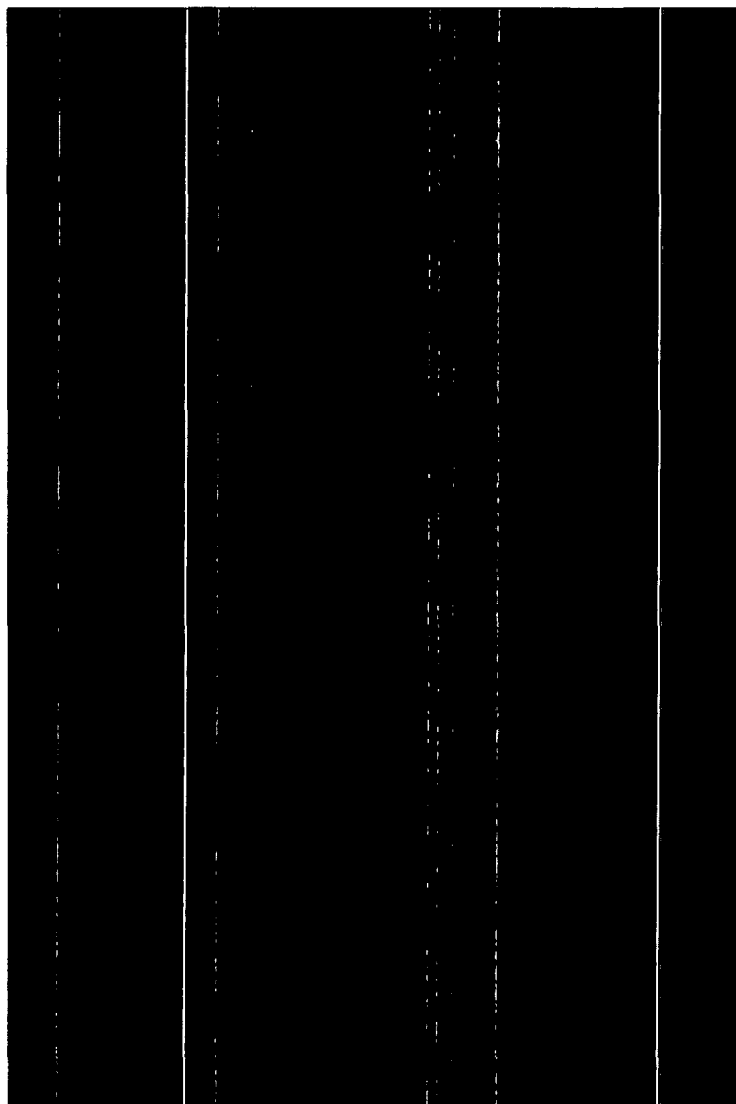


Report No. S7439-03



**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Radiated Electromagnetic Field
IEC 1000-4-3/ENV 50140

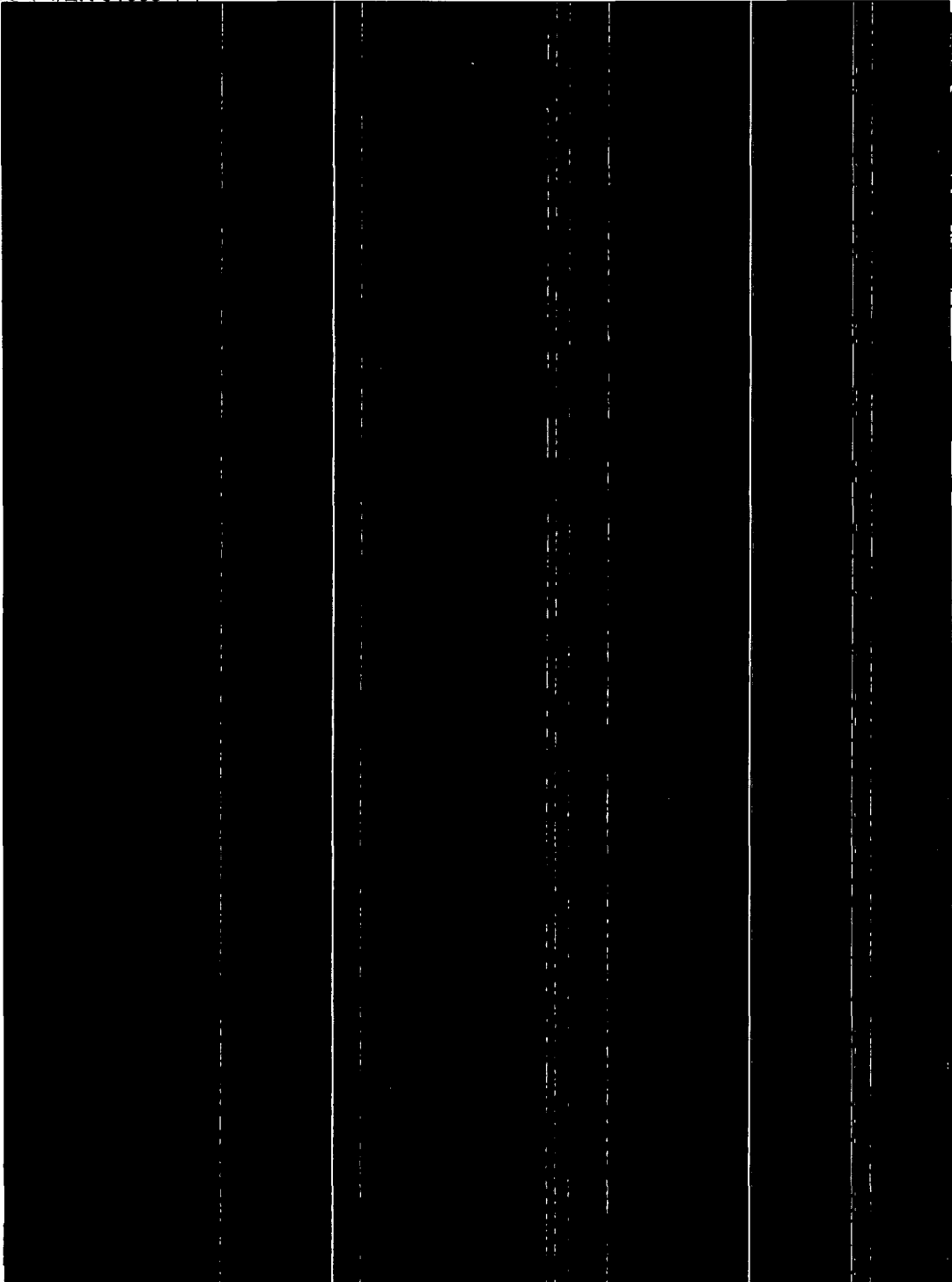




Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Fast transients (BURST)
IEC 1000-4-4/EN 61000-4-4





Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
SURGE Transients
IEC 1000-4-5

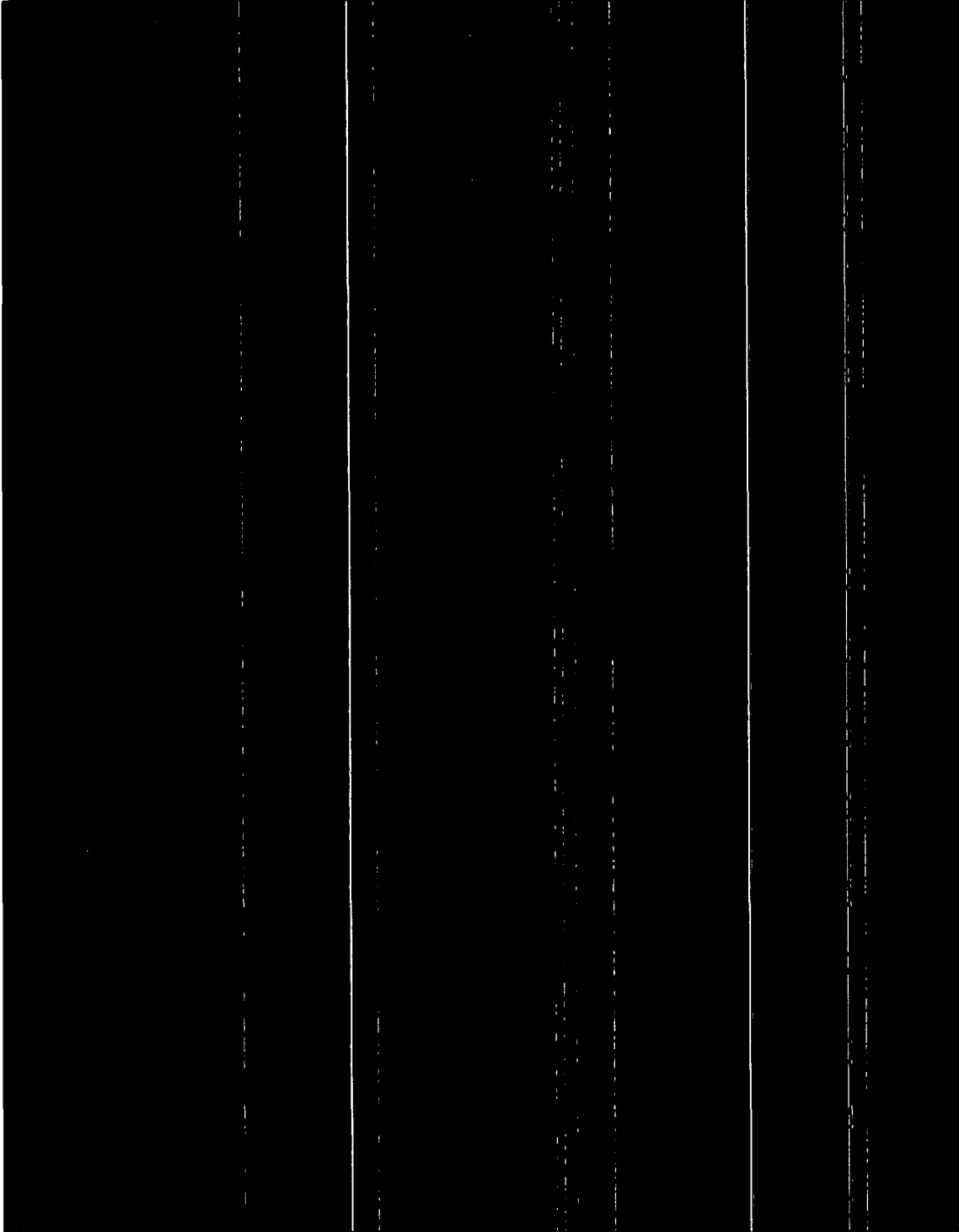




Report No. S7439-03

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Conducted Disturbance
ENV 50141



Page A8 of A12

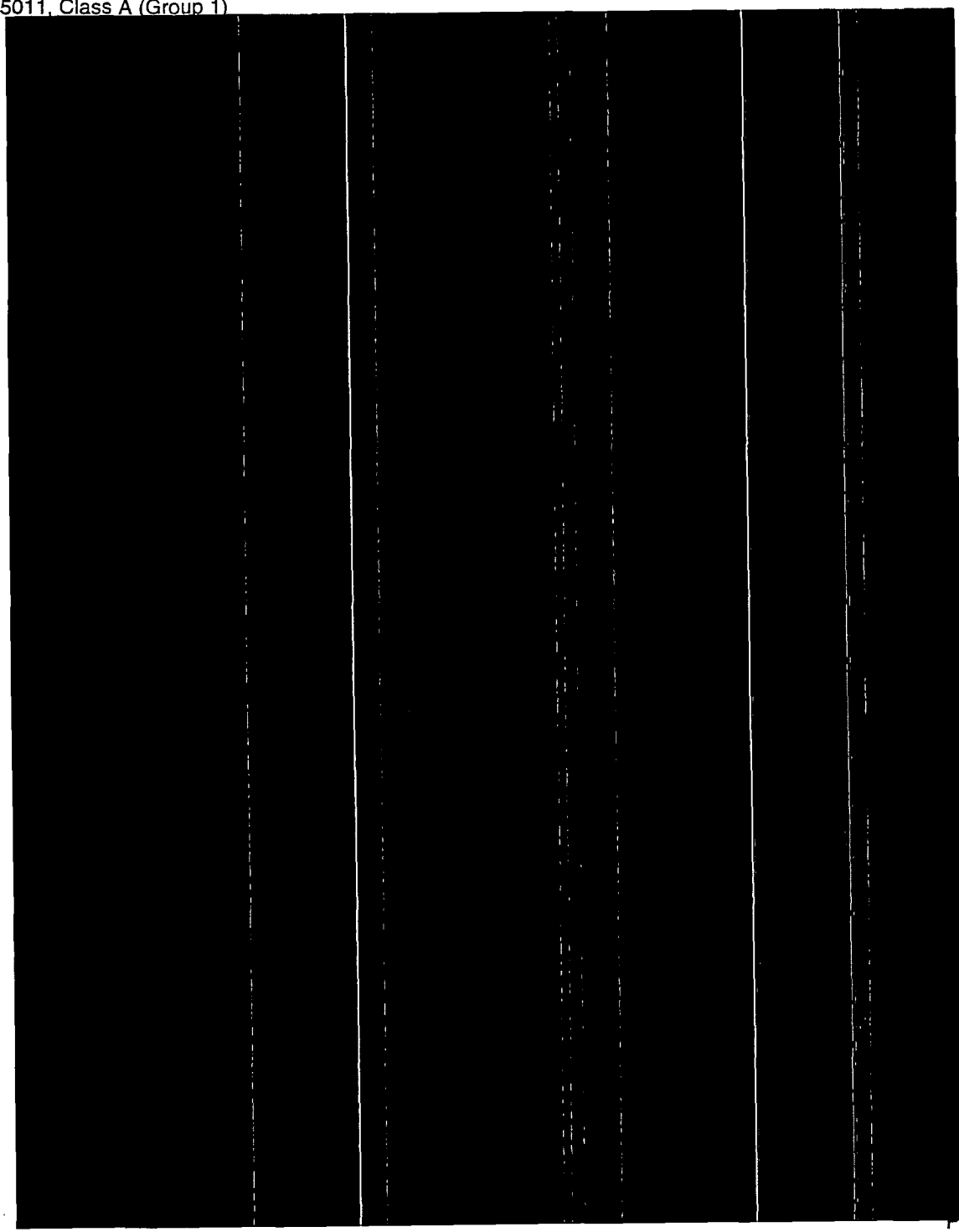
Rev.No 1.0



Report No. S7439-03

 BUSINESS SENSITIVE

Photograph of Test Setup:
Radiated Emissions
EN 55011, Class A (Group 1)

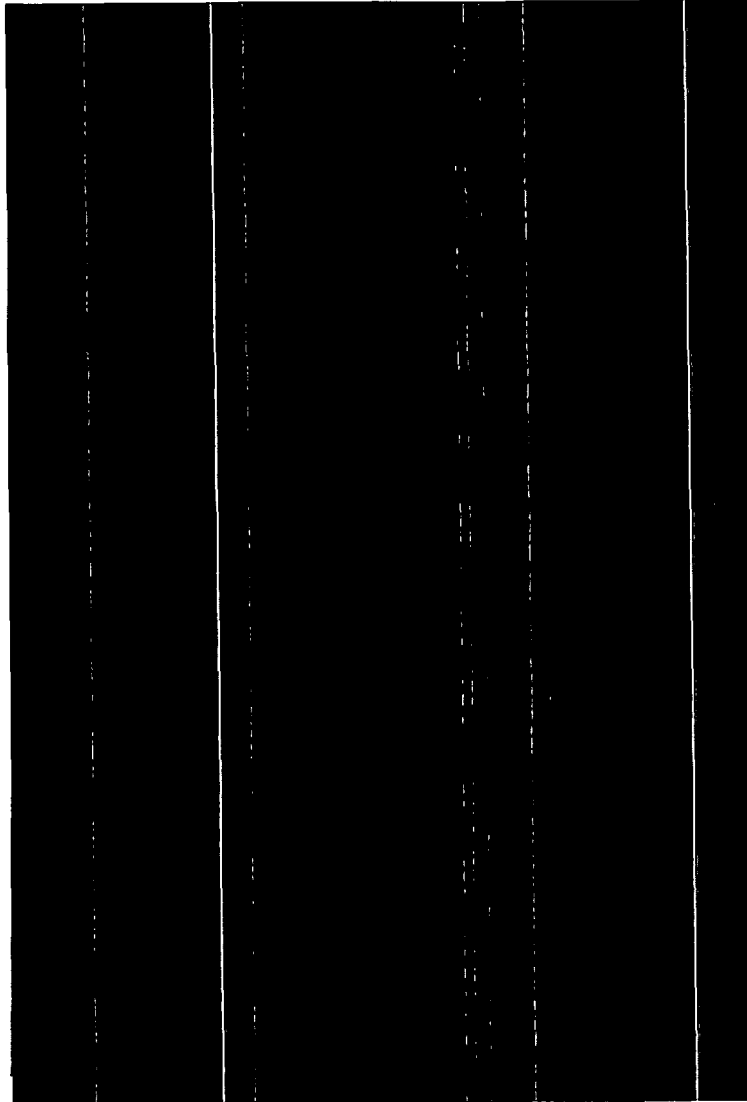




Report No. S7439-03

BUSINESS
SENSITIVE

Photograph of Test Setup:
Conducted Emissions
EN 55011, Class A (Group 1)

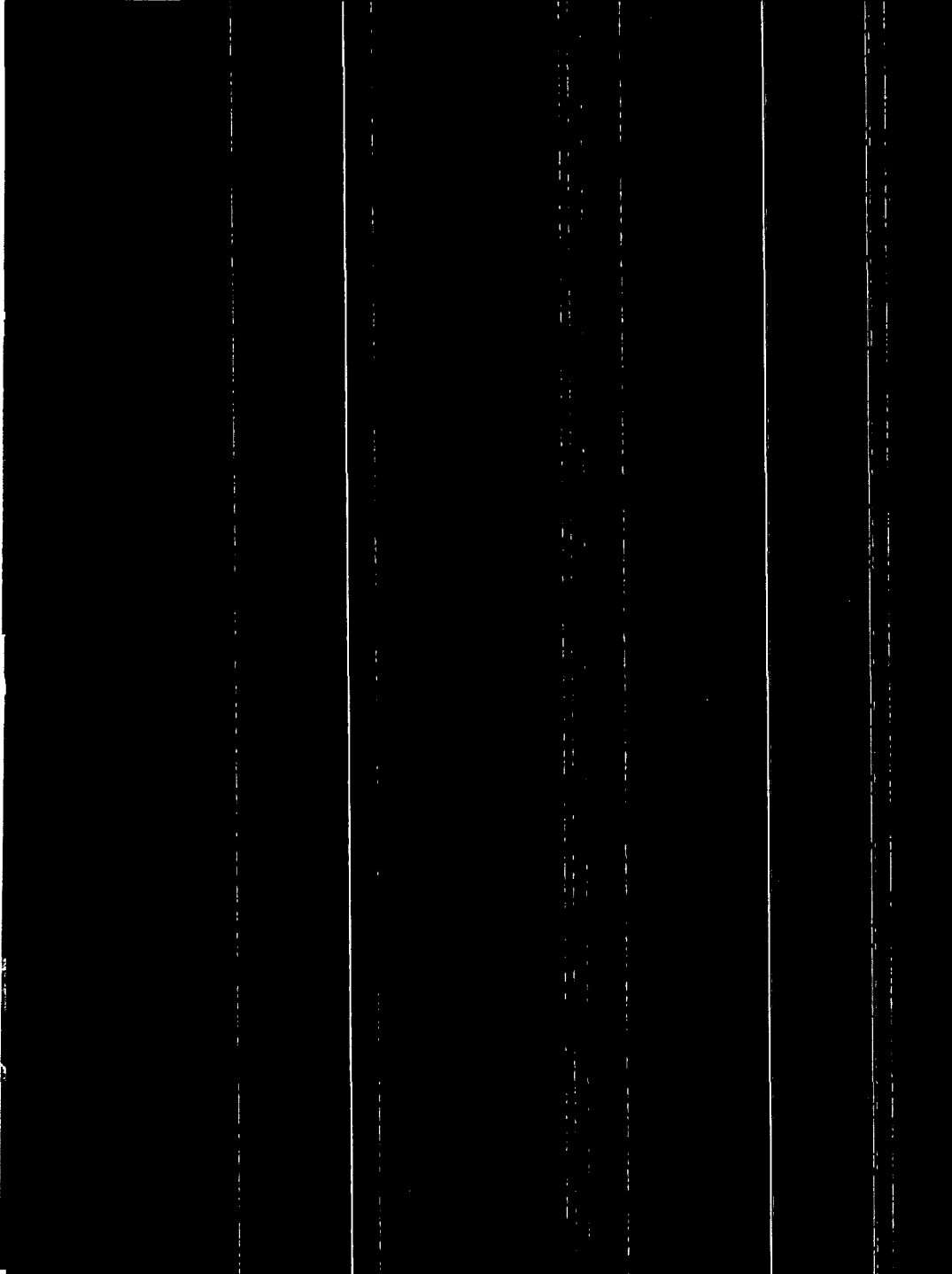




Report No. S7439-03

BUSINESS
SENSITIVE

Photograph of Test Setup:
RF Conducted Emissions
(CE102) MIL-STD-461D



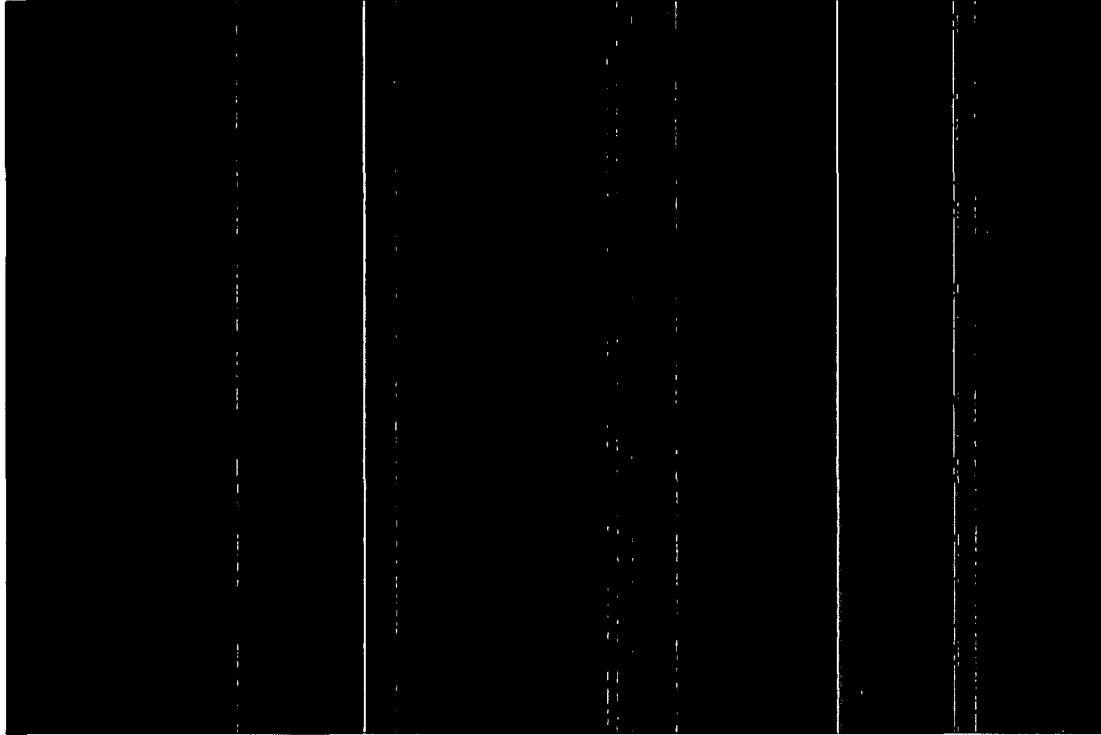


Report No. S7439-03



BUSINESS
SENSITIVE

Photograph of Test Setup:
RF Conducted Susceptibility
(CS101) MIL-STD-461D





Report No. S7439-03

Appendix B

Product Information Form(s)



Report No. S7439-03

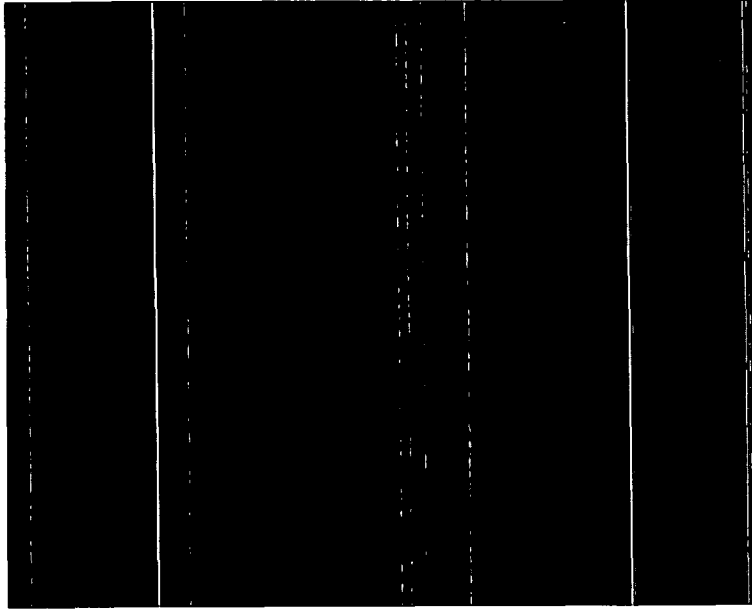
BUSINESS SENSITIVE

CUSTOMER INFORMATION					
COMPANY NAME:		SORRENTO ELECTRONICS			
COMPANY ADDRESS:		10240 Flanders Court			
		San Diego, CA 92121			
PHONE NUMBER:		619 457 8954			
FAX NUMBER:		619 453 4675			
CUSTOMER CONTACT:		Walter Wong			
PRODUCT DESCRIPTION					
NAME, MODEL, SERIAL # OF EUT:		Radiation Monitor, Single Channel, Model RM-1000, S/N MKT 012			
DESCRIPTION OF EUT:		RM-1000 module assembly, detector assembly with interconnecting cable and power supply.			
Components of EUT					
Description	Model Number	Serial Number	SE ID Number		
Module Assembly	RM-1000	MKT 012	04505101-001		
Detector Assembly	RD25-03	N/A	02810033-003		
Power Supply	S-25-24	C97740368	50015631-001		
Cable Assembly	N/A	N/A	50000837-001		
OPERATING MODE(S):					
EUT CONFIGURATIONS:					
FREQUENCY/AC/DC VOLTAGE:					
PHASES (ϕ)/CURRENT (amps):					
OSCILLATOR FREQUENCIES:					
DESCRIPTION:					
MANUFACTURER, MODEL #, S/N #					
SWITCHING FREQUENCY:					
POWERLINE FILTER: MODEL #:					
DESCRIPTION OF ENCLOSURE:					
CRITICAL EMI COMPONENTS:					
INTERFACING AND/OR SIMULATORS PERIPHERAL EQUIPMENT:					
BLOCK DIAGRAM:		See page B3.			



Report No. S7439-03

**BUSINESS
SENSITIVE**



Report No. S7439-03



Appendix C

Change History

Not Applicable



Appendix D

Testing Facilities

Certificates of Approval

VCCI (3), NVLAP, EN 45001



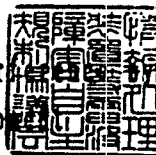
CERTIFICATE

Facility: Enclosure No. 1
(Conducted Interference Measurement)
Company : TÜV Product Service Inc.
Address : 7562 Trade Street, San Diego,
CA 92121 U. S. A.

*This is to certify that the following measuring facility
has been registered in accordance with the Regulations
for Voluntary Control Measures, Article 8.*

Registration No. : C-211
Date of Registration : December 26, 1994
This Certificate is valid until October 5, 1997.

Voluntary Control Council for Inter
Information Technology Equip





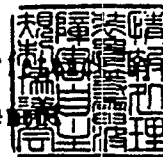
CERTIFICATE

Facility: Enclosure No. 2
(Conducted Interference Measurement)
Company : TÜV Product Service Inc.
Address : 7562 Trade Street, San Diego,
CA 92121 U. S. A.

*This is to certify that the following measuring facility
has been registered in accordance with the Regulations
for Voluntary Control Measures, Article 8.*

Registration No. : C-212
Date of Registration : December 26, 1994
This Certificate is valid until October 5, 1997.

Voluntary Control Council for Interference
Information Technology Equipment





CERTIFICATE

Facility: Carroll Canyon Site
(Radiation 3, 10, 30meter site)

Company : TÜV Product Service Inc.

Address : 7562 Trade Street, San Diego,
CA 92121 U. S. A.

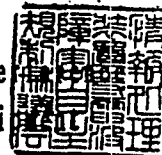
*This is to certify that the following measuring facility
has been registered in accordance with the Regulations
for Voluntary Control Measures, Article 8.*

Registration No. : R-212

Date of Registration : December 26, 1994

This Certificate is valid until October 5, 1997.

Voluntary Control Council for International
Information Technology Equipment

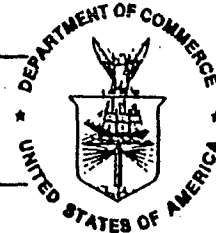


United States Department of Commerce
National Institute of Standards and Technology

NVLAP[®]

ISO/IEC GUIDE 25:1990
ISO 9002:1987

Certificate of Accreditation



TUV PRODUCT SERVICE, INC.
SAN DIEGO, CA

is recognized under the National Voluntary Laboratory Accreditation Program for satisfactory compliance with criteria established in Title 15, Part 285 Code of Federal Regulations. These criteria encompass the requirements of ISO/IEC Guide 25 and the relevant requirements of ISO 9002 (ANSI/ASQC Q92-1987) as suppliers of calibration or test results. Accreditation is awarded for specific services, listed on the Scope of Accreditation for:

**ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS
FCC**

December 31, 1997

Effective through

For the National Institute of Standards and Technology
NVLAP Lab Code: 100268-0

NVLAP-01C (11-98)

PRODUCT SERVICE



25402-011-V1A-HARA-00266-001
General Atomics HARA
RIM-1000 EMC Test Report T/A (Non-Prop)



UNITED STATES DEPARTMENT OF COMMERCE
National Institute of Standards and Technology
Gaithersburg, Maryland 20899-0001

December 19, 1996

[REDACTED]
TUV Product Service, Inc.
10040 Mesa Rim Road
San Diego, CA 92121

NVLAP Lab Code: 100268-0

Dear Mr. Smith:

I am pleased to inform you that continuing accreditation for specific test methods in Electromagnetic Compatibility & Telecommunications, FCC is granted to your organization under the National Voluntary Laboratory Accreditation Program (NVLAP). This accreditation is effective until December 31, 1997, provided that your organization continues to comply with accreditation requirements contained in the NVLAP Procedures.

Your Certificate of Accreditation is enclosed along with a statement of your Scope of Accreditation. You may reproduce these documents in their entirety and announce your organization's accreditation status using the NVLAP logo in business publications, the trade press, and other business-oriented literature. Accreditation does not relieve your organization from observing and complying with any applicable existing laws and/or regulations.

We are pleased to have you participate in NVLAP and look forward to your continued association with this program. If you have any questions concerning your NVLAP accreditation, please direct them to Jon Crickenberger, Sr. Program Manager, Laboratory Accreditation Program, National Institute of Standards and Technology, Building 820, Room 282, Gaithersburg, MD 20899-0001; (301) 975-4016.

Sincerely,

[REDACTED SIGNATURE]

Laboratory Accreditation Program

Enclosure(s)

NIST

Page D6 of D16



National Institute of Standards and Technology **NVLAP**® National Voluntary Laboratory Accreditation Program

ISO/IEC GUIDE 25:1990
ISO 9002:1987

Scope of Accreditation

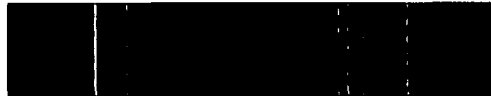


Page: 1 of 1

**ELECTROMAGNETIC COMPATIBILITY
AND TELECOMMUNICATIONS**

NVLAP LAB CODE 100268-0

TUV PRODUCT SERVICE, INC.
10040 Mesa Rim Road



NVLAP Code Designation / Description

International Special Committee on Radio Interference (CISPR) Methods

12/CIS22 IEC/CISPR 22:1993: Limits and methods of measurement of radio disturbance characteristics of information technology equipment

Federal Communications Commission (FCC) Methods

12/F01 FCC Method - 47 CFR Part 15 - Digital Devices
12/F01a Conducted Emissions, Power Lines, 450 KHz to 30 MHz
12/F01b Radiated Emissions

December 31, 1997

Effective through



For the National Institute of Standards and Technology

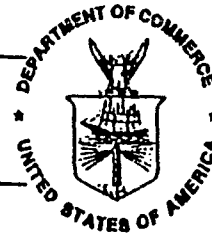
NVLAP-015 (11-95)

United States Department of Commerce
National Institute of Standards and Technology

NVLAP[®]

ISO/IEC GUIDE 25:1990
ISO 9002:1987

Certificate of Accreditation




TUV PRODUCT SERVICE, INC.
SAN DIEGO, CA

is recognized under the National Voluntary Laboratory Accreditation Program for satisfactory compliance with criteria established in Title 15, Part 285 Code of Federal Regulations. These criteria encompass the requirements of ISO/IEC Guide 25 and the relevant requirements of ISO 9002 (ANSI/ASQC Q92-1987) as suppliers of calibration or test results. Accreditation is awarded for specific services, listed on the Scope of Accreditation for:

**ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS
MIL-STD-462**

December 31, 1997

Effective through


For the National Institute of Standards and Technology
NVLAP Lab Code: 100268-0

NVLAP-01C (11-98)

PRODUCT SERVICE

TUV
General Atomics HARA
RM-1000 EMC Test Report TVA (Non-Prop)

25402-011-V1A-HARA-00266-001



UNITED STATES DEPARTMENT OF COMMERCE
National Institute of Standards and Technology
Gaithersburg, Maryland 20899-0001

December 19, 1996

[REDACTED]
TUV Product Service, Inc.
10040 Mesa Rim Road
San Diego, CA 92121

NVLAP Lab Code: 100268-0

Dear Mr. Smith:

I am pleased to inform you that continuing accreditation for specific test methods in Electromagnetic Compatibility, MIL-STD-462 is granted to your organization under the National Voluntary Laboratory Accreditation Program (NVLAP). This accreditation is effective until December 31, 1997, provided that your organization continues to comply with accreditation requirements contained in the NVLAP Procedures.

Your Certificate of Accreditation is enclosed along with a statement of your Scopes of Accreditation. You may reproduce these documents in their entirety and announce your organization's accreditation status using the NVLAP logo in business publications, the trade press, and other business-oriented literature. Accreditation does not relieve your organization from observing and complying with any applicable existing laws and/or regulations.

We are pleased to have you participate in NVLAP and look forward to your continued association with this program. If you have any questions concerning your NVLAP accreditation, please direct them to Jon Crickenberger, Sr. Program Manager, Laboratory Accreditation Program, National Institute of Standards and Technology, Building 820, Room 282, Gaithersburg, MD 20899-0001; (301) 975-4016.

Sincerely,

[REDACTED]

Laboratory Accreditation Program

Enclosure(s)

NIST

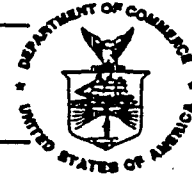
Page D9 of D16



National Institute of Standards and Technology **NVLAP**® National Voluntary Laboratory Accreditation Program

ISO/IEC GUIDE 25:1990
ISO 9002:1987

Scope of Accreditation



Page: 1 of 2

ELECTROMAGNETIC COMPATIBILITY, MIL-STD 462

NVLAP LAB CODE 100268-0

TUV PRODUCT SERVICE, INC.
10040 Mesa Rim Road
San Diego, CA 92121



Military Standard 462, Measurement of Electromagnetic Interference Characteristics
NVLAP Code Designation

Conducted Emissions:

- 12/A01 MIL-STD-462 Method CE01
- 12/A04 MIL-STD-462 Method CE02
- 12/A06 MIL-STD-462 Method CE03
- 12/A08 MIL-STD-462 Method CE04
- 12/A10 MIL-STD-462 Method CE06
- 12/A12 MIL-STD-462 Method CE07

Conducted Susceptibility:

- 12/B01 MIL-STD-462 Method CS01
- 12/B02 MIL-STD-462 Method CS02
- 12/B04 MIL-STD-462 Method CS03/CS04/CS05/CS08

December 31, 1997

Effective through



For the National Institute of Standards and Technology

NVLAP-015 (11-95)



National Institute
of Standards and Technology



National Voluntary
Laboratory Accreditation Program

ISO/IEC GUIDE 25:1990
ISO 9002:1987

Scope of Accreditation



Page: 2 of 2

ELECTROMAGNETIC COMPATIBILITY, MIL-STD 462

NVLAP LAB CODE 100268-0

TUV PRODUCT SERVICE, INC.

Military Standard 462, Measurement of Electromagnetic Interference Characteristics

NVLAP Code Designation

12/B05	MIL-STD-462 Method CS06
12/B06	MIL-STD-462 Method CS07
12/B07	MIL-STD-462 Method CS09

Radiated Emissions:

12/D01	MIL-STD-462 Method RE01
12/D02	MIL-STD-462 Method RE02
12/D03	MIL-STD-462 Method RE03

Radiated Susceptibility:

12/E01	MIL-STD-462 Method RS01
12/E02	MIL-STD-462 Method RS02
12/E03	MIL-STD-462 Method RS03 (Consult laboratory for field strengths available)
12/E04	MIL-STD-462 Method RS03 employing RADHAZ procedures for high level testing (Consult laboratory for field strengths available)

December 31, 1997

Effective through

For the National Institute of Standards and Technology

NVLAP-015 (11-95)

Page D11 of D16



FEDERAL COMMUNICATIONS COMMISSION

7435 Oakland Mills Road
Columbia, MD 21046
Telephone: 301-725-1585 (ext-218)
Facsimile: 301-344-2050

July 10, 1996

IN REPLY REFER TO
31040/SIT
1300F2

TUV Product Service
10040 Mesa Rim Road
San Diego, CA 92121-2912



**Re: Measurement facility located at Carroll Canyon, Site No. 2
(3 and 10 meters)**

Gentlemen:

Your submission of the description of the subject measurement facility has been reviewed and found to be in compliance with the requirements of Section 2.948 of the FCC Rules. The description has, therefore, been placed on file and the name of your organization added to the Commission's list of facilities whose measurement data will be accepted in conjunction with applications for certification or notification under Parts 15 or 18 of the Commission's Rules. Our list will also indicate that the facility complies with the radiated and AC line conducted test site criteria in ANSI C63.4-1992. Please note that this filing must be updated for any changes made to the facility, and at least every three years the data on file must be certified as current.

Per your request, the above mentioned facility has been also added to our list of those who perform these measurement services for the public on a fee basis. This list is published periodically and is also available on the Laboratory's Public Access Link as described in the enclosed Public Notice.

Sincerely,



Electronics Engineer
Customer Service Branch

Enclosure:
PAL PN



ENG 3/9
AJD

1 May 1997

TUV Product Service Inc
1775 Old Highway 8
Suite 104
New Brighton
MN 55112-1891
UNITED STATES OF AMERICA

Dear Sir

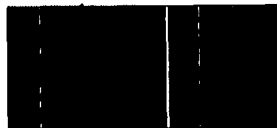
LABORATORY APPROVAL

Thank you for your submission of 11 April regarding the approval of your testing laboratories at New Brighton, Boulder and San Diego to the Ministry of Commerce's laboratory approval criteria. Thank you for your interest in this matter.

I am pleased to advise that your submission has been successful and these laboratories have been added to the list of Ministry-approved laboratories. Your approved status is valid until 1 April 1999. Renewal of your approval at this time will require further demonstration of your compliance with the approval criteria. You will be advised of the requirements of renewal prior to the expiry date of your approval.

If you have any further questions on this matter please do not hesitate to contact me.

Yours faithfully



Senior Technical Officer(Regulatory)

COMMUNICATIONS DIVISION - RADIO OPERATIONS

Ensuring New Zealand has the best possible communications environment

Head Office, Ministry of Commerce Building, 33 Bowen Street, P.O. Box 2847, Wellington, New Zealand. Telephone (04) 472 0030. Fax (04) 473 2489

Page D13 of D16



CERTIFICATE FOR LISTING
A97/TH/0098

TUV PRODUCT SERVICE
(SAN DIEGO)

is an AUSTEL listed test house having satisfied
NATA's (or its Associates with which it has a
MoU or MRA for mutual recognition of test houses)
requirements for testing to the following standards:

AS/NZS 3548 Limits and methods
of measurement of radio disturbance
characteristics of information technology
equipment



General Manager
Technical Branch

Date 11 February 1997

This certificate is valid as long as the accreditation is
maintained with NATA or its Associate.





BUSINESS
SENSITIVE

CERTIFICATE



CERTIFICATE OF COMPLIANCE OF THE QUALITY SYSTEM WITH REQUIREMENTS MENTIONED BELOW

TÜV PRODUCT SERVICE GmbH certifies that

**TÜV PRODUCT SERVICE Inc.,
USA**

in the facilities

Test Laboratories
10040 Mesa Rim Road, San Diego CA 92121

for the following areas:

Services for EMC and Product Safety Testing

has established and is operating a quality system which meets the
requirement(s) of the internal quality management system of TÜV
PRODUCT SERVICE GmbH which is based on EN 45001:05/90.

Munich, 18 May, 1995

TÜV PRODUCT SERVICE GmbH

For the Executive Committee of TÜV PRODUCT SERVICE



TÜV PRODUCT SERVICE GmbH, Ridlerstrasse 31, 80339 Munich, Germany



TAIWAN

Bureau of Commodity Inspection and Quarantine (BCIQ)
EMC Laboratory Accreditation Number
SL2-IN-E-25T

最遠件

經濟部商品檢驗局(函)

附件如文

中華民國捌拾陸年拾月拾肆日

受文者：新加坡商台德產品驗證顧問股份有限公司
檢台八十六字第

行文單位：正本：新加坡商台德產品驗證顧問股份有限公司台灣分公司

副本：本局第二組(二份)、資訊室、秘書室(秘四科)、

檢驗處、各分局(無附件)

主旨：有關 貴公司代理美國本土「TUV PRODUCT SERVICE, INC.」電磁相容檢測實驗室
申請本局電磁相容檢測領域認可案，經初步審查所附技術文件尚可接受，同意投
與臨時認可如說明，請查照。

說明：

一、復 貴公司八十六年七月十五日未列字號申請書。

二、核備登錄範圍如下：

實驗室名稱：TUV PRODUCT SERVICE, INC. SAN DIEGO, CA
實驗室地址：10040 Mesa Rim Road San Diego CA 92121 USA

認可代號	認可產品類別	報告簽署人
SL2-IN-E-25T	(II) 資訊設備 (CNS-13438)	JOHN G. SMITH

聯絡單位：新加坡商台德產品驗證顧問股份有限公司台灣分公司(盧基弘)

地址：台北縣三重市重新路五段888巷4號5樓

電話：(02) 999-3950

三、本臨時認可文件有效期限自即日起至八十七年六月三十日止，期間內本局將安排
人員實地評鑑，關於必備文件「中文品質手冊 (Quality Manual in Chinese)」
准寬限至文到三個月內送達本局，並請提供試驗室與附近國際機場之位置簡圖，
以利安排評鑑業務。

四、本臨時認可資格，僅限受理美國本土廠商之商品電磁相容委託測試案件。

五、上開已認可領域如有變更事項，請於變更日起二週內函送相關資料至本局核辦。

六、檢送「商品電磁相容型式試驗報告」格式乙份，請自行印製使用。

局長 陳佐鎮

依照分層負責規定授權單位主管代行



Report No. S7439-03

Appendix E

Supplemental Information

BUSINESS SENSITIVE

TEST PARAMETER	STANDARD	FREQUENCY RANGE	TEST LEVEL/LIMIT	ANTENNA DISTANCE	ANTENNA TYPE	REMARKS
HF Radiated RF Susceptibility	IEC 1000-4-3 (IEC 801-3)	27 MHz to 80 MHz 80 MHz to 1000 MHz	10 V/meter	3 meters	Biconical Log-periodic	
LF Conducted RF Susceptibility	MIL-STD-461D CS-101	30 Hz to 150 KHz	6.3 V rms	NA	NA	
HF Conducted RF Susceptibility	IEC 1000-4-6 (IEC 801-6)	150 KHz to 400 MHz	10 V (emf)	NA	NA	
Surge Susceptibility	IEC 1000-4-5 (IEC 801-5)	NA	± 3 KV (open circuit voltage)	NA	NA	
EFT Susceptibility	IEC 1000-4-4 (IEC 801-4)	NA	Power leads: ± 4 KV; Data/ctrl leads: + 2 KV	NA	NA	
ESD Susceptibility	IEC 1000-4-2 (IEC 801-2)	NA	Contact discharge: ± 4 KV; Air discharge: + 8 KV	NA	NA	
Radiated RF Emissions	CENELEC EN 55011, Group 1, Class A	30 MHz to 230 MHz 230 MHz to 1 GHz	30 dBµV/meter 37 dBµV/meter	30 meter 30 meter	Biconical Log-periodic	
Conducted RF Emissions	MIL-STD-461D CE-102	10 KHz to 500 KHz 500 KHz to 400 MHz*	100 dBµV 66 dBµV	NA	NA	

* TEST PLAN deviation stopped AT 100MHz

CE EN55011 GROUP1, CLASS A 150 kHz - 30 MHz TVA RM-1000 EMC TEST STANDARDS

W. Wong
11/10/97



PRODUCT SERVICE

APPENDIX B

TÜV Test Report

S8569-02

11Dec1998

**RM-1000 Radiation Monitor
Two Channel**



Report No. S8569-02

BUSINESS
SENSITIVE

EMC - TEST REPORT

EUROPEAN STANDARDS* EN 61000-4-2: 1995; EN 61000-4-3: 1995;
EN 61000-4-4: 1995; EN 61000-4-5: 1995; ENV 50141: 1993; EN 61000-
4-8: 1994; EN 61000-4-11: 1994; EN 55011;
UNITED STATES STANDARD* MIL-STD-461D: 1993, CS101 and
CE102

Test Report File No. : S8569-02 Date of Issue: 11 December 1998

Model / Serial No. : RM-1000 Radiation Monitor, Two Channel / ---

Product Type : RM-100 Radiation Monitor, Two Channel

Applicant : SORRENTO ELECTRONICS

Manufacturer : SORRENTO ELECTRONICS

License holder : SORRENTO ELECTRONICS

Address : 10240 Flanders Court
: San Diego, CA 92121

Test Result : [REDACTED]

Test Project Number References : S8569-02

Total pages - Test Report : 23

(* All tests performed per customer Test Procedure, Drawing No. 04509005.

TÜV Product Service, Inc. is a subcontractor to TÜV Product Service, GmbH according to the principles outlined in ISO/IEC Guide 25 and EN 45001.

TÜV Product Service reports apply only to the specific sample tested under stated test conditions. It is the manufacturer's responsibility to assure the continued compliance of production units of this model. TÜV Product Service, Inc. shall have no liability for any deductions, inferences or generalizations drawn by the client or others from TÜV Product Service, Inc. issued reports.

This report is the confidential property of the client. As a mutual protection to our clients, the public and ourselves, extracts from the test report shall not be reproduced except in full without our written approval. This report shall not be used by the client to claim product endorsement by NVLAP or any agency of the US government.

TÜV Product Service, Inc. and its professional staff hold government and professional organization certifications and are members of AAMI, ACIL, AEA, ANSI, IEEE, NVLAP, and VCCI



Report No. S8569-02

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Test Data Sheets and Test Setup Drawing(s)	TD1
--------------------------------------------	-----

Appendices

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Report No. S8569-02

Supplemental Information



Report No. S8569-02

TEST REGULATIONS :

The immunity and emissions tests were performed according to the following regulations :

-
- - EN 61000-4-2 / 1995*
 - - EN 61000-4-3 / 1995*
 - - EN 61000-4-4 / 1995*
 - - EN 61000-4-5 / 1995*
 - - EN 61000-4-8 / 1994*
 - - EN 61000-4-11 / 1994*
 - - EN 55011, Class A*

 - - ENV 50141 / 1993*

 - - MIL-STD-461D: 1993
 - - CS101*
 - - CE102*

(*) All tests performed per customer Test Procedure, Drawing No. 04509005.



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BUSINESS
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Environmental Conditions In The Laboratory:

	<u>Actual</u>
Temperature:	: 21-24 °C
Relative Humidity:	: 17-50 %
Atmospheric Pressure:	: 100.7-101.9 kPa

Power Supply Utilized:

Power supply system



Symbol Definitions:

- - Applicable
- - Not Applicable



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BUSINESS
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Immunity Test Conditions: ELECTROSTATIC DISCHARGE (ESD)

The immunity against *ELECTROSTATIC DISCHARGE (ESD)* events was performed in the following location at the San Diego Testing Facility :

- Test not applicable

- - TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :



Test Specification:

Discharge Voltage (Air):

Discharge Voltage (Contact):

Discharge Impedance:

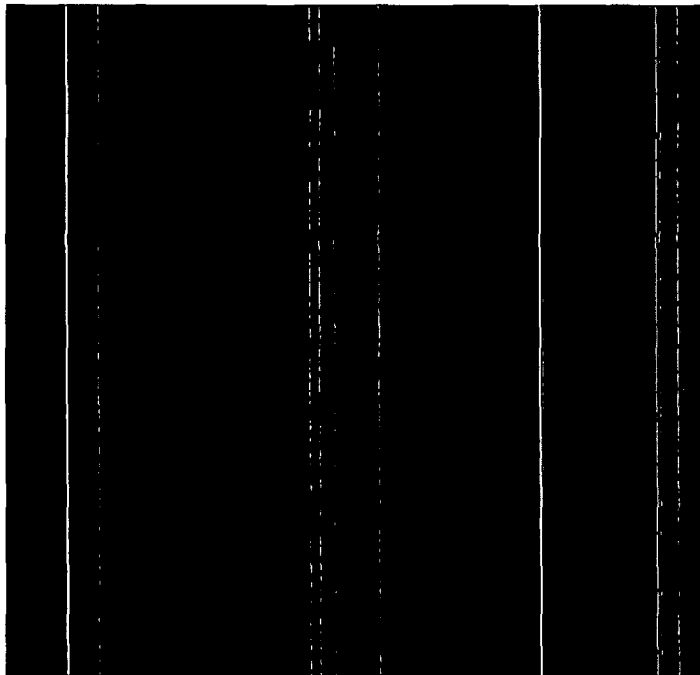
Discharge Repetition Rate:

Number of Discharges:

Kind of Discharges:

Polarity:

Location of Discharge:





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BUSINESS
SENSITIVE

Immunity Test Conditions: ELECTROSTATIC DISCHARGE (ESD), continued

Result :

[REDACTED]

Remarks:

[REDACTED]



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BUSINESS
SENSITIVE

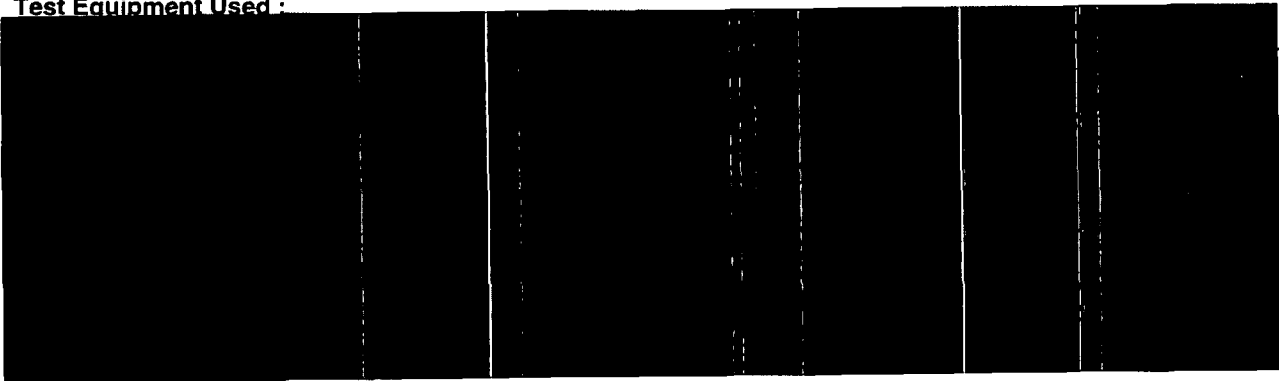
Immunity Test Conditions: RADIATED ELECTROMAGNETIC FIELDS

The immunity against *RADIATED ELECTROMAGNETIC FIELDS* exposure was performed in the following location at the San Diego Testing Facility:

- Test not applicable

- SR-1, Shielded Room, 12' x 24' x 10', Metal, Compact Anechoic Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber

Test Equipment Used :



Test Specification:

Frequency Range:

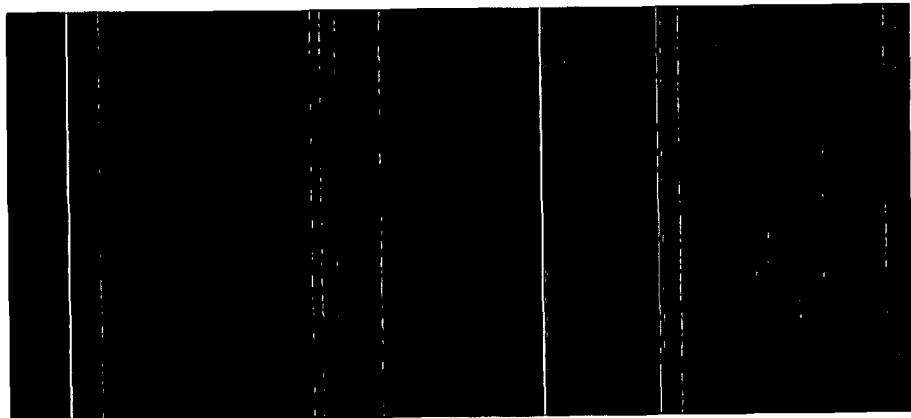
Field Strength:

Distance Antenna - EUT:

Modulation:

Step:

Polarization of Antenna:



Result :



Remarks:





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**BUSINESS
SENSITIVE**

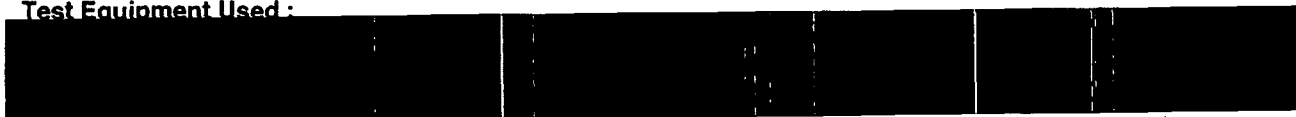
Immunity Test Conditions: FAST TRANSIENTS (BURST)

The immunity against *FAST TRANSIENTS (BURST)* events was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :



Test Specification:

Pulse Amplitude - AC Power Port:

Pulse Amplitude - DC Power Port:

Pulse Amplitude - Signal/Data
Non control Port:

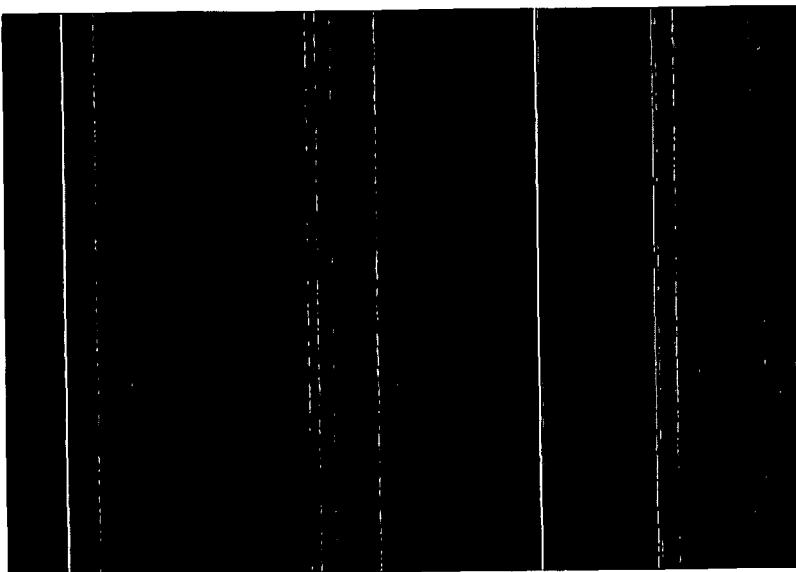
Pulse Amplitude - Process:
Measurement & Control Port

Burst Frequency:

Time of Coupling:

Coupling Method:

Polarity:





Report No. S8569-02

**BUSINESS
SENSITIVE**

Immunity Test Conditions: FAST TRANSIENTS (BURST), continued

Location of Coupling:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

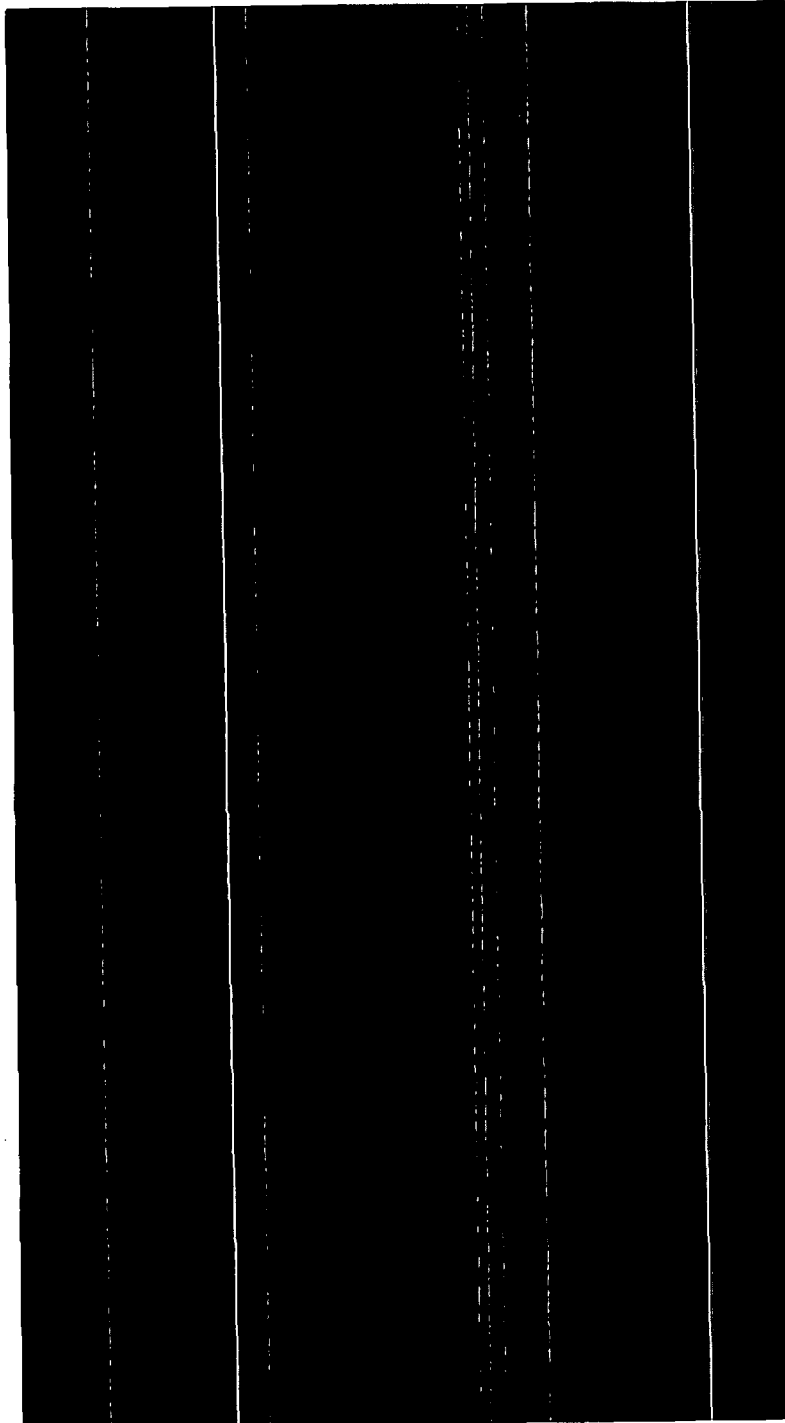
name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:





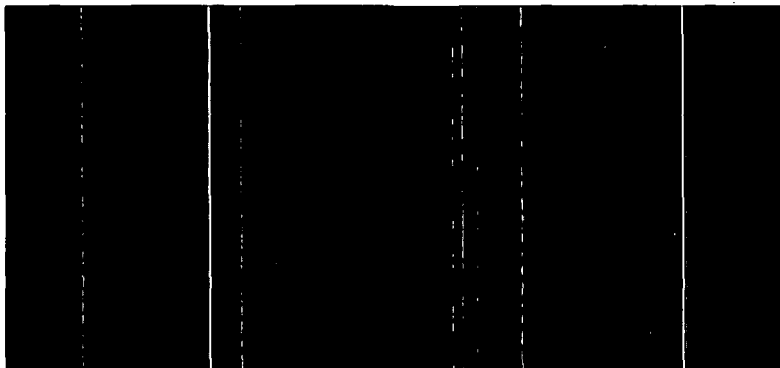
Report No. S8569-02

BUSINESS
SENSITIVE

Immunity Test Conditions: FAST TRANSIENTS (BURST), continued

Location of Coupling:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

Result:



Remarks:





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Immunity Test Conditions: SURGE TRANSIENTS

The immunity against *SURGE TRANSIENTS* events was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- - TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- TR-4, Non-Shielded Room, 10' x 19' x 9'
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber

Test Equipment Used :



Test Specification:

Pulse Amplitude - AC Power Port:
(Common Mode)

Source Impedance:
(Common Mode)

Pulse Amplitude - AC Power Port:
(Differential Mode)

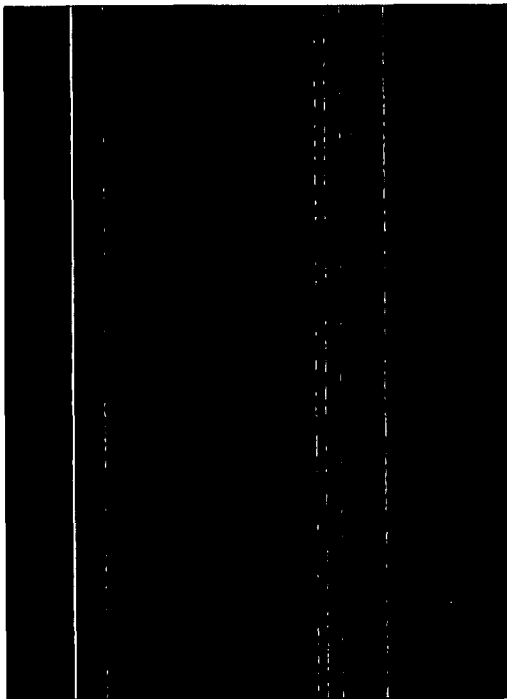
Source Impedance:
(Differential Mode)

Pulse Amplitude - DC Power Port:

Pulse Amplitude - Signal/Data
Non control Port:

Pulse Amplitude - Process:
Measurement & Control Port

Source Impedance:





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**BUSINESS
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Immunity Test Conditions: SURGE TRANSIENTS, continued

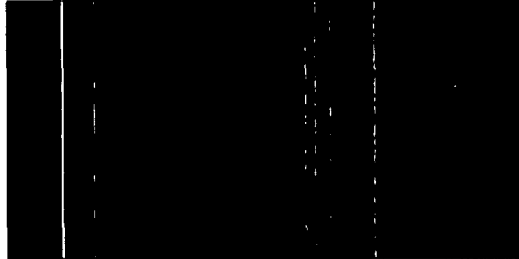
Test Specification (continued):

Number of Surges:

Angle:

Repetition Rate:

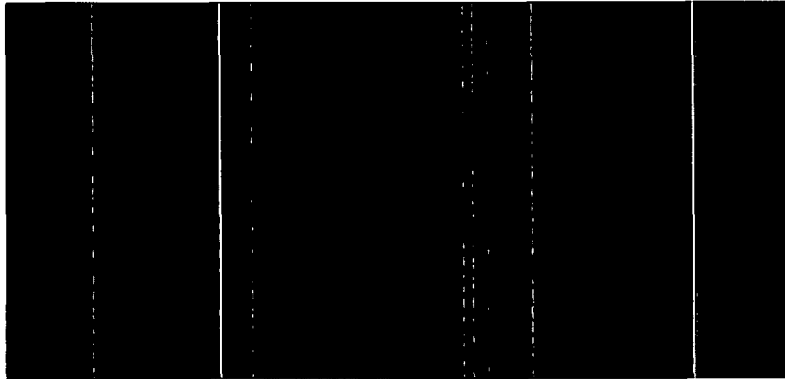
Polarity:



Location of Coupling:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



Result:



Remarks:





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BUSINESS SENSITIVE

Immunity Test Conditions: CONDUCTED SUSCEPTIBILITY, Power Leads (CS101)

The *CONDUCTED SUSCEPTIBILITY* test was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- - SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- - SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber

Test Equipment Used :

Model #	Prop #	Manufacturer	Description	Serial #
[REDACTED]				

Test Specification:

Frequency Range:

Test Level (dBuV):

Injected Voltage dBuV:

Injection Location:

Result :

Remarks:



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BUSINESS
SENSITIVE

Immunity Test Conditions: CONDUCTED DISTURBANCE

The immunity against *CONDUCTED DISTURBANCE* events, induced by radio frequency fields above 9 kHz, was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :



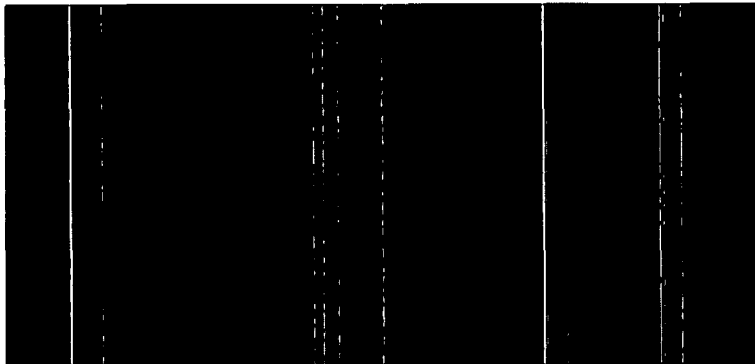
Test Specification:

Frequency Range:

Voltage Level (EMF):

Modulation:

Step:





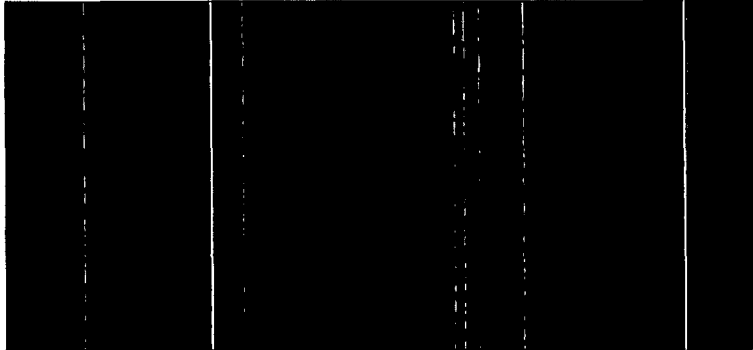
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BUSINESS
SENSITIVE

Immunity Test Conditions: CONDUCTED DISTURBANCE (continued)

Location of Coupling:

name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:



name of lines:
type of lines:
status of lines:
kind of transmission:
length of lines:

Result :



Remarks:





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BUSINESS
SENSITIVE

Immunity Test Conditions: POWER FREQUENCY MAGNETIC FIELD

The immunity against *RF FREQUENCY MAGNETIC FIELD* exposure, induced by radio frequency fields above 9 kHz, was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- - TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-2, Shielded Room, 12' x 24' x 10', Copper Screen Chamber
- SR-3, Shielded Room, 12' x 20' x 18', Metal Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
-

Test Equipment Used :

[Redacted]

Test Specification:

Frequency Range:

Field level (EMF):

Short Field (1-3 sec):

Duration:

Axis of Orientation:

[Redacted]

Result :

[Redacted]

Remarks: [Redacted]



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BUSINESS
SENSITIVE

Immunity Test Conditions: VOLTAGE DIPS, INTERRUPTIONS & VARIATIONS

The immunity against *VOLTAGE DIPS, INTERRUPTIONS & VARIATIONS* events, induced by radio frequency fields above 9 kHz, was performed in the following test location at the San Diego Testing Facility:

- Test not applicable

- - TR-1, Test Room
- TR-2, Non-Shielded Room, 10' x 19' x 9'
- TR-3, Non-Shielded Room, 10' x 19' x 9'
- SR-2, Shielded Room, 12' x 24' x 10', Copper Screen Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
-

Test Equipment Used :

[Redacted]

Test Specification:

Nominal Mains Voltage (V_{NOM}):

Level of Reduction (dip):

Duration:

Phase Angle:

[Redacted]

Result :

[Redacted]

Remarks:

[Redacted]



Report No. S8569-02

**BUSINESS
SENSITIVE**

Emissions Test Conditions: RADIATED EMISSIONS (Electric Field)

The *RADIATED EMISSIONS (ELECTRIC FIELD)* measurements, in the frequency range of 30 MHz-1000 MHz, were tested in a horizontal and vertical polarization at the following test location :

- Test not applicable

- Roof (Small Open Area Test Site)
- Canyon #1 (10- and 30-Meter Open Area Test Site), Carroll Canyon, San Diego
- Canyon #2 (3- and 10-Meter Open Area Test Site), Carroll Canyon, San Diego

Testing was performed at a test distance of :

[REDACTED]

Test Equipment Used :

[REDACTED]

Result :

[REDACTED]

Remarks:

[REDACTED]

[REDACTED]



Report No. S8569-02

BUSINESS
SENSITIVE

Emissions Test Conditions: CONDUCTED EMISSIONS (Interference Voltage)

The *CONDUCTED EMISSIONS (INTERFERENCE VOLTAGE)* measurements were performed at the following test location:

- Test not applicable

- SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber
- SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber
- SR-4, Shielded Room, 10' x 17' x 8', Copper Screen Chamber
- SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- CSR-1, Shielded Room, 10' x 7' x 7', Metal Chamber

Test Equipment Used :

[REDACTED]

Result :

[REDACTED]

Remarks:

[REDACTED]



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BUSINESS
SENSITIVE

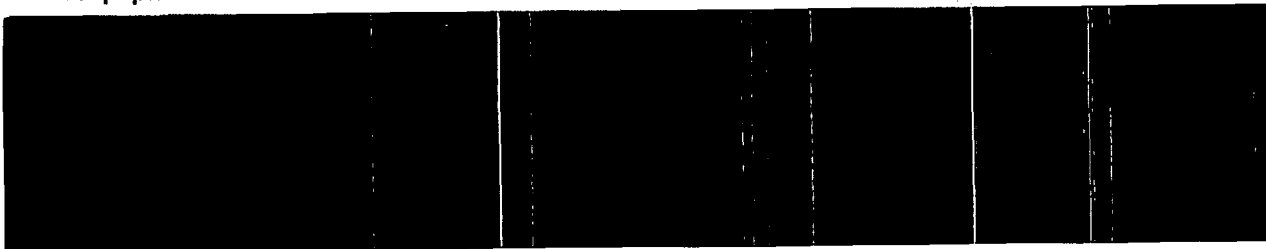
Test Conditions: CE102 - Conducted Emissions, Power Leads

The *Conducted Emissions, Power Lines* test was performed in the following location at the San Diego Testing Facility :

- Test not applicable

- - SR-5, Shielded Room, 16' x 28' x 15', Metal, Semi-Anechoic Chamber
- SR-2, Shielded Room, 12' x 24' x 10', Metal Chamber

Test Equipment Used :



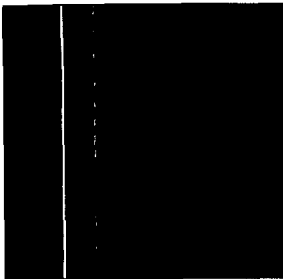
Test Specification:

Frequency:

Ground Bonding:

Current Probe:

Load:



Result :



Remarks:





Report No. S8569-02

Equipment Under Test (EUT) Test Operation Mode - Immunity Tests :

The equipment under test was operated under the following conditions during immunity testing :

- Standby
- Test Program (H - Pattern)
- Test Program (Color Bar)
- Test Program (Customer Specified)
- Practice Operation
- Normal Operating Mode

- _____

Configuration of the equipment under test:

- See Constructional Data Form in Appendix B - Page B2
- See Product Information Form(s) in Appendix B - Page B2

The following peripheral devices and interface cables were connected during the testing:

- | | |
|----------------------------------|--------------|
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |
| <input type="checkbox"/> - _____ | Type : _____ |

- unshielded power cable
- unshielded cables
- shielded cables
- customer specific cables

MPS. No.: _____

- _____

- _____



Report No. S8569-02

BUSINESS SENSITIVE

GENERAL REMARKS:

(*) All tests performed per customer test procedure



SUMMARY:

All tests according to the regulations cited on page 3 were

■ - Performed

□ - Not Performed

The Equipment Under Test

■ - **Fulfills** the general approval requirements cited on page 3.*

□ - **Does not** fulfill the general approval requirements cited on page 3.

Statement of Measurement Uncertainty

The data and results referenced in this document are true and accurate. There may be some degree or level of measurement uncertainty. As EN 45001 does not allow recommendations to be included in the test report, the reader is encouraged to request a copy of the TÜV policy concerning pass or fail judgment with respect to possible measurement uncertainties.

Equipment Received Date: 24 November 1998

Testing Start Date: 24 November 1998

Testing End Date: 25 November 1998

- TÜV PRODUCT SERVICE, INC. -

Responsible Engineer:

Responsible Test Engineer:



(EMC Engineer)

(EMC Test Engineer)



Report No. S8569-02

Technical Documentation

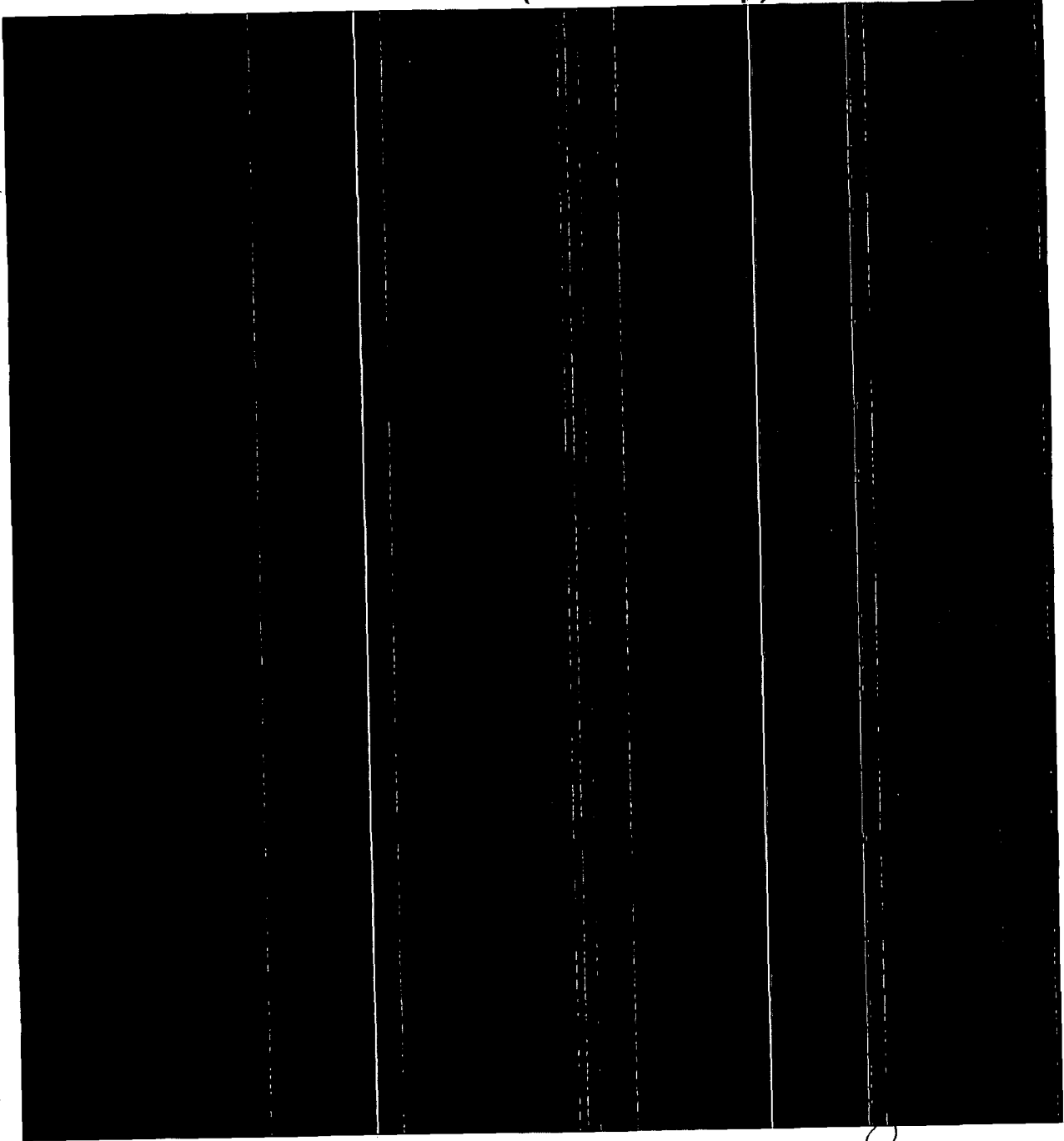
Test Data Sheets
and
Test Setup Drawing(s)



Report No. S8569-02

BUSINESS
SENSITIVE

ESD IMMUNITY (Test Point Map)




ESDMAP DOC Rev 03.97

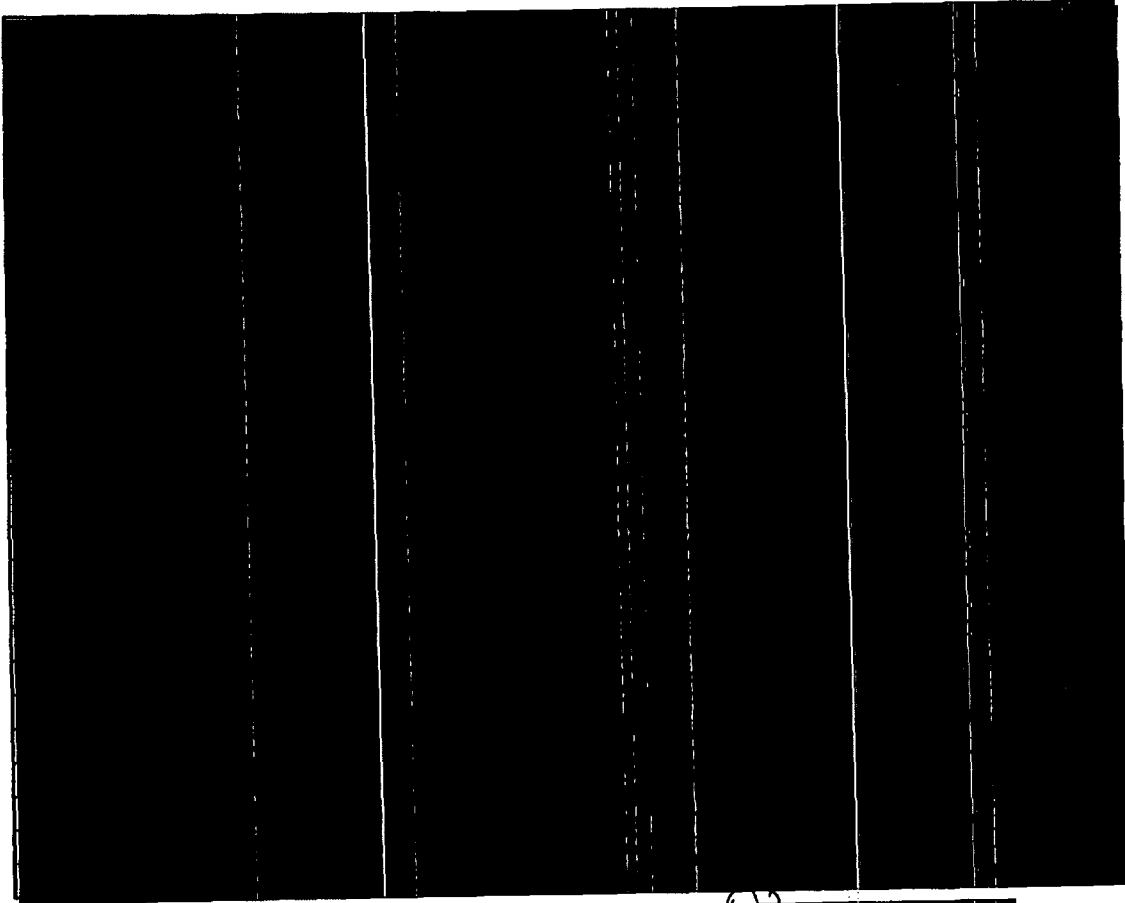


Report No. S8569-02

BUSINESS SENSITIVE

ESD IMMUNITY

Test Report #: <u>S-8569</u>	Test Area: <u>TR-1</u>	
Test Method: <u>EN 61000-4-2</u>	Date: <u>09 DEC 96</u>	
Tested per customer test procedure.		
EUT Model #: <u>RM 1000</u>	EUT POWER: <input checked="" type="checkbox"/> 230 Vac/50 Hz <input type="checkbox"/> 120 Vac/60 Hz <input type="checkbox"/> Other: _____	Temperature: <u>21</u> °C
EUT Description: <u>2 CH Radiation Monitor</u>		Air Pressure: <u>1012</u> kPa
NOTES: _____		Relative Humidity: <u>31</u> %



Tested by: _____
Reviewed by: _____
Printed _____ Signature _____

(*) Indirect (**) Contact

ESDC.DOC Rev 08.96

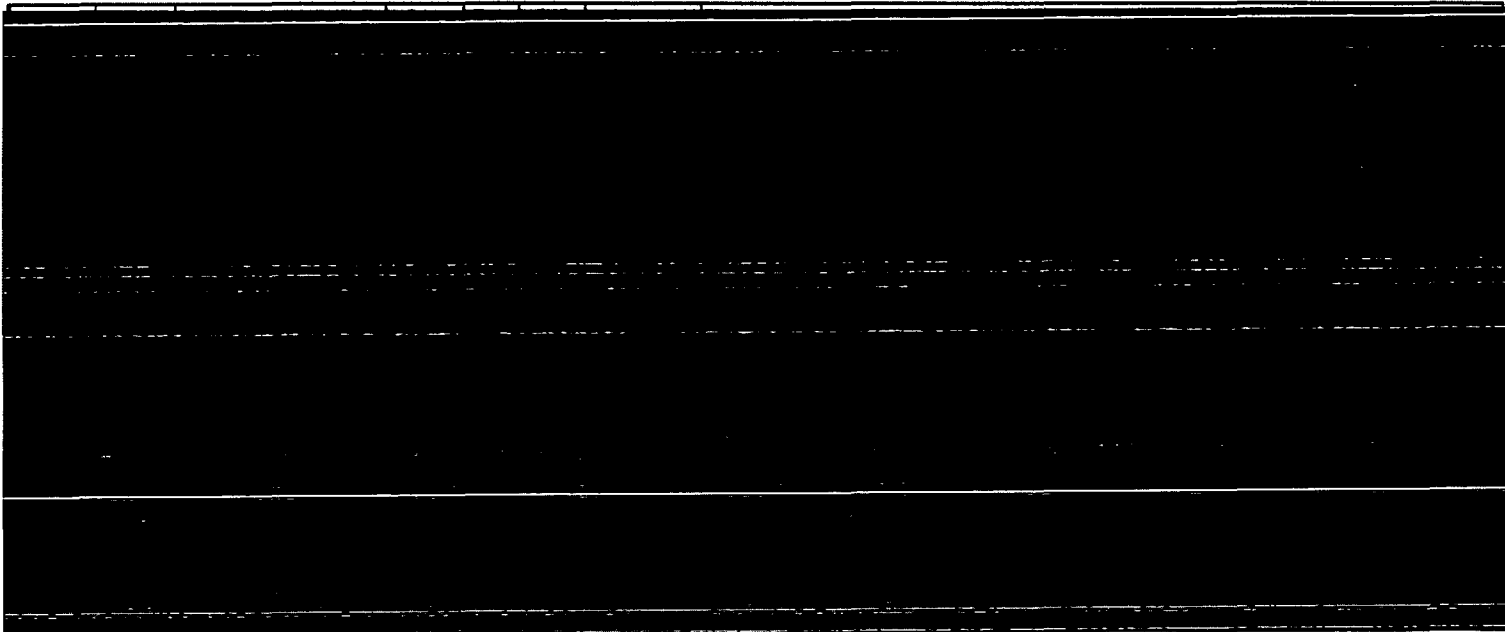
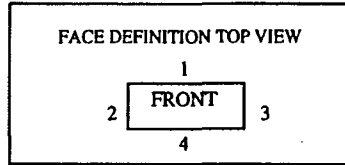
BUSINESS SENSITIVE



RADIATED IMMUNITY

Test Report #: S-8569 Test Area: SR-5
 Test Method: RN 61908-4-2 Radiated Immunity Date: 30 NOV 98
 Tested per customer test procedure. EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz
 EUT Model #: RM 1000 Other: _____
 EUT Description: 2 CH RADIATION MONITOR
 NOTES: _____

Temperature: 22 °C
 Air Pressure: 101.0 kPa
 Relative Humidity: 44 %



Tested by _____
 Reviewed _____
 Printed _____ Signature _____

RADIMU.DOC Rev 05.97



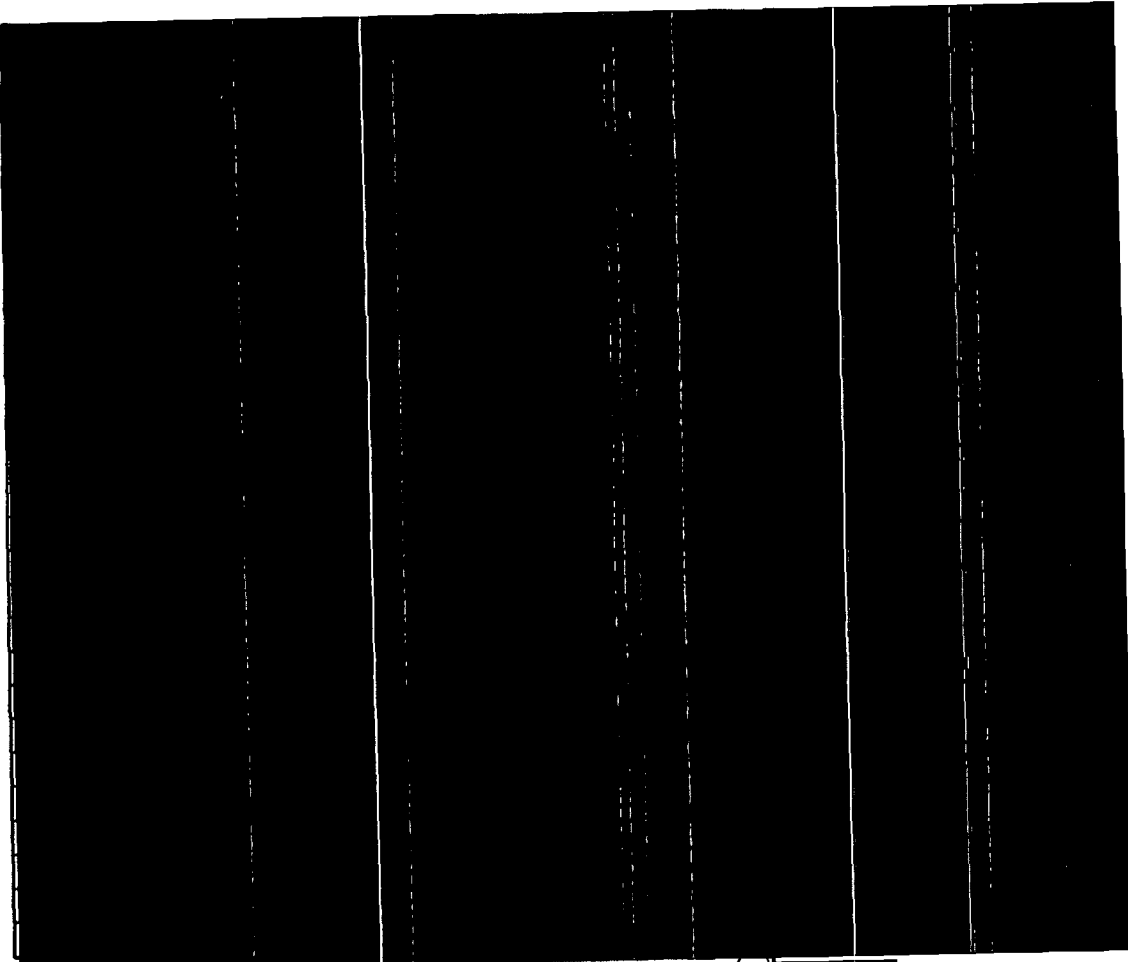


Report No. S8569-02

BUSINESS SENSITIVE

EFT/BURST IMMUNITY

Test Report #: S-8569 Test Area: SE-5
Test Method: EN 61000-4-4 Date: 03, 04 DEC 98
Tested per customer test procedure.
EUT Model #: RM 1000 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____ Temperature: 23 °C
EUT Description: 2 CH Radiation Monitor Air Pressure: 100.7 kPa
NOTES: _____ Relative Humidity: 46 %



Tested By: _____
Reviewed by: _____
Printed Signature

EFT.DOC Rev 03.97



Report No. S8569-02

BUSINESS SENSITIVE

SURGE IMMUNITY

Test Report #: S-8569
Test Method: EN 61000-4-5
Tested per customer test procedure.

Test Area: TR-1
Date: 09 Dec 98



EUT Model #: RM-1000

EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other:

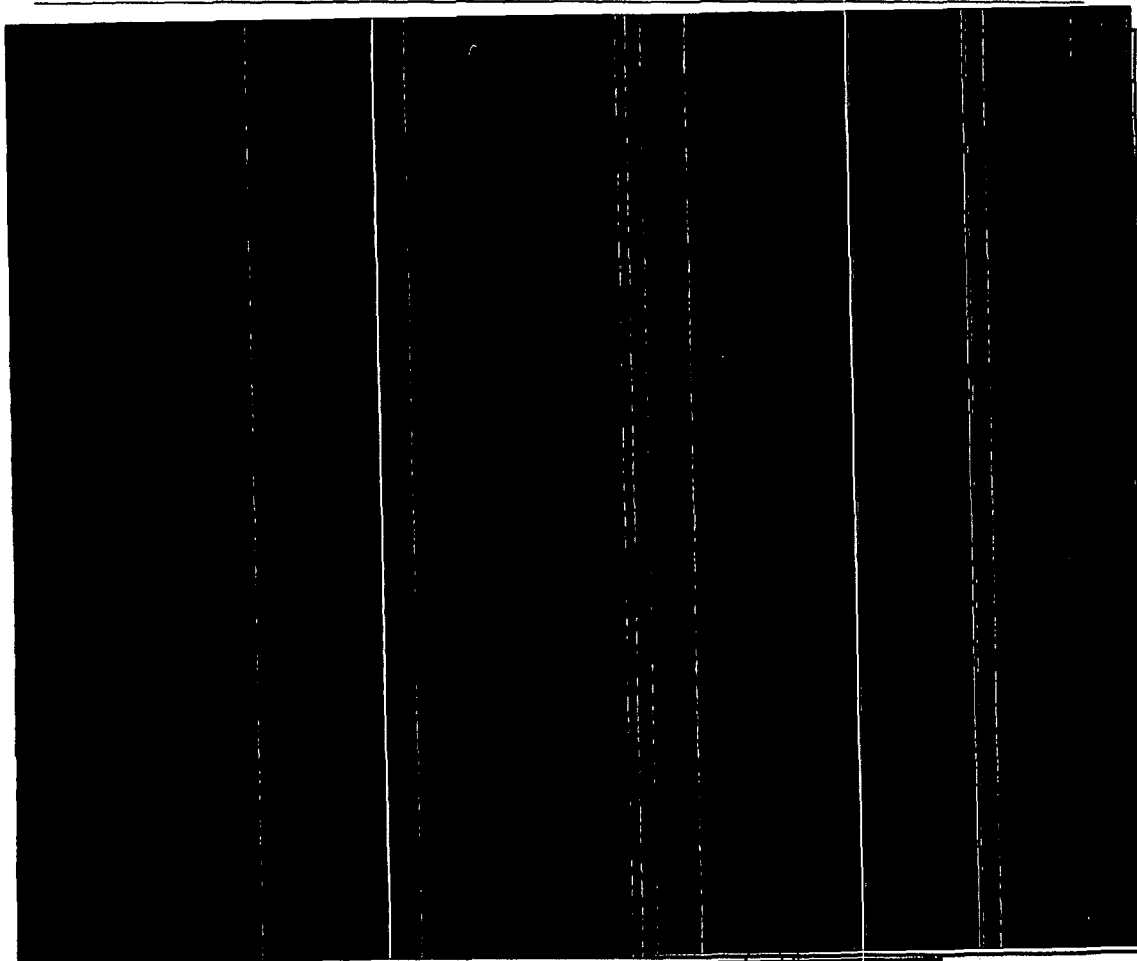
Temperature: 22 °C

EUT Description: 2 CH Radiation Monitor

Air Pressure: 101.2 kPa

NOTES: SH 1 OF 2

Relative Humidity: 26 %



Tested By: _____

Reviewed by: _____

Printed

Signature

SURG.DOC Rev 03.97



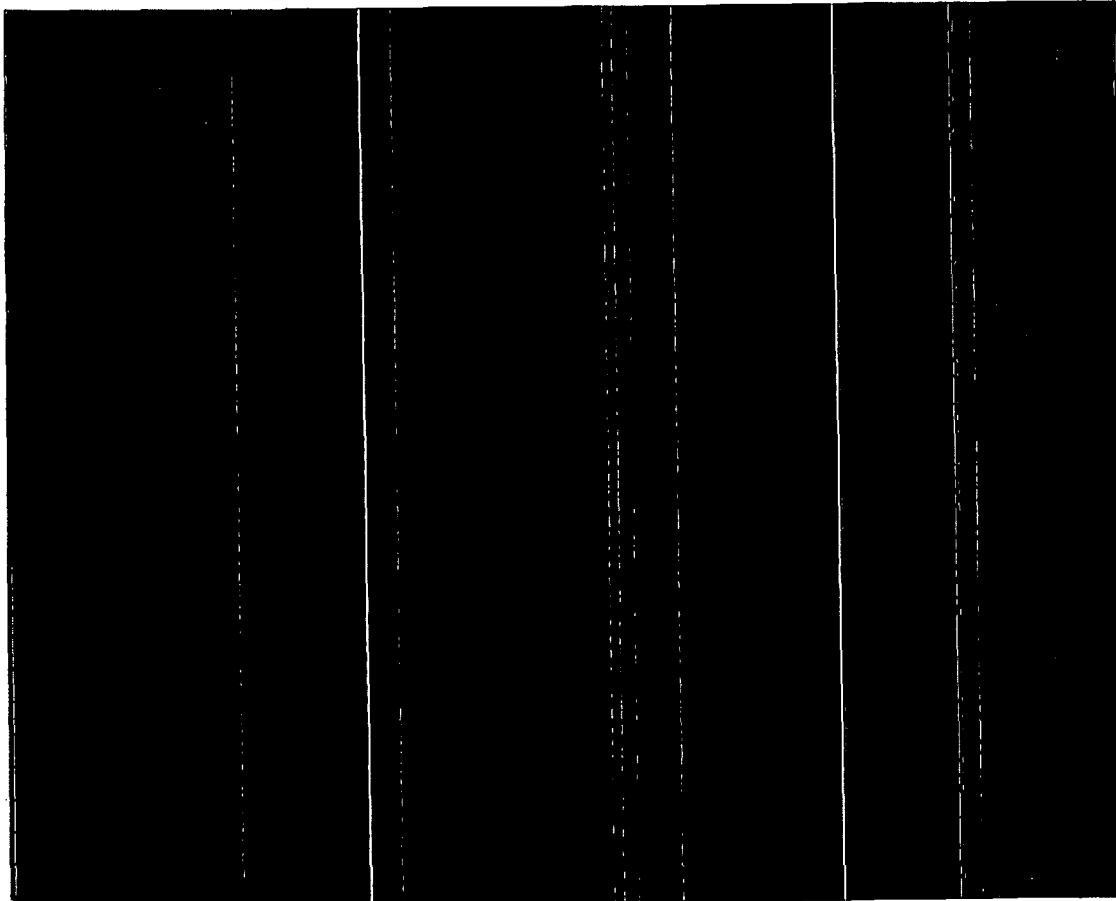
Report No. S8569-02

BUSINESS
SENSITIVE

MIL-STD-461D
CS101 Conducted Susceptibility



Test Report #: S-8569 Test Area: SE-5 Date: 03 Dec 98
EUT Model #: RM 1000 EUT Power: 120 Vac/400 28 Vdc Other: 230V
EUT Description: RADIATION MONITOR Tested per customer test procedure. 301FE



NOTES: 1. _____
2. _____

Tested by: _____
Witnessed by: _____
Printed Signature

CS01.DOC Rev 12.98

BUSINESS SENSITIVE



CONDUCTED RF IMMUNITY

Test Report #: S-8569 Test Area: SR-5
 Test Method: ENV 50141 :93 Date: 03 DEC 98
 Tested per customer test procedure.
 EUT Model #: RM-1000 EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other: _____
 EUT Description: RADIATION MONITOR
 NOTES: TEST LEVEL 3.0 VEME

Temperature: 24 °C
 Air Pressure: 101.9 kPa
 Relative Humidity: 50 %

TEST FREQ	TEST	MODULATION	CDN	INJECTION	DISCET	COMPLUS

Tested By: _____
 Reviewed by: _____
 Printed _____ Signature _____

COND.DOC Rev 03.97



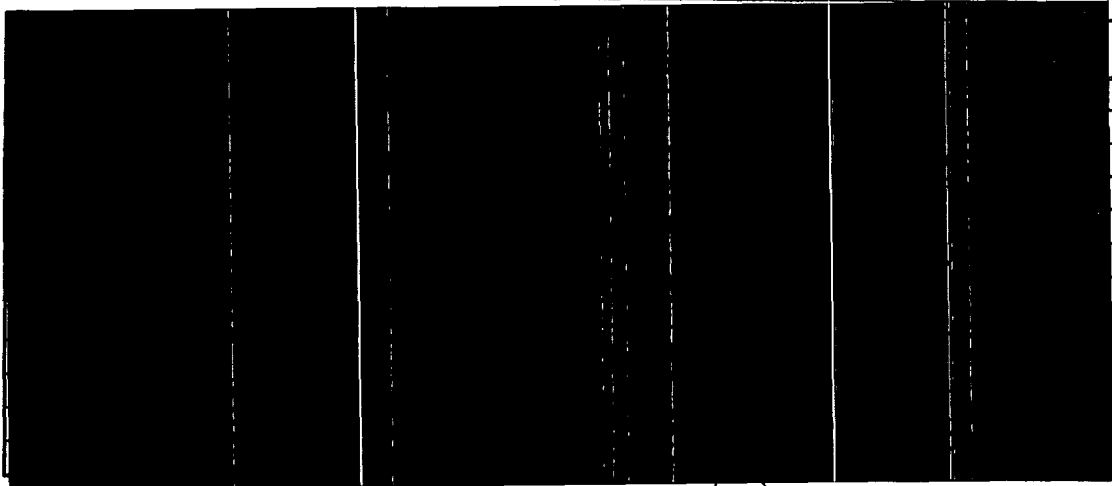


Report No. S8569-02

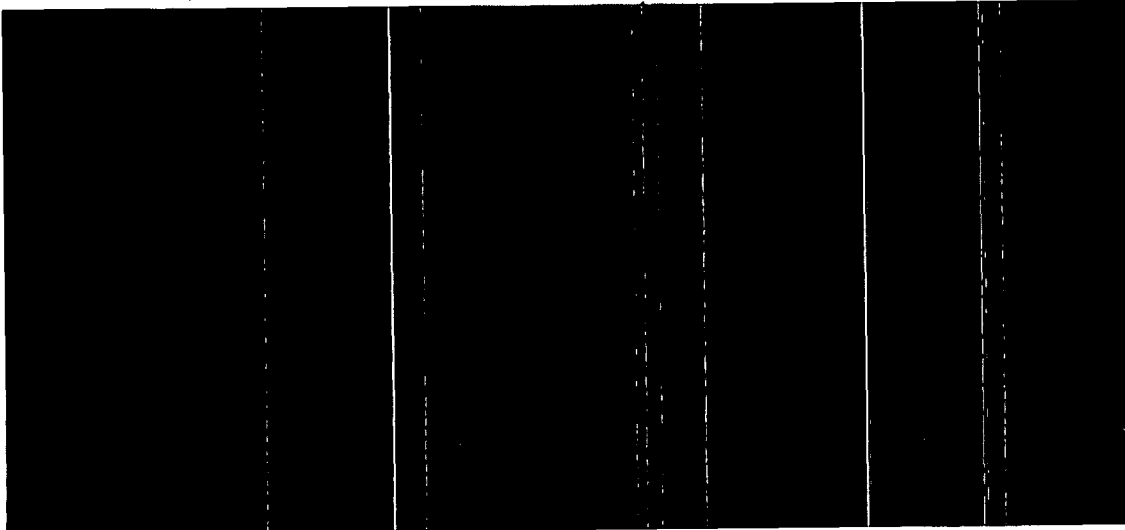
BUSINESS SENSITIVE

MAGNETIC FIELD IMMUNITY

Test Report #: S-8569 Test Area: TRI
Test Method: EN 61000-4-8 Date: 09 DEC 98
Tested per customer test procedure.
EUT Model #: RM 1000 EUT POWER: 230 Vac/50 Hz 120 Vac/60 Hz
EUT Description: RADIATION MONITOR 2 CH Other: _____
Temperature: 23 °C
Air Pressure: 101.1 kPa
Relative Humidity: 19 %
NOTES: _____



Tested By: _____
Reviewed by: _____
Printed Signature





Report No. S8569-02

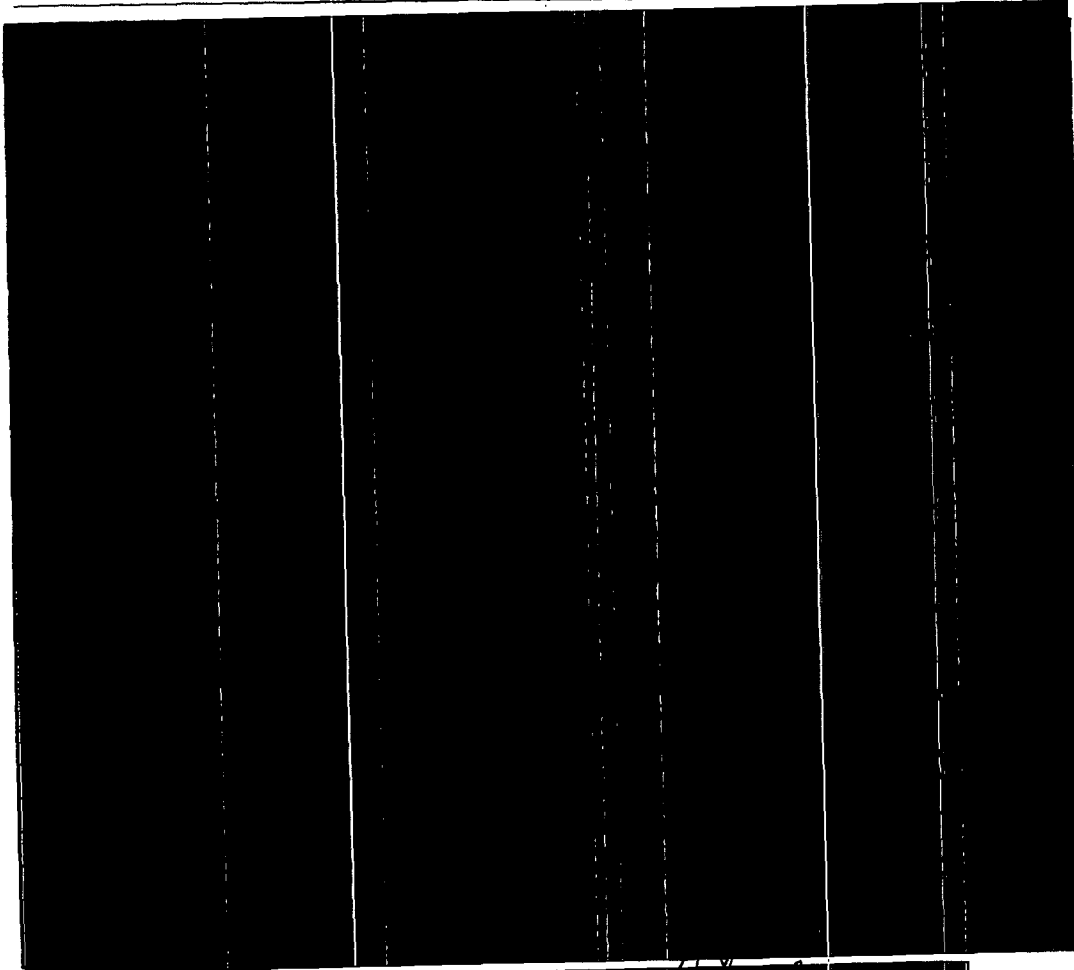
BUSINESS SENSITIVE

VOLTAGE DIPS & SHORT INTERRUPTIONS

Test Report #: S-8569 Test Area: TR-1
Test Method: EN 61000-4-11 Date: 09 DEC 96
Tested per customer test procedure.
EUT Model #: RM 1000 EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 Other:
EUT Description: 2 CH RADIATION MONITOR
NOTES:



Temperature: 23 °C
Air Pressure: 101.1 kPa
Relative Humidity: 17 %



Tested by: _____
Reviewed by: _____ Printed _____ Signature _____

VOLT.DOC Rev 08.97



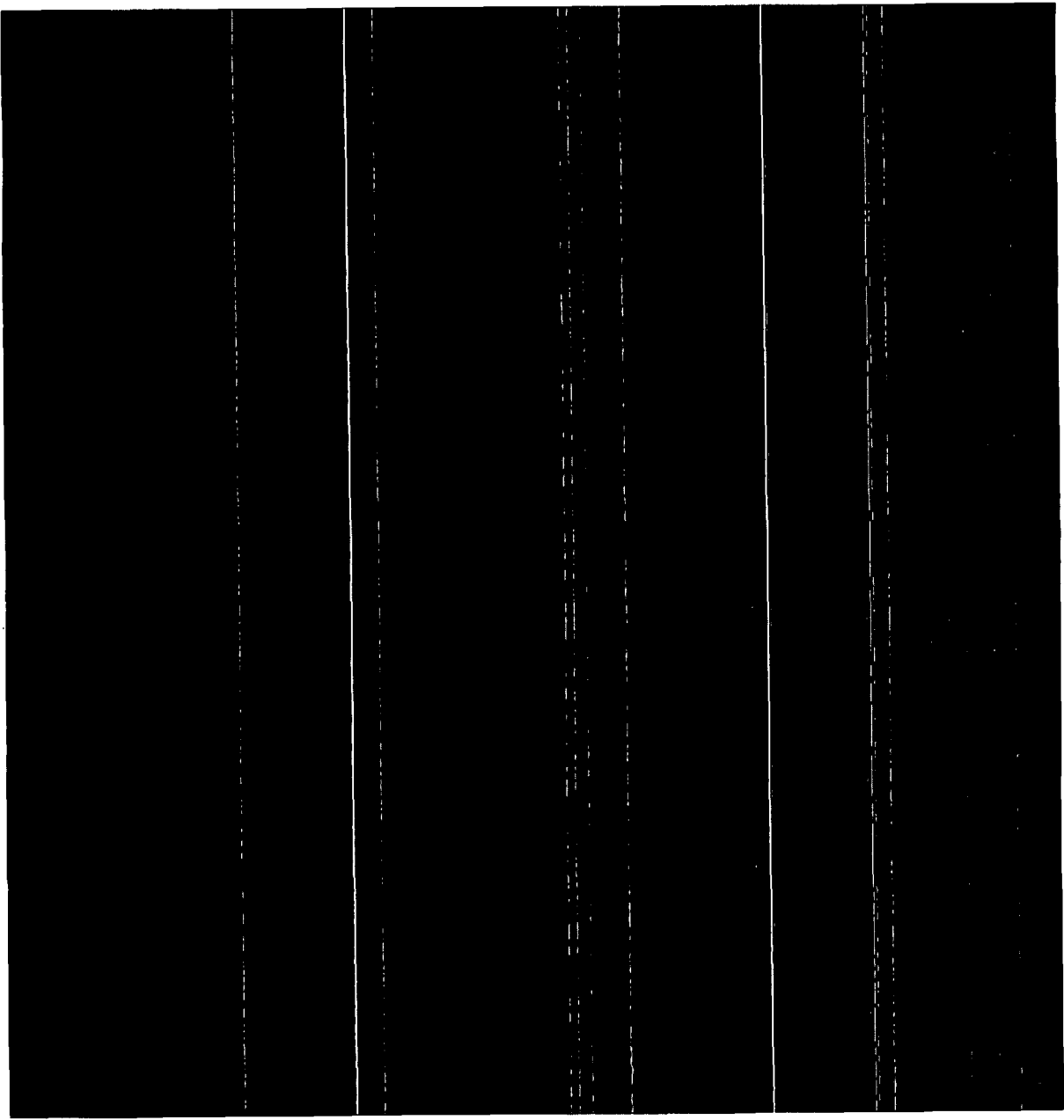
Report No. S8569-02

BUSINESS SENSITIVE

**TUV Product Service
Powerline Conducted RFI**

EUT: Model RM 1000 Radiation Monitor, 2 chan1
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A
Comment: [REDACTED]

Date: 25. Nov 98 09:29

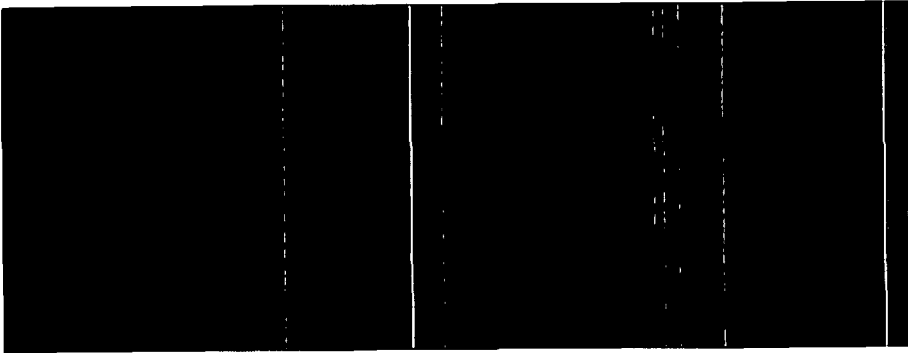




Report No. S8569-02 BUSINESS
SENSITIVE

TUV Product Service
Powerline Conducted RFI
EUT: Model RM 1000 Radiation Monitor, 2 chanl
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A
Comment: [REDACTED]
Date: 25. Nov 98 09:29

Final Measurement Results:





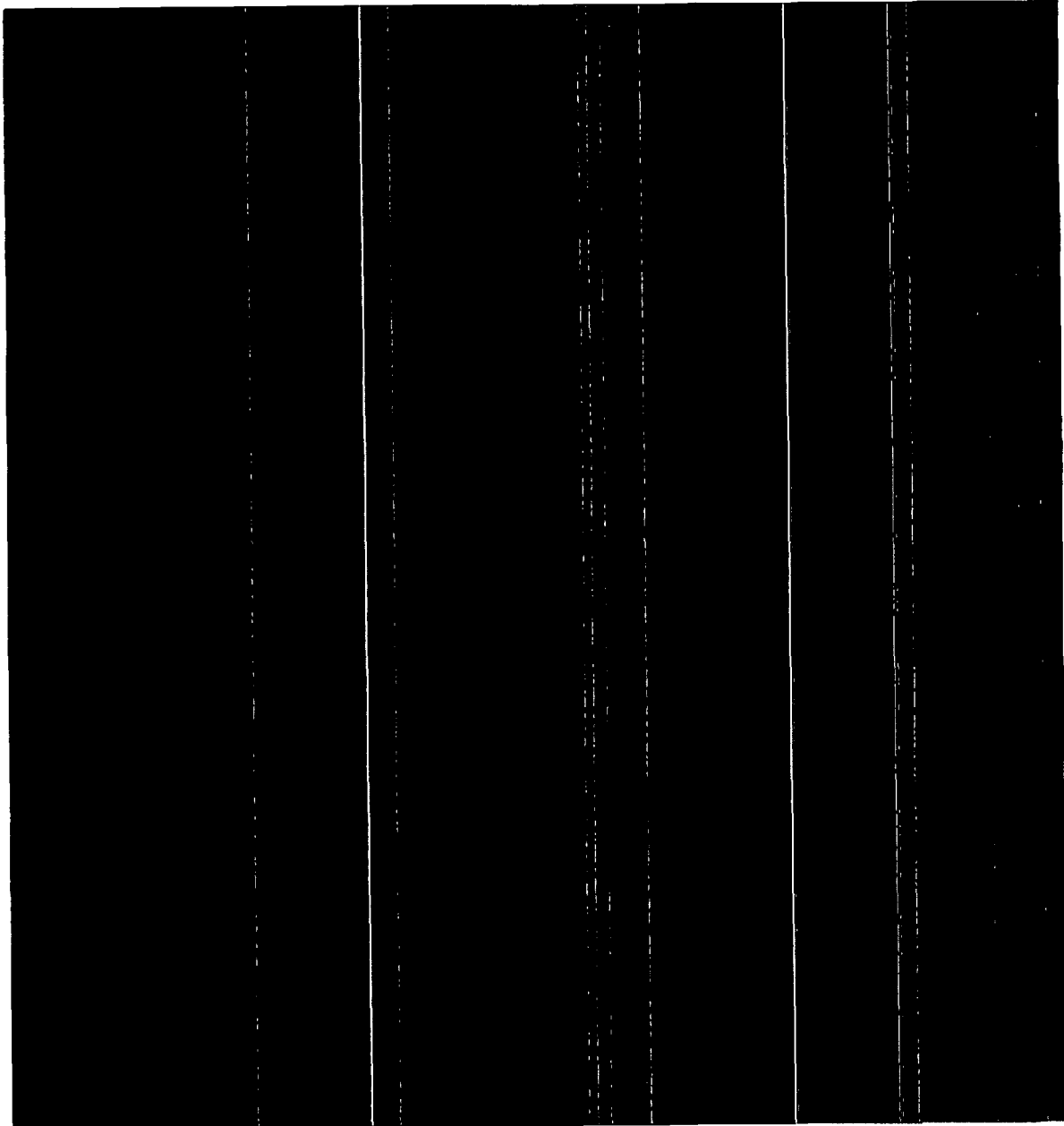
Report No. S8569-02

BUSINESS
SENSITIVE

**TUV Product Service
Powerline Conducted RFI**

EUT: Model RM 1000 Radiation Monitor, 2 chanl
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A
Comment: [REDACTED]

Date: 25. Nov 98 09:36





Report No. S8569-02

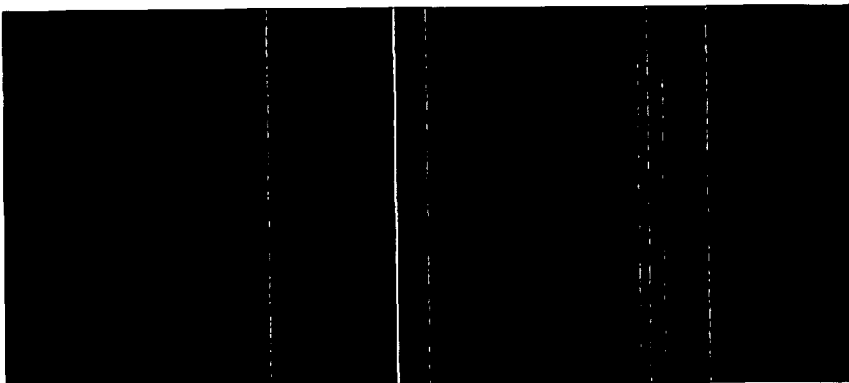
BUSINESS
SENSITIVE

**TUV Product Service
Powerline Conducted RFI**

EUT: Model RM 1000 Radiation Monitor, 2 chanl
Manuf: Sorrento Electronics
Op Cond: Normal
Operator: [REDACTED]
Test Spec: EN 55011 Class A
Comment: [REDACTED]

Date: 25. Nov 98 09:36

Final Measurement Results:





Report No. S8569-02

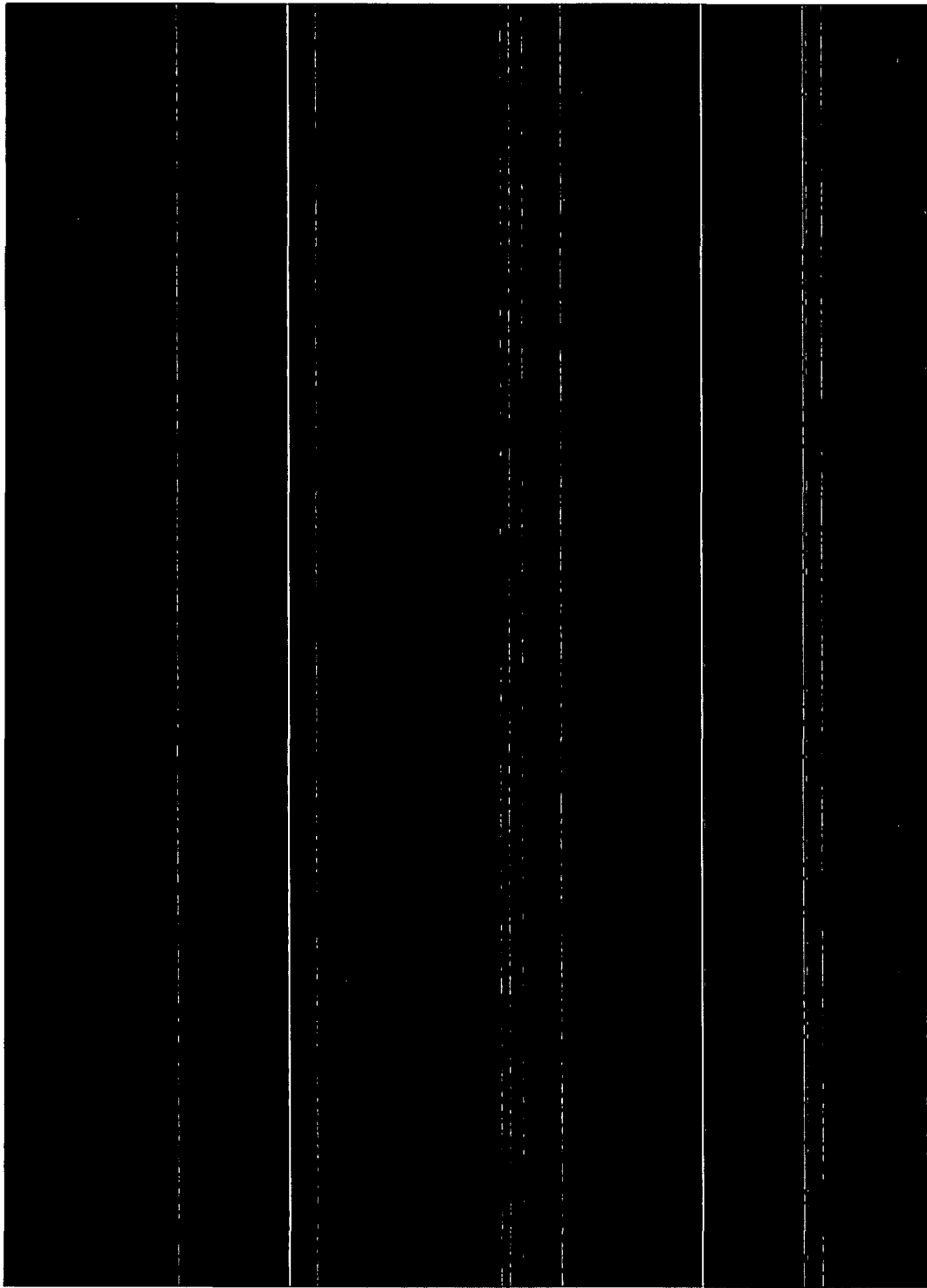
BUSINESS
SENSITIVE





Report No. S8569-02

BUSINESS
SENSITIVE

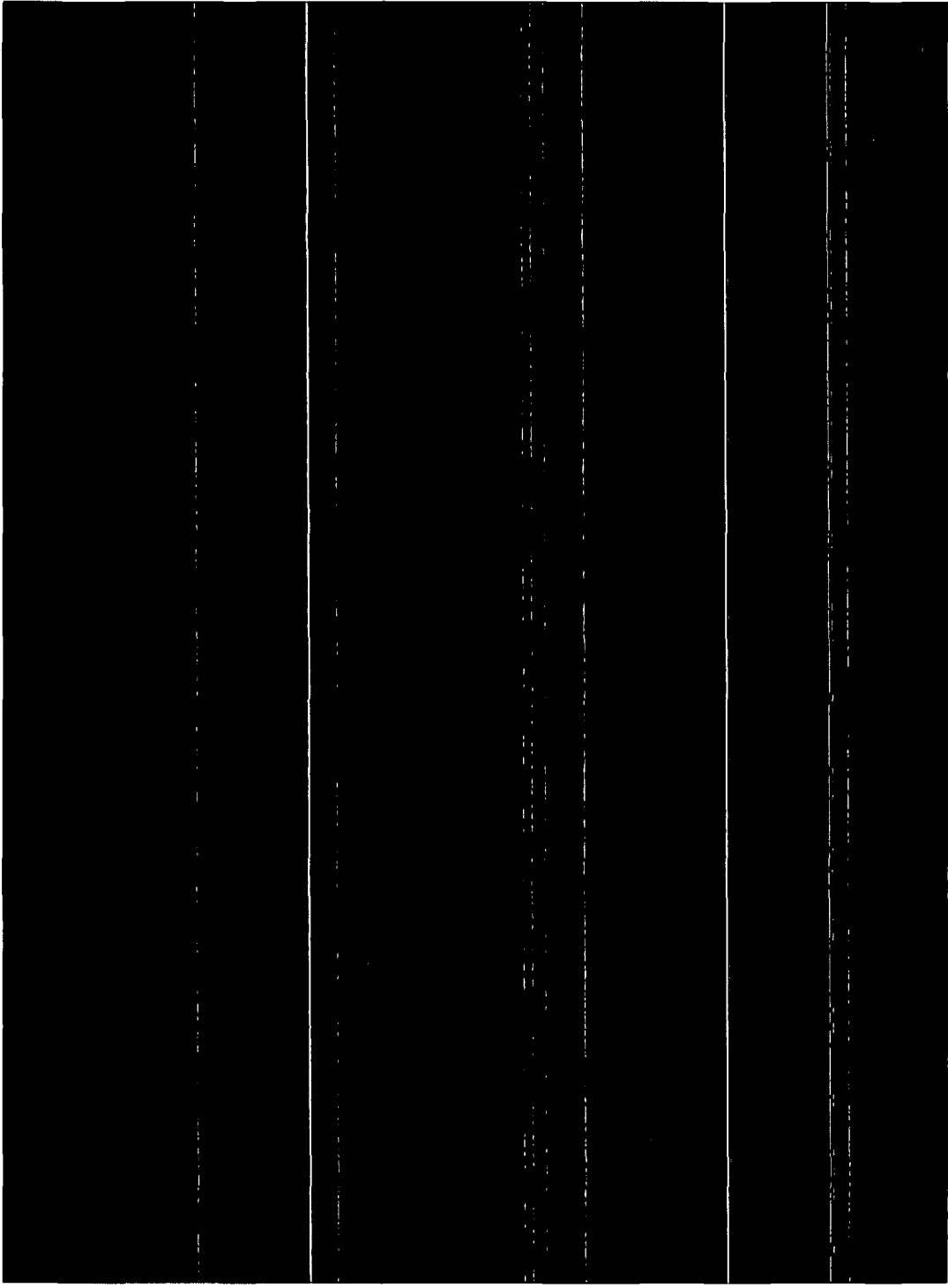




Report No. S8569-02



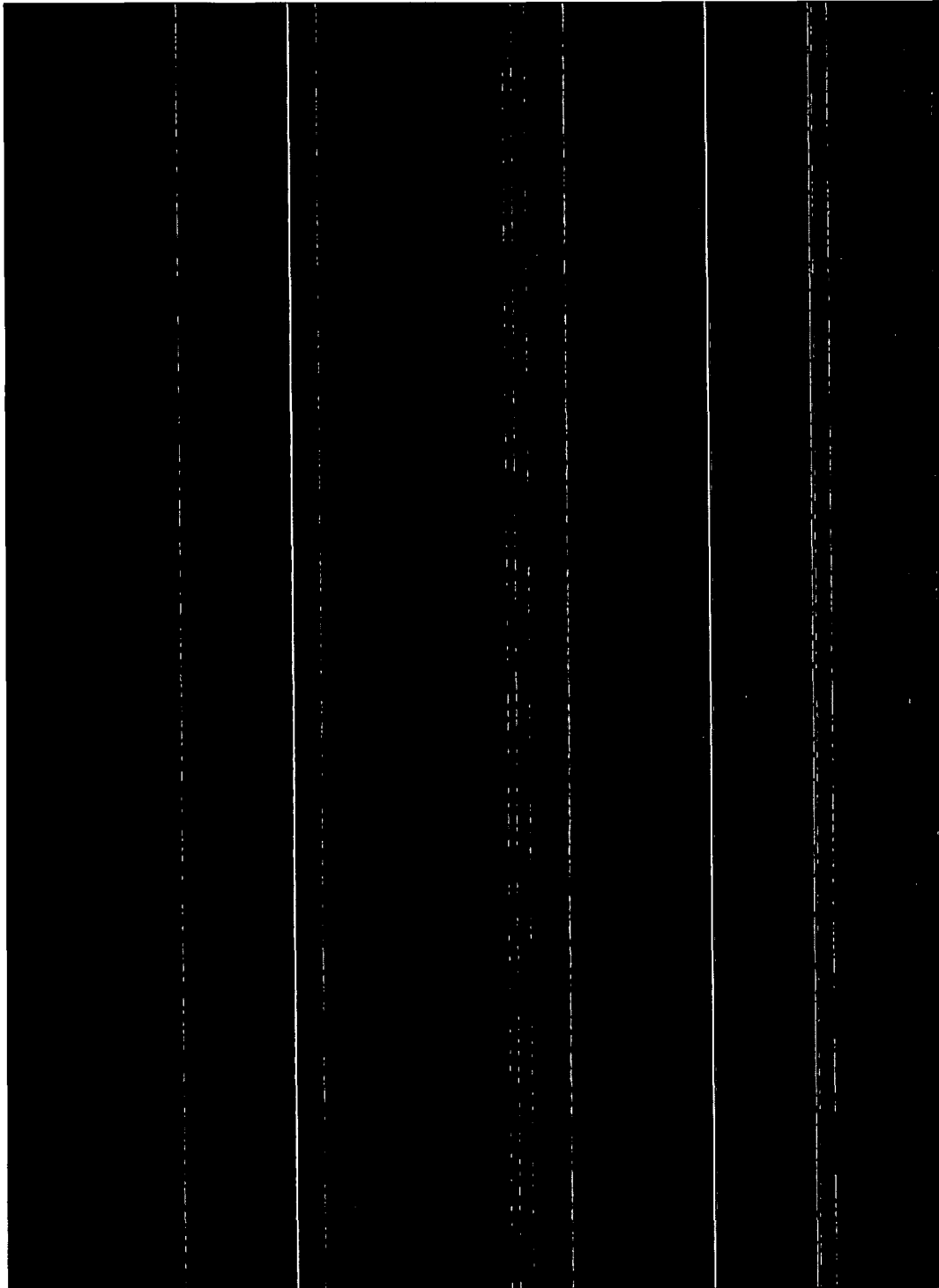
BUSINESS
SENSITIVE





Report No. S8569-02

BUSINESS
SENSITIVE

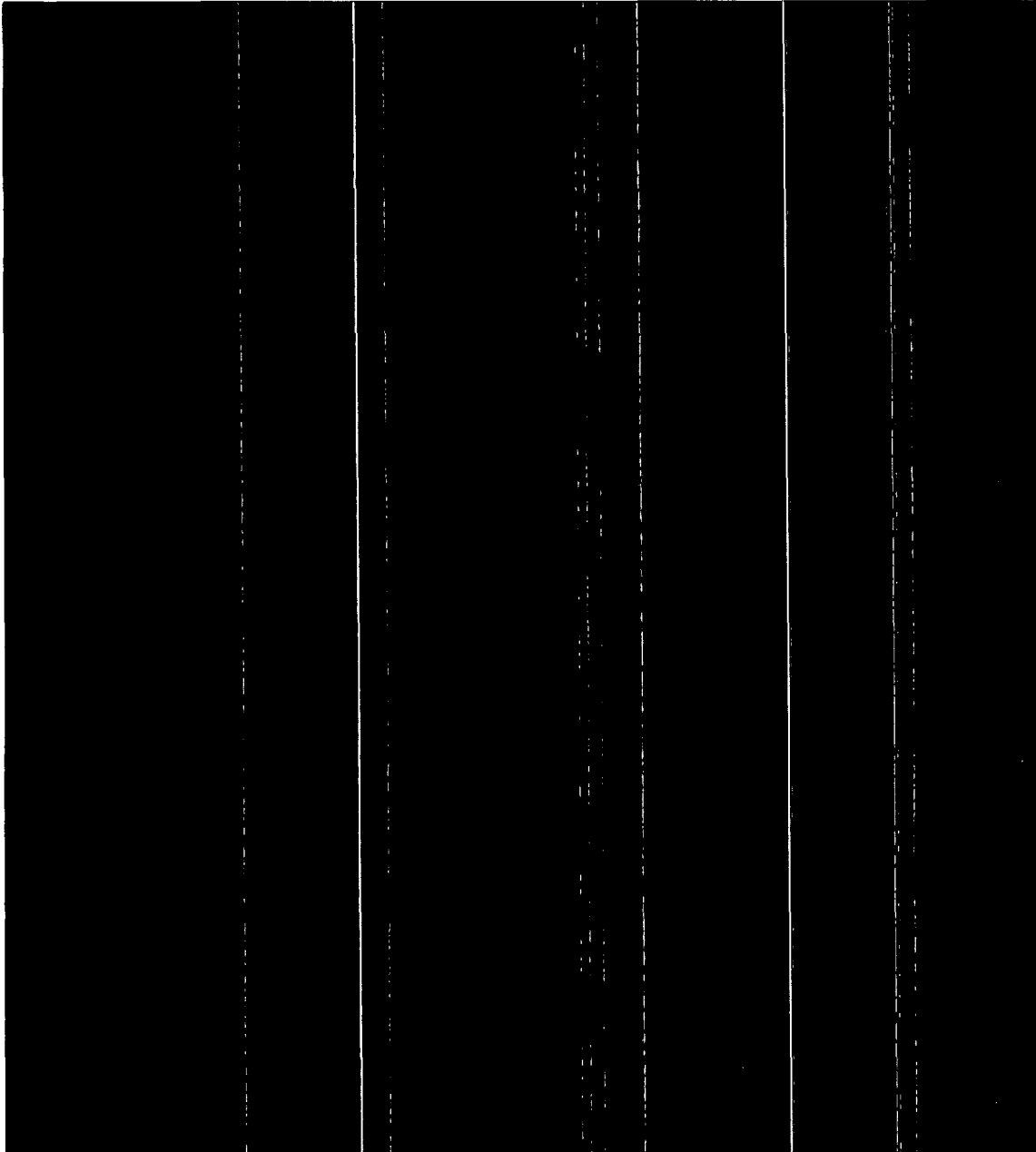




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BUSINESS
SENSITIVE

Test Configuration Reference for ESD, Floor-Standing Unit

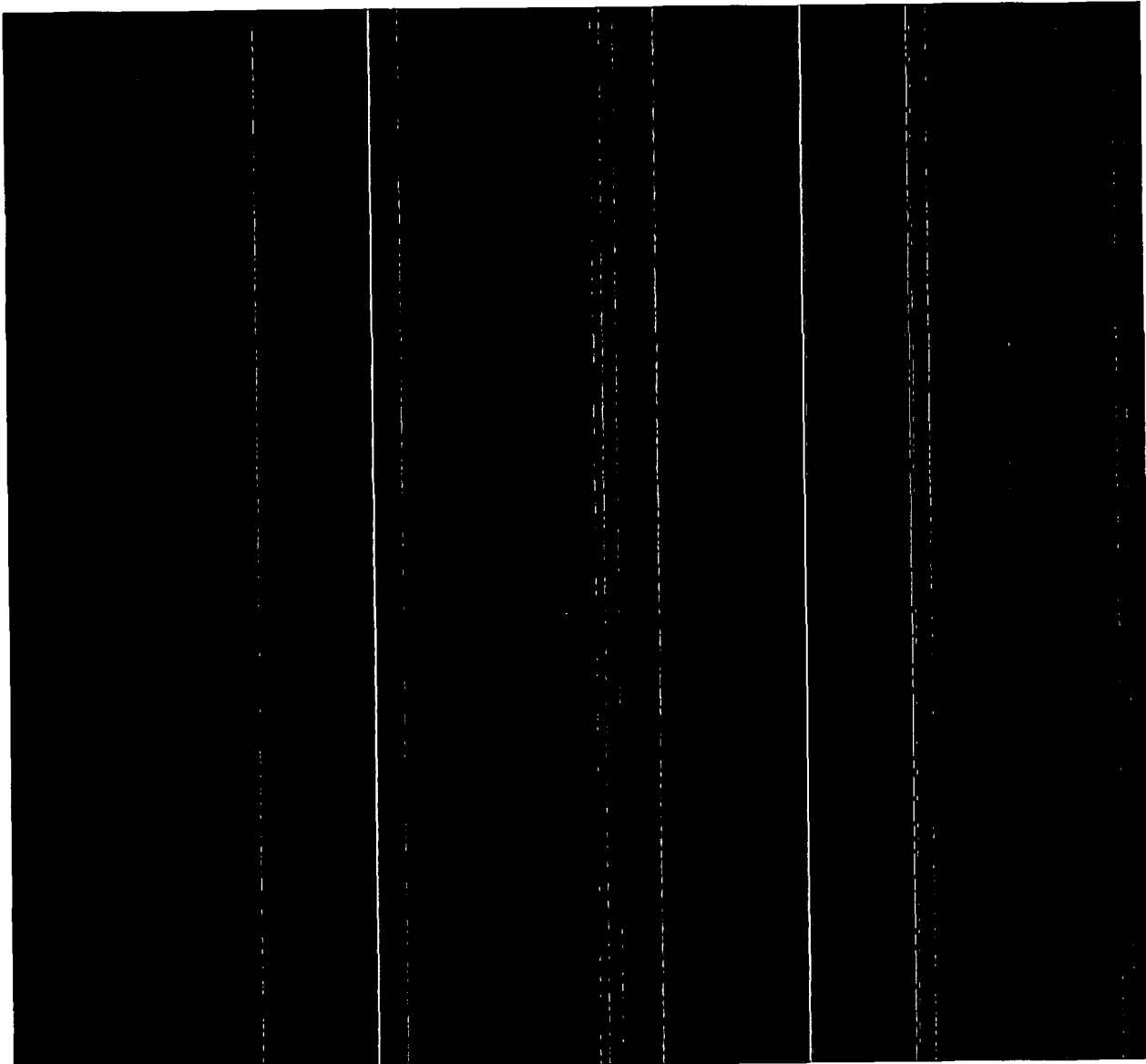




Report No. S8569-02

BUSINESS
SENSITIVE

Test Configuration for Radiated E-Fields Immunity

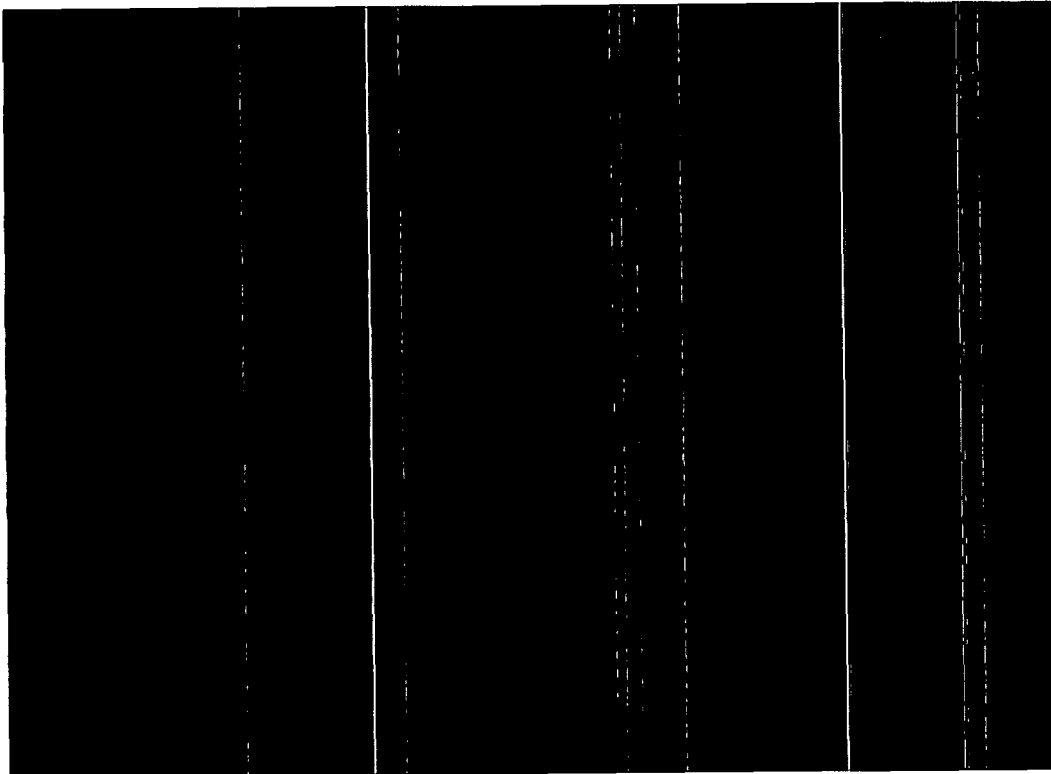




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BUSINESS
SENSITIVE

Test Configuration for Electrical Fast Transient/Burst Immunity

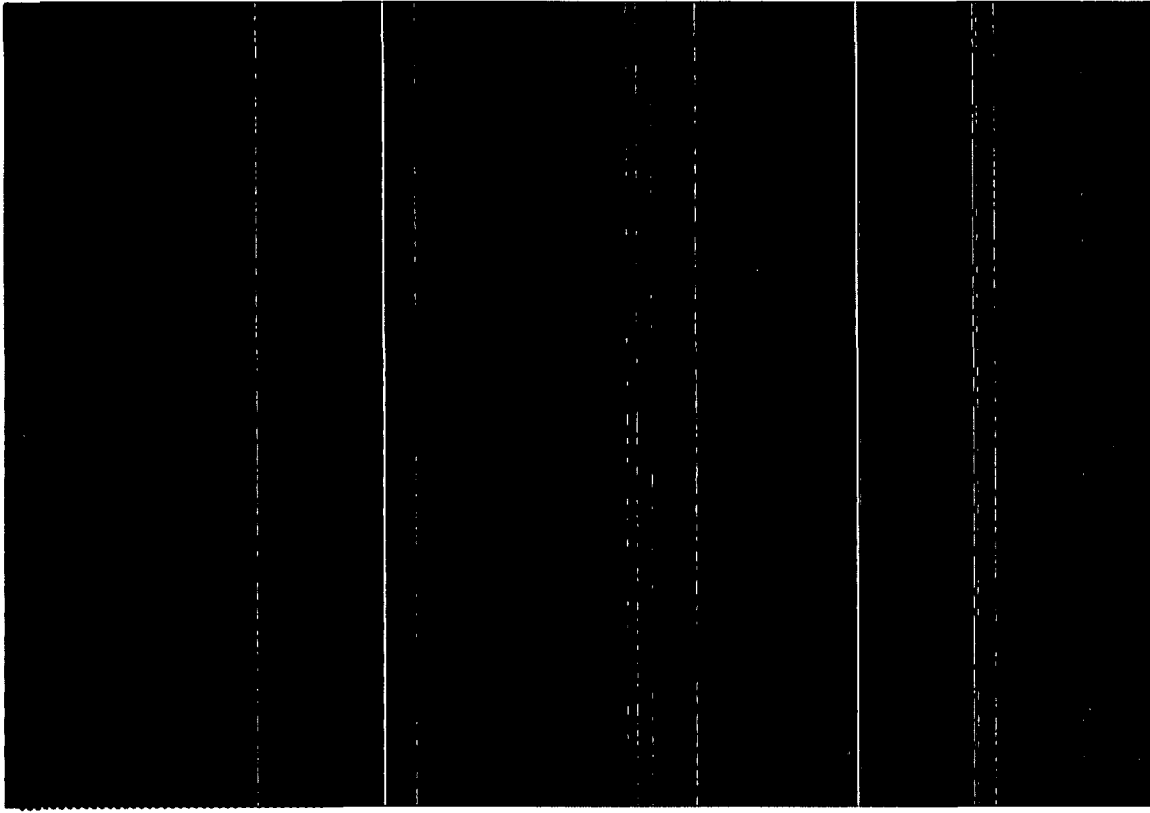




Report No. S8569-02

BUSINESS
SENSITIVE

Test Equipment Connections for Electrical Fast Transient/Burst Injection - Power Leads

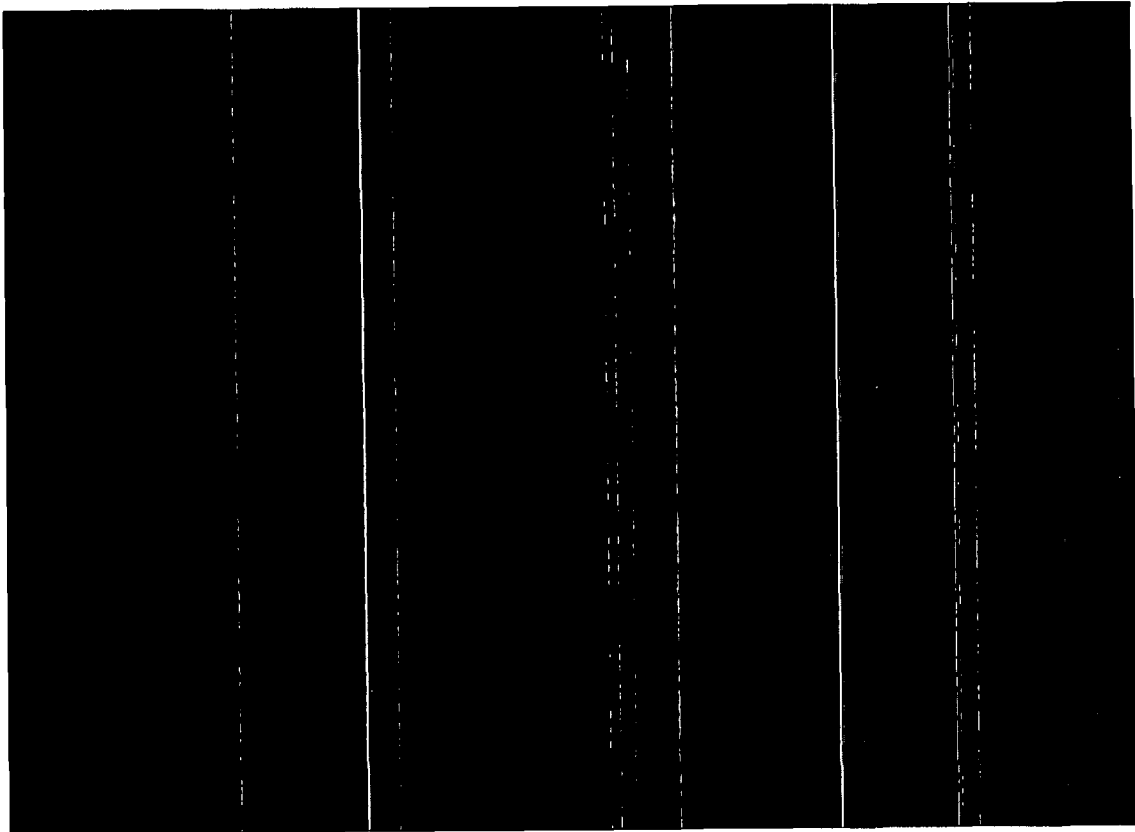




Report No. S8569-02

BUSINESS
SENSITIVE

Test Equipment Connections for Electrical Fast Transient/Burst Injection - Cables

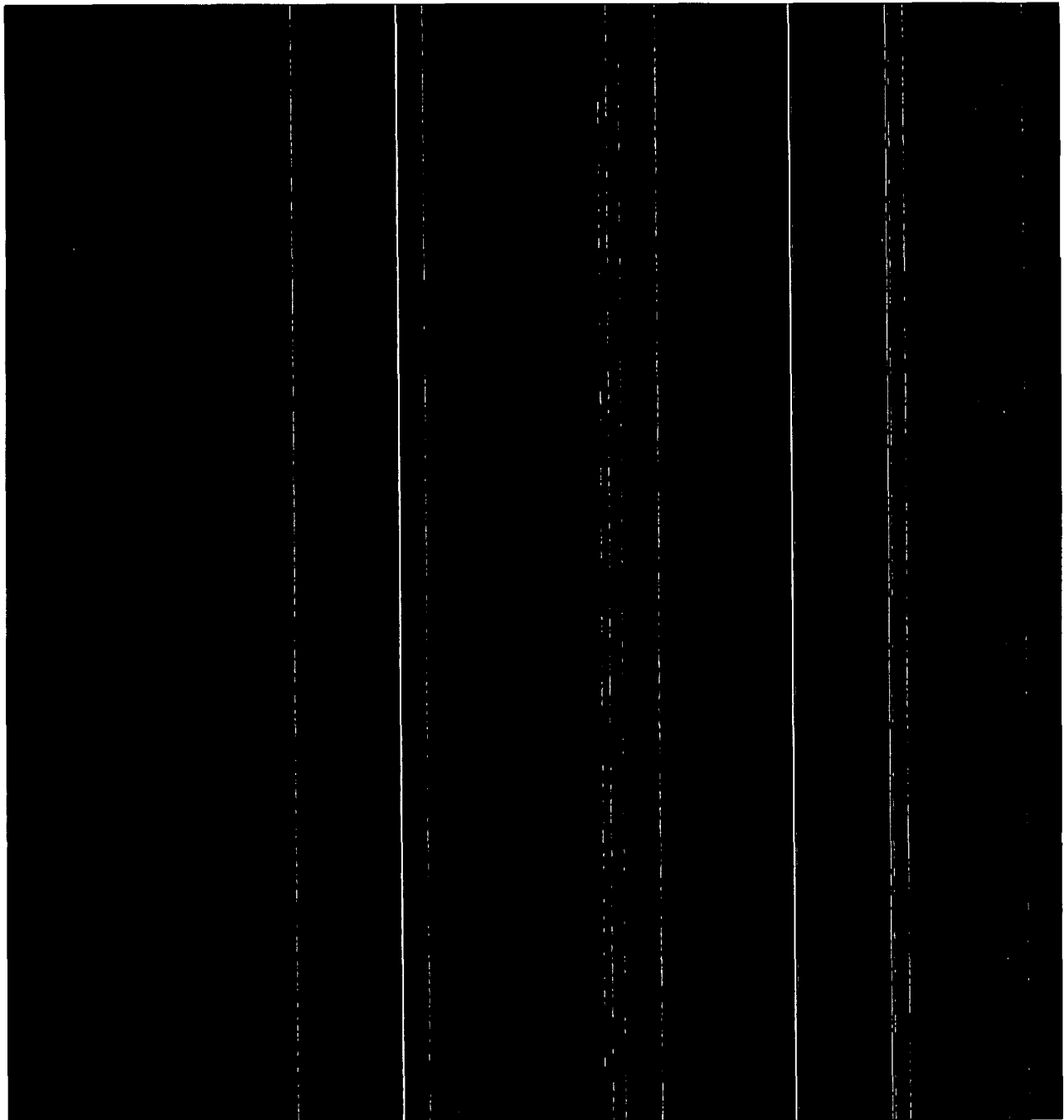




Report No. S8569-02

BUSINESS
SENSITIVE

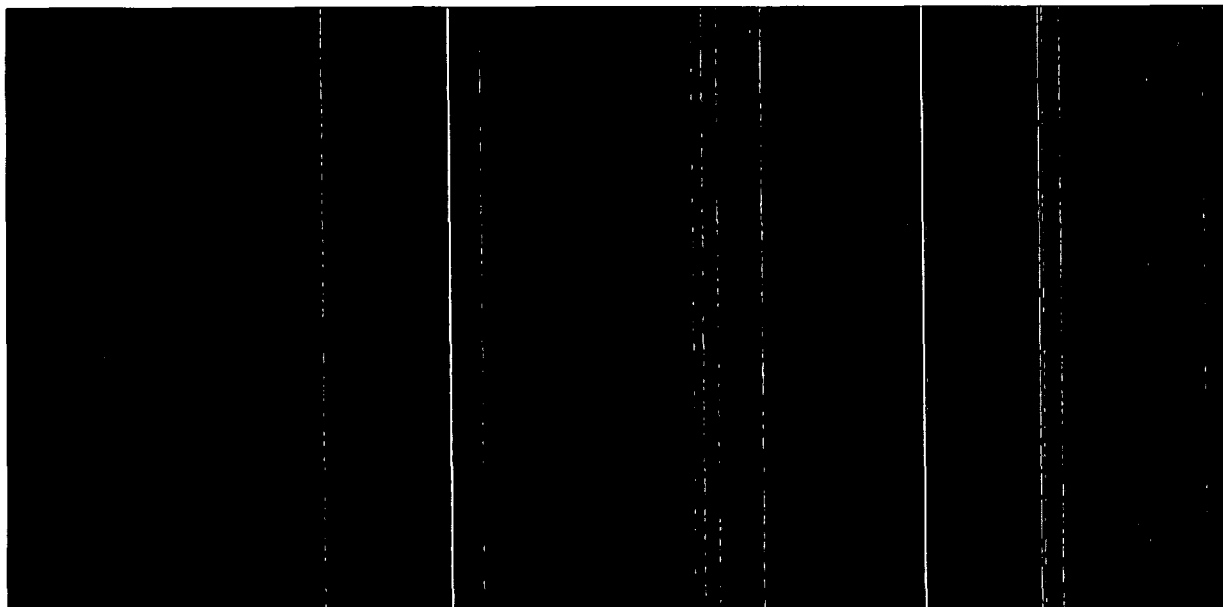
Test Configuration for Surge Immunity





Report No. S8569-02

BUSINESS
SENSITIVE

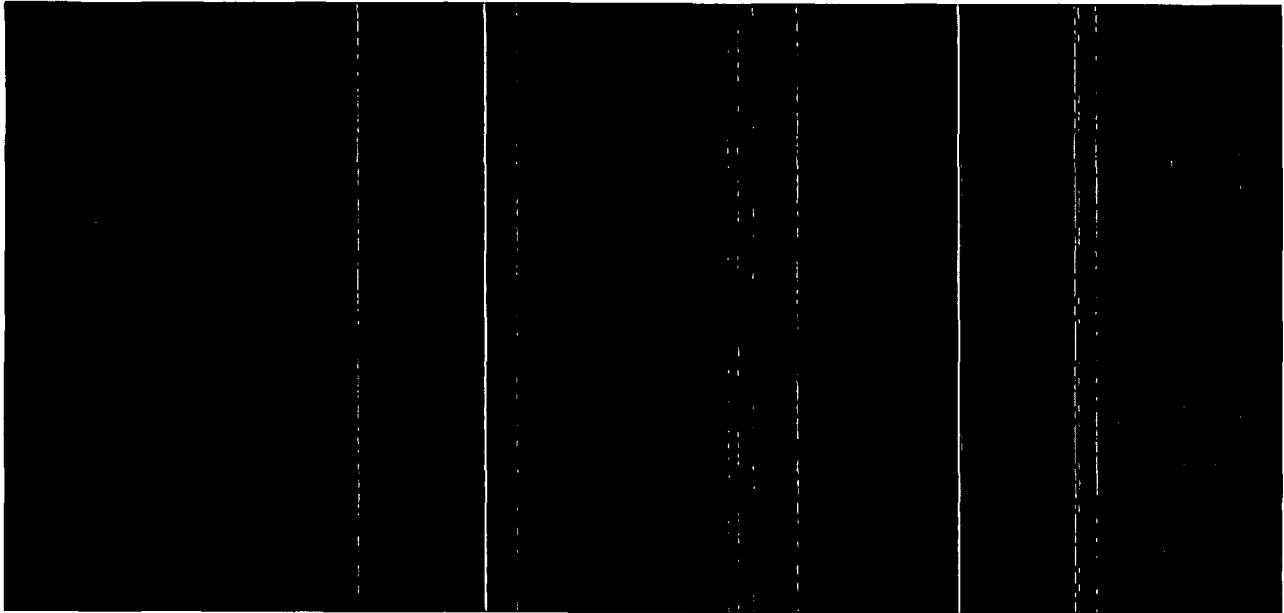




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BUSINESS
SENSITIVE

Test Configuration for Immunity to Conducted Disturbances

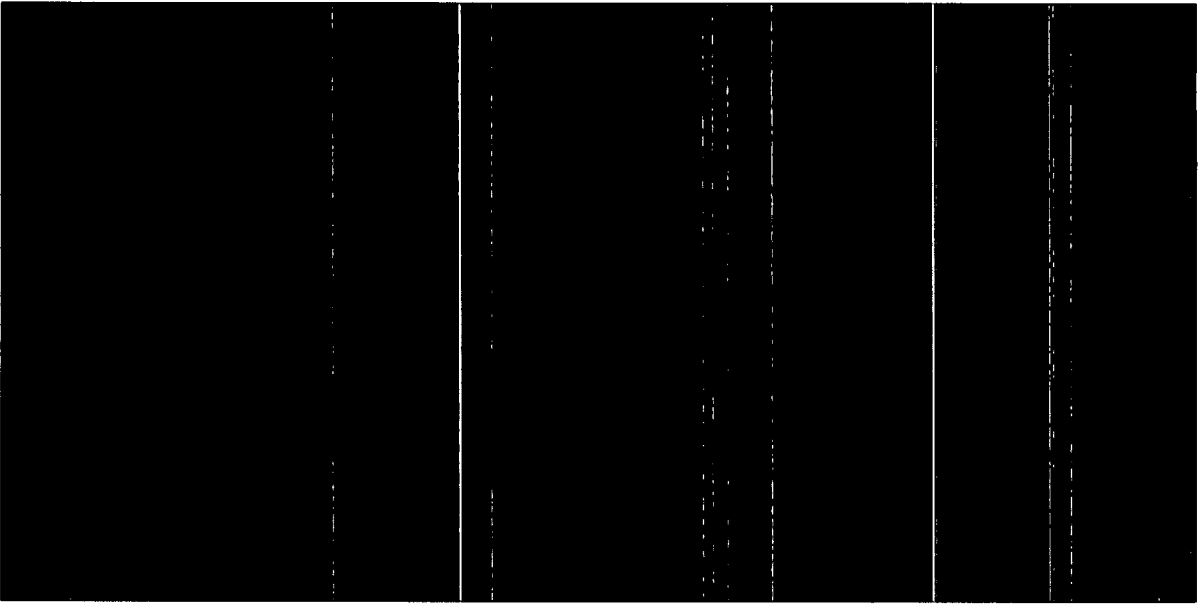




Report No. S8569-02

BUSINESS
SENSITIVE

Test Configuration for Immunity to Conducted Disturbances

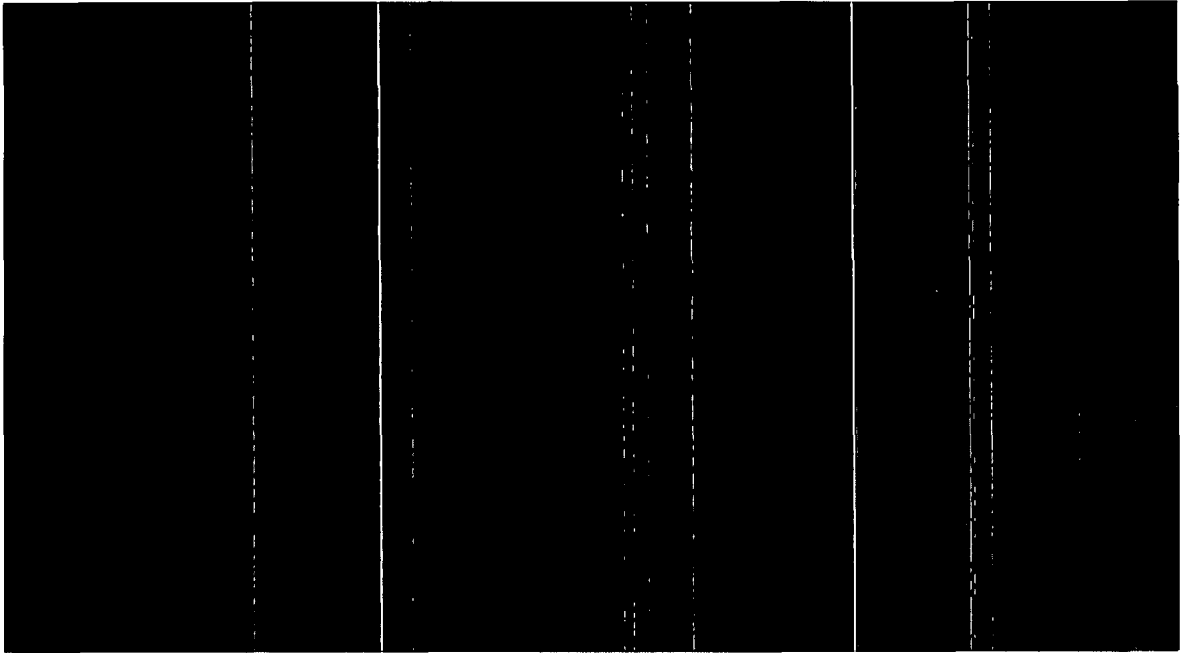




Report No. S8569-02

BUSINESS
SENSITIVE

Test Setup for Voltage Dips, Interruptions and Variations Immunity

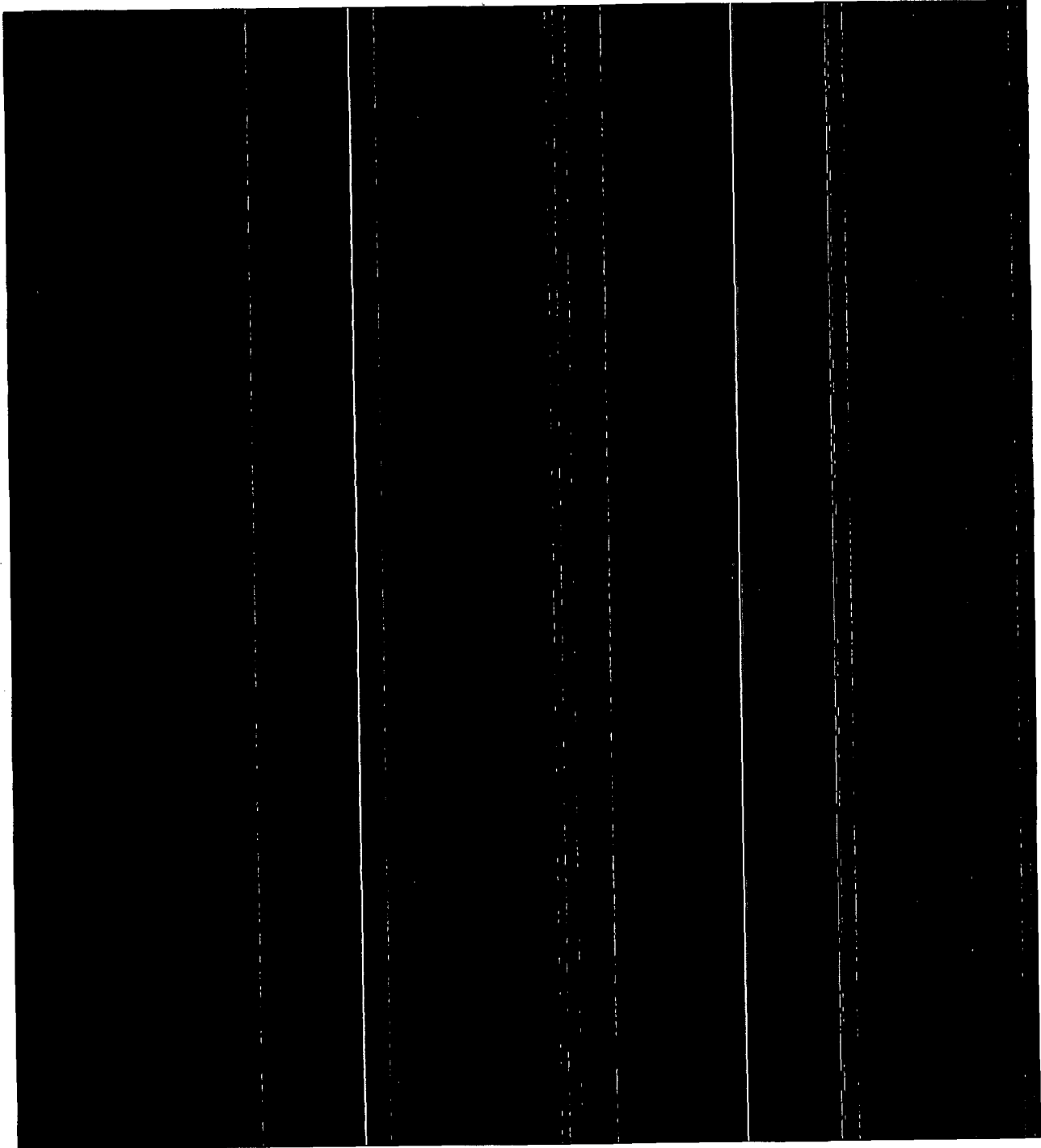




Report No. S8569-02

BUSINESS
SENSITIVE

Radiated Emission Test Setup, 30 to 1,000 MHz

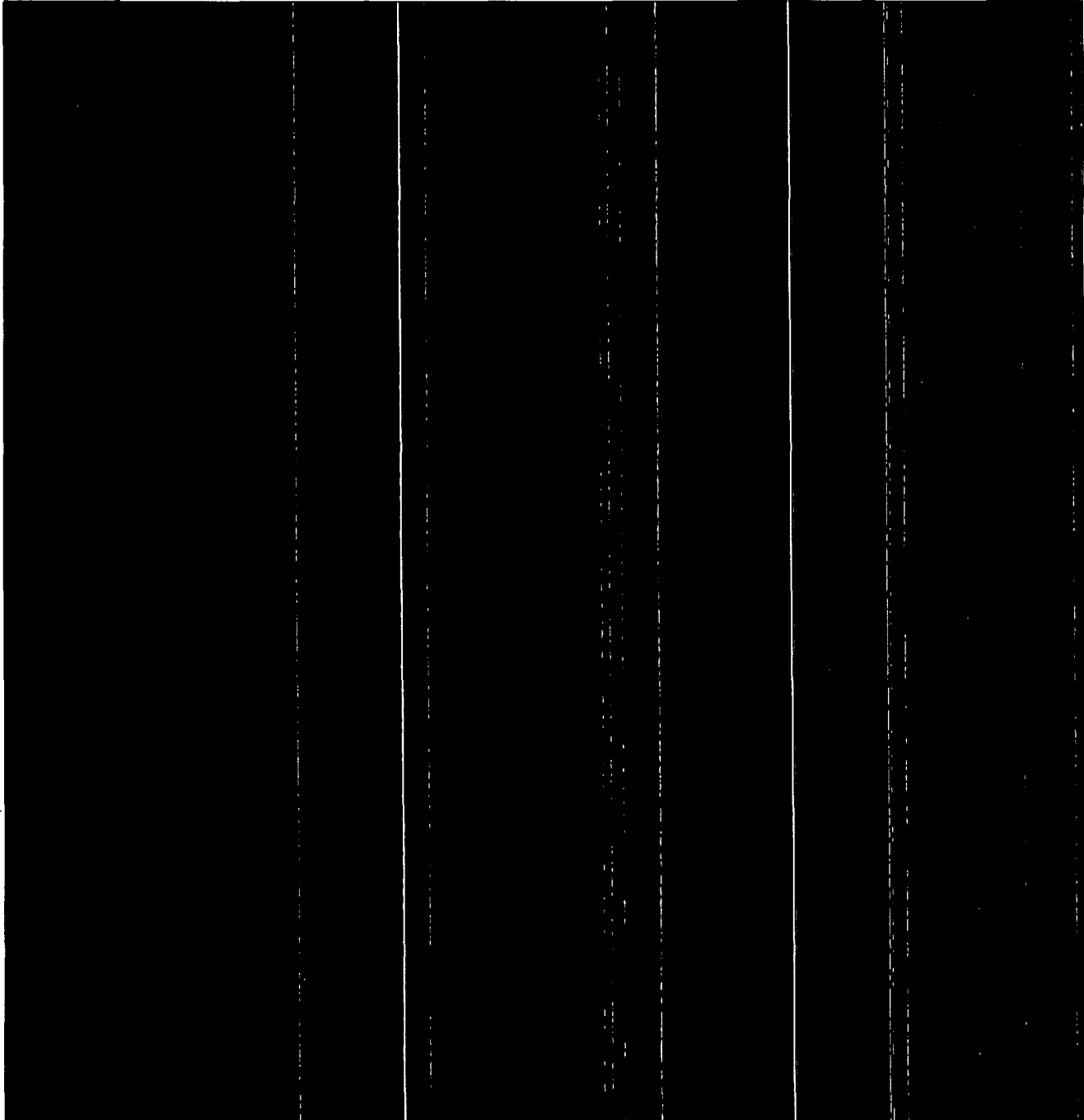




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BUSINESS
SENSITIVE

Conducted Emission Test Setup, 0.15 to 30 MHz





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BUSINESS
SENSITIVE





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Appendix A

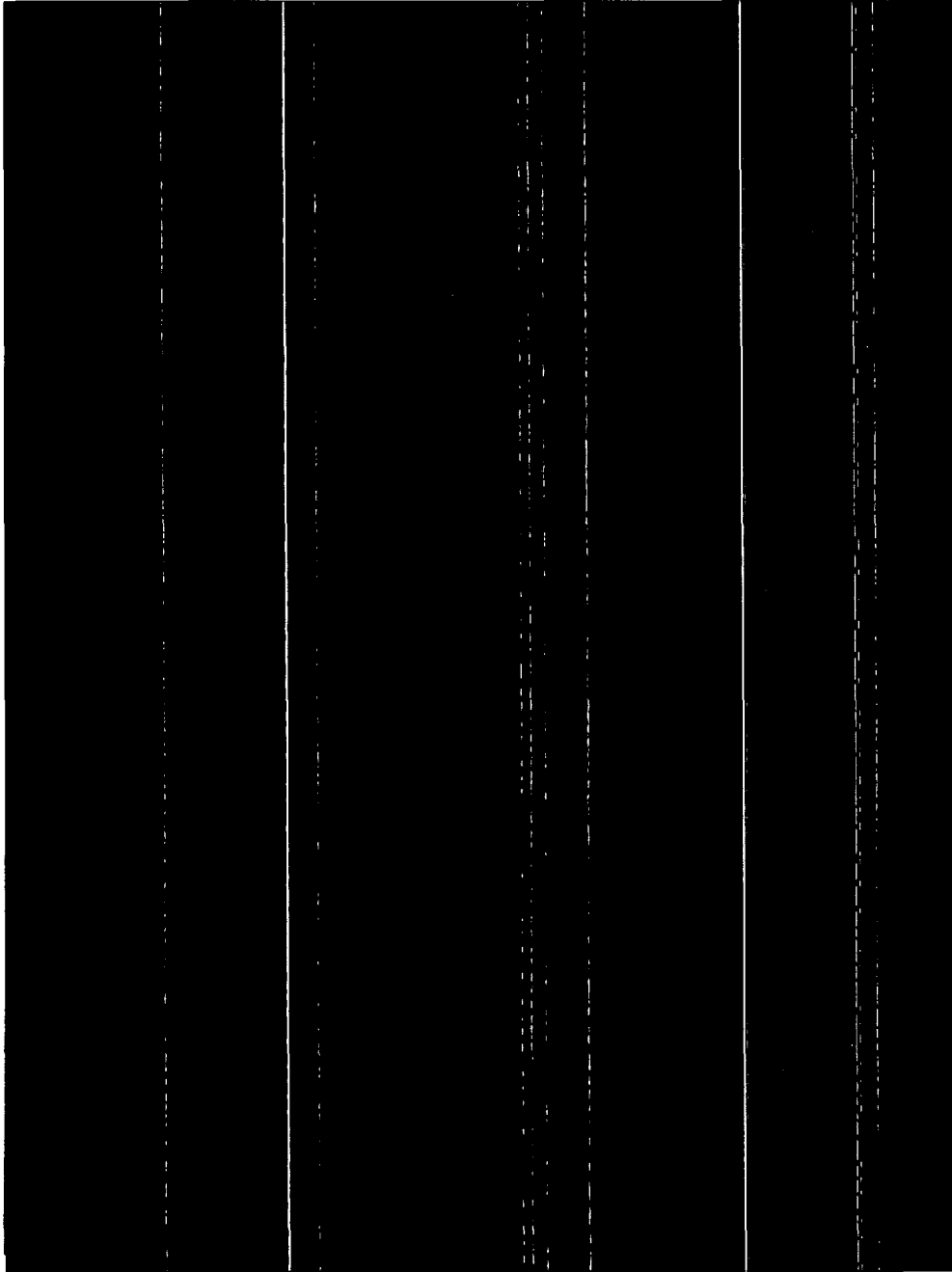
Photographs



Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Electrostatic Discharge (ESD)
EN 61000-4-2



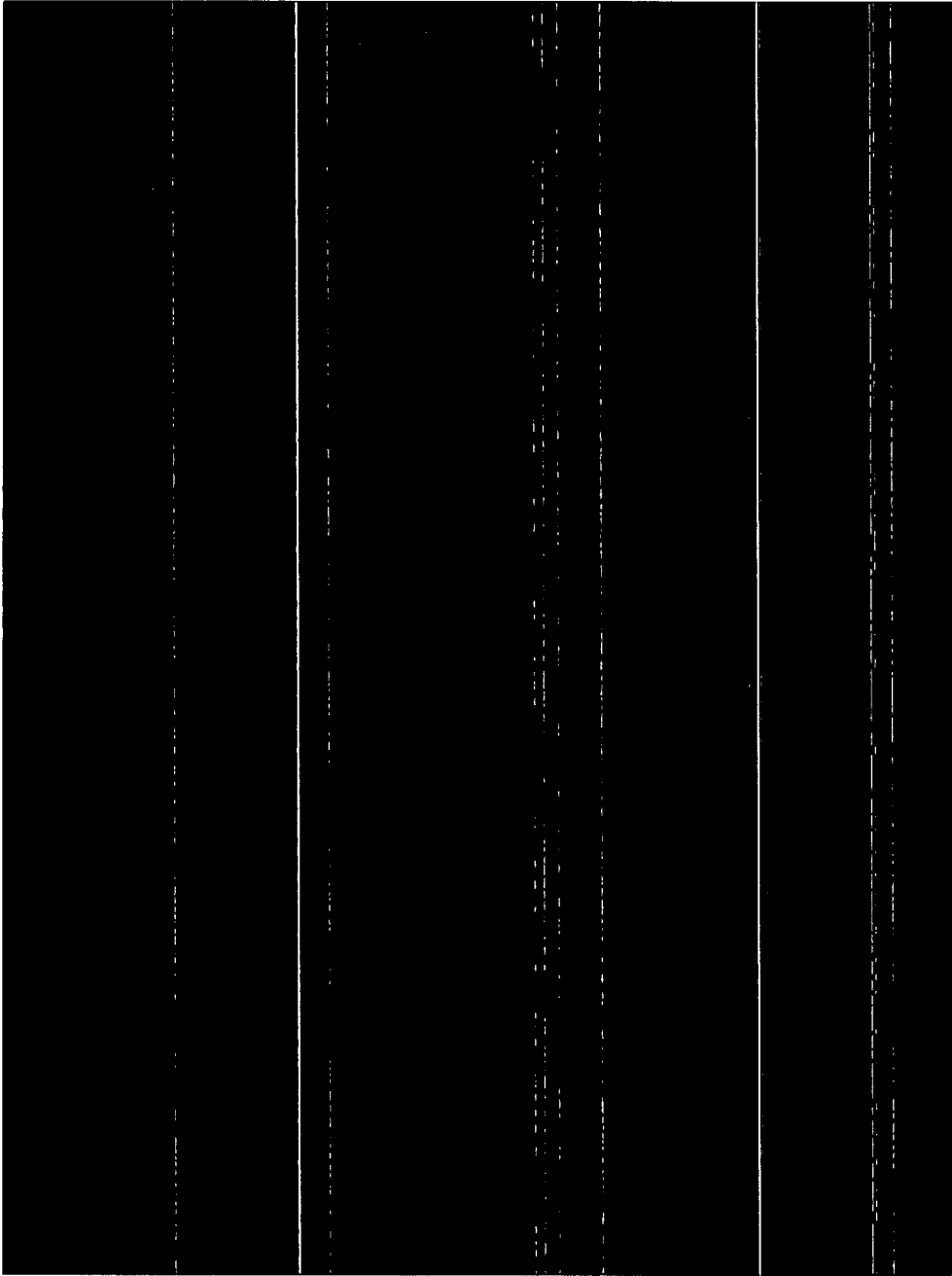


Report No. S8569-02



BUSINESS
SENSITIVE

Photograph of Test Setup:
Electrostatic Discharge (ESD)
EN 61000-4-2



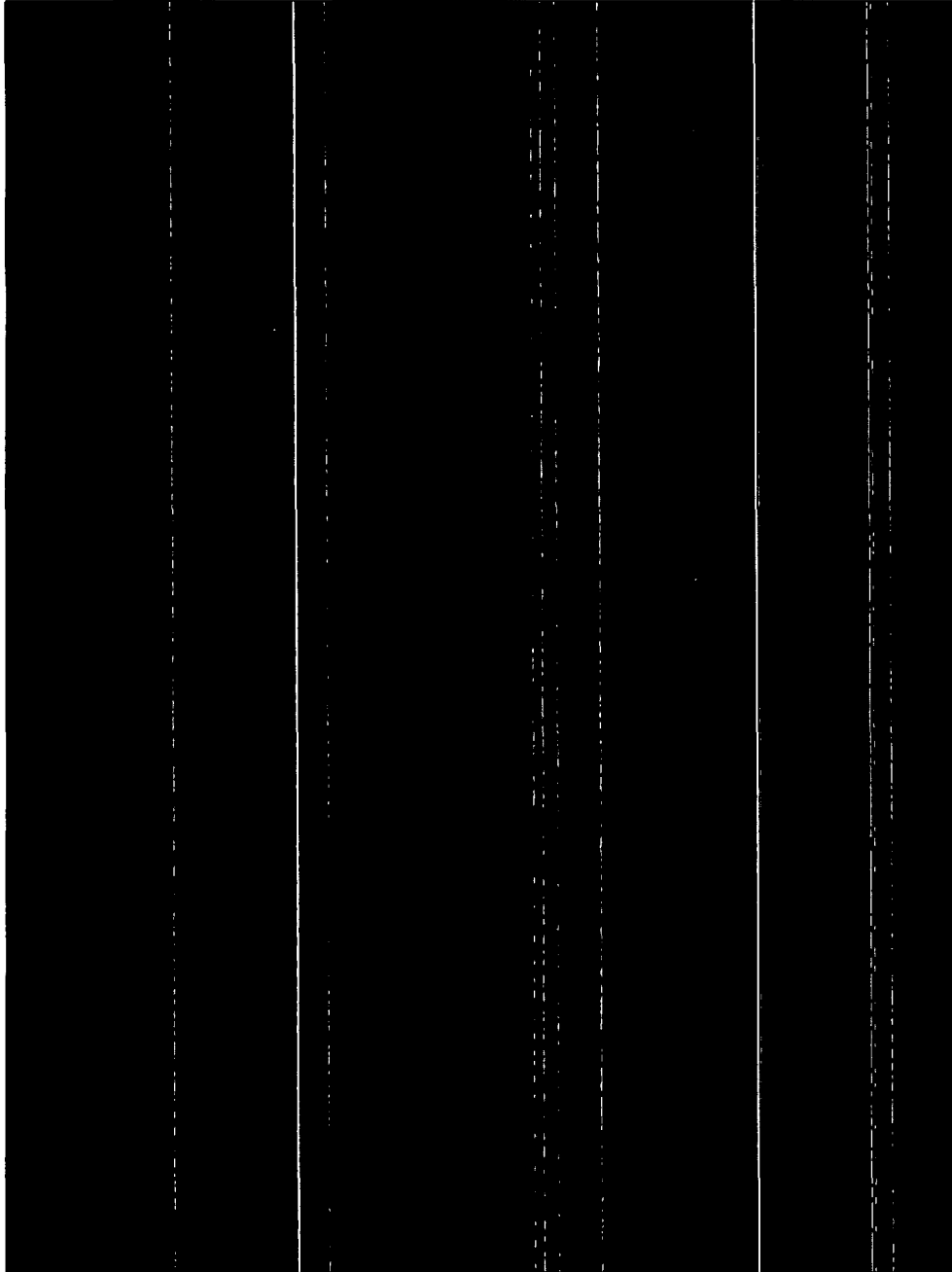


Report No. S8569-02



BUSINESS
SENSITIVE

Photograph of Test Setup:
Electrostatic Discharge (ESD)
EN 61000-4-2

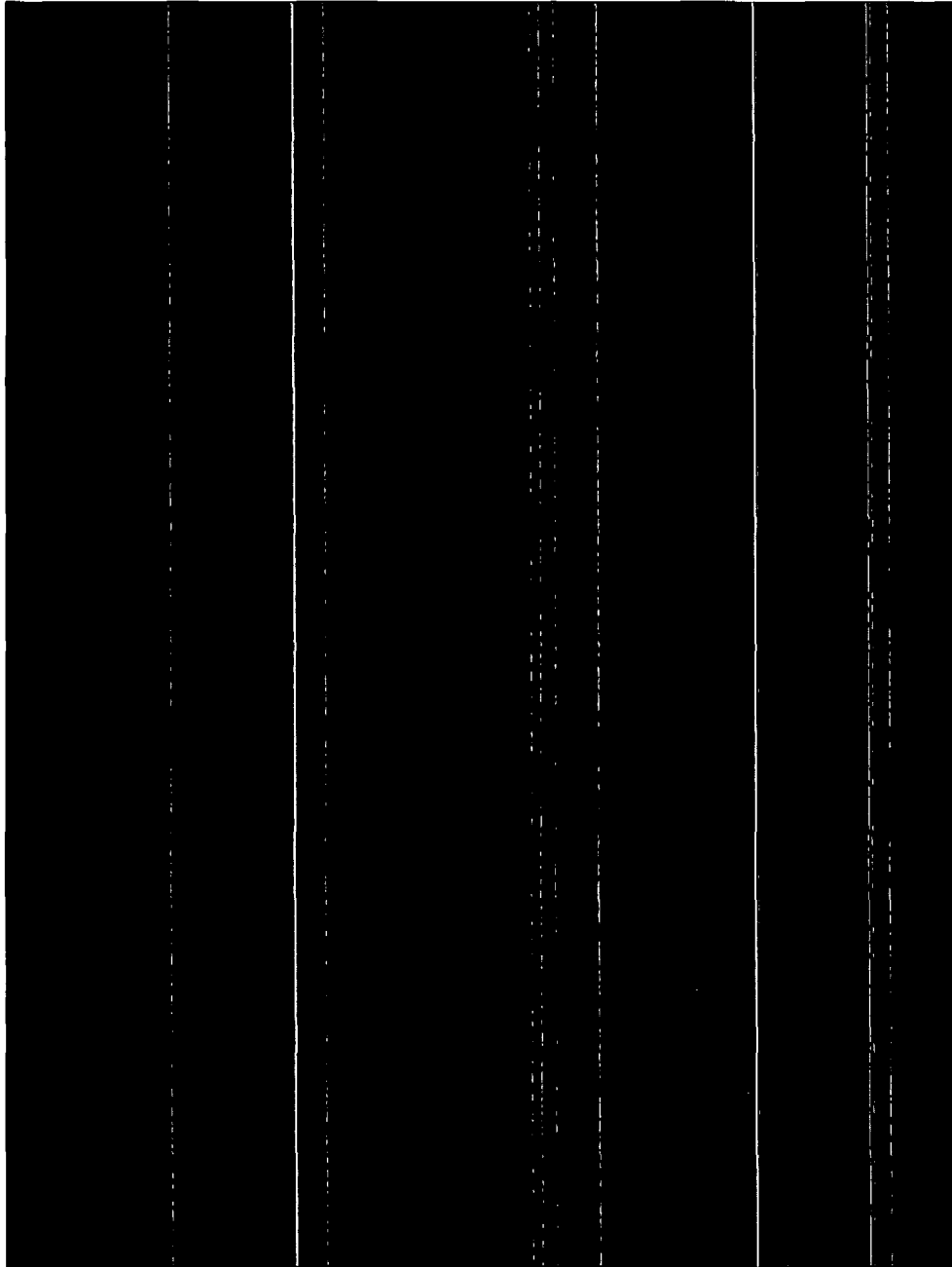




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BUSINESS
SENSITIVE

Photograph of Test Setup:
Radiated Electromagnetic Field
EN 61000-4-3





Report No. S8569-02

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Radiated Electromagnetic Field
EN 61000-4-3

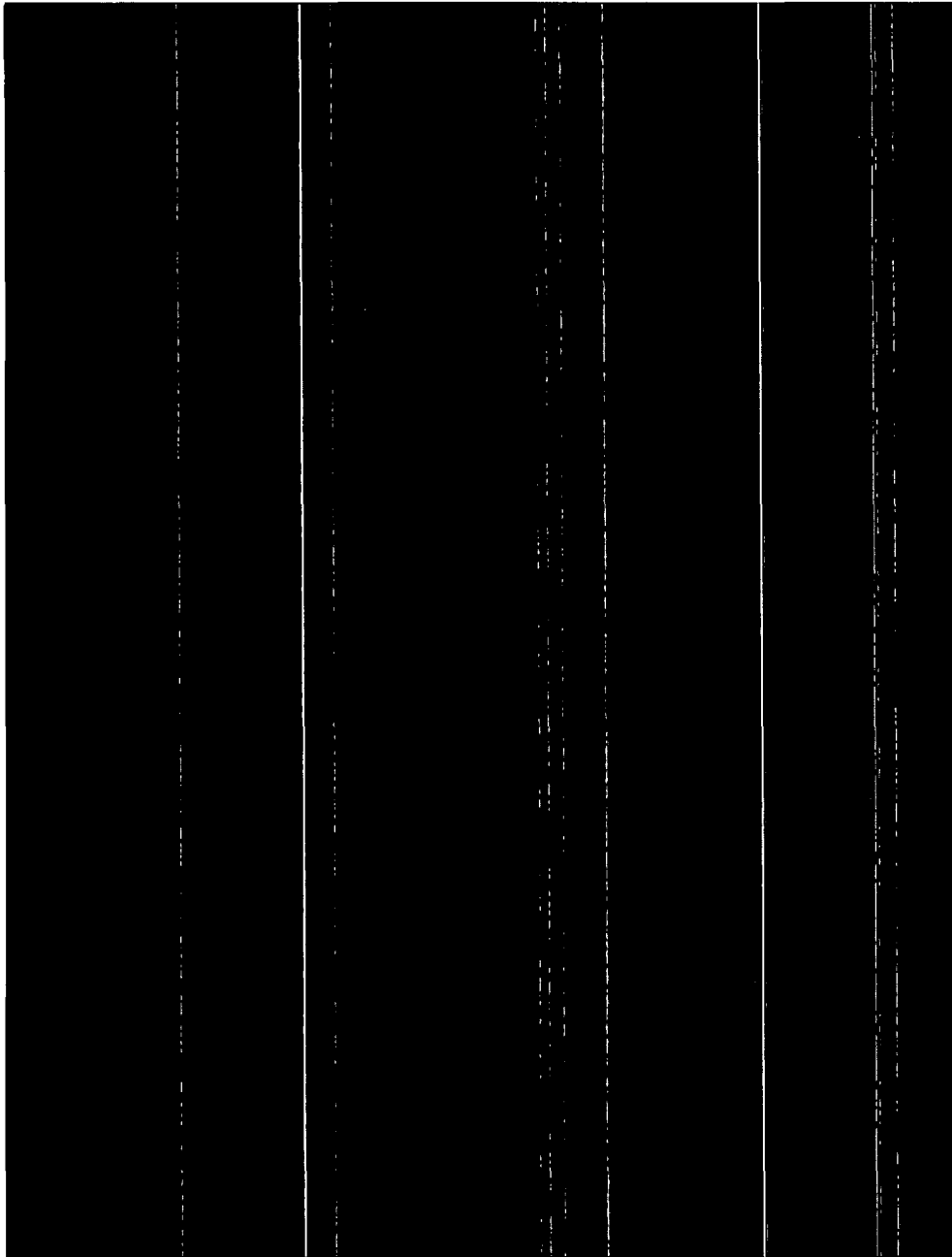




Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Fast transients (BURST)
EN 61000-4-4





Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Fast transients (BURST)
EN 61000-4-4





Report No. S8569-02

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
SURGE Transients
EN 61000-4-5





Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Conducted Susceptibility
CS101



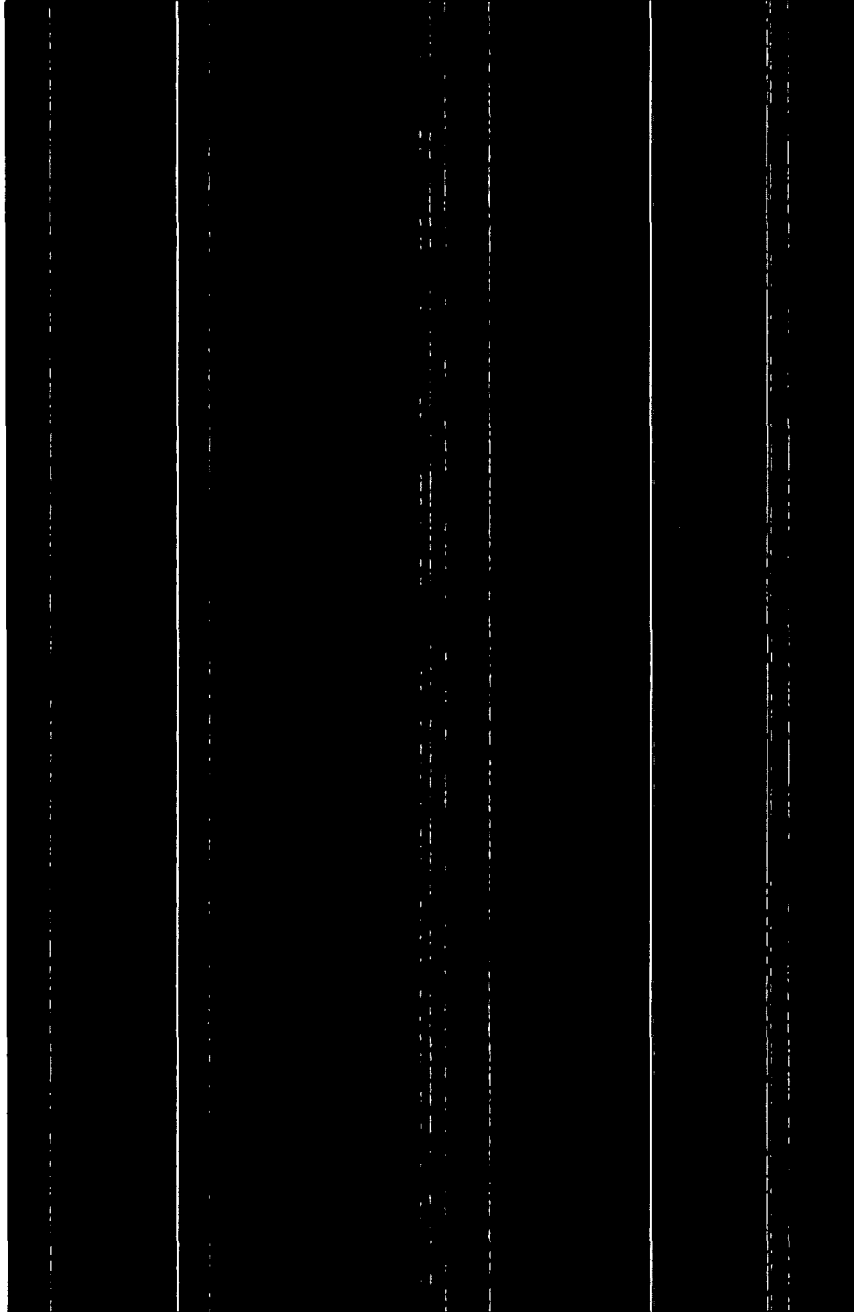


Report No. S8569-02



BUSINESS
SENSITIVE

Photograph of Test Setup:
Conducted Disturbance
ENV 50141

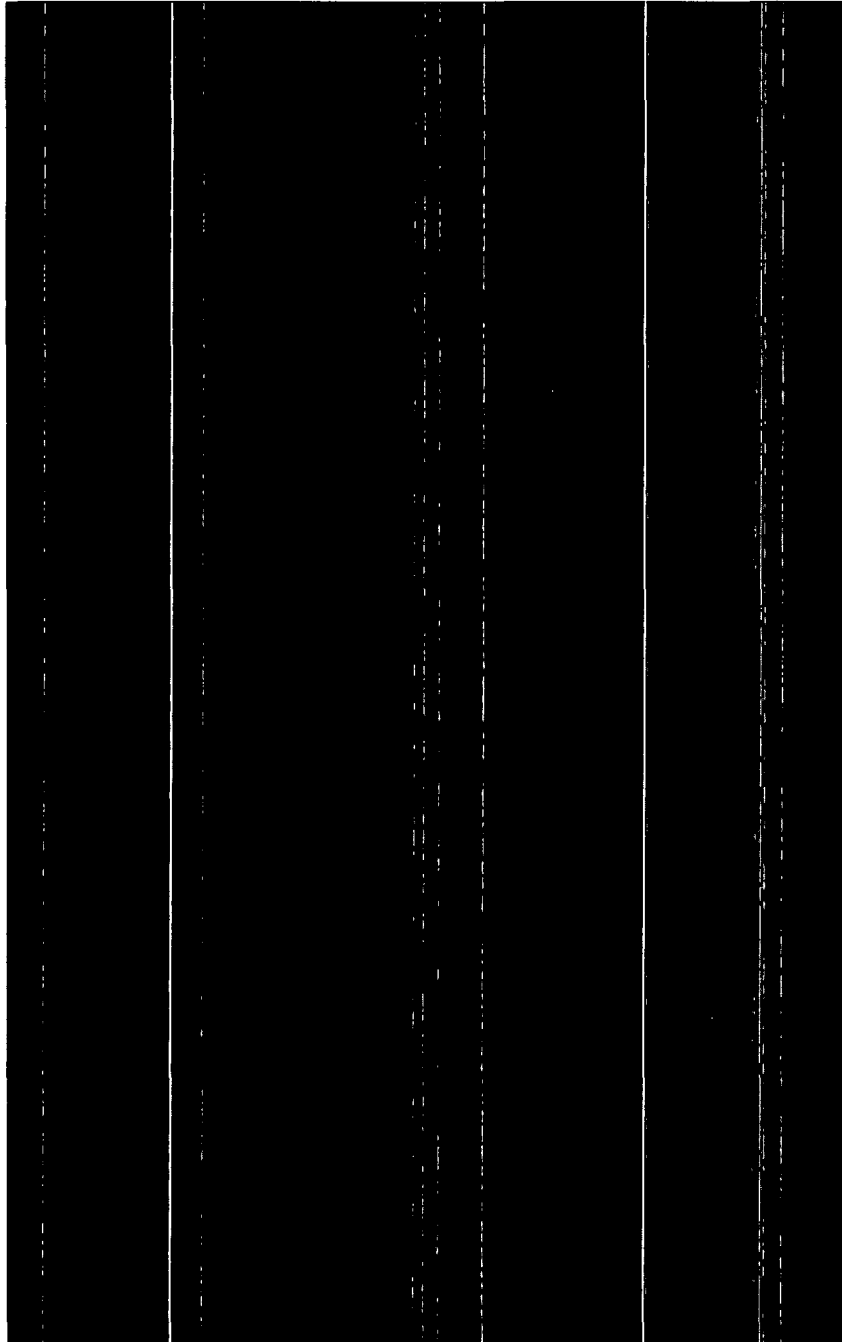




Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Conducted Disturbance
ENV 50141

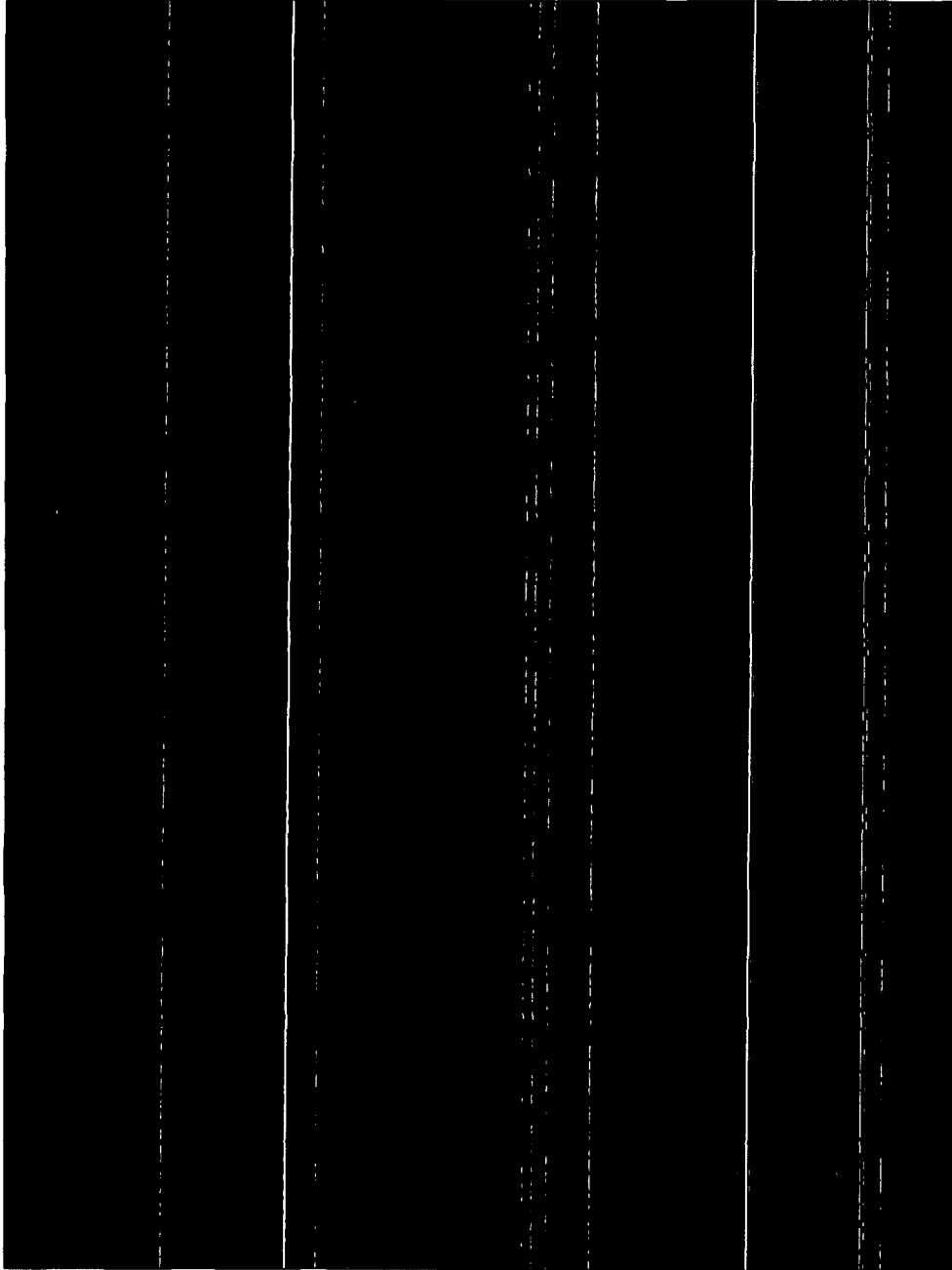




Report No. S8569-02

 BUSINESS SENSITIVE

Photograph of Test Setup:
Magnetic Field
EN 61000-4-8



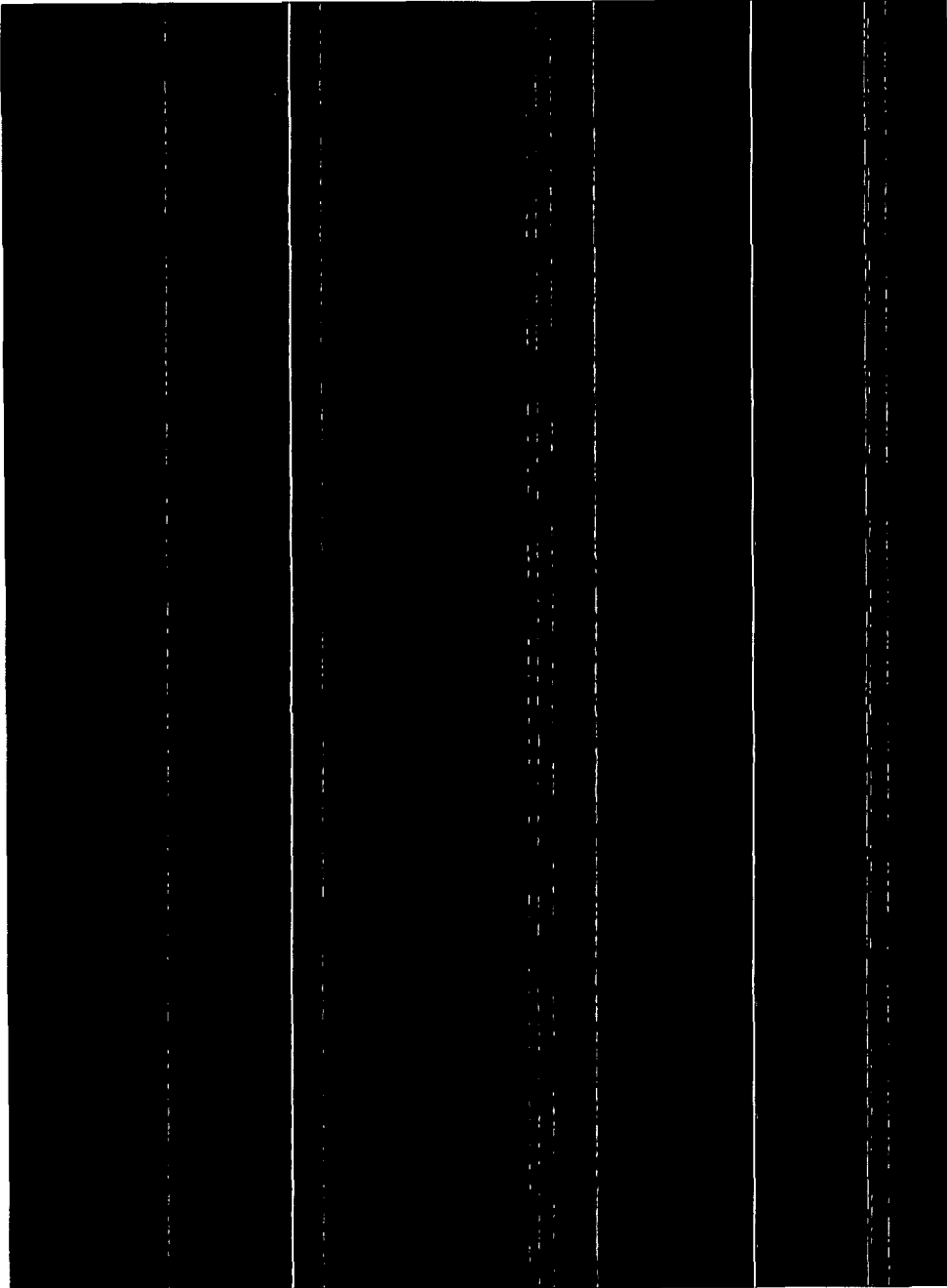


Report No. S8569-02



BUSINESS
SENSITIVE

Photograph of Test Setup:
Voltage Dips
EN 61000-4-11





Report No. S8569-02



BUSINESS
SENSITIVE

Photograph of Test Setup:
Radiated Emissions
EN 55011

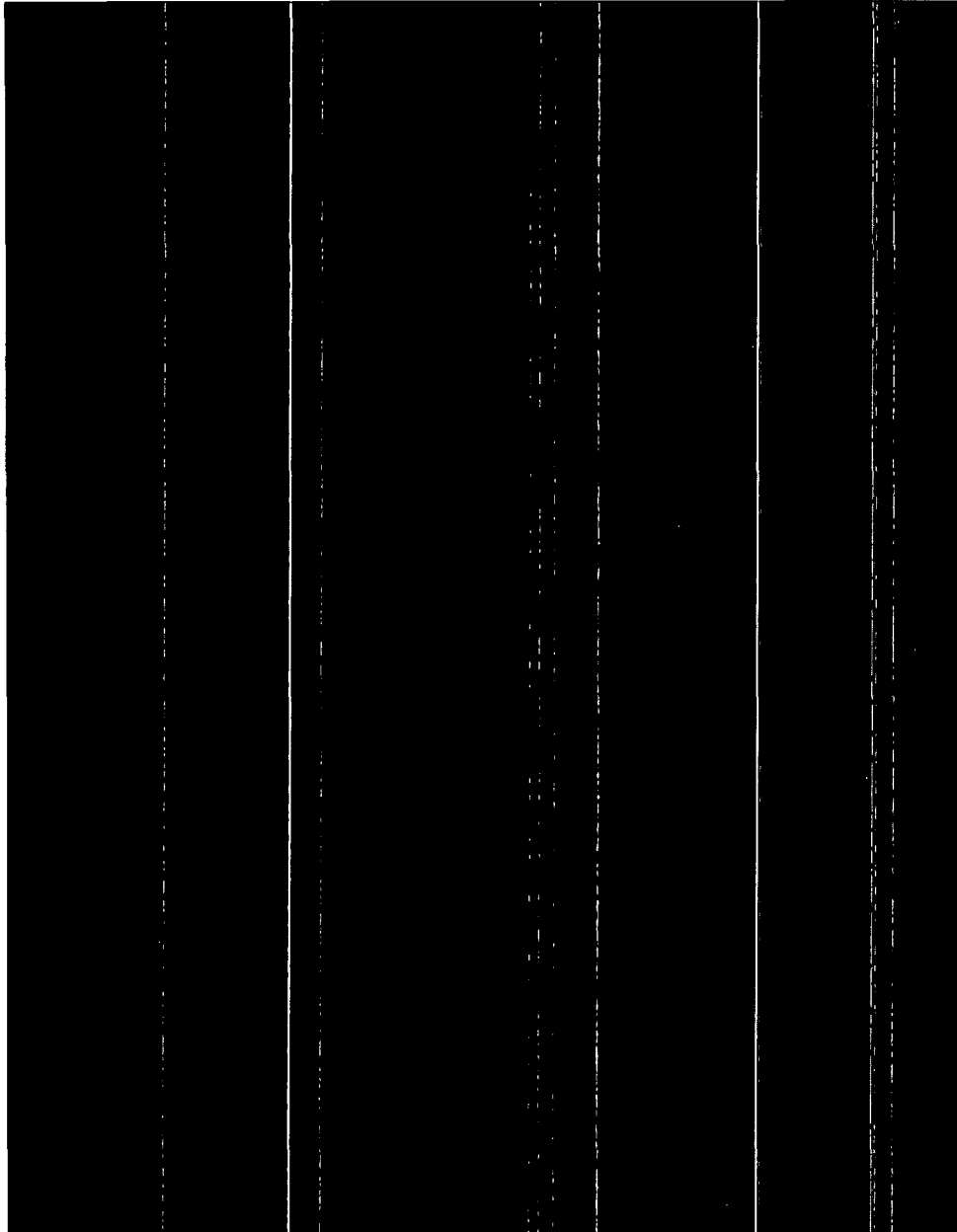




Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Radiated Emissions
EN 55011

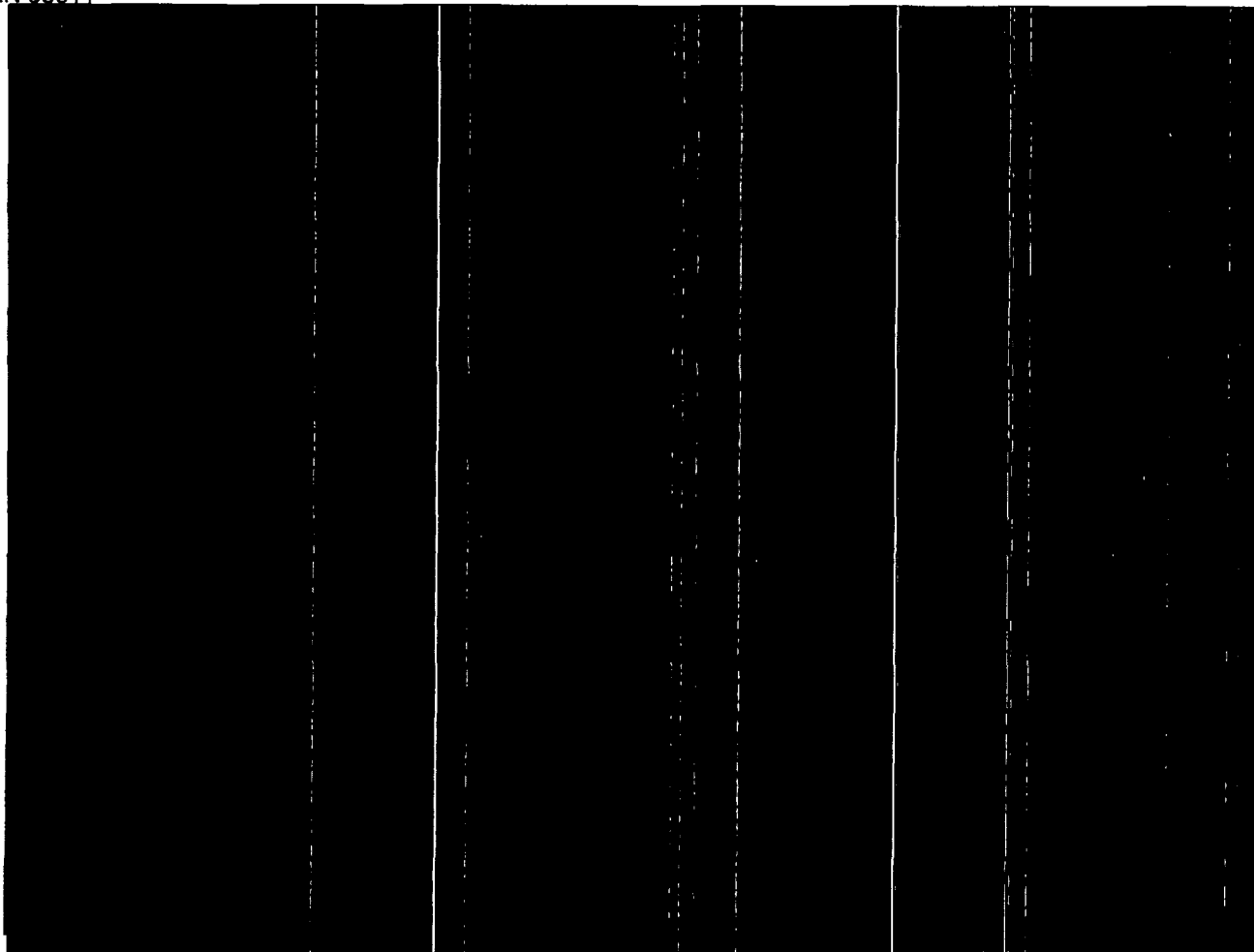




Report No. S8569-02

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Conducted Emissions
EN 55011

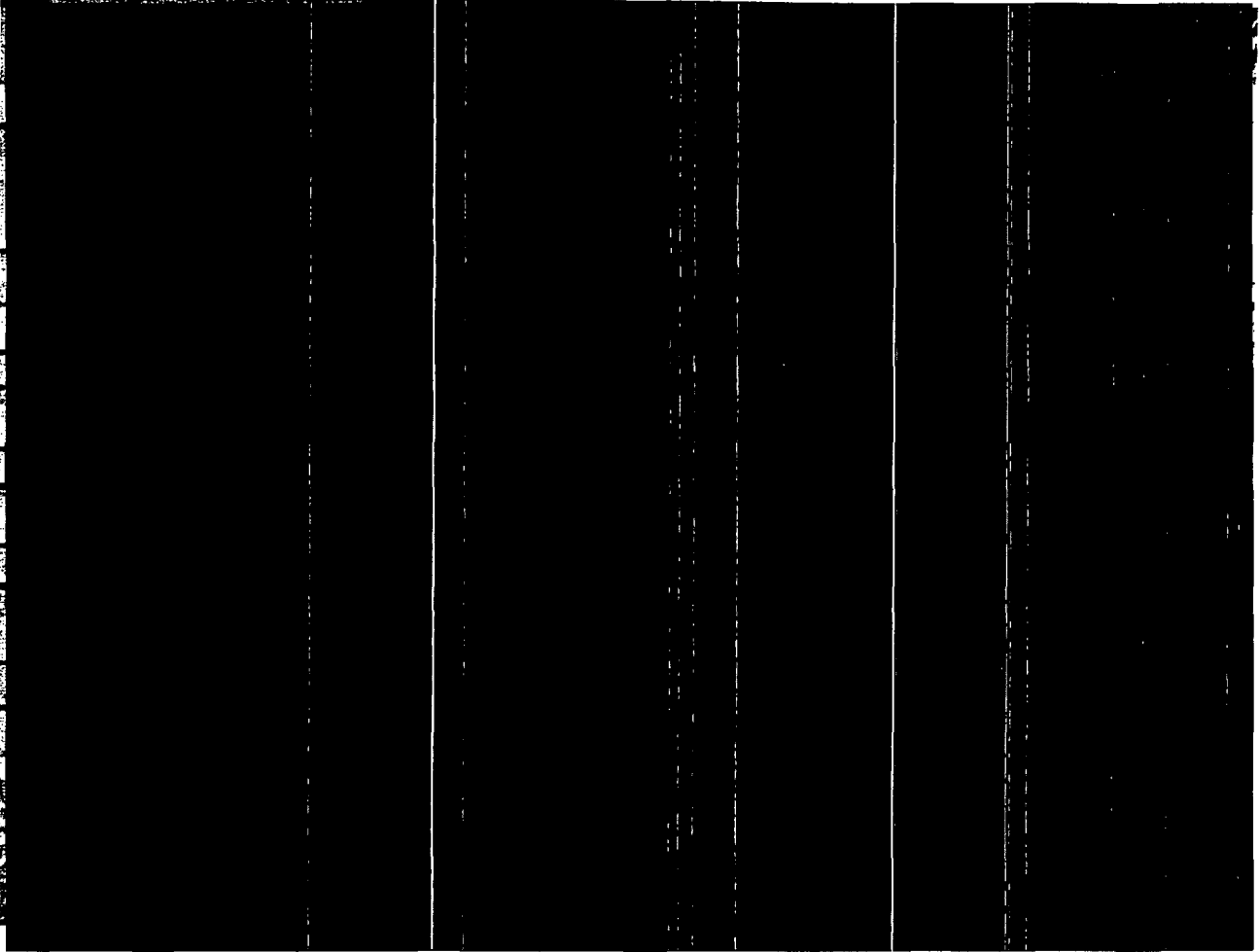




Report No. S8569-02

BUSINESS
SENSITIVE

Photograph of Test Setup:
Conducted Emissions, Power Leads
CE102





PRODUCT SERVICE

Report No. S8569-02

**BUSINESS
SENSITIVE**

Photograph of Test Setup:
Conducted Emissions, Power Leads
CE102





Report No. S8569-02

Appendix B

Product Information Form(s)



Report No. S8569-02

BUSINESS SENSITIVE

CUSTOMER INFORMATION	
COMPANY NAME:	SORRENTO ELECTRONICS
COMPANY ADDRESS:	10240 Flanders Court San Diego, CA 92121
PHONE NUMBER:	619 457 8954 / 8820
FAX NUMBER/E-MAIL ADDRESS:	619 457 8933 / walterwong@gat.com
CUSTOMER CONTACT:	[REDACTED]
PRODUCT DESCRIPTION	
NAME, MODEL, SERIAL # OF EUT:	RM-1000 Radiation Monitor, Two channel
DESCRIPTION OF EUT:	[REDACTED]
Components of EUT	
[REDACTED]	[REDACTED]
OPERATING MODE(S):	Equipment will be electrically energized and placed in normal operation. The low range channel monitors its radiation source strength. The high range channel is placed in test mode to provide simulated radiation level for display during test.
[REDACTED]	[REDACTED]



Report No. S8569-02

BUSINESS
SENSITIVE

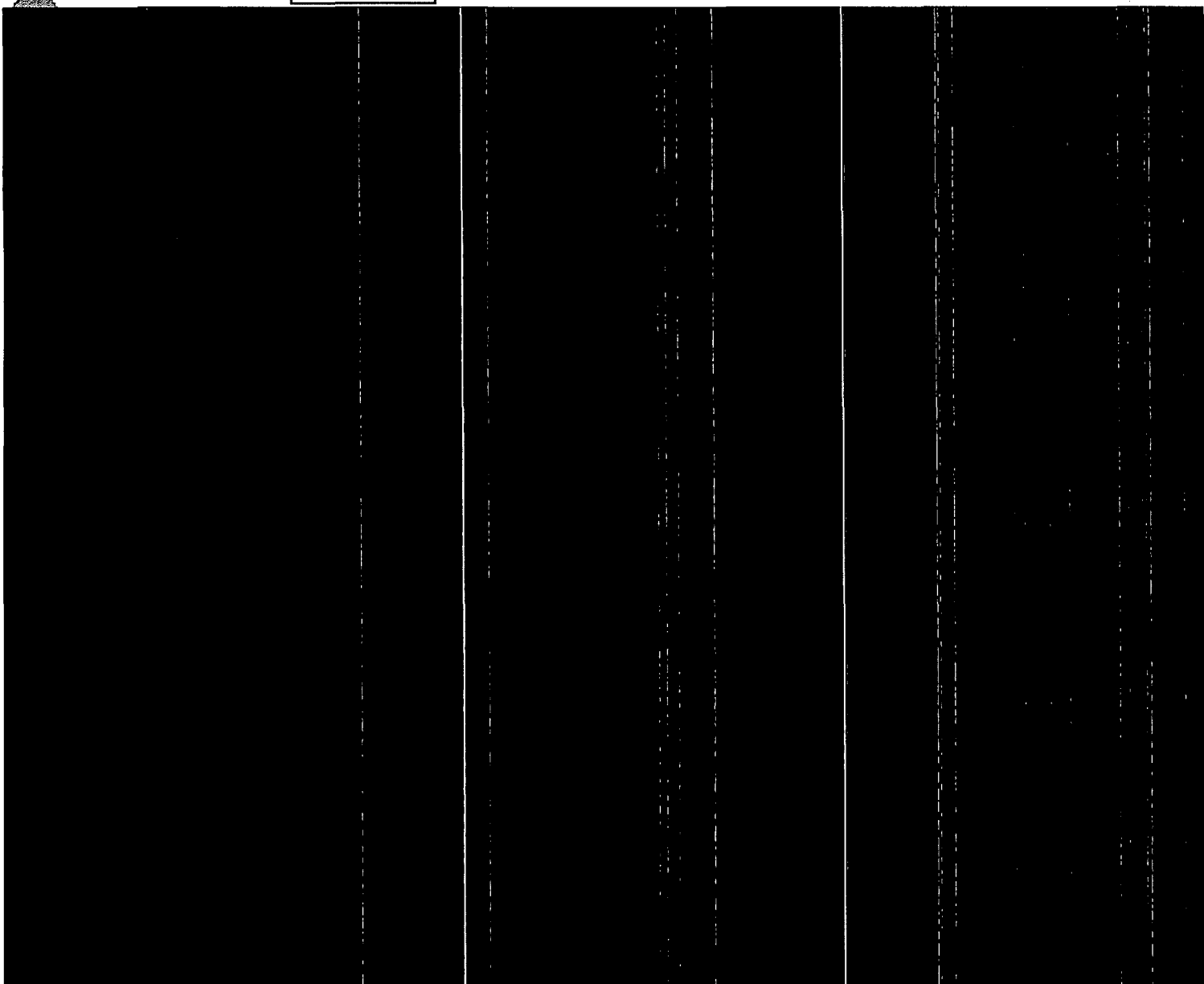




PRODUCT SERVICE

Report No. S8569-02

BUSINESS
SENSITIVE





Report No. S8569-02

Appendix C

Change History

Not Applicable



Report No. S8569-02

Appendix D

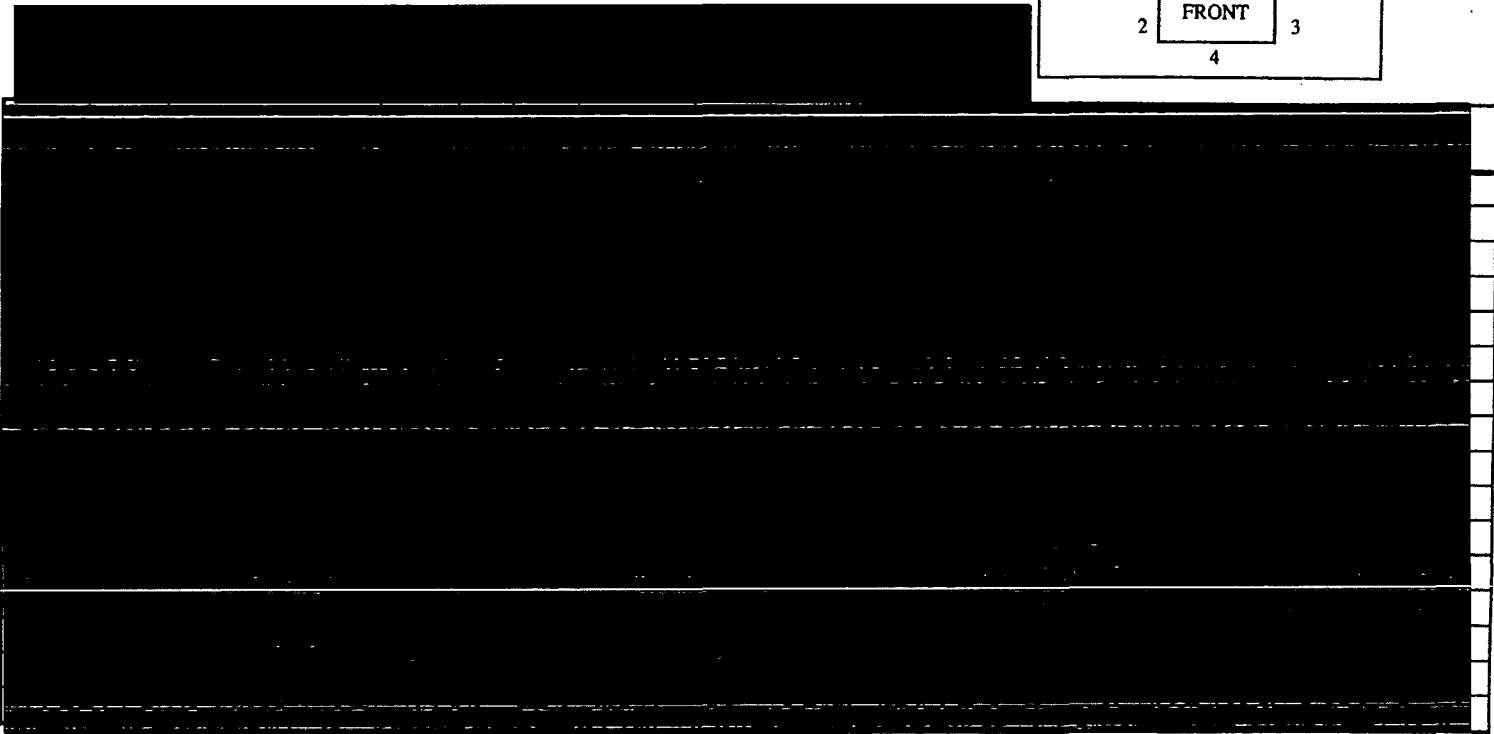
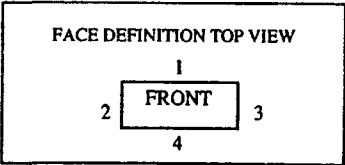
Supplemental Information

BUSINESS SENSITIVE



RADIATED IMMUNITY

Test Report #: S-8569 Test Area: SR-5
 Test Method: RADIATED IMMUNITY ENV 50140 Date: 01 DEC 98
 Tested per customer test procedure. EUT POWER:
 230 Vac/50 Hz 120 Vac/60 Hz
 EUT Model #: RM 1000 Other: _____
 EUT Description: RADIATION MONITOR Temperature: 23 °C
 Air Pressure: 1010 kPa



Tested by: _____
 Reviewed: _____
 Printed: _____ Signature: _____

RADIMU.DOC Rev 05.97



PRODUCT SERVICE



Report No. S8569-02

REVISIONS																													
REV	DESCRIPTION																						DATE	APPROVED					
<p>INFORMATION</p> <p>NOV 25 1998</p> <p>ONLY</p> <div style="display: flex; justify-content: space-around; align-items: center; margin-top: 20px;"> <div style="background-color: black; width: 150px; height: 100px;"></div> <div style="border: 1px solid black; padding: 5px; text-align: center;"> <p>DOCUMENT CLASSIFICATION CHANGE</p> </div> </div>																													
SHEET	29	30	31	32	33	34	35	36	37	38	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54	55	56	
REV																													
SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22	23	24	25	26	27	28	
REV																													
DRAWN <i>James Luciano</i>		DATE <i>11-23-98</i>		<p>RM-1000 EMC EMISSION AND SUSCEPTIBILITY TEST PROCEDURE</p>																									
CHECKED <i>J. Ryan</i>		DATE <i>11-24-98</i>																											
ENCHR <i>James Luciano</i>		DATE <i>11-23-98</i>																											
ENCHR REV <i>Ch. Wong</i>		DATE <i>11-23-98</i>																											
PROJ MGR <i>Ch. Wong</i>		DATE <i>11-24-98</i>																											
MFG ENGR				SIZE	FSOM NO.	DRAWING NO.		REV																					
				A	58307	04509005		-																					
QUAL MGR <i>C.M. Miller</i>		DATE <i>11-24-98</i>		RELEASE	<i>Ch. Wong 11/23/98</i>		SHEET																						
				DRAWING LEVEL	3		1 OF 23																						

04509005

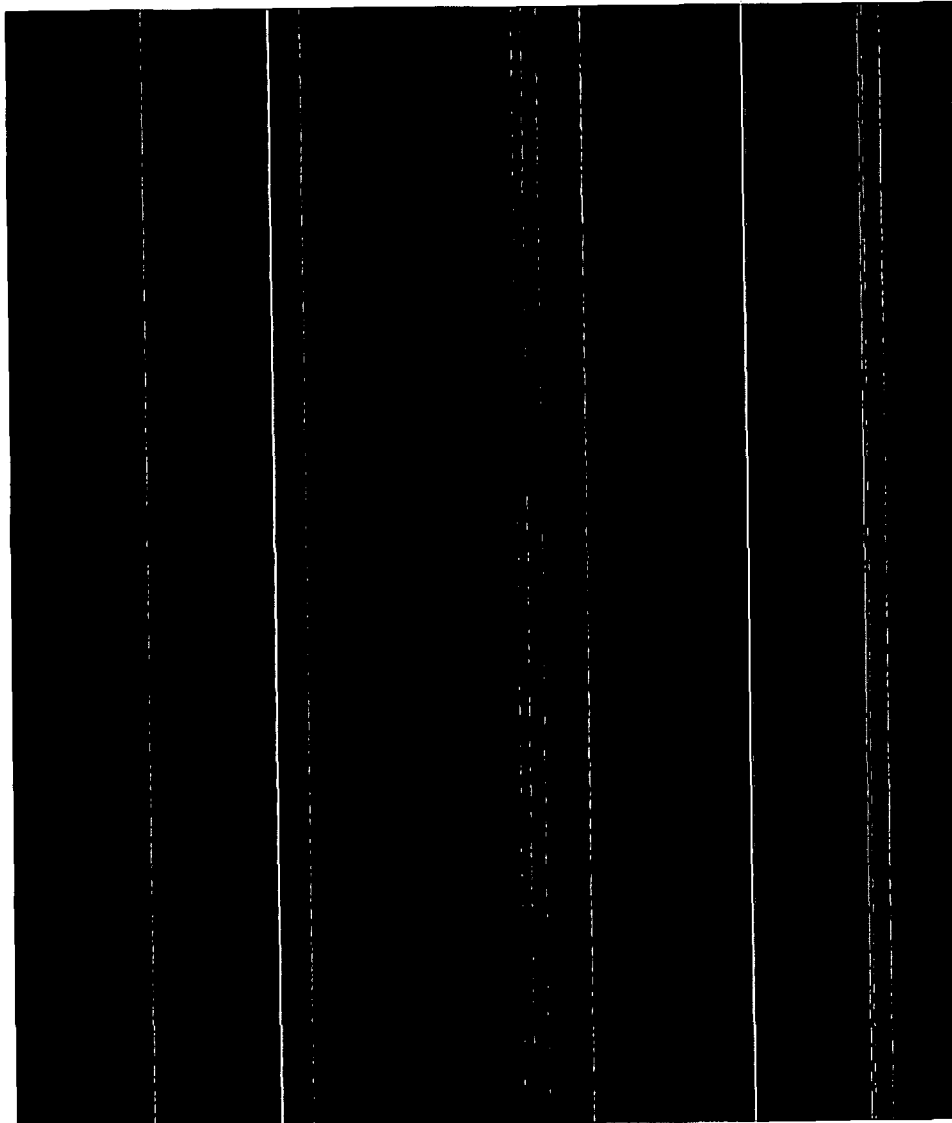
SE-0009 3/97



Report No. S8569-02

BUSINESS
SENSITIVE

1 PURPOSE AND SCOPE..... 4
2 REFERENCE DOCUMENTS..... 4
3 EQUIPMENT TO BE TESTED 4
4 ELECTROMAGNETIC EMISSIONS AND SUSCEPTIBILITY REQUIREMENTS 5



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SENSITIVE



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1 PURPOSE AND SCOPE

This Test Procedure (TP) defines the steps necessary to test the Electromagnetic Compatibility (EMC) of the Sorrento Electronics (SE) RM-1000 Radiation Monitor. The EMC test consists of Electromagnetic Interference and Radio Frequency Interference (EMI/RFI) Emissions and Susceptibility. The TP establishes and the test fulfills the requirements for the TVA/KOLA/BEZNAU RM-1000 EMC test. The TP also establishes and the test fulfills the requirements for testing the Class 1E SE RM-1000 Radiation Monitor to EMC International Standards. The TP includes the SE procedure and references to the Vendor procedure and Test Plan to qualify the Class 1E RM-1000 radiation monitoring processor modules, current to frequency (I/F) converter module and associated equipment, as well as to provide a place for recording such data for future traceability.

2 REFERENCE DOCUMENTS

The EMC standards to which the system will be tested are listed below and are summarized in Table 1 TVA/KOLA/BEZNAU RM-1000 EMC TEST STANDARDS. Note that these are international standards and United States military standards referenced by the EPRI TR-102323-1994 Guidelines for Electromagnetic Interference Testing in Power Plants.

TEST PARAMETER	STANDARDS
Electrostatic Discharge Immunity	EN 61000-4-2 (1995) (IEC 1000-4-2)
Radiated RF Immunity	ENV 50140 (1993) (IEC 1000-4-3)
EFT Immunity	EN 61000-4-4 (1995) (IEC 1000-4-4)
Surge Immunity	EN 61000-4-5 (1995) (IEC 1000-4-5)
LF Conducted RF Immunity	MIL-STD-461D (1993) CS-101
HF Conducted RF Immunity	ENV 50141 (1993) (IEC 1000-4-6)
Magnetic Field Immunity	EN 61000-4-8 (1994) (IEC 1000-4-8)
Voltage Dips, Short Interruptions & Voltage Variations Immunity	EN 61000-4-11 (1994) (IEC 1000-4-11)
Radiated RF Emissions (Commercial)	EN 50081-1 (1992) EN 55022, Class B
Conducted RF Emissions (Commercial)	EN 55022, Class B
Conducted RF Emissions (Industrial)	MIL-STD-461D (1993) CE-102

3 EQUIPMENT TO BE TESTED

The equipment to be tested is:

ITEM	SE Part No.
2 RM-1000 Radiation Monitor Modules: High Range, Low Range	04501000-001
Current to Frequency (I-F) Signal converter	04506150-001
Local Indicator Assembly	03600270-007

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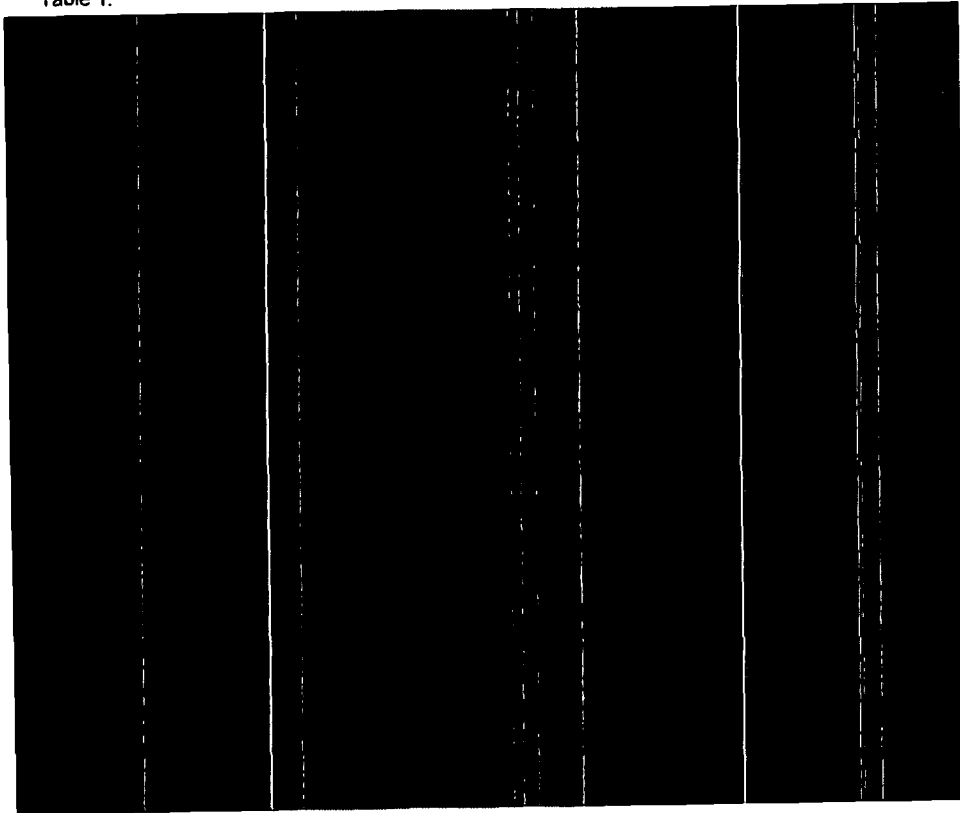
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RD-23 Detector Assembly	03602062-001
RD-1 Detector Assembly	02810059-001
5 volt dc Signal Converter Power Supply	04631151-002
2 RM-1000 24 volt dc Power Supplies	04502005-001
Relay Panel	03604634-001
2 Relays 24 volt dc	50005829-001
Relay Power Supply 24 volt dc	04631151-001
Analog Panel	50015725-001
220 volt ac Line filter	50015670-001
Test Equipment Rack containing some of the above items, interconnecting wires/cables and associated components. Conduit assembly containing the RD-23 detector high voltage and signal cables.	

4 ELECTROMAGNETIC EMISSIONS AND SUSCEPTIBILITY REQUIREMENTS

The Equipment Under Test (EUT) shall be subjected to the conducted and radiated susceptibility standards listed in Section 2 of this Test Procedure. These requirements are summarized in Table 1.

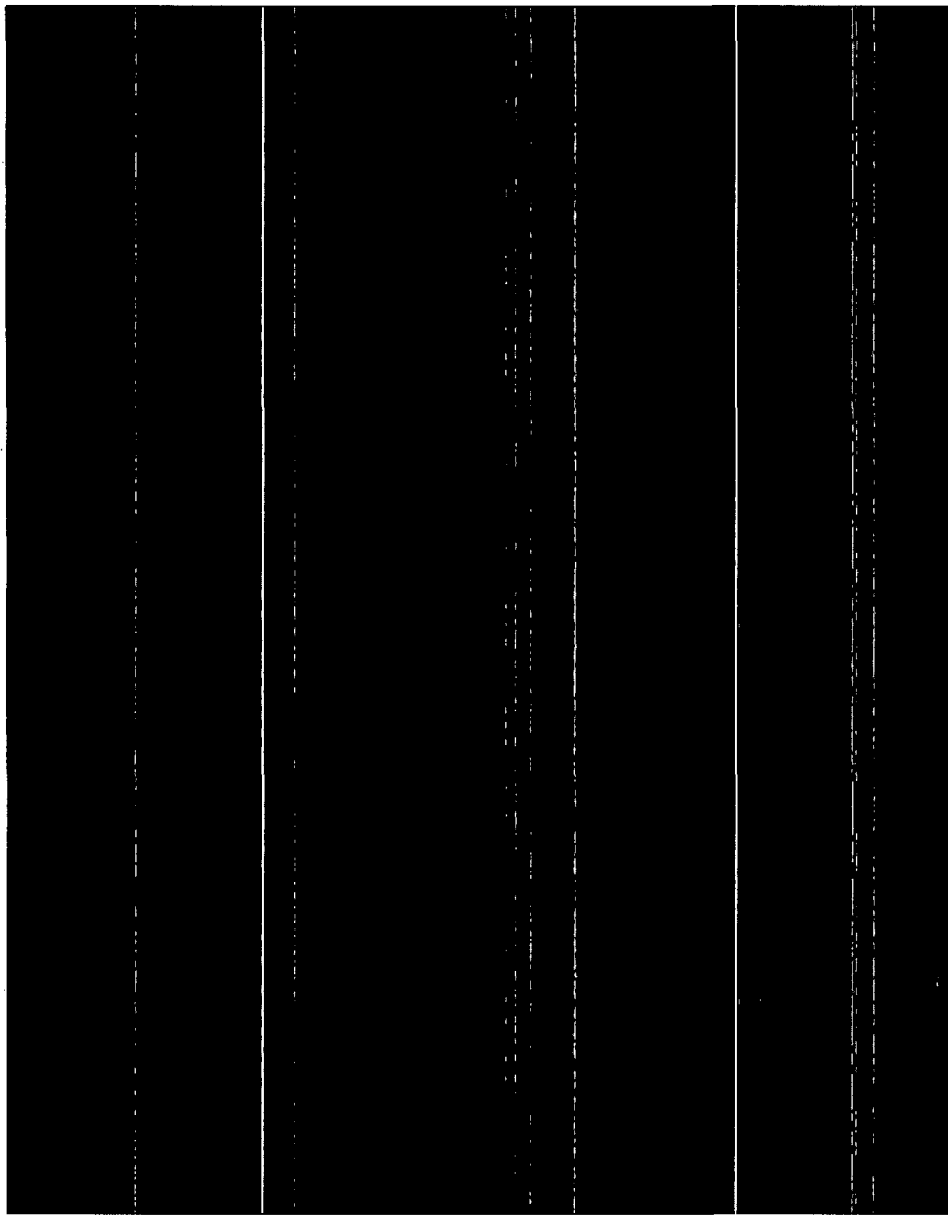


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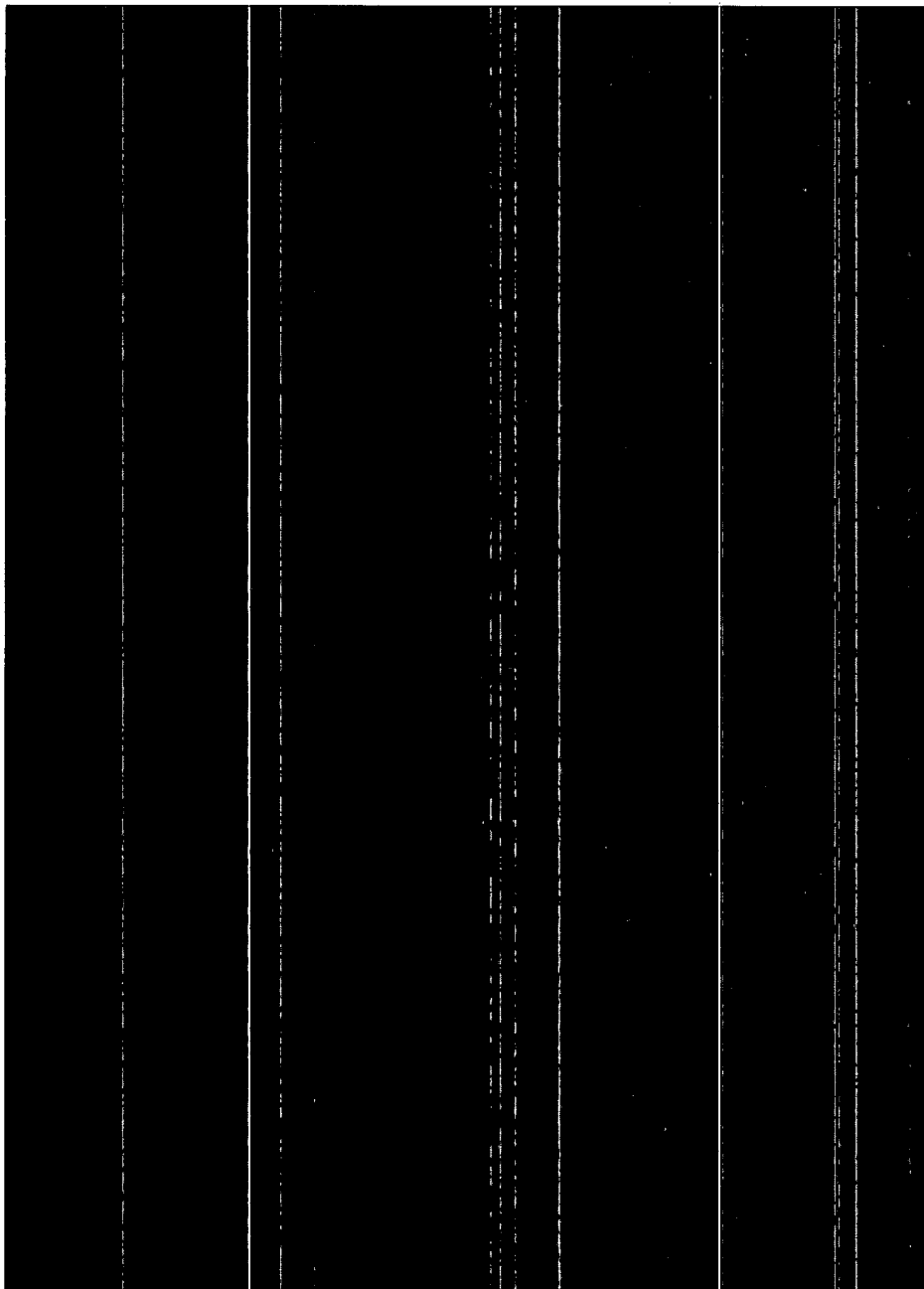
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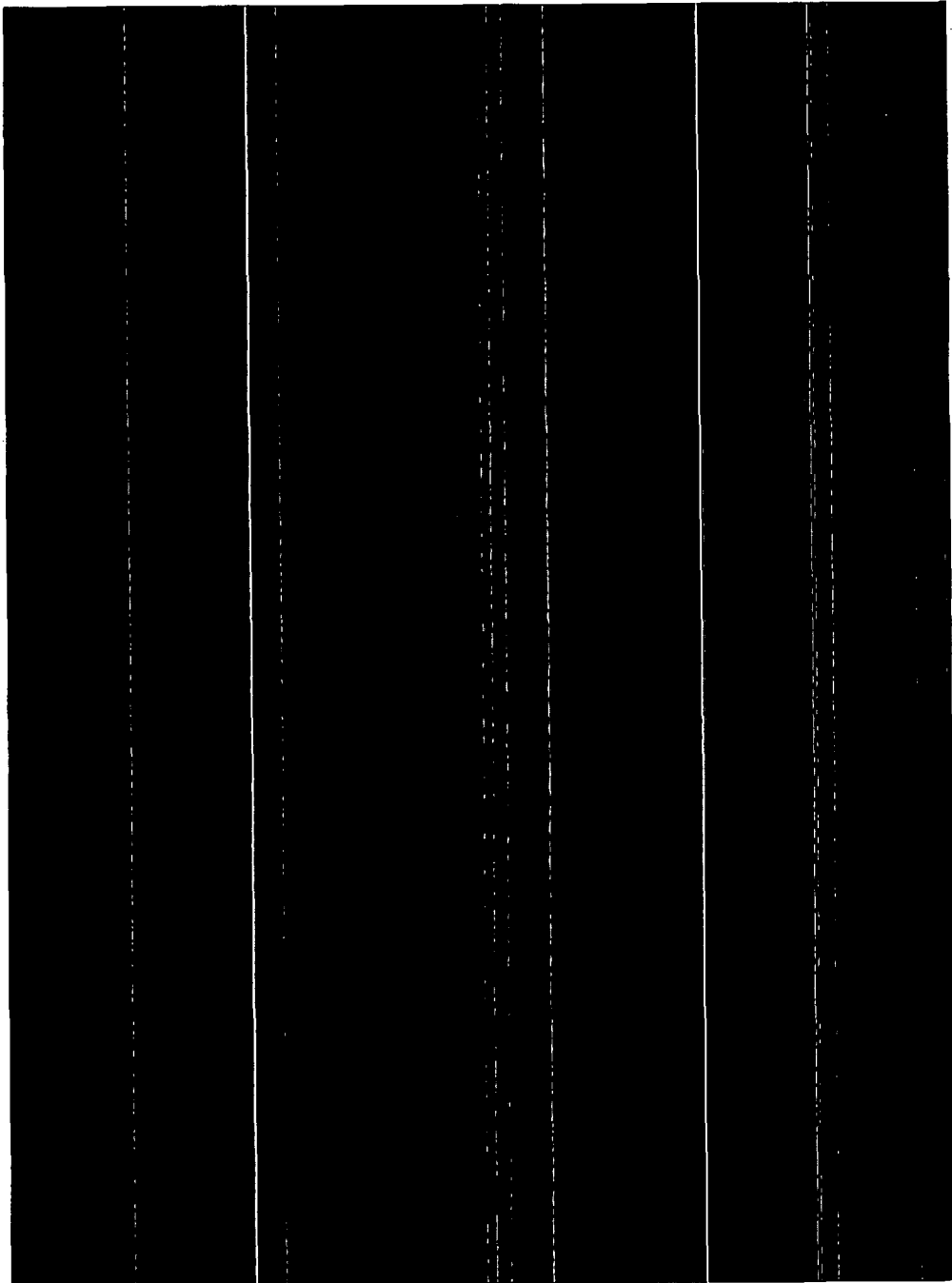
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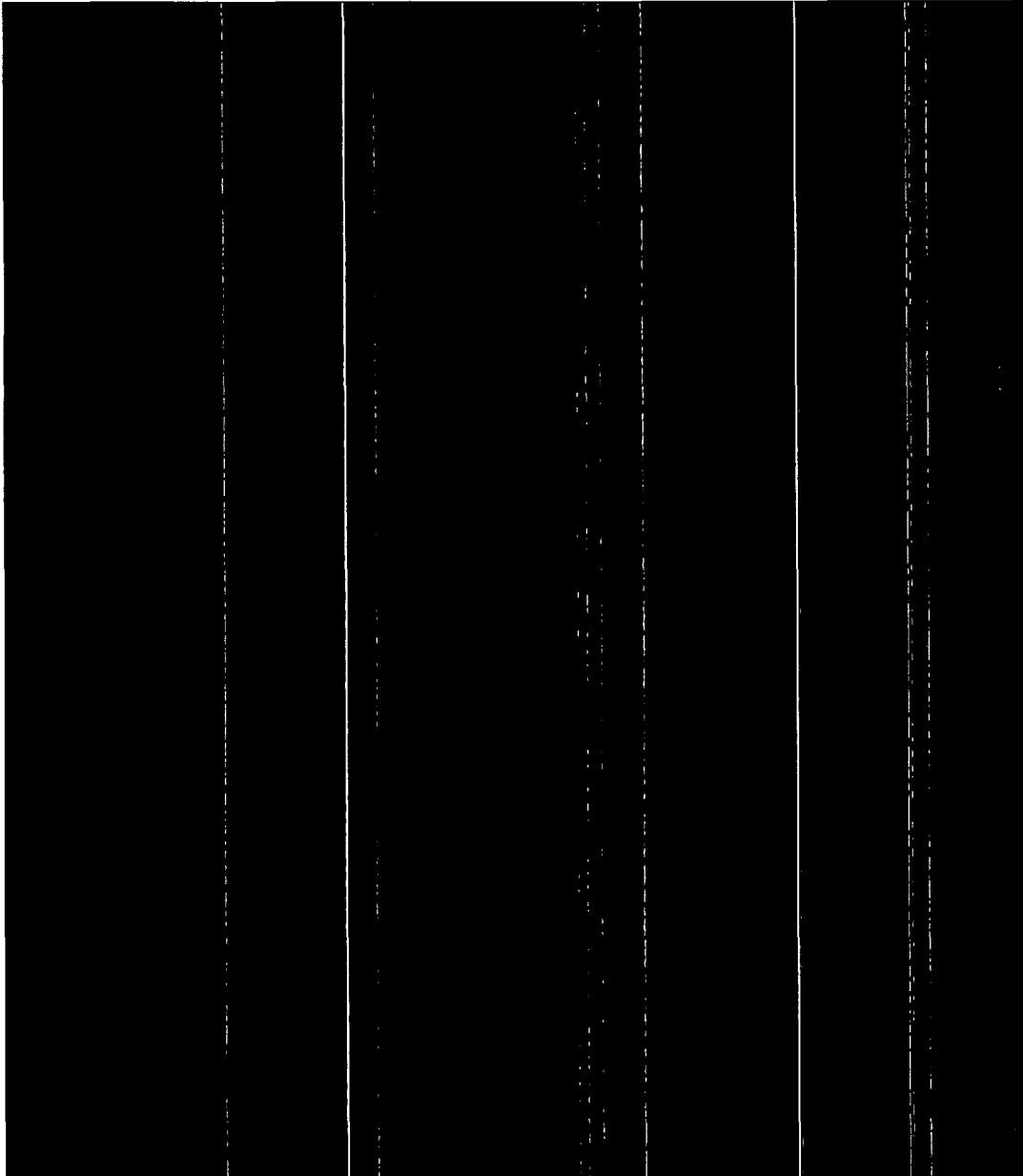
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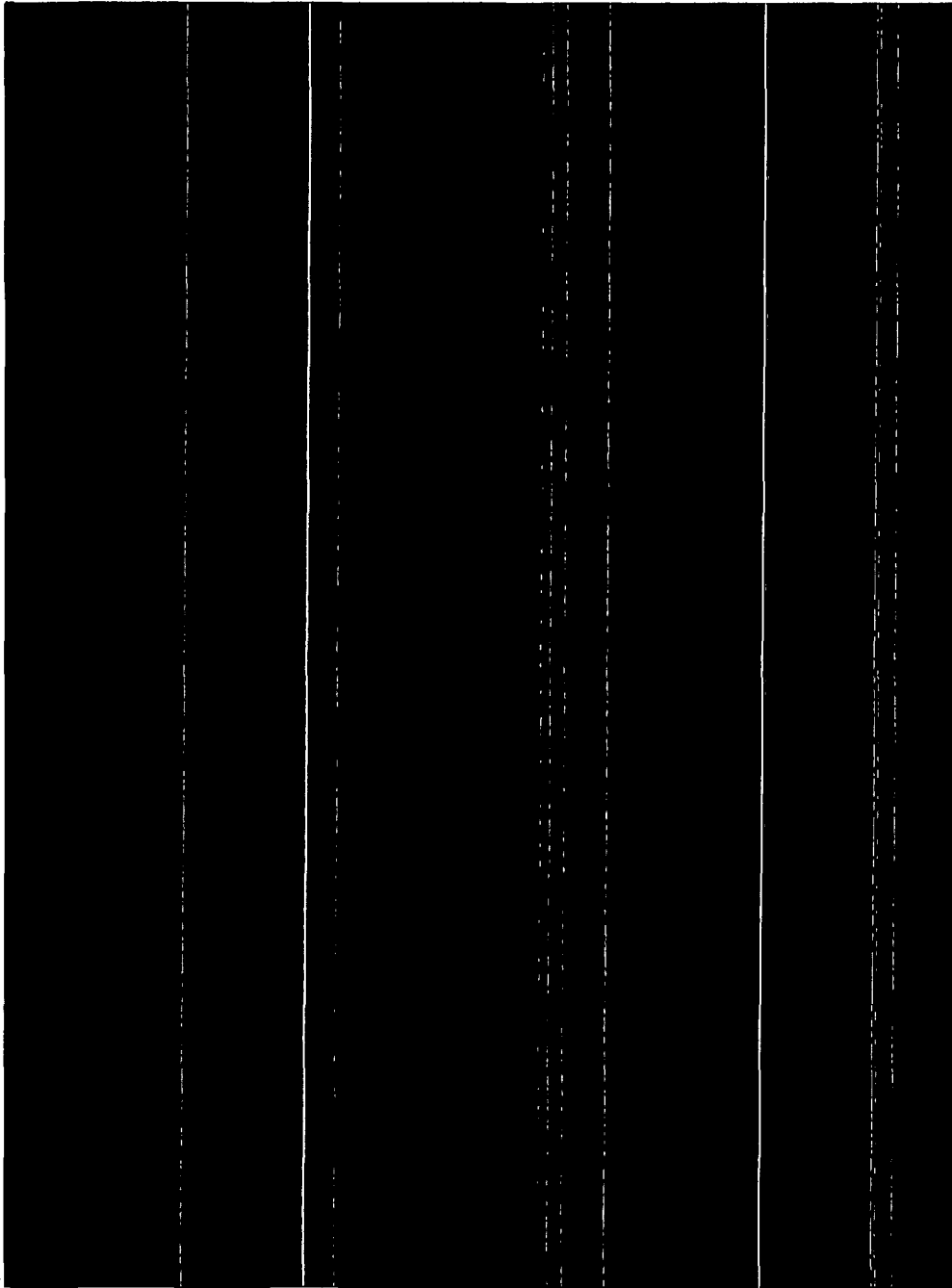
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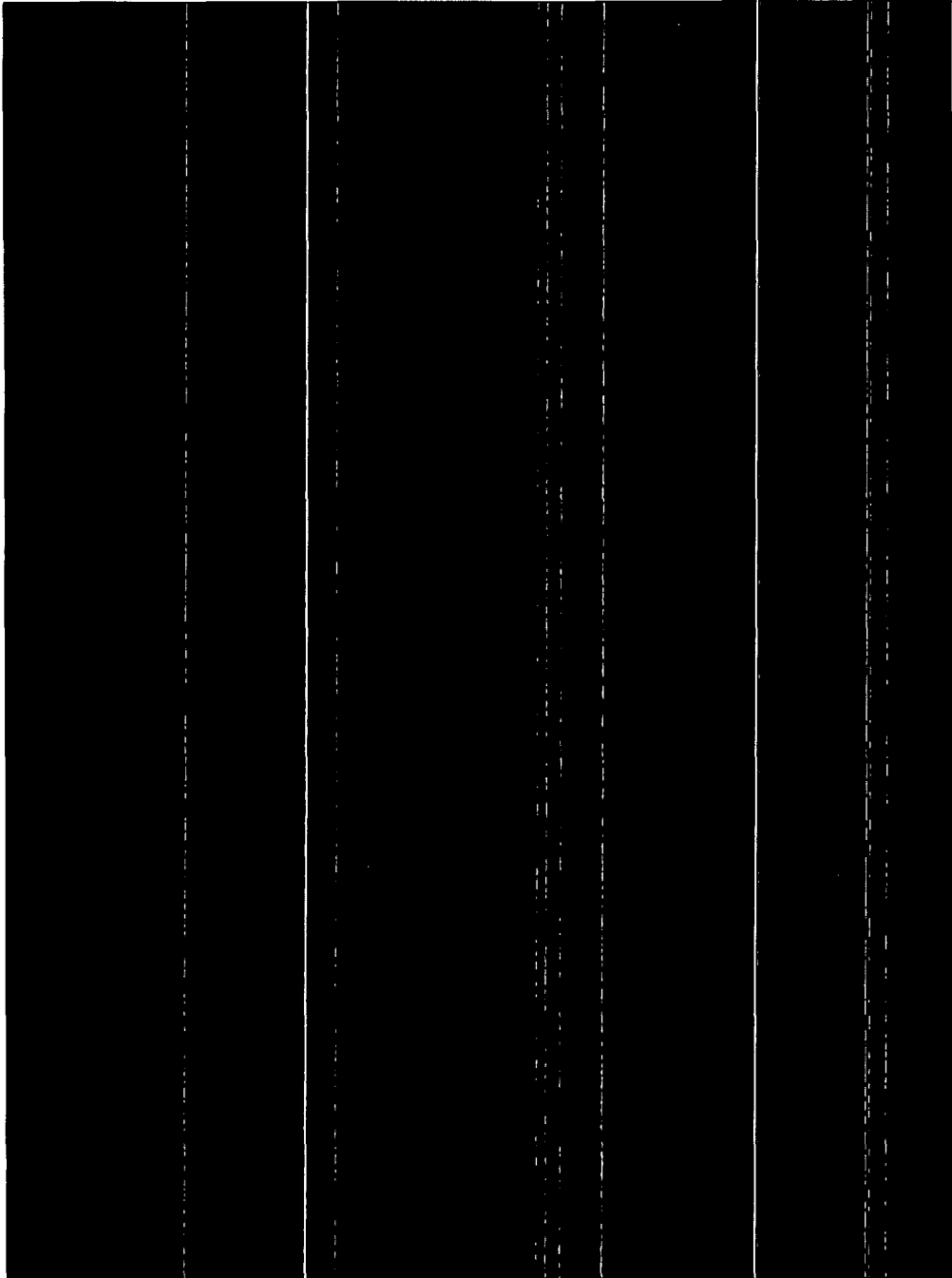
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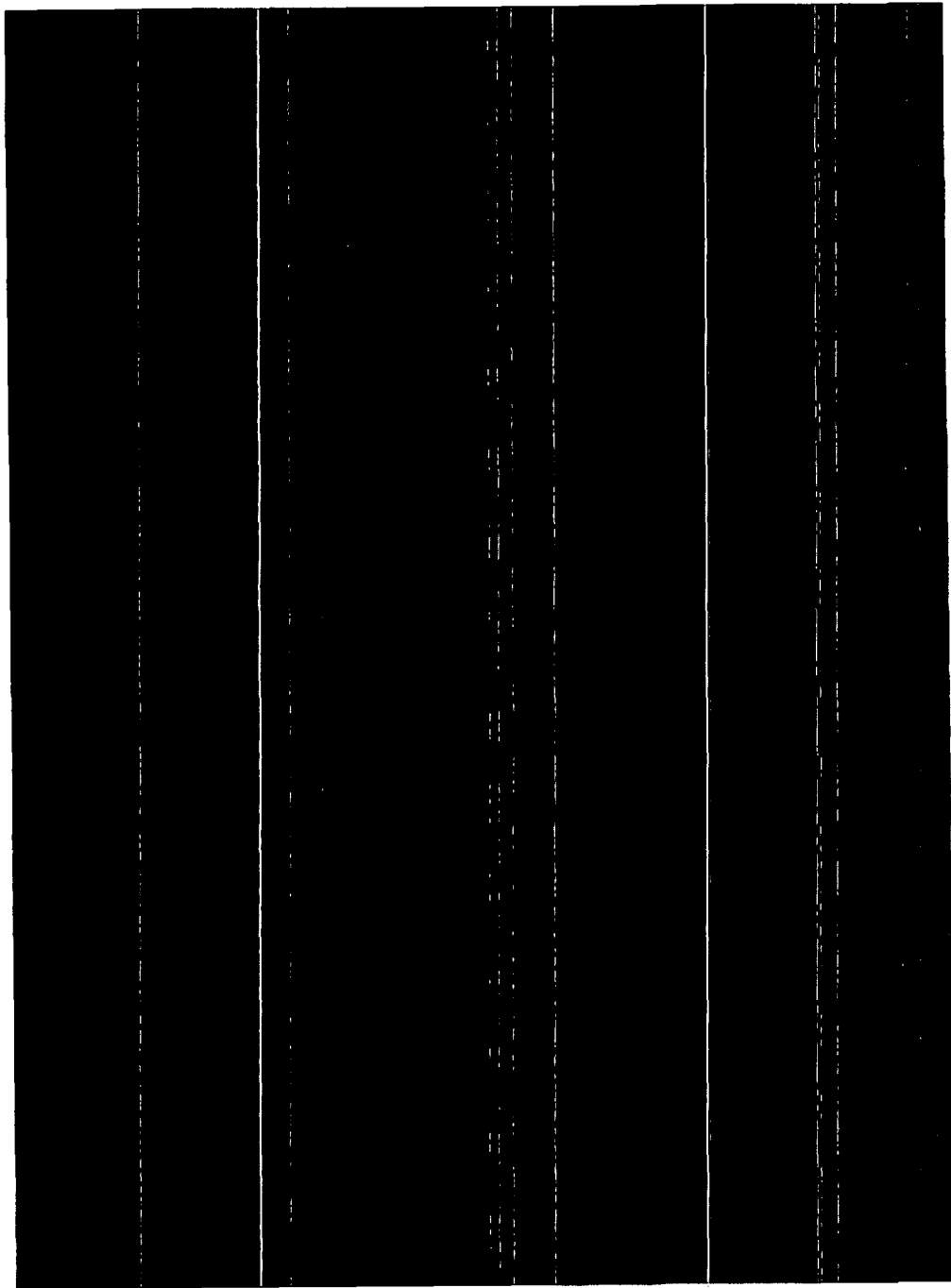
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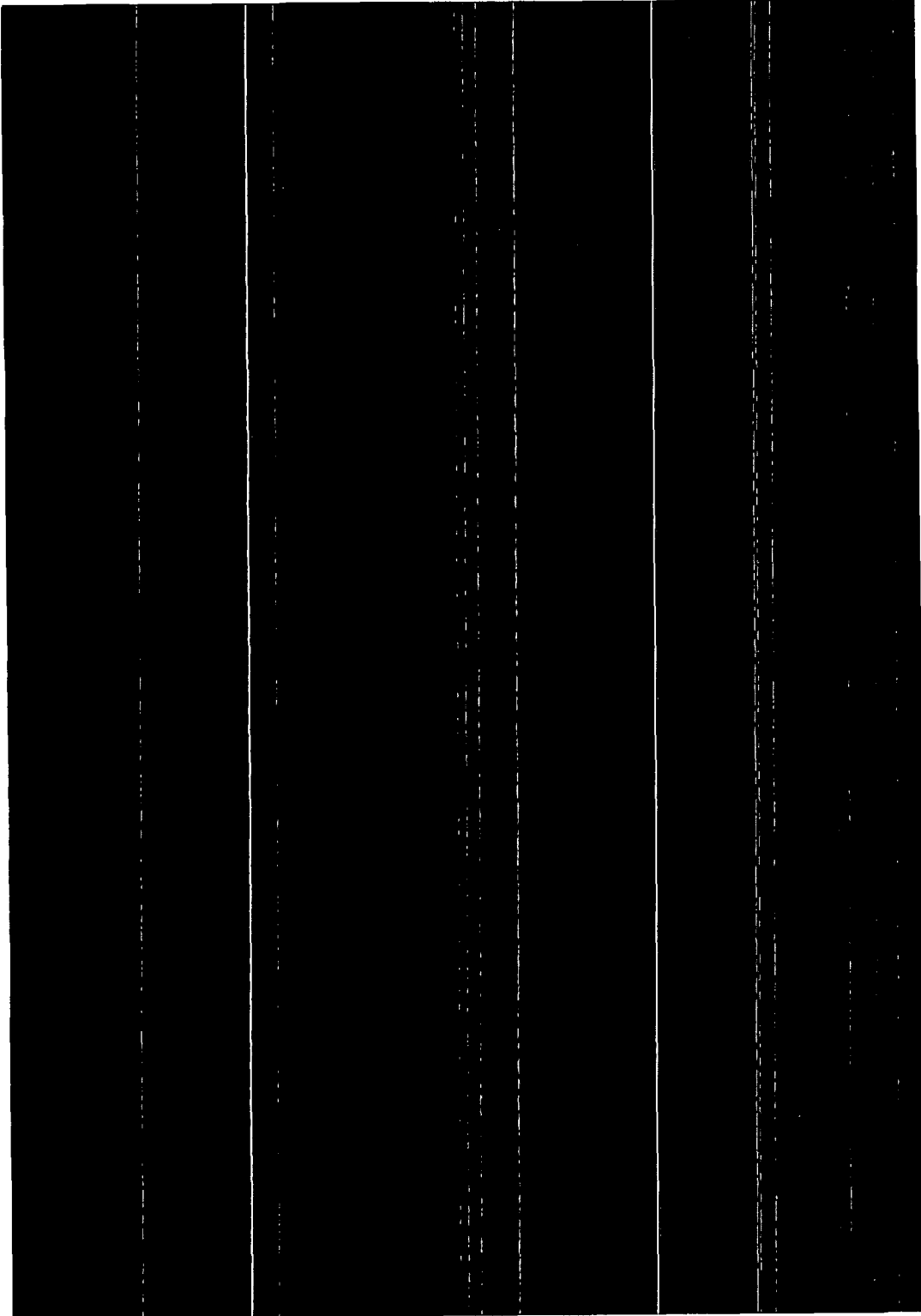
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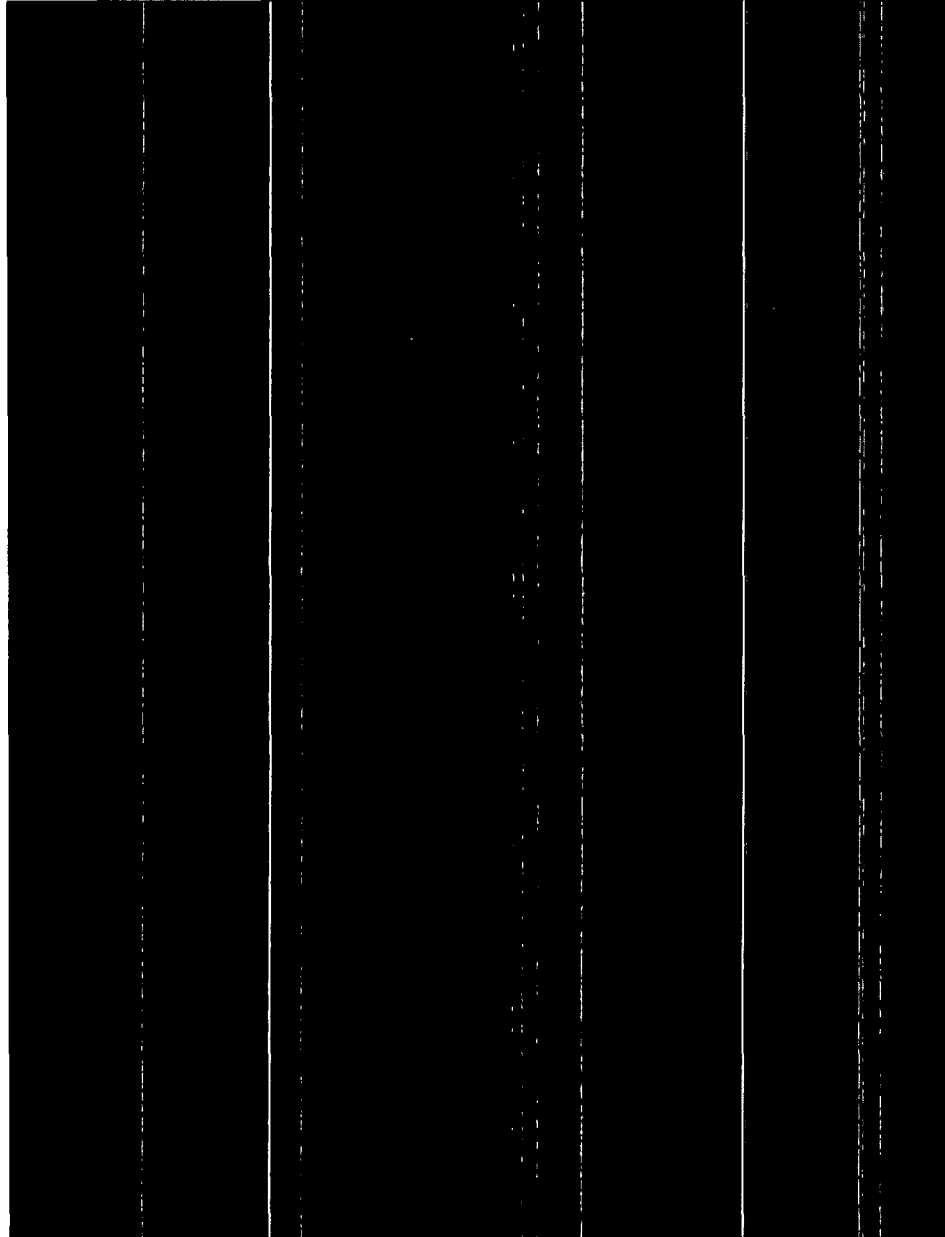




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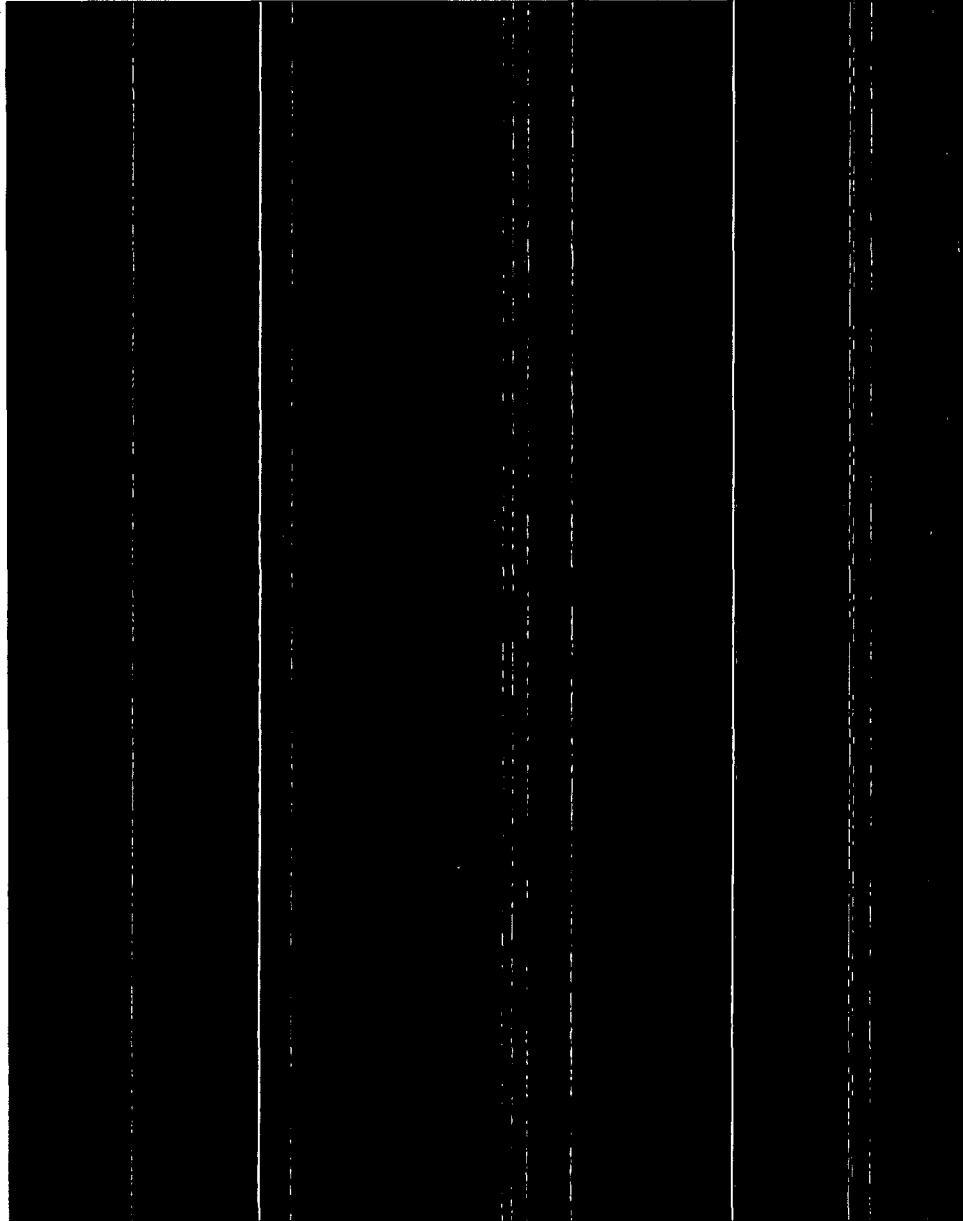
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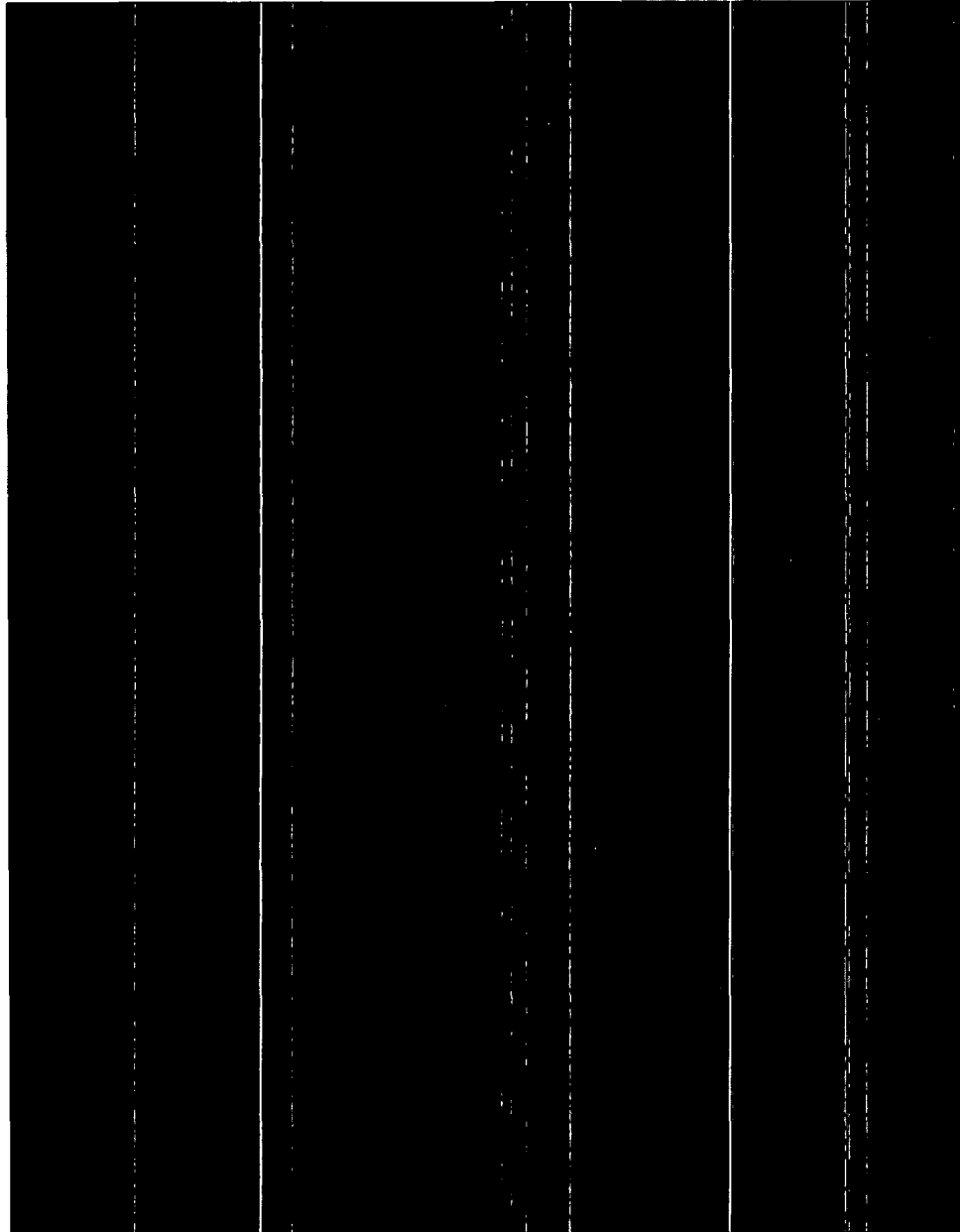
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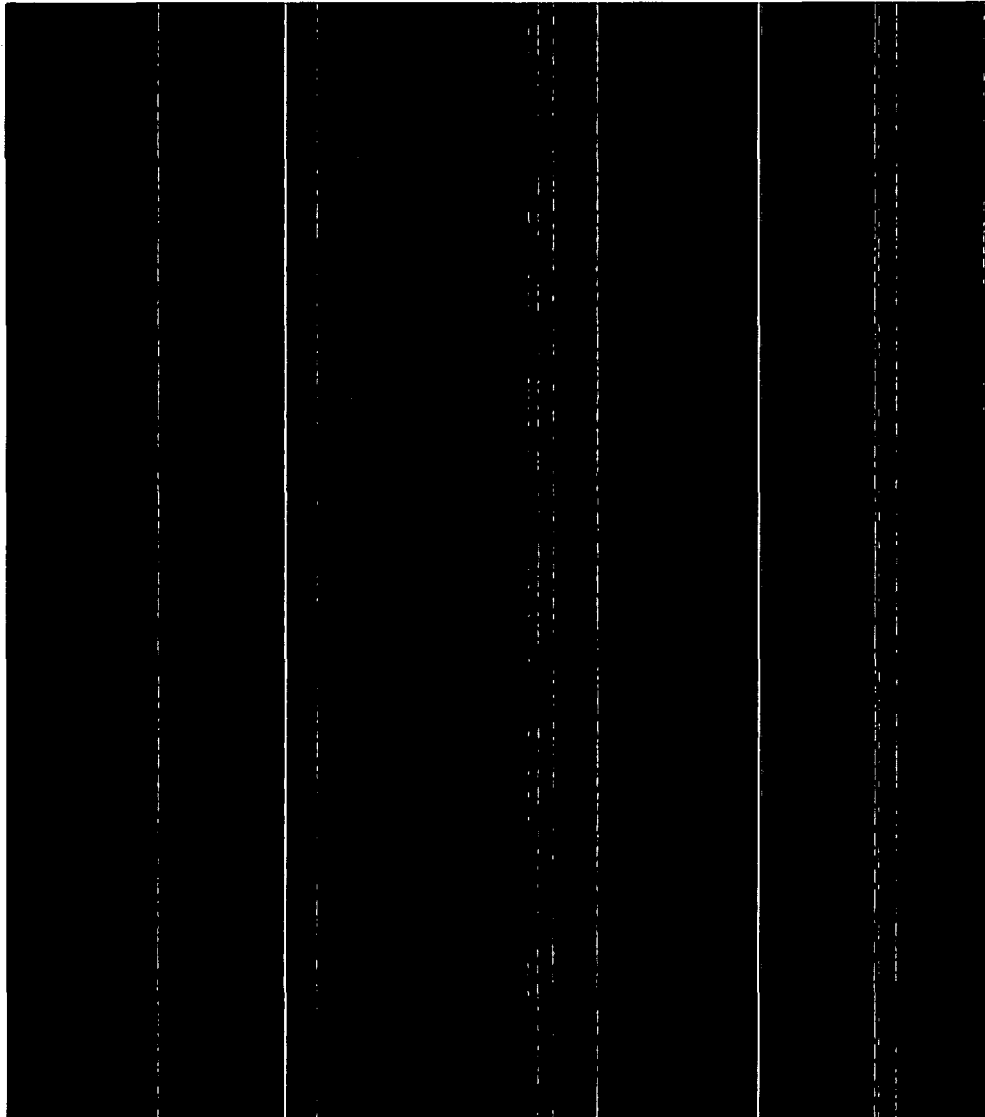
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Appendix A MISCELLANEOUS INFORMATION

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Appendix B PRE EMC FUNCTIONAL TEST

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Appendix C ABBREVIATED EMC FUNCTIONAL TEST

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Appendix D POST EMC FUNCTIONAL TEST

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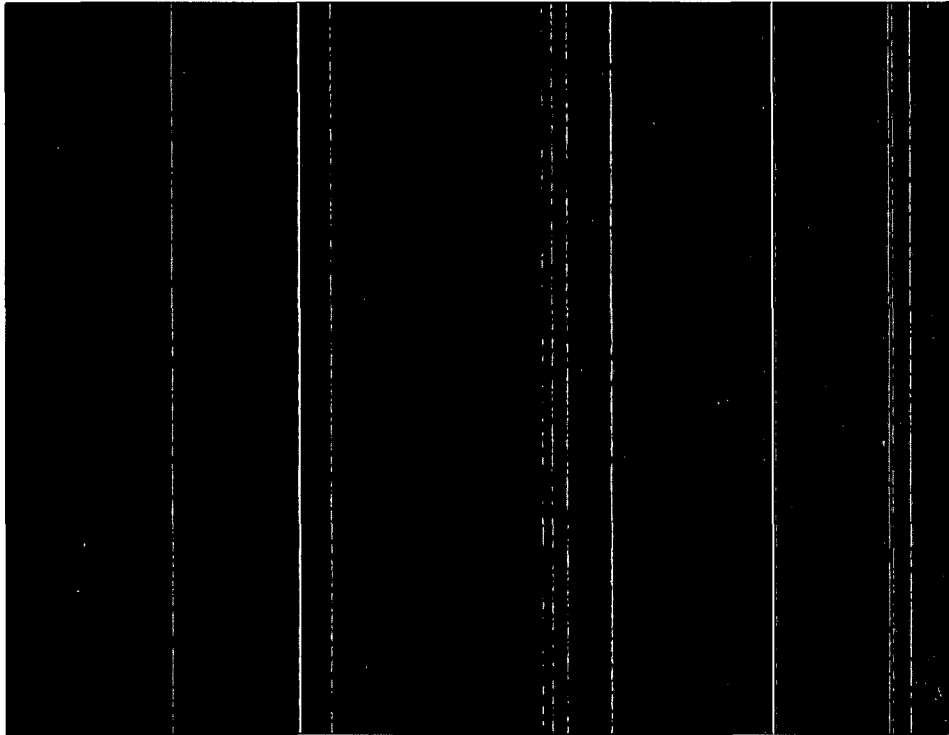
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